Radiation Report

TPS7H6025-SP Total Ionizing Dose (TID) Report

ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H6025-SP radiation hardness-assured 22V, 1.3A, 2.5A, half bridge gate driver. The study was done to determine TID effects at 100krad(Si) high dose rate (HDR). The results show that all samples pass within device specified test limits.

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Trademarks

1 Device Information

1.1 Product Description

The TPS7H6025-SP is a 22V radiation-hardness-assured, gate driver for GaN FETs for space applications. The TPS7H6025-SP is designed for high-frequency, high-efficiency applications. The driver features adjustable dead time capability, small 30ns propagation delay and 5.5ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs which specifies a drive voltage of 5V regardless of supply voltage. The TPS7H6025-SP is packaged in a 56-DCA (HTSSOP) package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 100 krad(Si)	
Device Function	Half Bridge Gate Driver
Die Name	RTPS7H6005A0VM
Package	56-pin HTSSOP DCA
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • Five biased and five unbiased units at 100-krad(Si) levels • Two correlation units
Lot Accept/Reject	Passes 100krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	4095497TI1 / 4476157ML4
HDR Dose Rate	171.3 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MIL-STD-750

Figure 1-1. Device Used in Exposure (Front)

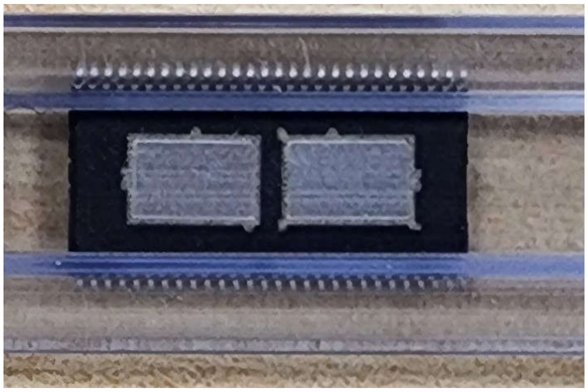


Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H6025-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H6025-SP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 171.3 rad (Si) / s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI's Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Table 2-1. DUT Power Supply Bias and V_{out} Measurements

Power Supply Bias				
	Edge Connector	BUS	Typical	Comments
Power Supply	BUS A	VIN	14VDC	14VDC - Fixed power supply
	BUS D	BOOT	12VDC	14VDCWRTSW - Floating power supply WRT to SW
	BUS B	ASW	0-150V	Increase HV gradually. Recommend using safety interlock HV protection when working with high voltage.
DUT Vout Measurements				
Test Points	TP_VIN	VIN	14V	14VDC - Fixed power supply
	TP_BOOT	BOOT	12V	12VDCWRTSW - Floating power supply WRT to SW
	TP_SW	SW = PSW = ASW	0-150V	SW = PSW = ASW

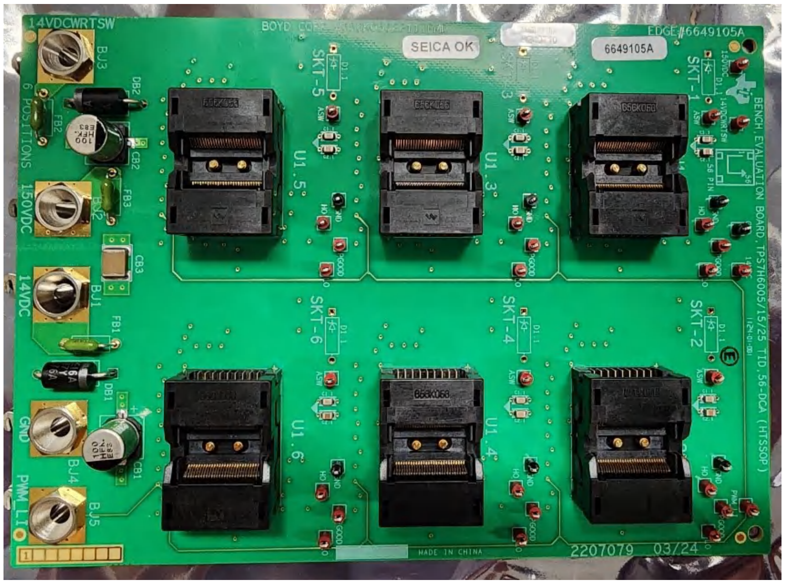


Figure 2-1. HDR TID Hardware

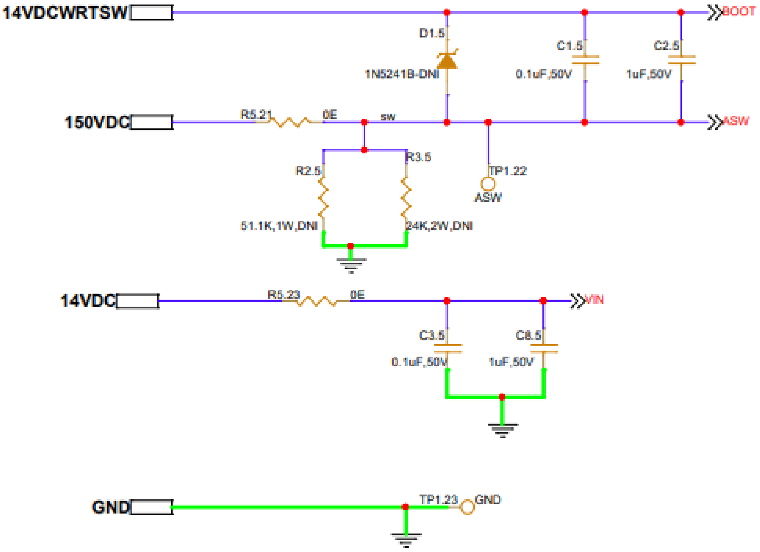


Figure 2-2. Supplies and GND HDR TID Bias Diagram

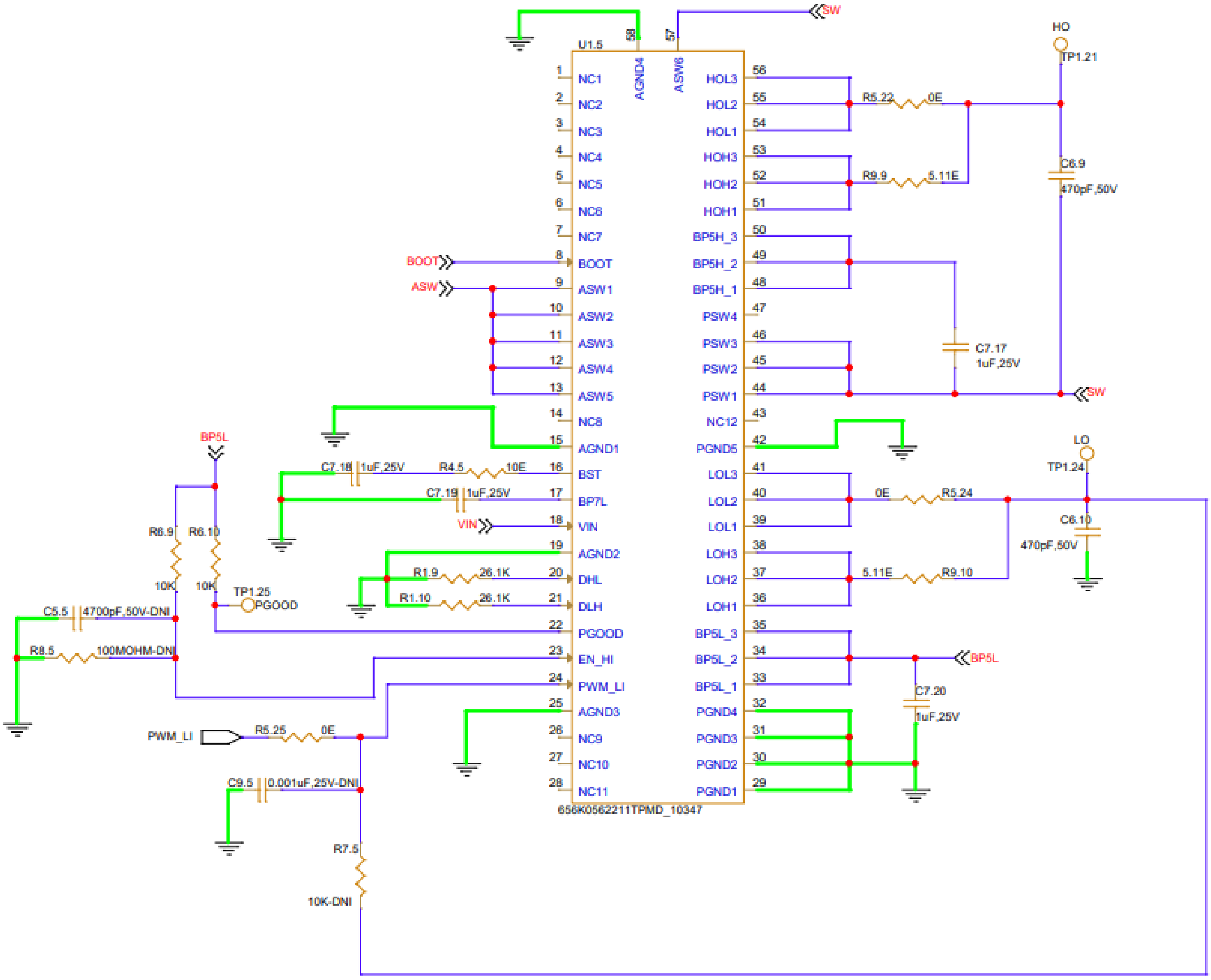


Figure 2-3. HDR TID Bias Diagram

2.4 Test Configuration and Conditions

HDR devices were stressed up to 100krad (Si) for biased and unbiased conditions.

Table 2-2. HDR Biased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	100krad (Si)
1, 2	23, 24, 25, 26, 27

Table 2-3. HDR Unbiased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	100krad (Si)
1, 2	48, 49, 50, 51, 52

3 TID Characterization Test Results

3.1 TID Characterization Results Summary

The results show that all TPS7H6025-SP devices were fully functional and within specification limits up to 100krad (Si) HDR. Overall, the TPS7H6025-SP show a strong degree of hardness to TID HDR exposure levels at 100krad (Si) under bias and unbiased conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. (see Section 3.2 for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See Appendix A for HDR report.

3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature TA = 25°C, VIN = 10V to 14V, VBP5L = VBP5H = 5V, and no load on LOH, LOL, HOH, and HOL (unless otherwise noted).

Table 3-1. TPS7H60205-SP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I_{QLS}	Low-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM, EN = 0V		6.8	mA	35.0, 36.0, 37.0
			MODE = IIM LI = HI = 0V		8		35.2, 36.2, 37.2
I_{QHS}	High-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM EN = 0V		6.3	mA	35.1, 36.1, 37.1
			MODE = IIM LI = HI = 0V		6.3		35.3, 36.3, 37.3
I_{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		9	mA	35.6, 36.6, 37.6
			f = 1MHz		11		35.8, 36.8, 37.8
			f = 2MHz		16		35.1, 36.1, 37.1
			f = 5MHz		30		35.12, 36.12, 37.12
		MODE = IIM, no load for HOL and HOH	f = 500kHz		9		35.14, 36.14, 37.14
			f = 1MHz		12		35.16, 36.16, 37.16
			f = 2MHz		17		35.18, 36.18, 37.18
			f = 5MHz		30		35.2, 36.2, 37.2
I_{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		6.5	mA	35.7, 36.7, 37.7
			f = 1MHz		8		35.9, 36.9, 37.9
			f = 2MHz		10.5		35.11, 36.11, 37.11
			f = 5MHz		19		35.13, 36.13, 37.13
		MODE = IIM, no load for HOL and HOH	f = 500kHz		6.5		35.15, 36.15, 37.15
			f = 1MHz		8		35.17, 36.17, 37.17
			f = 2MHz		10.5		35.19, 36.19, 37.19
			f = 5MHz		15		35.21, 36.21, 37.21
GATE DRIVER							
V_{OL}	Low-level output voltage	I_{OL} = 100mA			0.15	V	45.0, 46.0, 47.0
BP5x – V_{OH}	High-level output voltage	I_{OH} = 100mA			0.3	V	45.2, 46.2, 47.2
I_{OH}	Peak source current	HOH, LOH = 0V, BP5x = 5V		0.7	2.3	A	50, 50.1, 51, 51.1, 52, 52.1
I_{OL}	Peak sink current	HOL, LOL = 5V, BP5x = 5V		1.6	4.6	A	50.2, 51.2, 52.2
INTERNAL REGULATORS							
V_{BP5L}	Low-side 5V regulator output voltage	C_{BP5L} = 1µF		4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.1, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.1, 62.13, 62.16, 62.19, 62.22
V_{BP5H}	High-side 5V regulator output voltage	C_{BP5H} = 1µF		4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.2, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.2, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.2, 62.23
V_{BP7L}	7V regulator output voltage	C_{BP7L} = 1µF		6.65	7.35	V	60.0, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62.0, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21
UNDERVOLTAGE PROTECTION							
BP5H_R	BP5H UVLO rising threshold	C_{BP5H} = 1µF		4	4.5	V	85.1, 86.1, 87.1(1)
BP5H_F	BP5H UVLO falling threshold	C_{BP5H} = 1µF		3.8	4.3	V	85.2, 86.2, 87.2(1)
BP5L_R	BP5L UVLO rising threshold	C_{BP5L} = 1µF		4	4.5	V	80.1, 81.1, 82.1(1)
BP5L_F	BP5L UVLO falling threshold	C_{BP5L} = 1µF		3.8	4.3	V	80.2, 81.2, 82.2(1)
BP7L_R	BP7L UVLO rising threshold	C_{BP7L} = 1µF		6.2	6.8	V	80.4, 81.4, 82.4(1)

Table 3-1. TPS7H60205-SP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
$BP7L_F$	BP7L UVLO falling threshold	C_{BP7L} = 1μF		5.9	6.5	V	80.5, 81.5, 82.5(1)
VIN_R	VIN UVLO rising threshold			8	9	V	70.0
VIN_F	VIN UVLO falling threshold			7.5	8.5	V	70.1
$BOOT_R$	BOOT UVLO rising threshold			6.6	7.4	V	75.0
$BOOT_F$	BOOT UVLO falling threshold			6.2	7	V	75.1
INPUT PINS							
V_{IR}	Input rising edge threshold			1.80	2.65	V	90.0, 91.0, 92.0, 90.3, 91.3, 92.3
V_{IF}	Input falling edge threshold			1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4
R_{PD}	Input pull-down resistance	V = 2.15V applied at input (EN_HI or PWM_LI)		100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7
PROGRAMMABLE DEAD TIME							
T_{DLH}	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2MHz	RLH = 3.32kΩ	0	10	ns	95.0, 95.5, 95.1, 96, 96.5, 96.10, 97, 97.5, 97.1
			RLH = 11.8kΩ	8	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T_{DHL}	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2MHz	RHL = 7.87kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3kΩ	6	14		95.20, 95.25, 95.30, 96.20, 96.25, 96.30, 97.20, 97.25, 97.30
			RHL = 23.7kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113kΩ	81	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I_{BST_SW} = 1mA		0.8	1.2	kΩ	100.1, 101.1, 102.1
POWER GOOD							
	Logic-low output	I_{FLT}= 1mA			0.4	V	105.0, 106.0, 107.0
	PGOOD internal resistance	BP5L = 5V, BP7L = 7V, VIN = 12V		0.7	1.9	MΩ	105.2, 106.2, 107.2
	Minimum BP5L voltage for valid PGOOD output				2.45	V	105.1, 106.1, 107.1

(1) Tests are only tested in production or SPI test mode.

Table 3-2. TPS7H6025-SP Switching Characteristics

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
t_{LPHL}	LO turnoff propagation delay	MODE = PWM	PWM rising to LOL falling		48	ns	110, 111, 112
		MODE = IIM	LI falling to LOL falling		38	ns	110.3, 110.7, 111.3, 111.7, 112.3, 112.7
t_{LPLH}	LO turnon propagation delay	MODE = IIM	LI rising to LOH rising		38	ns	110.2, 110.6, 111.2, 111.6, 112.2, 112.6
t_{HPHL}	HO turnoff propagation delay	MODE = PWM	PWM falling to HOL falling		50	ns	110.1, 111.1,112.1
		MODE = IIM	HI falling to HOL falling		40		110.5, 110.9, 111.5, 111.9, 112.5, 112.9
t_{HPLH}	HO turnon propagation delay	MODE = IIM	HI rising to HOH rising		40	ns	110.4, 110.8, 111.4, 111.8, 112.4, 112.8
t_{MON}	Delay matching LO on and HO off	MODE = IIM			12	ns	110.12, 111.12, 112.12
t_{MOFF}	Delay matching LO off and HO on	MODE = IIM			4	ns	110.11, 110.13, 111.11, 111.13, 112.11, 112.13
t_{HRC}	HO rise time	C_L = 1000pF	10% to 90%		7.5	ns	115, 116, 117
t_{LRC}	LO rise time				7.5	ns	115.2, 116.2, 117.2
t_{HFC}	HO fall time		90% to 10%		5.5	ns	115.1, 116.1, 117.1
t_{LFC}	LO fall time				5.5	ns	115.3, 116.3, 117.3
t_{PW_IIM}	Minimum input pulse width (turn-on)	MODE = IIM			8	ns	120, 120.2, 120.4, 121, 121.2, 121.4, 122, 122.2, 122.4
$t_{PW\_IIM\_OFF}$	Minimum input pulse width (turn-off)	MODE = IIM			12	ns	120.1, 120.3, 120.5, 121.1, 121.3, 121.5, 122.1, 122.3, 122.5

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H6025-SP Radiation-Hardness-Assured 22-V, 1.3A, 2.5A, Half-Bridge GaN FET Gate Driver*, data sheet.
- Texas Instruments, *TPS7H6005EVM-CVAL Evaluation Module User's Guide*, EVM user's guide.
- Texas Instruments, *TPS7H6005-SP Single-Event Effects (SEE) Report*, radiation report.

4.2 Reference Documents

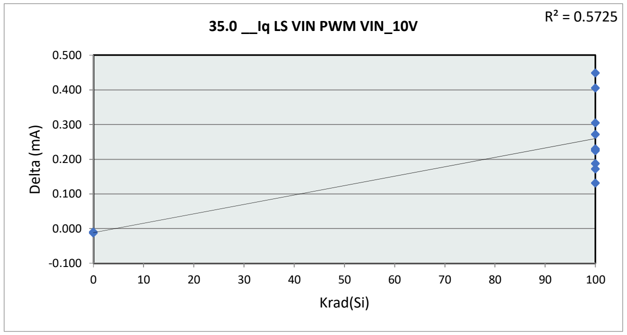
Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report

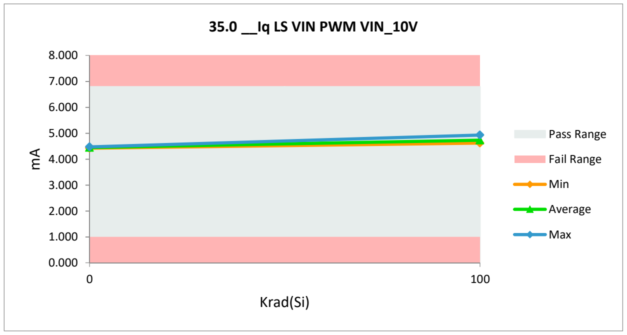
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.0 __Iq LS VIN PWM VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.8	6.8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.481	4.471	-0.010
0	2	4.433	4.420	-0.013
100	23	4.538	4.668	0.131
100	24	4.492	4.796	0.304
100	25	4.517	4.922	0.405
100	26	4.289	4.737	0.449
100	27	4.532	4.803	0.271
100	48u	4.441	4.628	0.187
100	49u	4.408	4.635	0.227
100	50u	4.446	4.617	0.171
100	51u	4.437	4.667	0.230
100	52u	4.590	4.814	0.224
	Max	4.590	4.922	0.449
	Average	4.467	4.681	0.215
	Min	4.289	4.420	-0.013
	Std Dev	0.078	0.144	0.140

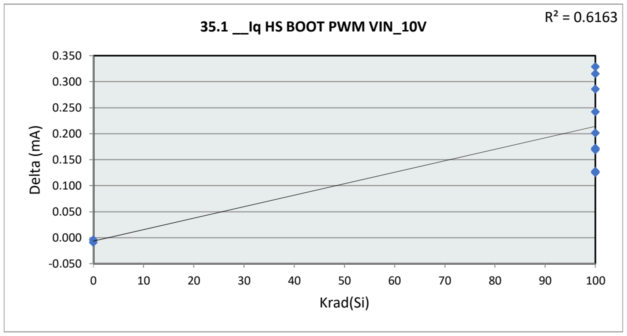


	35.0 __Iq LS VIN PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.420	4.617
Average	4.445	4.729
Max	4.471	4.922
UL	6.800	6.800

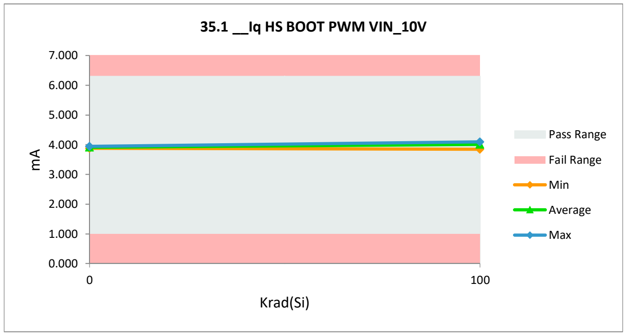


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.1 __Iq HS BOOT PWM VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.3	6.3	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.881	3.877	-0.004
0	2	3.957	3.948	-0.009
100	23	3.770	4.099	0.329
100	24	3.802	4.088	0.286
100	25	3.779	4.094	0.315
100	26	3.742	3.914	0.172
100	27	3.746	3.988	0.242
100	48u	3.936	4.061	0.125
100	49u	3.838	4.039	0.202
100	50u	3.876	4.004	0.128
100	51u	3.682	3.851	0.169
100	52u	3.784	3.956	0.172
	Max	3.957	4.099	0.329
	Average	3.816	3.993	0.177
	Min	3.682	3.851	-0.009
	Std Dev	0.083	0.086	0.109

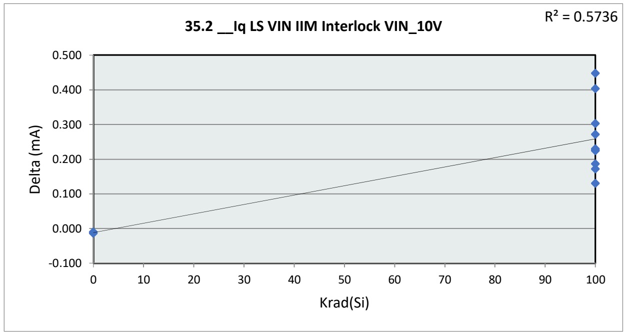


	35.1 __Iq HS BOOT PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.877	3.851
Average	3.913	4.009
Max	3.948	4.099
UL	6.300	6.300

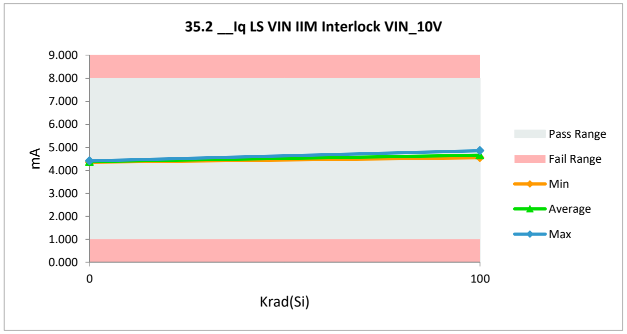


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.2 __Iq LS VIN IIM Interlock V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.409	4.399	-0.010
0	2	4.362	4.348	-0.014
100	23	4.465	4.595	0.130
100	24	4.421	4.723	0.302
100	25	4.445	4.848	0.403
100	26	4.217	4.664	0.447
100	27	4.461	4.732	0.271
100	48u	4.369	4.555	0.187
100	49u	4.336	4.562	0.226
100	50u	4.374	4.545	0.171
100	51u	4.366	4.595	0.229
100	52u	4.519	4.742	0.224
	Max	4.519	4.848	0.447
	Average	4.395	4.609	0.214
	Min	4.217	4.348	-0.014
	Std Dev	0.078	0.144	0.139

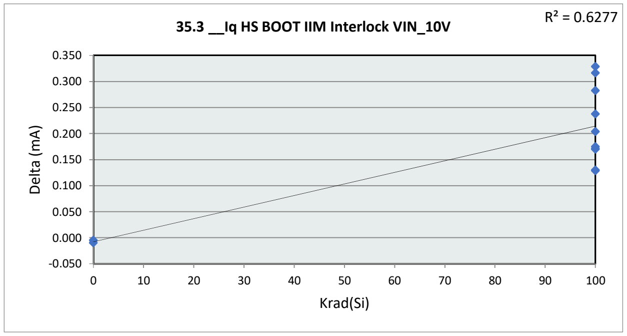


	35.2 __Iq LS VIN IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.348	4.545
Average	4.374	4.656
Max	4.399	4.848
UL	8.000	8.000

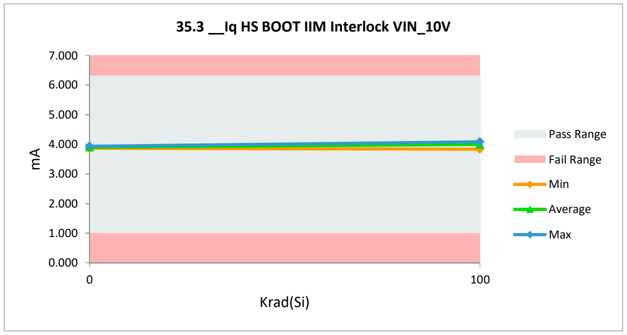


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.3 __Iq HS BOOT IIM Interloc		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.3	6.3	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.868	3.863	-0.005
0	2	3.945	3.935	-0.010
100	23	3.757	4.086	0.329
100	24	3.790	4.073	0.282
100	25	3.765	4.081	0.316
100	26	3.728	3.899	0.171
100	27	3.733	3.971	0.238
100	48u	3.923	4.051	0.128
100	49u	3.825	4.028	0.204
100	50u	3.863	3.993	0.130
100	51u	3.669	3.839	0.170
100	52u	3.772	3.947	0.175
	Max	3.945	4.086	0.329
	Average	3.803	3.981	0.177
	Min	3.669	3.839	-0.010
	Std Dev	0.083	0.086	0.109

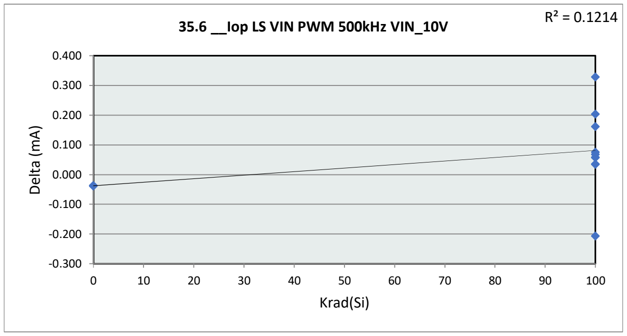


	35.3 __Iq HS BOOT IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.863	3.839
Average	3.899	3.997
Max	3.935	4.086
UL	6.300	6.300

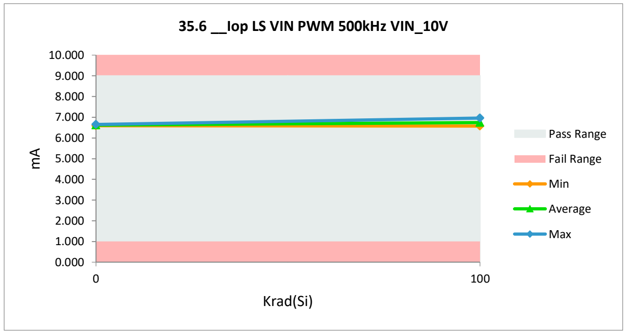


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.6 __Iop LS VIN PWM 500kHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.696	6.659	-0.036
0	2	6.634	6.595	-0.039
100	23	6.791	6.584	-0.207
100	24	6.690	6.852	0.162
100	25	6.755	6.959	0.203
100	26	6.477	6.806	0.329
100	27	6.721	6.779	0.058
100	48u	6.536	6.570	0.035
100	49u	6.611	6.646	0.035
100	50u	6.612	6.680	0.068
100	51u	6.670	6.745	0.075
100	52u	6.785	6.843	0.057
	Max	6.791	6.959	0.329
	Average	6.665	6.727	0.062
	Min	6.477	6.570	-0.207
	Std Dev	0.096	0.124	0.133



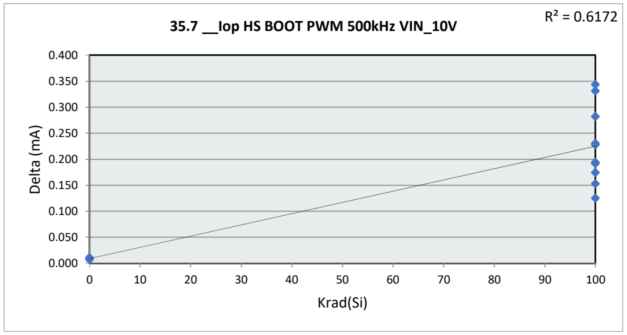
	35.6 __Iop LS VIN PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.595	6.570
Average	6.627	6.746
Max	6.659	6.959
UL	9.000	9.000



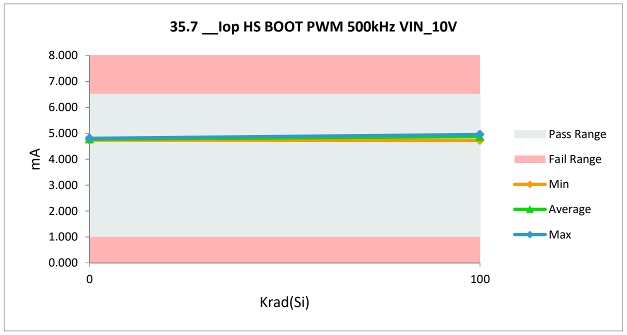
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	35.7 __Iop HS BOOT PWM 500kH	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	6.5	6.5
Min Limit	1	1

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.723	4.734	0.011
0	2	4.798	4.805	0.007
100	23	4.608	4.951	0.343
100	24	4.643	4.924	0.282
100	25	4.619	4.950	0.331
100	26	4.578	4.753	0.174
100	27	4.586	4.814	0.228
100	48u	4.778	4.931	0.153
100	49u	4.673	4.904	0.230
100	50u	4.720	4.845	0.125
100	51u	4.524	4.718	0.194
100	52u	4.623	4.814	0.192
	Max	4.798	4.951	0.343
	Average	4.656	4.845	0.189
	Min	4.524	4.718	0.007
	Std Dev	0.084	0.085	0.107

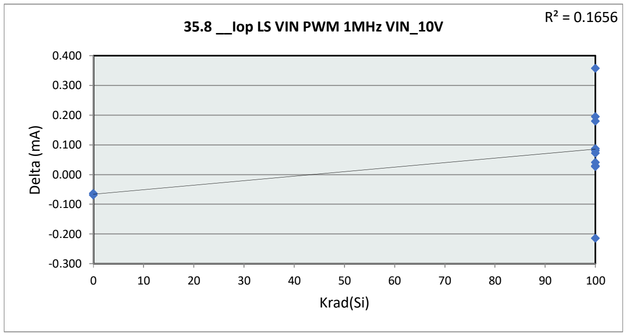


	35.7 __Iop HS BOOT PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.734	4.718
Average	4.769	4.860
Max	4.805	4.951
UL	6.500	6.500

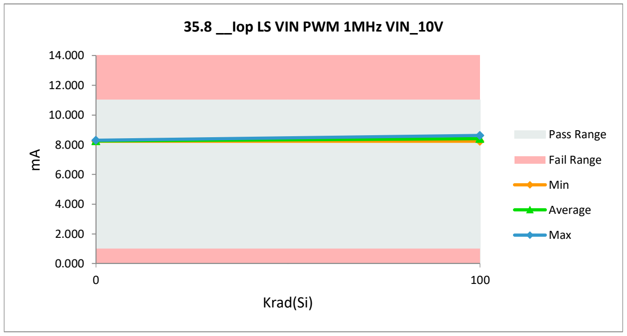


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.8 __Iop LS VIN PWM 1MHz VI		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	11	11	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.353	8.290	-0.063
0	2	8.300	8.231	-0.069
100	23	8.452	8.238	-0.214
100	24	8.352	8.531	0.180
100	25	8.422	8.617	0.195
100	26	8.141	8.498	0.357
100	27	8.384	8.456	0.072
100	48u	8.201	8.228	0.026
100	49u	8.280	8.310	0.030
100	50u	8.277	8.364	0.087
100	51u	8.333	8.414	0.080
100	52u	8.452	8.493	0.041
	Max	8.452	8.617	0.357
	Average	8.329	8.389	0.060
	Min	8.141	8.228	-0.214
	Std Dev	0.096	0.132	0.145

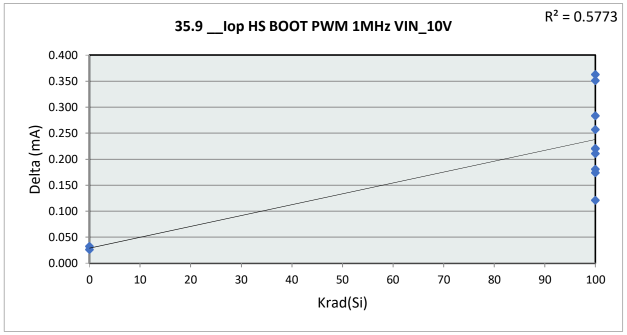


	35.8 __Iop LS VIN PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.231	8.228
Average	8.260	8.415
Max	8.290	8.617
UL	11.000	11.000

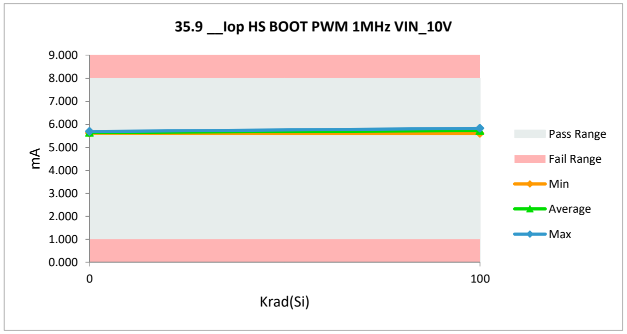


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.9 __Iop HS BOOT PWM 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.578	5.610	0.032
0	2	5.655	5.681	0.026
100	23	5.460	5.822	0.362
100	24	5.498	5.781	0.283
100	25	5.474	5.825	0.351
100	26	5.430	5.610	0.180
100	27	5.440	5.661	0.220
100	48u	5.637	5.811	0.173
100	49u	5.528	5.785	0.257
100	50u	5.578	5.699	0.121
100	51u	5.383	5.602	0.220
100	52u	5.477	5.687	0.211
	Max	5.655	5.825	0.362
	Average	5.511	5.715	0.203
	Min	5.383	5.602	0.026
	Std Dev	0.085	0.086	0.107

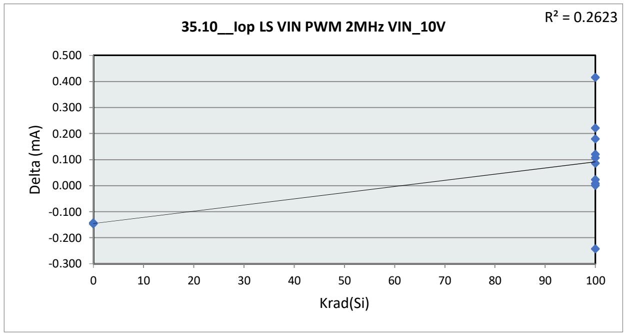


35.9 __Iop HS BOOT PWM 1MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.610	5.603
Average	5.646	5.728
Max	5.681	5.825
UL	8.000	8.000

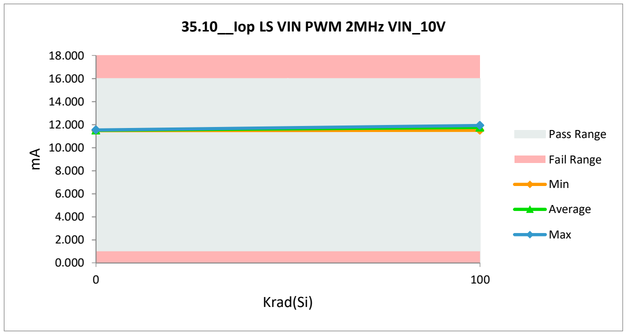


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.10__Iop LS VIN PWM 2MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		16	16	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.668	11.524	-0.144
0	2	11.629	11.482	-0.147
100	23	11.770	11.527	-0.243
100	24	11.665	11.887	0.221
100	25	11.750	11.929	0.179
100	26	11.468	11.883	0.415
100	27	11.707	11.813	0.106
100	48u	11.515	11.516	0.001
100	49u	11.615	11.637	0.022
100	50u	11.606	11.725	0.120
100	51u	11.657	11.743	0.086
100	52u	11.788	11.795	0.008
	Max	11.788	11.929	0.415
	Average	11.653	11.705	0.052
	Min	11.468	11.482	-0.243
	Std Dev	0.096	0.163	0.180

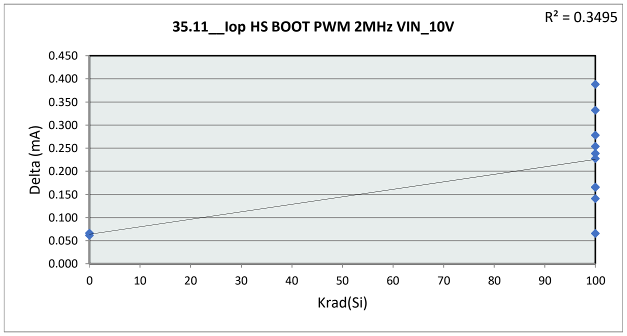


	35.10__Iop LS VIN PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.482	11.516
Average	11.503	11.745
Max	11.524	11.929
UL	16.000	16.000

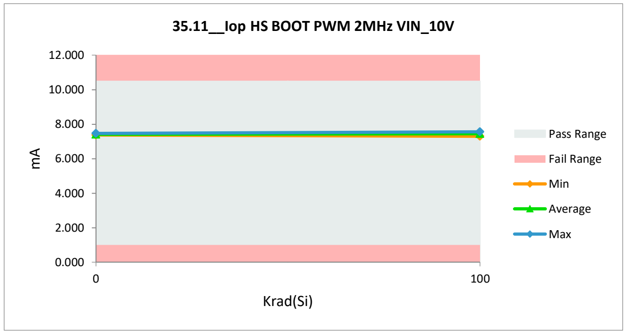


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.11__Iop HS BOOT PWM 2MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.314	7.375	0.061
0	2	7.394	7.461	0.066
100	23	7.148	7.536	0.388
100	24	7.203	7.480	0.278
100	25	7.220	7.552	0.332
100	26	7.164	7.305	0.141
100	27	7.181	7.345	0.165
100	48u	7.376	7.542	0.166
100	49u	7.262	7.516	0.254
100	50u	7.322	7.388	0.066
100	51u	7.132	7.360	0.228
100	52u	7.206	7.445	0.239
	Max	7.394	7.552	0.388
	Average	7.243	7.442	0.199
	Min	7.132	7.305	0.061
	Std Dev	0.089	0.086	0.107

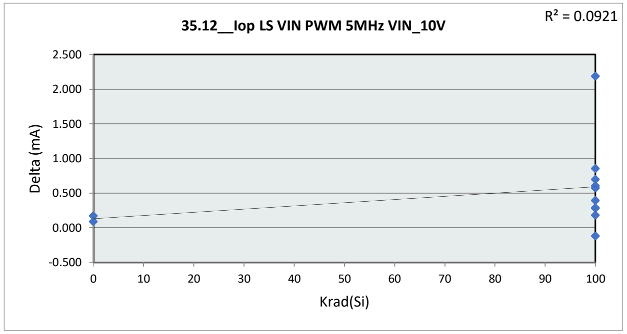


	35.11__Iop HS BOOT PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.375	7.305
Average	7.418	7.447
Max	7.461	7.553
UL	10.500	10.500

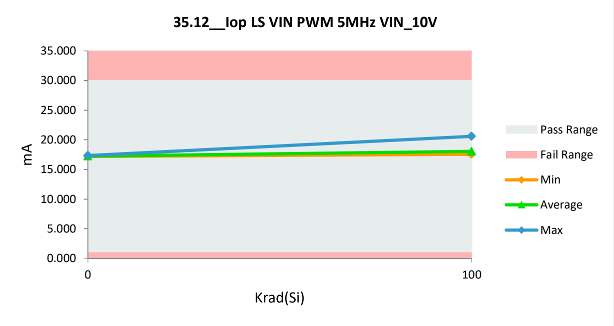


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.12__Iop LS VIN PWM 5MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.155	17.325	0.170
0	2	17.086	17.176	0.089
100	23	17.719	17.600	-0.119
100	24	17.569	17.850	0.281
100	25	17.380	18.233	0.852
100	26	16.965	17.659	0.694
100	27	17.687	17.867	0.181
100	48u	17.288	17.858	0.570
100	49u	17.278	17.672	0.394
100	50u	17.282	17.568	0.287
100	51u	17.095	17.700	0.606
100	52u	18.383	20.572	2.188
	Max	18.383	20.572	2.188
	Average	17.407	17.923	0.516
	Min	16.965	17.176	-0.119
	Std Dev	0.389	0.877	0.595

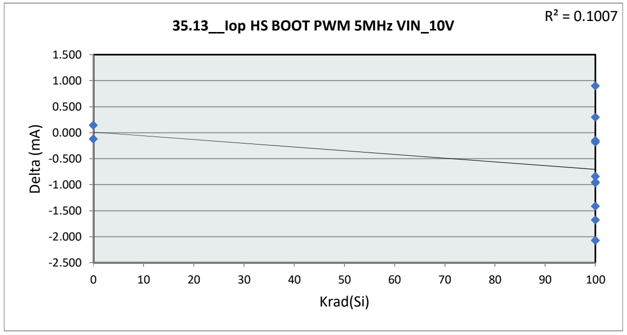


35.12__Iop LS VIN PWM 5MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.176	17.568
Average	17.250	18.058
Max	17.325	20.572
UL	30.000	30.000

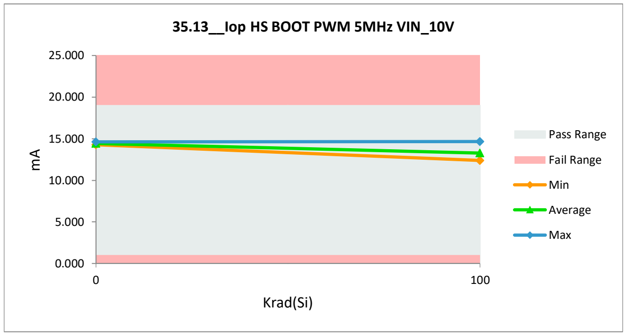


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.13__Iop HS BOOT PWM 5MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		19	19	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	14.467	14.610	0.143
0	2	14.392	14.274	-0.118
100	23	12.556	12.404	-0.152
100	24	13.258	13.556	0.298
100	25	14.222	13.381	-0.841
100	26	14.162	13.197	-0.965
100	27	14.326	13.372	-0.954
100	48u	14.572	12.499	-2.073
100	49u	14.372	12.696	-1.675
100	50u	14.430	13.016	-1.414
100	51u	13.997	13.816	-0.181
100	52u	13.777	14.679	0.902
	Max	14.572	14.679	0.902
	Average	14.044	13.458	-0.586
	Min	12.556	12.404	-2.073
	Std Dev	0.593	0.769	0.880

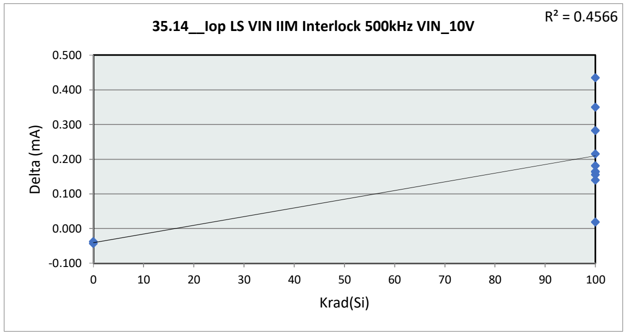


	35.13__Iop HS BOOT PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.274	12.404
Average	14.442	13.262
Max	14.610	14.679
UL	19.000	19.000

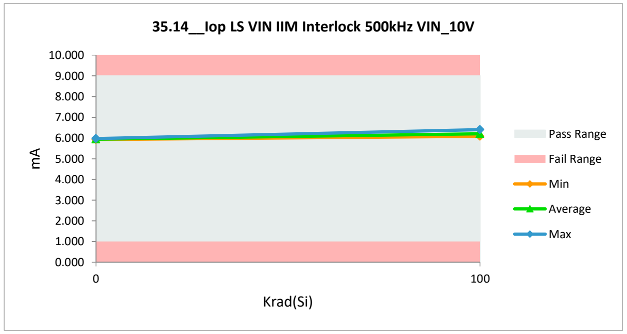


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.14__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.013	5.975	-0.038
0	2	5.964	5.921	-0.043
100	23	6.087	6.106	0.018
100	24	6.023	6.305	0.282
100	25	6.060	6.410	0.349
100	26	5.817	6.251	0.434
100	27	6.057	6.273	0.215
100	48u	5.936	6.076	0.139
100	49u	5.945	6.109	0.164
100	50u	5.967	6.122	0.155
100	51u	5.978	6.159	0.181
100	52u	6.119	6.282	0.163
	Max	6.119	6.410	0.434
	Average	5.997	6.166	0.168
	Min	5.817	5.921	-0.043
	Std Dev	0.081	0.143	0.144

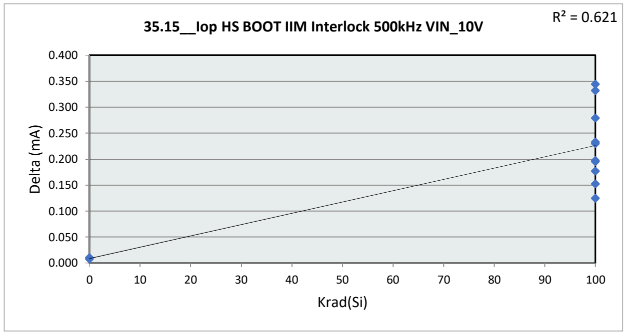


	35.14__Iop LS VIN IIM Interlock 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.921	6.076
Average	5.948	6.209
Max	5.975	6.410
UL	9.000	9.000

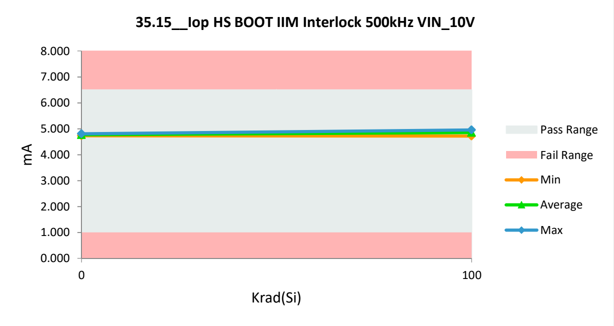


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.15__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.718	4.727	0.010
0	2	4.795	4.802	0.008
100	23	4.605	4.950	0.344
100	24	4.642	4.921	0.279
100	25	4.615	4.946	0.332
100	26	4.575	4.751	0.176
100	27	4.581	4.810	0.229
100	48u	4.776	4.927	0.152
100	49u	4.671	4.904	0.233
100	50u	4.718	4.843	0.125
100	51u	4.522	4.719	0.197
100	52u	4.621	4.816	0.195
	Max	4.795	4.950	0.344
	Average	4.653	4.843	0.190
	Min	4.522	4.719	0.008
	Std Dev	0.084	0.085	0.107

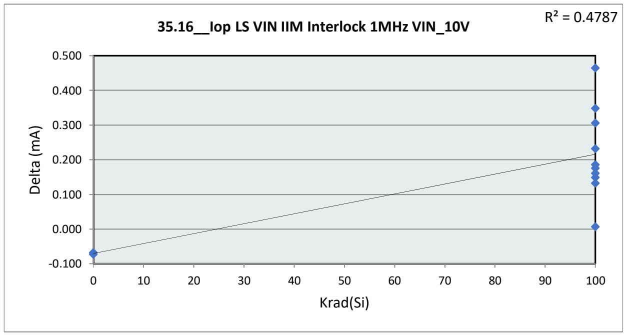


	35.15__Iop HS BOOT IIM Interlock 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.727	4.719
Average	4.765	4.859
Max	4.802	4.950
UL	6.500	6.500

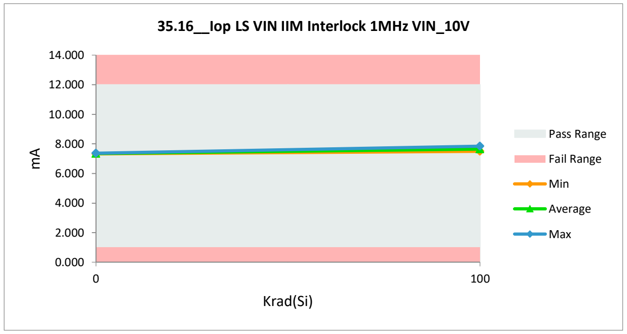


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.16__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.448	7.380	-0.068
0	2	7.400	7.327	-0.073
100	23	7.524	7.530	0.007
100	24	7.456	7.762	0.306
100	25	7.497	7.845	0.348
100	26	7.254	7.719	0.465
100	27	7.495	7.727	0.232
100	48u	7.372	7.504	0.132
100	49u	7.385	7.546	0.161
100	50u	7.404	7.580	0.176
100	51u	7.413	7.599	0.186
100	52u	7.558	7.706	0.148
	Max	7.558	7.845	0.465
	Average	7.434	7.602	0.168
	Min	7.254	7.327	-0.073
	Std Dev	0.081	0.156	0.161

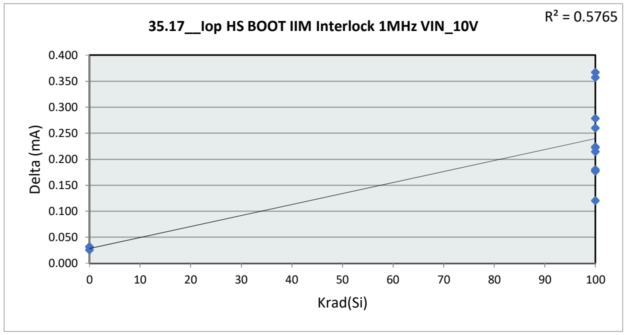


	35.16__Iop LS VIN IIM Interlock 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.327	7.504
Average	7.354	7.652
Max	7.380	7.845
UL	12.000	12.000

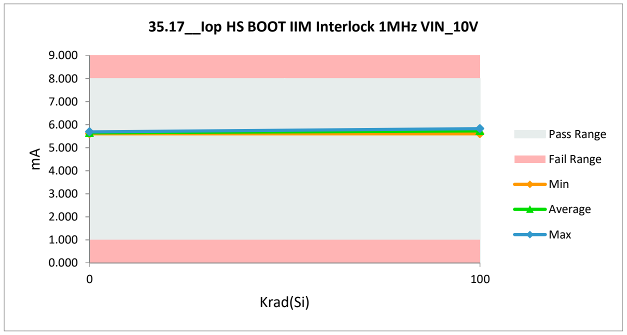


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.17__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.572	5.604	0.032
0	2	5.651	5.676	0.025
100	23	5.459	5.825	0.367
100	24	5.499	5.778	0.278
100	25	5.466	5.823	0.357
100	26	5.425	5.605	0.180
100	27	5.435	5.658	0.223
100	48u	5.633	5.809	0.176
100	49u	5.524	5.784	0.260
100	50u	5.578	5.698	0.120
100	51u	5.379	5.601	0.223
100	52u	5.473	5.688	0.215
	Max	5.651	5.825	0.367
	Average	5.508	5.713	0.205
	Min	5.379	5.601	0.025
	Std Dev	0.085	0.088	0.108

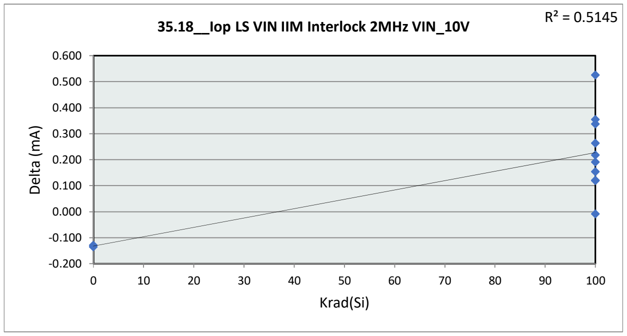


	35.17__Iop HS BOOT IIM Interlock 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.604	5.601
Average	5.640	5.727
Max	5.677	5.825
UL	8.000	8.000

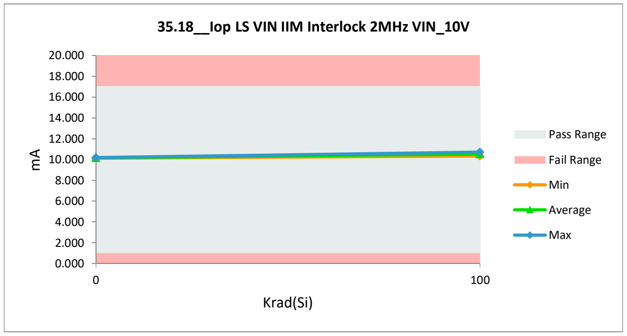


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.18__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		17	17	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	10.306	10.177	-0.129
0	2	10.262	10.127	-0.135
100	23	10.383	10.374	-0.008
100	24	10.314	10.669	0.354
100	25	10.362	10.700	0.338
100	26	10.120	10.646	0.525
100	27	10.358	10.622	0.264
100	48u	10.231	10.350	0.119
100	49u	10.256	10.411	0.155
100	50u	10.268	10.486	0.218
100	51u	10.273	10.464	0.191
100	52u	10.424	10.545	0.121
	Max	10.424	10.700	0.525
	Average	10.296	10.464	0.168
	Min	10.120	10.127	-0.135
	Std Dev	0.081	0.187	0.195

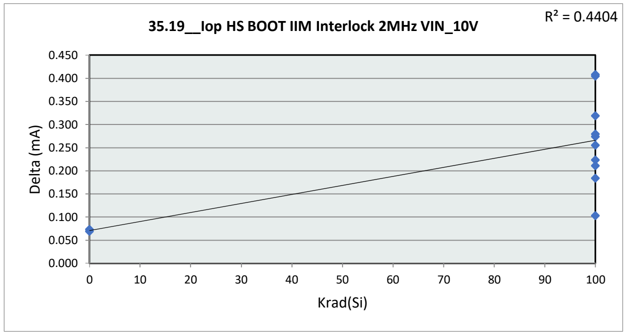


	35.18__Iop LS VIN IIM Interlock 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.127	10.350
Average	10.152	10.527
Max	10.177	10.700
UL	17.000	17.000

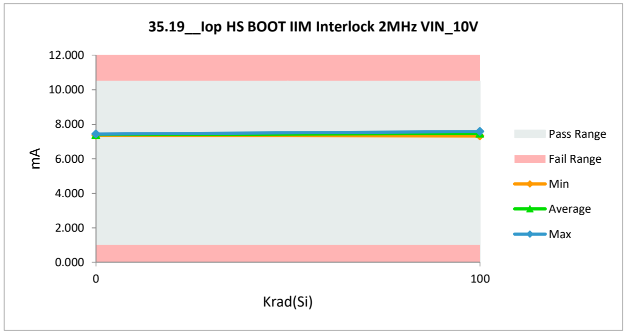


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.19__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.281	7.354	0.073
0	2	7.361	7.430	0.069
100	23	7.167	7.574	0.407
100	24	7.215	7.488	0.274
100	25	7.175	7.579	0.404
100	26	7.129	7.313	0.184
100	27	7.142	7.353	0.211
100	48u	7.350	7.573	0.223
100	49u	7.230	7.549	0.319
100	50u	7.301	7.404	0.103
100	51u	7.095	7.374	0.279
100	52u	7.182	7.437	0.255
	Max	7.361	7.579	0.407
	Average	7.219	7.452	0.233
	Min	7.095	7.313	0.069
	Std Dev	0.087	0.097	0.114

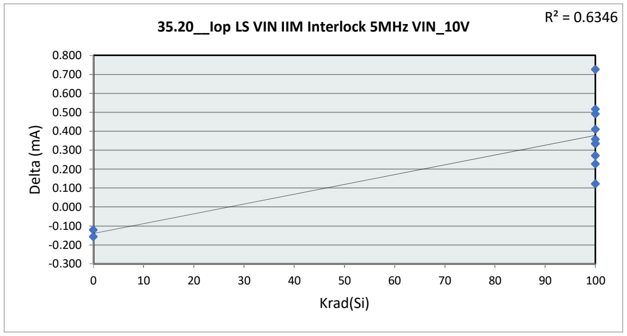


	35.19__Iop HS BOOT IIM Interlock 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.354	7.313
Average	7.392	7.464
Max	7.430	7.579
UL	10.500	10.500

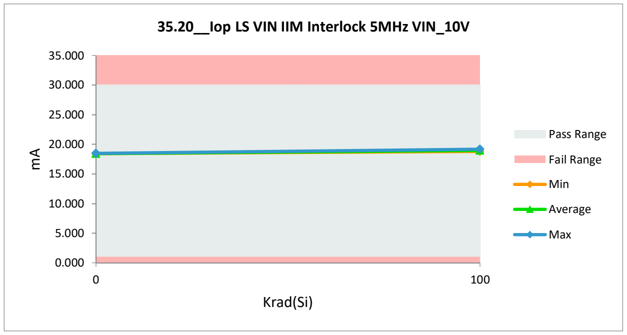


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.20__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.589	18.467	-0.122
0	2	18.568	18.411	-0.157
100	23	18.675	18.797	0.122
100	24	18.602	19.092	0.490
100	25	18.662	19.179	0.516
100	26	18.402	19.127	0.725
100	27	18.655	19.012	0.357
100	48u	18.525	18.795	0.270
100	49u	18.551	18.885	0.334
100	50u	18.568	18.903	0.335
100	51u	18.562	18.971	0.409
100	52u	18.717	18.944	0.227
	Max	18.717	19.179	0.725
	Average	18.590	18.882	0.292
	Min	18.402	18.411	-0.157
	Std Dev	0.083	0.239	0.253

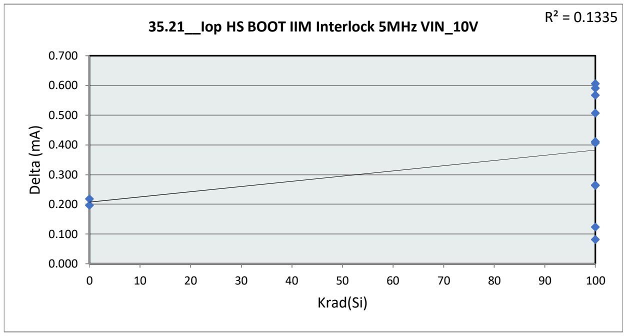


	35.20__Iop LS VIN IIM Interlock 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.411	18.795
Average	18.439	18.970
Max	18.467	19.179
UL	30.000	30.000

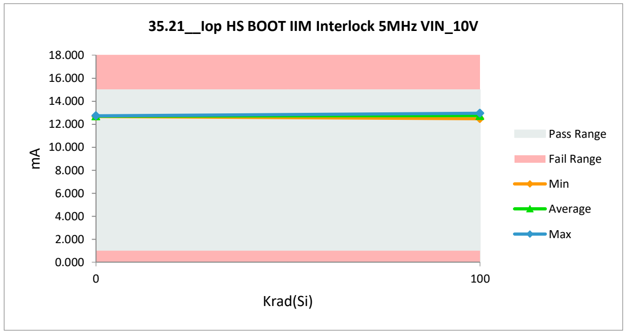


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.21__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.457	12.675	0.218
0	2	12.538	12.735	0.197
100	23	12.310	12.900	0.590
100	24	12.360	12.623	0.264
100	25	12.320	12.926	0.606
100	26	12.267	12.531	0.264
100	27	12.352	12.476	0.124
100	48u	12.539	12.946	0.407
100	49u	12.359	12.926	0.567
100	50u	12.468	12.549	0.082
100	51u	12.236	12.743	0.507
100	52u	12.349	12.761	0.411
	Max	12.539	12.946	0.606
	Average	12.380	12.733	0.353
	Min	12.236	12.476	0.082
	Std Dev	0.099	0.166	0.186



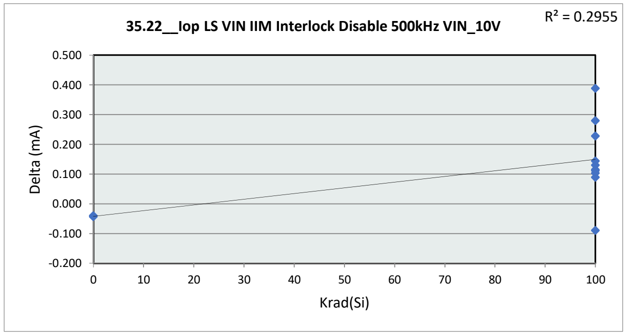
	35.21__Iop HS BOOT IIM Interlock 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.675	12.476
Average	12.705	12.738
Max	12.735	12.946
UL	15.000	15.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

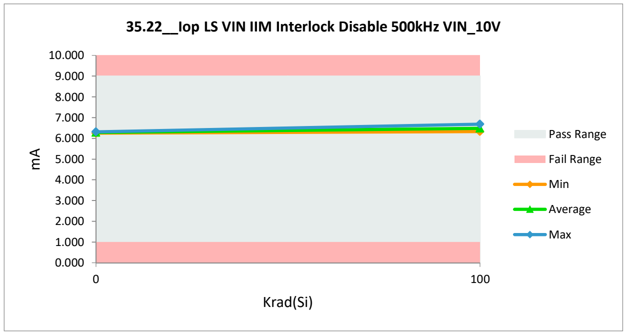
35.22__Iop LS VIN IIM Interlock

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.354	6.314	-0.041
0	2	6.296	6.253	-0.044
100	23	6.438	6.348	-0.090
100	24	6.357	6.585	0.228
100	25	6.405	6.684	0.279
100	26	6.146	6.534	0.388
100	27	6.388	6.532	0.144
100	48u	6.235	6.324	0.089
100	49u	6.276	6.379	0.103
100	50u	6.289	6.404	0.115
100	51u	6.322	6.451	0.129
100	52u	6.450	6.561	0.111
	Max	6.450	6.684	0.388
	Average	6.330	6.447	0.118
	Min	6.146	6.253	-0.090
	Std Dev	0.088	0.131	0.137



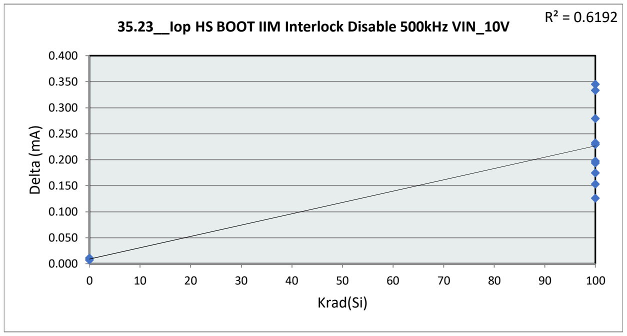
35.22__Iop LS VIN IIM Interlock Disable 500kHz VIN_1

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.253	6.324
Average	6.283	6.480
Max	6.314	6.684
UL	9.000	9.000

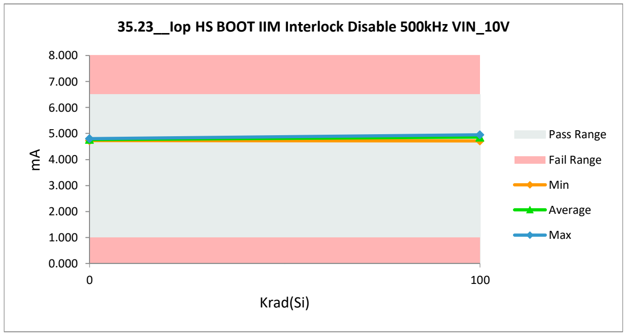


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.23__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.717	4.728	0.011
0	2	4.794	4.801	0.007
100	23	4.604	4.949	0.345
100	24	4.641	4.920	0.279
100	25	4.614	4.947	0.333
100	26	4.574	4.748	0.174
100	27	4.581	4.811	0.229
100	48u	4.774	4.927	0.153
100	49u	4.671	4.903	0.232
100	50u	4.716	4.843	0.126
100	51u	4.521	4.718	0.197
100	52u	4.620	4.813	0.193
	Max	4.794	4.949	0.345
	Average	4.652	4.842	0.190
	Min	4.521	4.718	0.007
	Std Dev	0.084	0.086	0.108

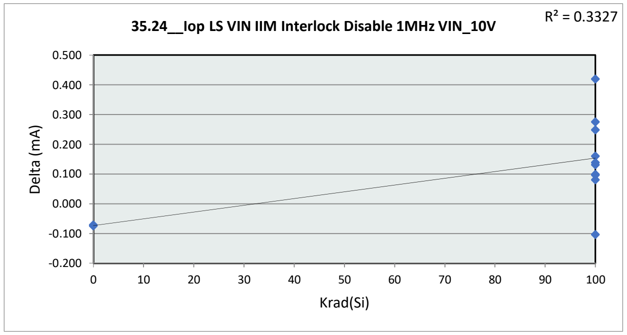


	35.23__Iop HS BOOT IIM Interlock Disable 500kHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.728	4.718
Average	4.764	4.858
Max	4.801	4.949
UL	6.500	6.500

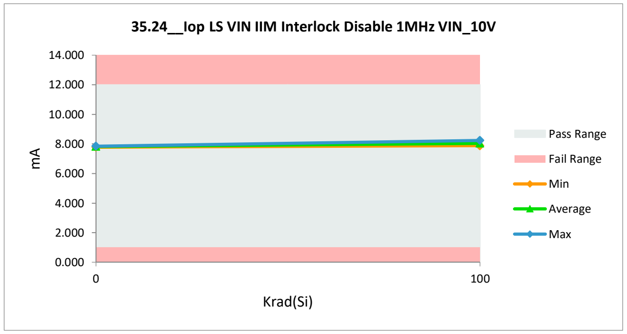


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.24__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	6025_Post	Delta
0	1	7.914	7.842	-0.072
0	2	7.860	7.785	-0.075
100	23	8.002	7.898	-0.103
100	24	7.918	8.167	0.248
100	25	7.969	8.244	0.275
100	26	7.709	8.128	0.419
100	27	7.952	8.112	0.160
100	48u	7.798	7.878	0.080
100	49u	7.844	7.942	0.098
100	50u	7.852	7.991	0.139
100	51u	7.884	8.015	0.131
100	52u	8.016	8.112	0.096
	Max	8.016	8.244	0.419
	Average	7.893	8.009	0.116
	Min	7.709	7.785	-0.103
	Std Dev	0.088	0.144	0.153

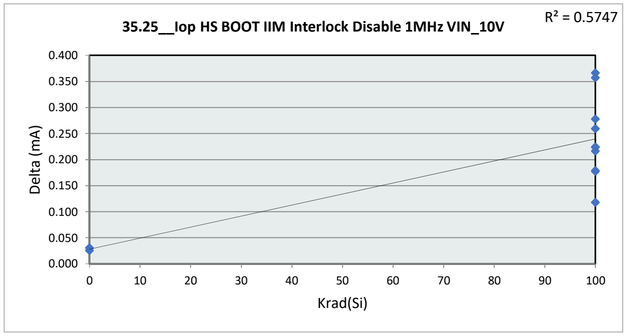


	35.24__Iop LS VIN IIM Interlock Disable 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.785	7.878
Average	7.814	8.049
Max	7.842	8.244
UL	12.000	12.000

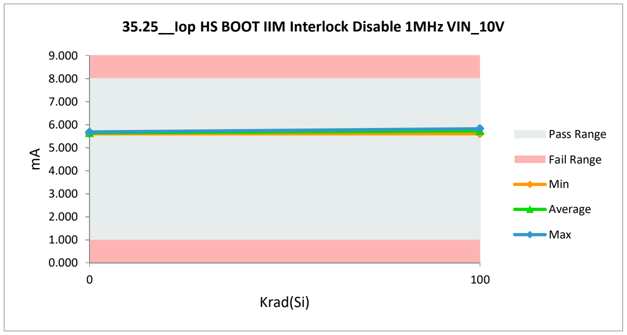


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.25__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.570	5.601	0.031
0	2	5.649	5.675	0.026
100	23	5.457	5.824	0.366
100	24	5.497	5.775	0.278
100	25	5.465	5.822	0.357
100	26	5.425	5.603	0.178
100	27	5.433	5.656	0.223
100	48u	5.631	5.808	0.177
100	49u	5.524	5.783	0.259
100	50u	5.578	5.695	0.118
100	51u	5.378	5.602	0.224
100	52u	5.471	5.687	0.216
	Max	5.649	5.824	0.366
	Average	5.507	5.711	0.204
	Min	5.378	5.601	0.026
	Std Dev	0.085	0.088	0.109

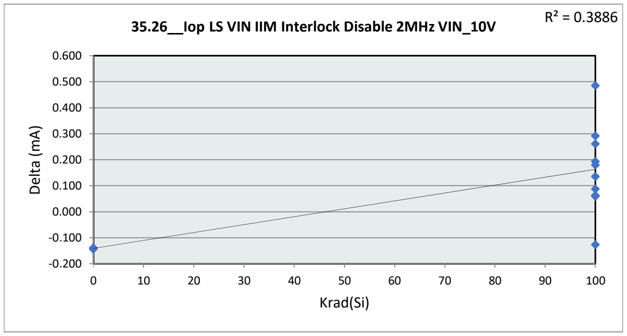


	35.25__Iop HS BOOT IIM Interlock Disable 1MHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.601	5.602
Average	5.638	5.726
Max	5.675	5.824
UL	8.000	8.000

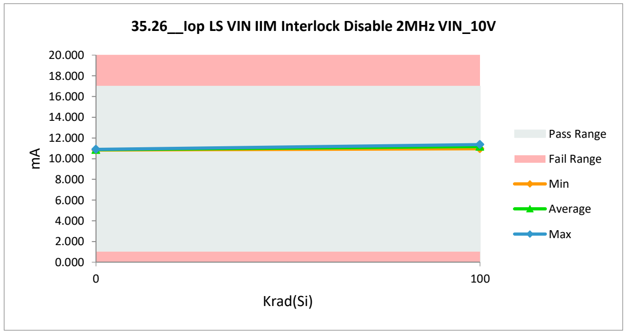


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.26__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.025	10.886	-0.139
0	2	10.975	10.832	-0.143
100	23	11.117	10.990	-0.127
100	24	11.032	11.324	0.292
100	25	11.087	11.348	0.262
100	26	10.825	11.310	0.485
100	27	11.069	11.263	0.194
100	48u	10.910	10.972	0.063
100	49u	10.968	11.055	0.087
100	50u	10.970	11.150	0.180
100	51u	10.995	11.130	0.135
100	52u	11.137	11.196	0.059
	Max	11.137	11.348	0.485
	Average	11.009	11.122	0.112
	Min	10.825	10.832	-0.143
	Std Dev	0.089	0.175	0.190



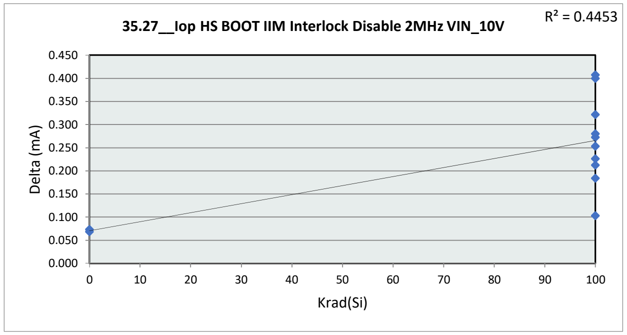
	35.26__Iop LS VIN IIM Interlock Disable 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.832	10.972
Average	10.859	11.174
Max	10.886	11.348
UL	17.000	17.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

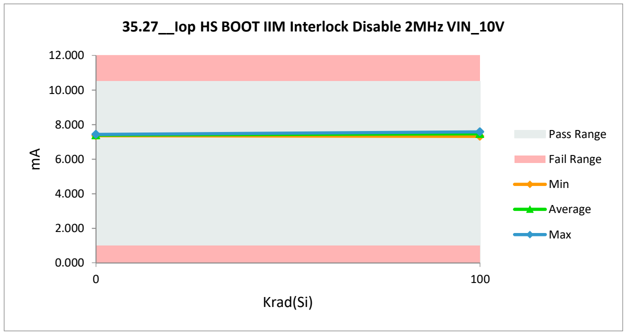
35.27__Iop HS BOOT IIM Interlo

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.279	7.351	0.073
0	2	7.359	7.427	0.068
100	23	7.167	7.574	0.407
100	24	7.214	7.486	0.272
100	25	7.174	7.573	0.399
100	26	7.128	7.312	0.184
100	27	7.140	7.352	0.212
100	48u	7.348	7.573	0.226
100	49u	7.227	7.548	0.321
100	50u	7.299	7.401	0.102
100	51u	7.092	7.372	0.280
100	52u	7.180	7.433	0.253
	Max	7.359	7.574	0.407
	Average	7.217	7.450	0.233
	Min	7.092	7.312	0.068
	Std Dev	0.087	0.097	0.114



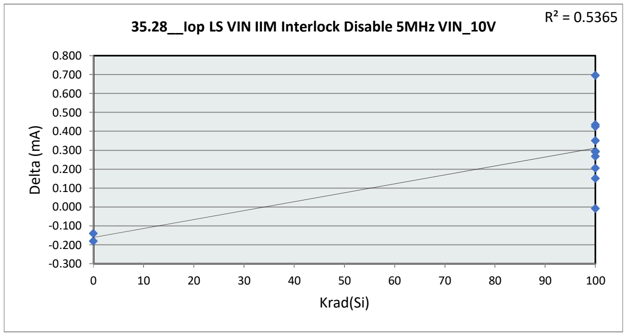
35.27__Iop HS BOOT IIM Interlock Disable 2MHz VIN_1

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.351	7.312
Average	7.389	7.463
Max	7.427	7.574
UL	10.500	10.500

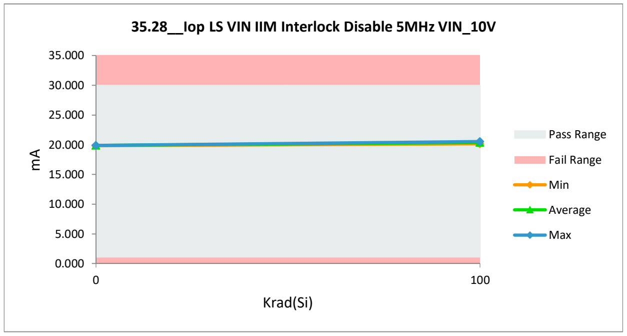


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.28__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	20.025	19.886	-0.139
0	2	20.017	19.837	-0.181
100	23	20.136	20.129	-0.007
100	24	20.045	20.471	0.425
100	25	20.111	20.546	0.436
100	26	19.832	20.528	0.696
100	27	20.090	20.381	0.291
100	48u	19.933	20.138	0.205
100	49u	19.983	20.251	0.268
100	50u	19.998	20.293	0.295
100	51u	20.011	20.361	0.350
100	52u	20.160	20.312	0.152
	Max	20.160	20.546	0.696
	Average	20.029	20.261	0.233
	Min	19.832	19.837	-0.181
	Std Dev	0.091	0.229	0.250

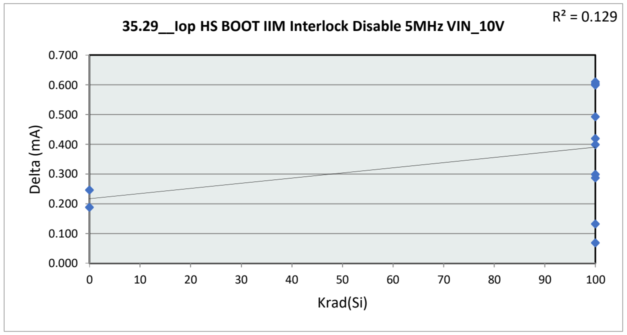


	35.28__Iop LS VIN IIM Interlock Disable 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.837	20.129
Average	19.861	20.341
Max	19.886	20.546
UL	30.000	30.000

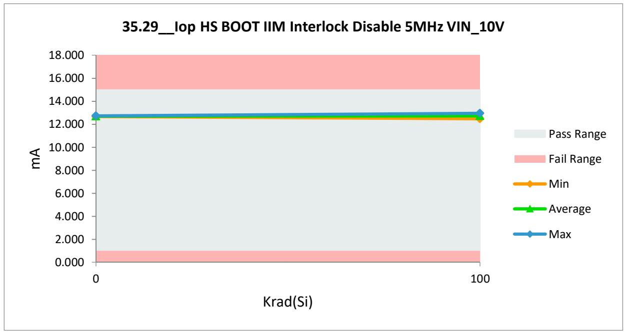


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		35.29__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.426	12.672	0.246
0	2	12.548	12.736	0.188
100	23	12.289	12.898	0.610
100	24	12.330	12.616	0.286
100	25	12.324	12.926	0.603
100	26	12.231	12.530	0.299
100	27	12.337	12.469	0.132
100	48u	12.545	12.943	0.398
100	49u	12.324	12.923	0.599
100	50u	12.488	12.556	0.068
100	51u	12.247	12.740	0.493
100	52u	12.340	12.759	0.419
	Max	12.548	12.943	0.610
	Average	12.369	12.731	0.362
	Min	12.231	12.469	0.068
	Std Dev	0.108	0.167	0.188

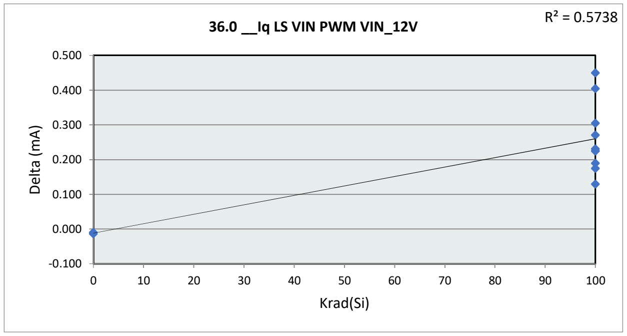


	35.29__Iop HS BOOT IIM Interlock Disable 5MHz VIN_1(	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.672	12.469
Average	12.704	12.736
Max	12.736	12.943
UL	15.000	15.000

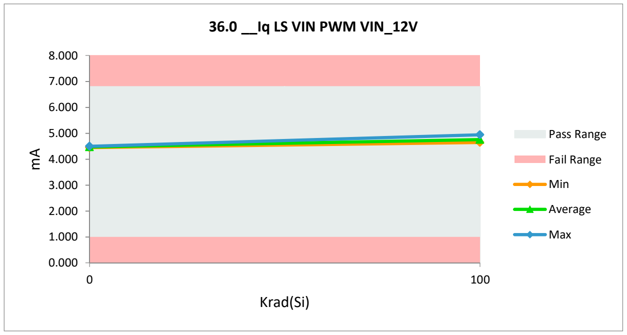


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.0 __Iq LS VIN PWM VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.8	6.8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.504	4.495	-0.010
0	2	4.457	4.443	-0.014
100	23	4.561	4.690	0.129
100	24	4.515	4.819	0.304
100	25	4.540	4.943	0.404
100	26	4.312	4.762	0.449
100	27	4.555	4.825	0.270
100	48u	4.463	4.652	0.189
100	49u	4.430	4.656	0.225
100	50u	4.468	4.642	0.174
100	51u	4.459	4.690	0.231
100	52u	4.613	4.837	0.224
	Max	4.613	4.943	0.449
	Average	4.490	4.704	0.215
	Min	4.312	4.443	-0.014
	Std Dev	0.077	0.144	0.140

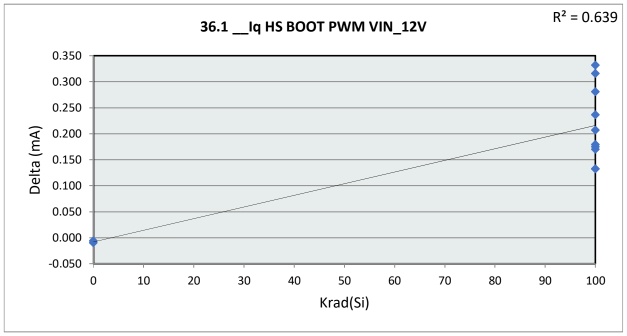


	36.0 __Iq LS VIN PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.443	4.642
Average	4.469	4.752
Max	4.495	4.943
UL	6.800	6.800

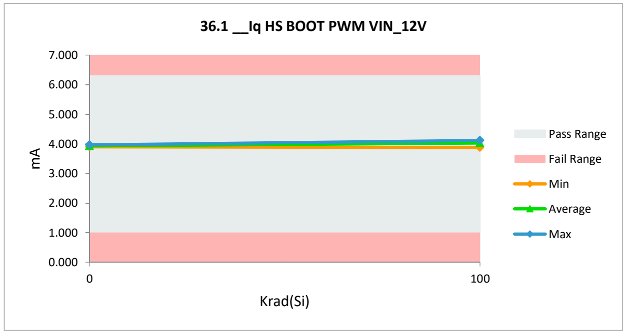


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.1 __Iq HS BOOT PWM VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.3	6.3	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.902	3.896	-0.006
0	2	3.977	3.968	-0.010
100	23	3.788	4.120	0.332
100	24	3.822	4.103	0.281
100	25	3.798	4.114	0.316
100	26	3.761	3.931	0.170
100	27	3.765	4.002	0.237
100	48u	3.956	4.089	0.132
100	49u	3.858	4.064	0.207
100	50u	3.896	4.029	0.132
100	51u	3.703	3.877	0.175
100	52u	3.805	3.984	0.179
	Max	3.977	4.120	0.332
	Average	3.836	4.015	0.179
	Min	3.703	3.877	-0.010
	Std Dev	0.083	0.085	0.109

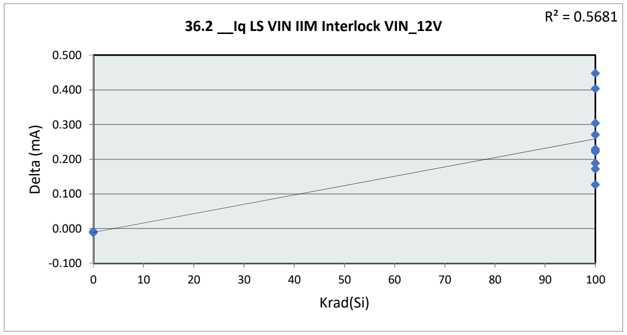


	36.1 __Iq HS BOOT PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.896	3.877
Average	3.932	4.031
Max	3.968	4.120
UL	6.300	6.300

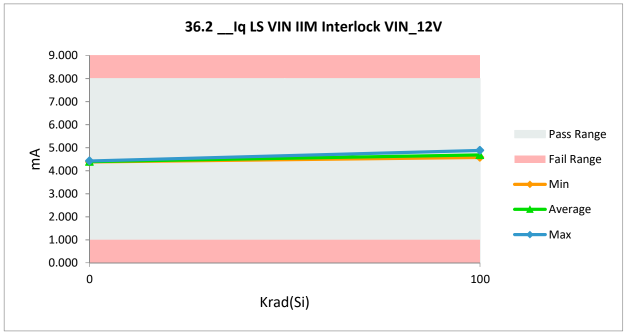


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.2 __Iq LS VIN IIM Interlock V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.432	4.423	-0.009
0	2	4.384	4.372	-0.012
100	23	4.490	4.616	0.127
100	24	4.443	4.747	0.303
100	25	4.467	4.871	0.403
100	26	4.240	4.687	0.447
100	27	4.482	4.753	0.270
100	48u	4.391	4.578	0.188
100	49u	4.359	4.584	0.225
100	50u	4.397	4.568	0.172
100	51u	4.388	4.617	0.229
100	52u	4.542	4.764	0.222
	Max	4.542	4.871	0.447
	Average	4.418	4.632	0.214
	Min	4.240	4.372	-0.012
	Std Dev	0.078	0.143	0.139

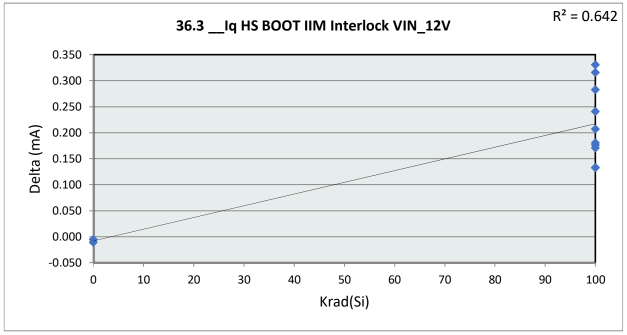


36.2 __Iq LS VIN IIM Interlock VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.372	4.568
Average	4.397	4.678
Max	4.423	4.871
UL	8.000	8.000

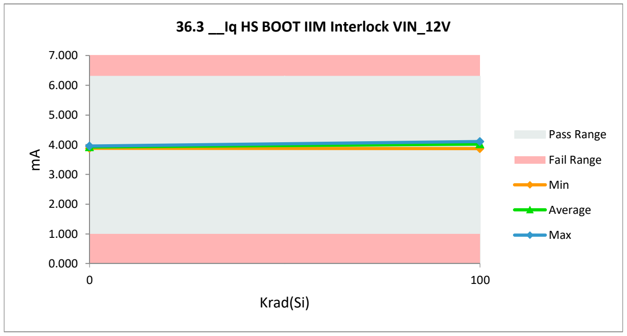


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.3 __Iq HS BOOT IIM Interloc		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.3	6.3	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.888	3.883	-0.005
0	2	3.965	3.955	-0.011
100	23	3.776	4.107	0.331
100	24	3.809	4.092	0.283
100	25	3.785	4.101	0.316
100	26	3.749	3.920	0.171
100	27	3.752	3.993	0.241
100	48u	3.944	4.076	0.133
100	49u	3.845	4.051	0.207
100	50u	3.884	4.016	0.132
100	51u	3.690	3.866	0.176
100	52u	3.792	3.973	0.181
	Max	3.965	4.107	0.331
	Average	3.823	4.003	0.179
	Min	3.690	3.866	-0.011
	Std Dev	0.083	0.085	0.109

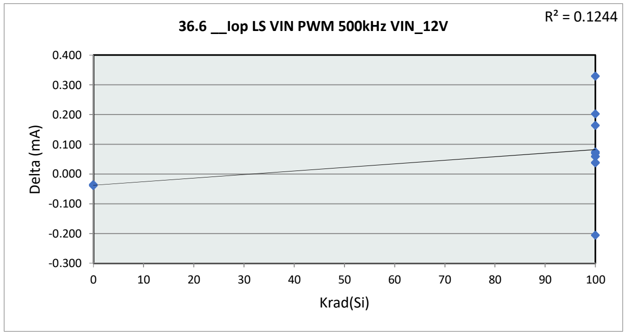


	36.3 __Iq HS BOOT IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.883	3.866
Average	3.919	4.020
Max	3.955	4.107
UL	6.300	6.300

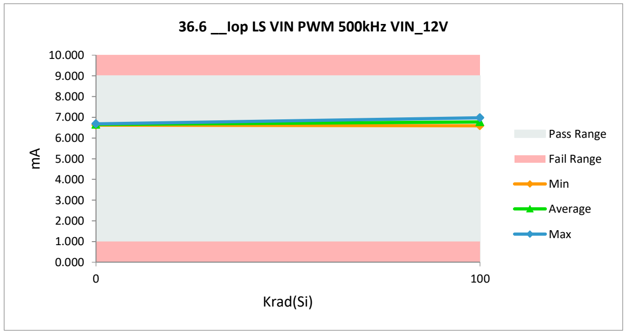


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.6 __Iop LS VIN PWM 500kHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.718	6.682	-0.036
0	2	6.656	6.617	-0.040
100	23	6.814	6.608	-0.206
100	24	6.714	6.876	0.163
100	25	6.779	6.981	0.202
100	26	6.501	6.830	0.329
100	27	6.743	6.802	0.059
100	48u	6.558	6.595	0.037
100	49u	6.634	6.672	0.038
100	50u	6.634	6.704	0.070
100	51u	6.695	6.769	0.074
100	52u	6.809	6.868	0.059
	Max	6.814	6.981	0.329
	Average	6.688	6.750	0.062
	Min	6.501	6.595	-0.206
	Std Dev	0.096	0.123	0.133

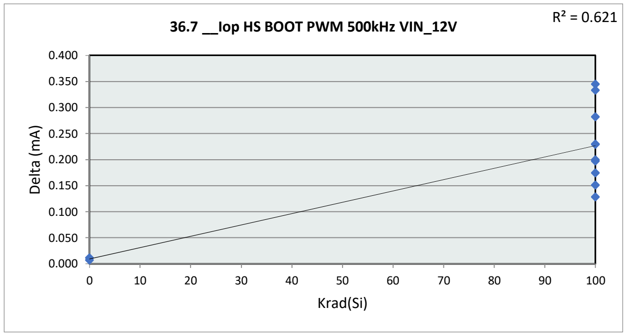


	36.6 __Iop LS VIN PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.617	6.595
Average	6.649	6.771
Max	6.682	6.981
UL	9.000	9.000

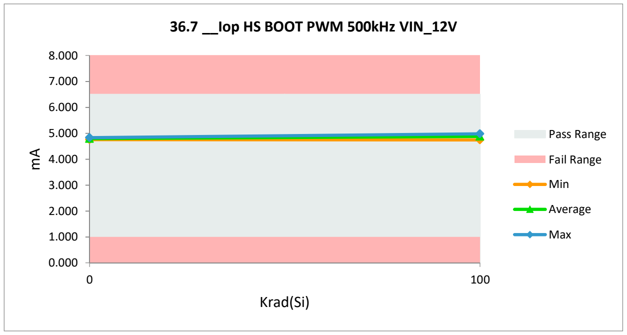


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.7 __Iop HS BOOT PWM 500kH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.744	4.755	0.011
0	2	4.819	4.826	0.007
100	23	4.628	4.972	0.345
100	24	4.664	4.945	0.282
100	25	4.639	4.972	0.333
100	26	4.600	4.774	0.174
100	27	4.606	4.835	0.229
100	48u	4.800	4.951	0.151
100	49u	4.696	4.926	0.229
100	50u	4.740	4.869	0.128
100	51u	4.546	4.745	0.199
100	52u	4.643	4.840	0.197
	Max	4.819	4.972	0.345
	Average	4.677	4.868	0.191
	Min	4.546	4.745	0.007
	Std Dev	0.084	0.084	0.107

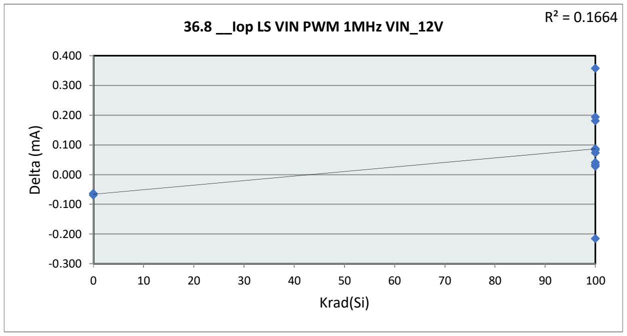


	36.7 __Iop HS BOOT PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.755	4.745
Average	4.791	4.883
Max	4.826	4.972
UL	6.500	6.500

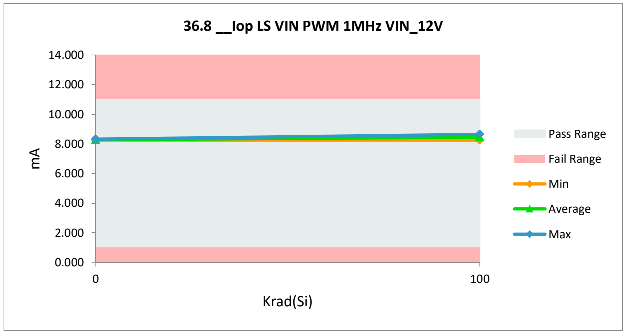


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.8 __Iop LS VIN PWM 1MHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		11	11	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.377	8.314	-0.063
0	2	8.323	8.255	-0.069
100	23	8.476	8.261	-0.215
100	24	8.376	8.557	0.181
100	25	8.446	8.640	0.194
100	26	8.166	8.524	0.358
100	27	8.408	8.481	0.073
100	48u	8.224	8.252	0.028
100	49u	8.304	8.337	0.034
100	50u	8.301	8.388	0.087
100	51u	8.357	8.440	0.083
100	52u	8.477	8.518	0.041
	Max	8.477	8.640	0.358
	Average	8.353	8.414	0.061
	Min	8.166	8.252	-0.215
	Std Dev	0.096	0.132	0.145

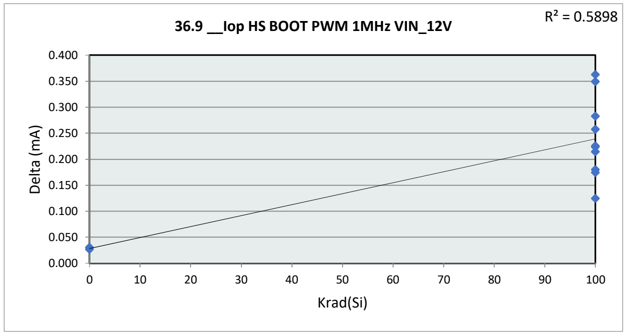


	36.8 __Iop LS VIN PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.255	8.252
Average	8.284	8.440
Max	8.314	8.640
UL	11.000	11.000

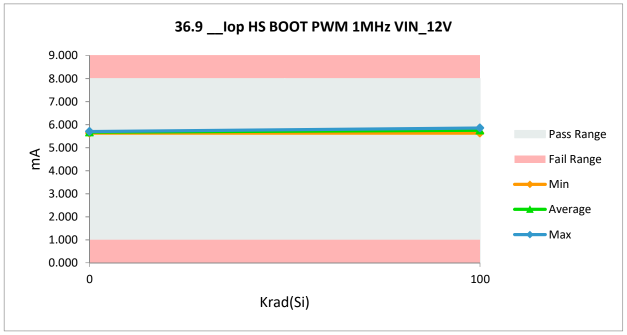


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.9 __Iop HS BOOT PWM 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.599	5.629	0.030
0	2	5.676	5.702	0.026
100	23	5.481	5.844	0.363
100	24	5.518	5.801	0.282
100	25	5.496	5.845	0.349
100	26	5.450	5.630	0.180
100	27	5.459	5.683	0.224
100	48u	5.659	5.833	0.174
100	49u	5.549	5.807	0.258
100	50u	5.600	5.725	0.124
100	51u	5.403	5.628	0.225
100	52u	5.499	5.713	0.214
	Max	5.676	5.845	0.363
	Average	5.532	5.737	0.204
	Min	5.403	5.628	0.026
	Std Dev	0.085	0.086	0.107

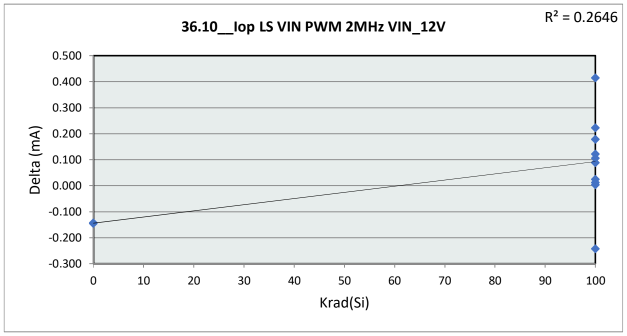


36.9 __Iop HS BOOT PWM 1MHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.629	5.628
Average	5.666	5.751
Max	5.702	5.845
UL	8.000	8.000

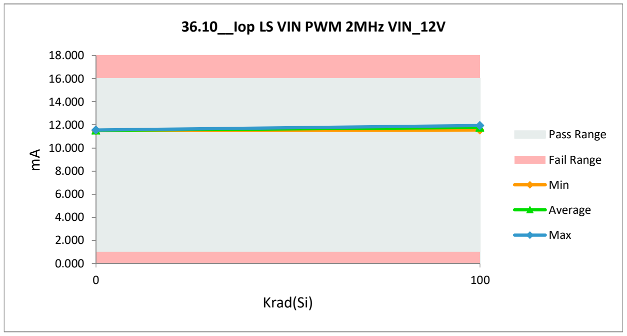


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.10__Iop LS VIN PWM 2MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.694	11.551	-0.143
0	2	11.654	11.509	-0.145
100	23	11.796	11.554	-0.242
100	24	11.692	11.915	0.222
100	25	11.776	11.954	0.178
100	26	11.496	11.911	0.415
100	27	11.733	11.838	0.106
100	48u	11.540	11.545	0.004
100	49u	11.642	11.666	0.024
100	50u	11.631	11.753	0.122
100	51u	11.682	11.771	0.089
100	52u	11.811	11.823	0.012
	Max	11.811	11.954	0.415
	Average	11.679	11.732	0.053
	Min	11.496	11.509	-0.242
	Std Dev	0.096	0.162	0.179

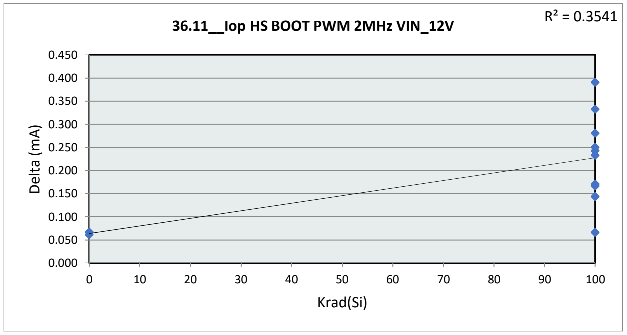


	36.10__Iop LS VIN PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.509	11.545
Average	11.530	11.773
Max	11.551	11.954
UL	16.000	16.000

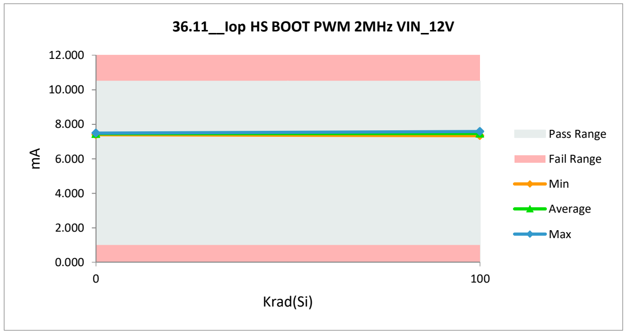


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.11__Iop HS BOOT PWM 2MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.333	7.394	0.061
0	2	7.418	7.484	0.067
100	23	7.167	7.558	0.391
100	24	7.223	7.503	0.280
100	25	7.243	7.575	0.332
100	26	7.184	7.328	0.144
100	27	7.200	7.365	0.166
100	48u	7.396	7.566	0.170
100	49u	7.285	7.535	0.250
100	50u	7.345	7.411	0.066
100	51u	7.153	7.386	0.233
100	52u	7.229	7.472	0.243
	Max	7.418	7.575	0.391
	Average	7.265	7.465	0.200
	Min	7.153	7.328	0.061
	Std Dev	0.090	0.086	0.107

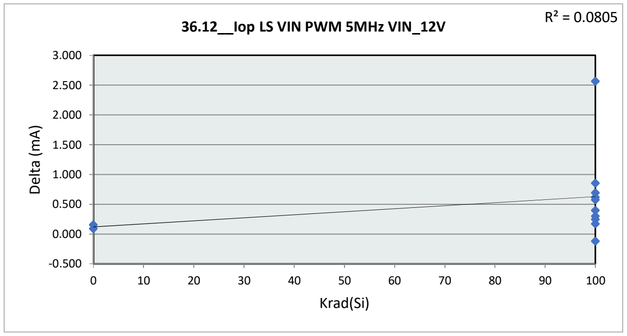


	36.11__Iop HS BOOT PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.394	7.328
Average	7.439	7.470
Max	7.485	7.575
UL	10.500	10.500

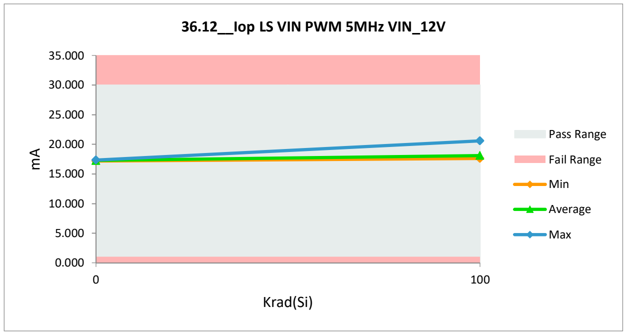


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.12__Iop LS VIN PWM 5MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.177	17.327	0.151
0	2	17.111	17.201	0.090
100	23	17.744	17.620	-0.124
100	24	17.594	17.836	0.243
100	25	17.406	18.261	0.855
100	26	16.990	17.680	0.690
100	27	17.707	17.875	0.168
100	48u	17.313	17.886	0.573
100	49u	17.307	17.700	0.393
100	50u	17.306	17.602	0.296
100	51u	17.122	17.740	0.617
100	52u	18.041	20.603	2.562
	Max	18.041	20.603	2.562
	Average	17.402	17.944	0.543
	Min	16.990	17.201	-0.124
	Std Dev	0.311	0.880	0.695

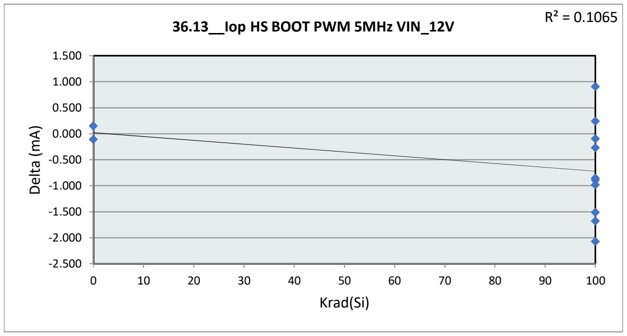


	36.12__Iop LS VIN PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.201	17.602
Average	17.264	18.080
Max	17.327	20.603
UL	30.000	30.000

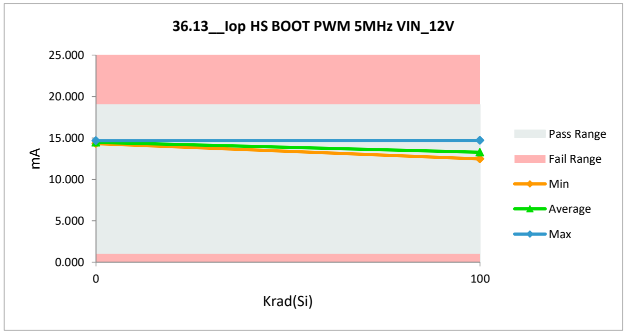


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.13__Iop HS BOOT PWM 5MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		19	19	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	14.497	14.648	0.151
0	2	14.419	14.309	-0.109
100	23	12.567	12.472	-0.095
100	24	13.425	13.665	0.239
100	25	14.247	13.394	-0.853
100	26	14.194	13.214	-0.980
100	27	14.335	13.448	-0.887
100	48u	14.601	12.531	-2.070
100	49u	14.402	12.727	-1.676
100	50u	14.501	12.988	-1.513
100	51u	14.068	13.797	-0.271
100	52u	13.796	14.703	0.908
	Max	14.601	14.703	0.908
	Average	14.088	13.491	-0.596
	Min	12.567	12.472	-2.070
	Std Dev	0.584	0.768	0.883

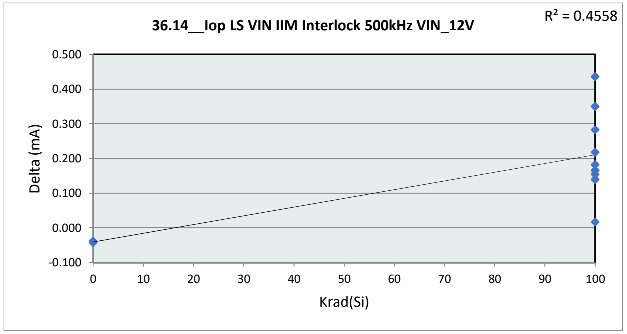


	36.13__Iop HS BOOT PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.309	12.472
Average	14.479	13.294
Max	14.648	14.703
UL	19.000	19.000

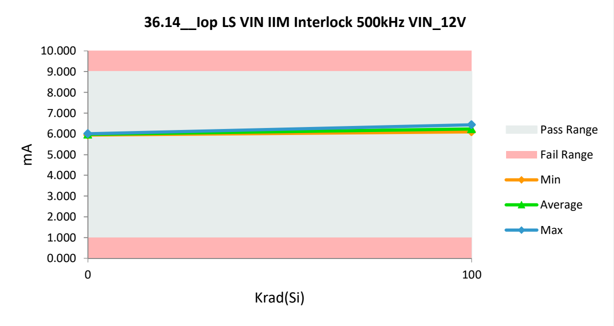


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.14__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.037	5.998	-0.039
0	2	5.988	5.945	-0.042
100	23	6.111	6.128	0.016
100	24	6.046	6.328	0.282
100	25	6.082	6.432	0.350
100	26	5.841	6.276	0.435
100	27	6.080	6.298	0.217
100	48u	5.959	6.098	0.139
100	49u	5.968	6.134	0.166
100	50u	5.991	6.145	0.154
100	51u	6.002	6.184	0.182
100	52u	6.142	6.307	0.165
	Max	6.142	6.432	0.435
	Average	6.021	6.189	0.169
	Min	5.841	5.945	-0.042
	Std Dev	0.081	0.143	0.145

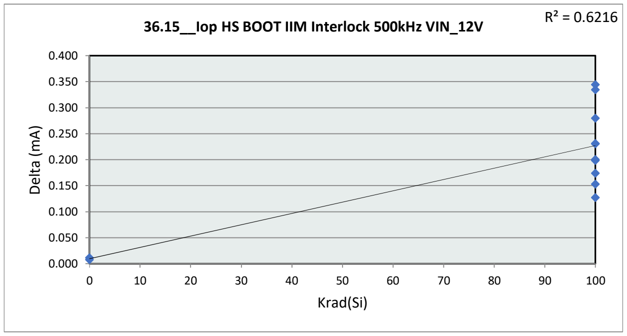


36.14__Iop LS VIN IIM Interlock 500kHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.945	6.099
Average	5.972	6.233
Max	5.998	6.432
UL	9.000	9.000

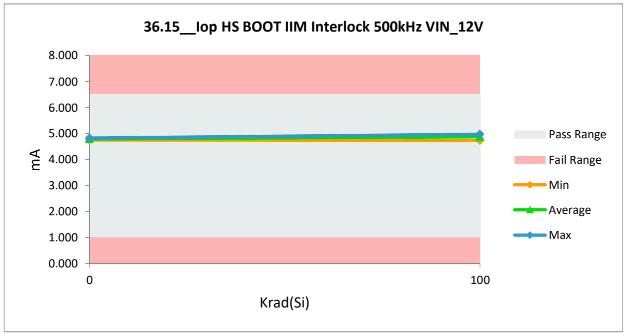


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.15__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.738	4.750	0.012
0	2	4.817	4.825	0.008
100	23	4.627	4.971	0.345
100	24	4.664	4.944	0.280
100	25	4.635	4.969	0.335
100	26	4.597	4.771	0.174
100	27	4.602	4.832	0.230
100	48u	4.797	4.950	0.153
100	49u	4.693	4.924	0.231
100	50u	4.741	4.868	0.127
100	51u	4.543	4.743	0.200
100	52u	4.641	4.840	0.198
	Max	4.817	4.971	0.345
	Average	4.674	4.865	0.191
	Min	4.543	4.743	0.008
	Std Dev	0.084	0.085	0.107

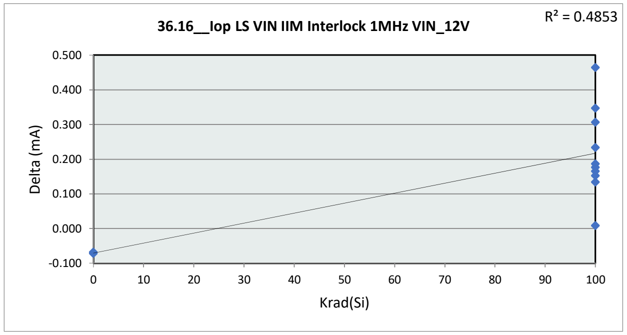


	36.15__Iop HS BOOT IIM Interlock 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.750	4.743
Average	4.787	4.881
Max	4.825	4.971
UL	6.500	6.500

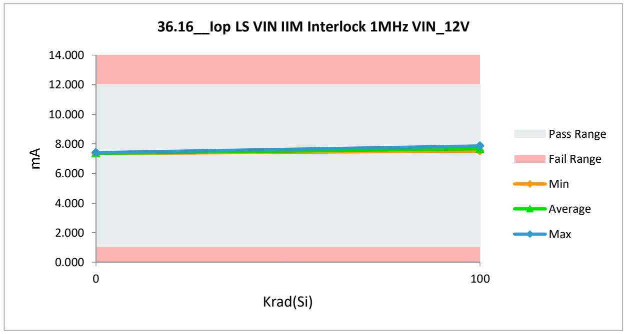


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.16__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.472	7.404	-0.069
0	2	7.424	7.352	-0.072
100	23	7.548	7.556	0.008
100	24	7.481	7.787	0.306
100	25	7.521	7.868	0.347
100	26	7.280	7.744	0.464
100	27	7.518	7.751	0.233
100	48u	7.394	7.528	0.134
100	49u	7.409	7.574	0.165
100	50u	7.428	7.604	0.177
100	51u	7.438	7.624	0.186
100	52u	7.581	7.733	0.152
	Max	7.581	7.868	0.464
	Average	7.458	7.627	0.169
	Min	7.280	7.352	-0.072
	Std Dev	0.081	0.156	0.161



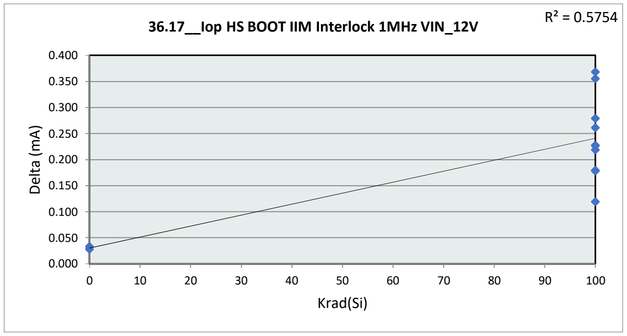
	36.16__Iop LS VIN IIM Interlock 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.352	7.528
Average	7.378	7.677
Max	7.404	7.868
UL	12.000	12.000



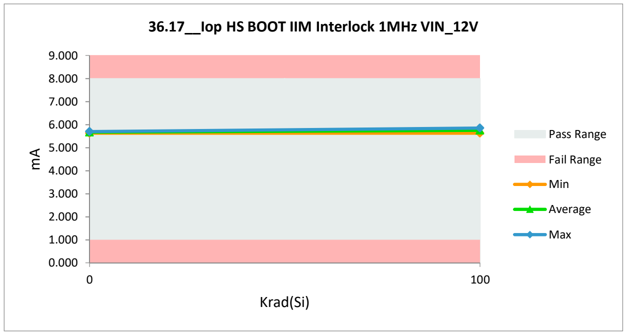
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	36.17__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	8	8
Min Limit	1	1

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.592	5.624	0.032
0	2	5.672	5.700	0.028
100	23	5.480	5.848	0.368
100	24	5.521	5.800	0.279
100	25	5.489	5.844	0.355
100	26	5.448	5.627	0.179
100	27	5.456	5.682	0.227
100	48u	5.654	5.832	0.178
100	49u	5.546	5.807	0.261
100	50u	5.602	5.720	0.119
100	51u	5.400	5.627	0.227
100	52u	5.495	5.713	0.218
	Max	5.672	5.848	0.368
	Average	5.530	5.735	0.206
	Min	5.400	5.624	0.028
	Std Dev	0.085	0.087	0.108

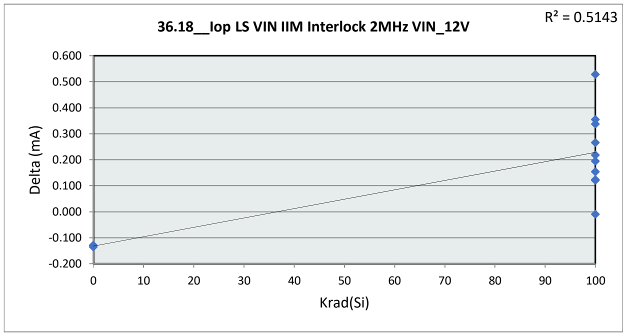


	36.17__Iop HS BOOT IIM Interlock 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.625	5.627
Average	5.662	5.750
Max	5.700	5.848
UL	8.000	8.000

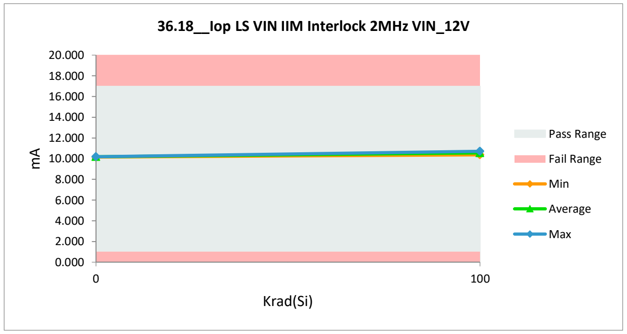


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.18__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		17	17	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	10.332	10.203	-0.128
0	2	10.289	10.154	-0.135
100	23	10.411	10.401	-0.009
100	24	10.342	10.696	0.355
100	25	10.388	10.726	0.338
100	26	10.145	10.673	0.528
100	27	10.384	10.649	0.266
100	48u	10.256	10.377	0.121
100	49u	10.284	10.438	0.155
100	50u	10.294	10.513	0.219
100	51u	10.299	10.493	0.194
100	52u	10.450	10.573	0.124
	Max	10.450	10.726	0.528
	Average	10.323	10.491	0.169
	Min	10.145	10.154	-0.135
	Std Dev	0.081	0.187	0.196

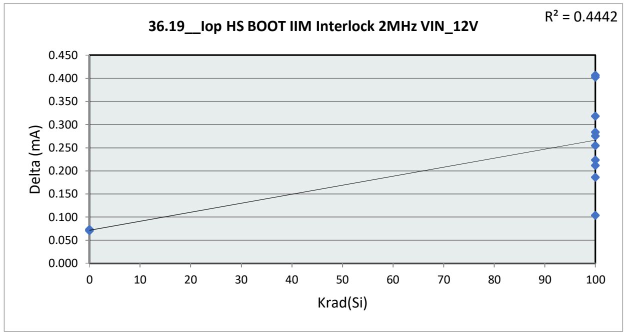


	36.18__Iop LS VIN IIM Interlock 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.154	10.378
Average	10.179	10.554
Max	10.203	10.726
UL	17.000	17.000

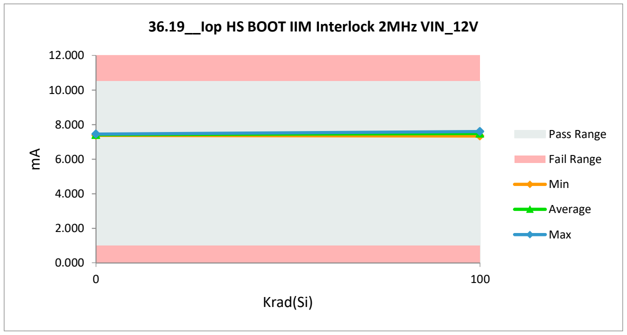


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.19__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	10.5	10.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.302	7.375	0.073
0	2	7.384	7.454	0.070
100	23	7.190	7.597	0.407
100	24	7.236	7.511	0.275
100	25	7.198	7.600	0.402
100	26	7.149	7.335	0.186
100	27	7.162	7.374	0.212
100	48u	7.372	7.595	0.223
100	49u	7.252	7.570	0.318
100	50u	7.323	7.427	0.104
100	51u	7.116	7.399	0.283
100	52u	7.205	7.459	0.254
	Max	7.384	7.600	0.407
	Average	7.241	7.475	0.234
	Min	7.116	7.335	0.070
	Std Dev	0.087	0.097	0.114

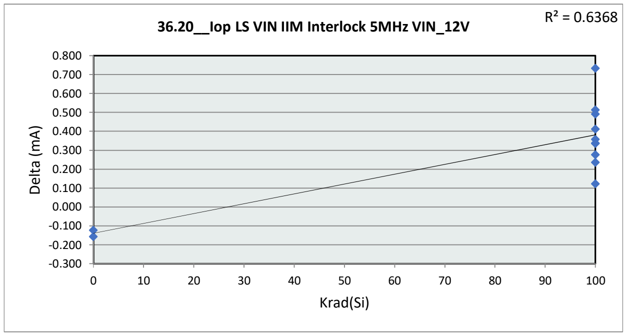


	36.19__Iop HS BOOT IIM Interlock 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.375	7.335
Average	7.414	7.487
Max	7.454	7.600
UL	10.500	10.500

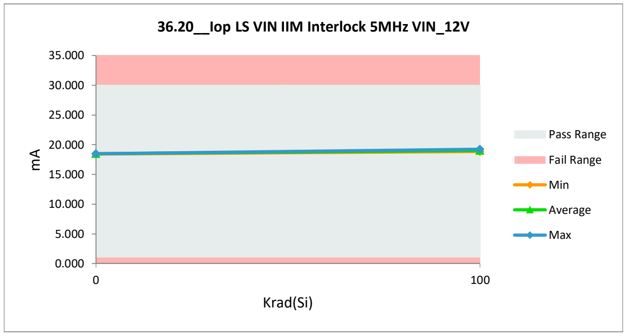


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.20__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.620	18.497	-0.123
0	2	18.600	18.444	-0.156
100	23	18.706	18.829	0.123
100	24	18.635	19.126	0.491
100	25	18.695	19.207	0.513
100	26	18.435	19.167	0.733
100	27	18.688	19.045	0.357
100	48u	18.557	18.833	0.277
100	49u	18.588	18.924	0.336
100	50u	18.604	18.941	0.337
100	51u	18.599	19.011	0.411
100	52u	18.745	18.981	0.236
	Max	18.745	19.207	0.733
	Average	18.623	18.917	0.294
	Min	18.435	18.444	-0.156
	Std Dev	0.082	0.240	0.254

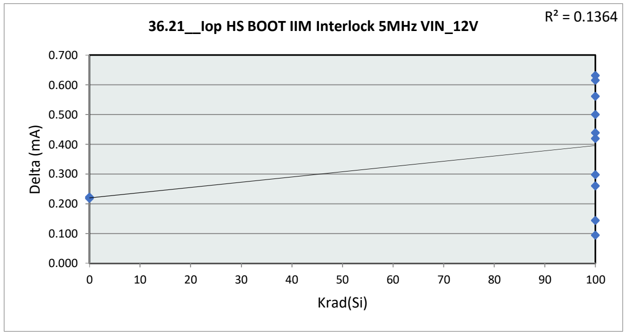


	36.20__Iop LS VIN IIM Interlock 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.444	18.829
Average	18.471	19.006
Max	18.498	19.207
UL	30.000	30.000

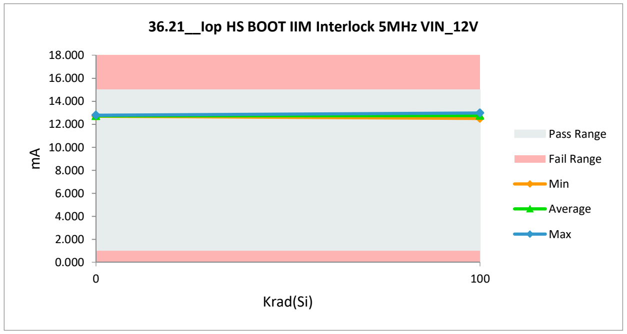


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.21__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		15	15	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.475	12.692	0.217
0	2	12.548	12.770	0.222
100	23	12.308	12.923	0.615
100	24	12.378	12.637	0.259
100	25	12.326	12.957	0.631
100	26	12.286	12.583	0.297
100	27	12.351	12.495	0.144
100	48u	12.550	12.969	0.419
100	49u	12.379	12.940	0.561
100	50u	12.490	12.583	0.094
100	51u	12.273	12.772	0.499
100	52u	12.345	12.783	0.438
	Max	12.550	12.969	0.631
	Average	12.392	12.759	0.366
	Min	12.273	12.495	0.094
	Std Dev	0.099	0.164	0.185

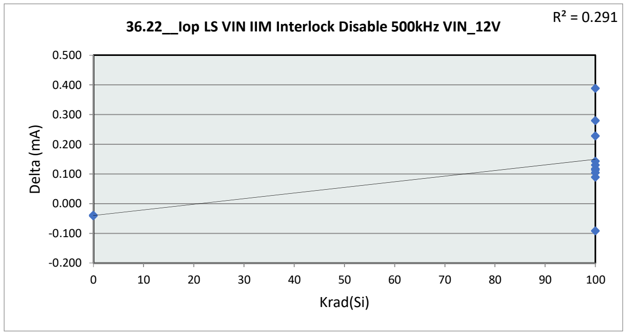


	36.21__Iop HS BOOT IIM Interlock 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.692	12.495
Average	12.731	12.764
Max	12.770	12.969
UL	15.000	15.000

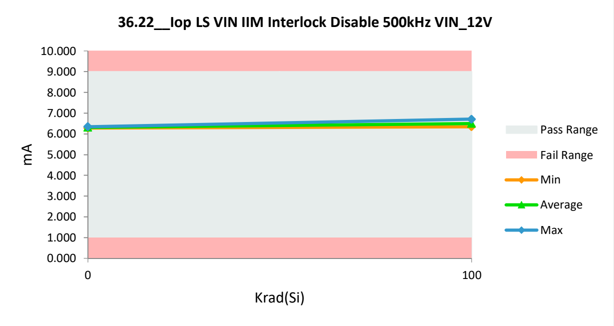


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.22__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.376	6.338	-0.039
0	2	6.319	6.278	-0.042
100	23	6.462	6.370	-0.092
100	24	6.379	6.607	0.228
100	25	6.428	6.707	0.279
100	26	6.169	6.557	0.388
100	27	6.412	6.555	0.143
100	48u	6.259	6.348	0.089
100	49u	6.300	6.405	0.104
100	50u	6.312	6.429	0.116
100	51u	6.345	6.475	0.129
100	52u	6.473	6.587	0.114
	Max	6.473	6.707	0.388
	Average	6.353	6.471	0.118
	Min	6.169	6.278	-0.092
	Std Dev	0.088	0.131	0.137



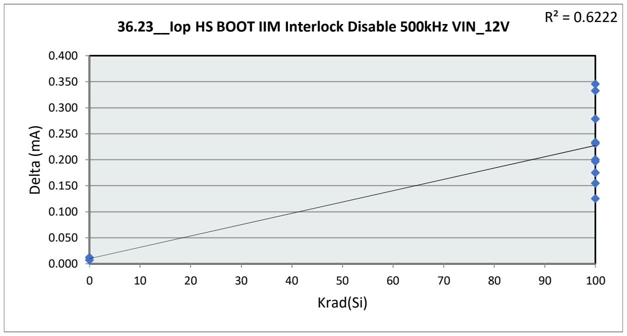
	36.22__Iop LS VIN IIM Interlock Disable 500kHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.278	6.348
Average	6.308	6.504
Max	6.338	6.707
UL	9.000	9.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

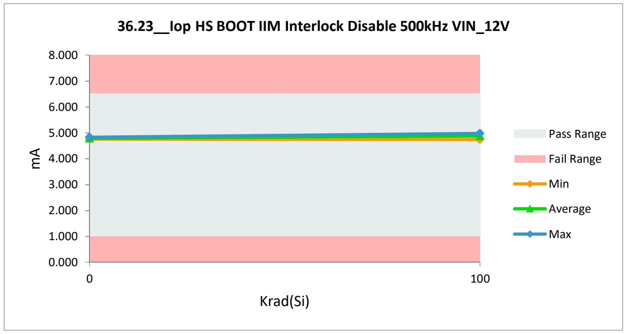
36.23__Iop HS BOOT IIM Interlo

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.738	4.750	0.012
0	2	4.816	4.823	0.007
100	23	4.626	4.972	0.346
100	24	4.664	4.943	0.279
100	25	4.635	4.968	0.333
100	26	4.595	4.771	0.175
100	27	4.602	4.833	0.231
100	48u	4.796	4.950	0.155
100	49u	4.692	4.926	0.234
100	50u	4.740	4.866	0.125
100	51u	4.542	4.742	0.200
100	52u	4.641	4.838	0.197
	Max	4.816	4.972	0.346
	Average	4.674	4.865	0.191
	Min	4.542	4.742	0.007
	Std Dev	0.084	0.085	0.107



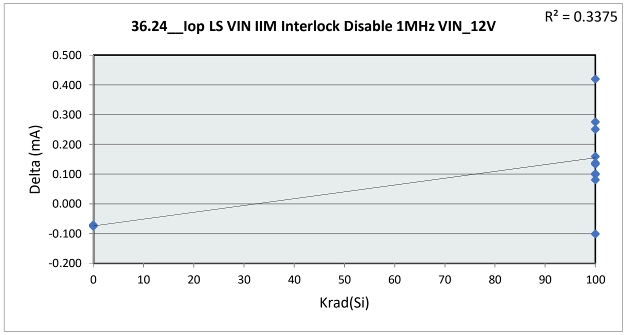
36.23__Iop HS BOOT IIM Interlock Disable 500kHz VIN

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.750	4.742
Average	4.787	4.881
Max	4.823	4.972
UL	6.500	6.500

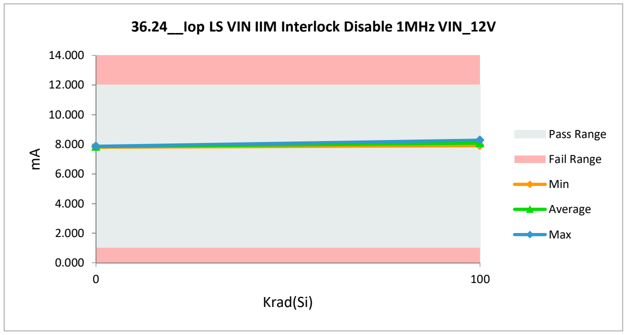


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.24__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.939	7.867	-0.072
0	2	7.885	7.808	-0.076
100	23	8.025	7.924	-0.102
100	24	7.942	8.192	0.250
100	25	7.994	8.269	0.275
100	26	7.734	8.153	0.419
100	27	7.977	8.136	0.159
100	48u	7.822	7.902	0.080
100	49u	7.869	7.969	0.101
100	50u	7.877	8.015	0.137
100	51u	7.908	8.040	0.133
100	52u	8.040	8.138	0.098
	Max	8.040	8.269	0.419
	Average	7.918	8.034	0.117
	Min	7.734	7.808	-0.102
	Std Dev	0.088	0.144	0.153

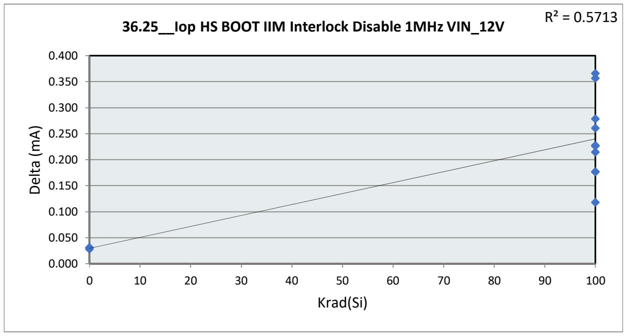


	36.24__Iop LS VIN IIM Interlock Disable 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.808	7.902
Average	7.838	8.074
Max	7.867	8.269
UL	12.000	12.000

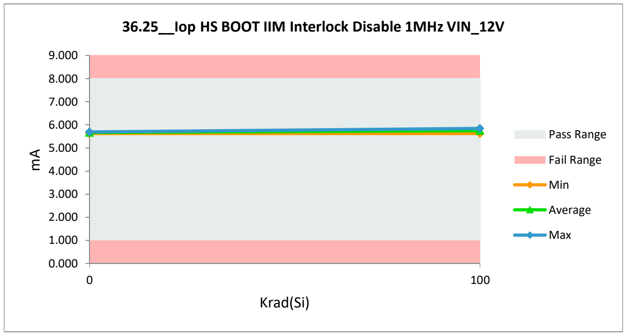


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
		36.25__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
0	1	5.593	5.624	0.031
0	2	5.672	5.700	0.028
100	23	5.480	5.846	0.366
100	24	5.520	5.799	0.279
100	25	5.488	5.844	0.357
100	26	5.448	5.625	0.177
100	27	5.455	5.681	0.226
100	48u	5.654	5.830	0.176
100	49u	5.545	5.806	0.261
100	50u	5.601	5.719	0.118
100	51u	5.399	5.627	0.227
100	52u	5.495	5.710	0.214
	Max	5.672	5.846	0.366
	Average	5.529	5.734	0.205
	Min	5.399	5.624	0.028
	Std Dev	0.085	0.087	0.108

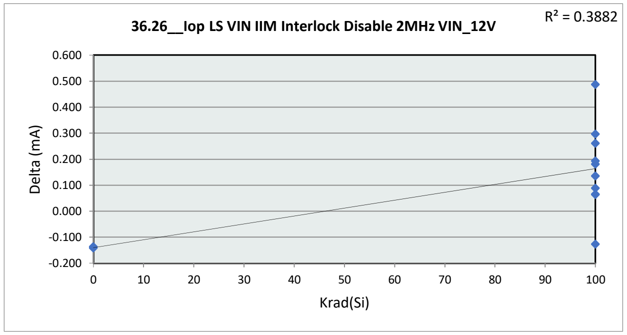


	36.25__Iop HS BOOT IIM Interlock Disable 1MHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.624	5.625
Average	5.662	5.749
Max	5.700	5.846
UL	8.000	8.000

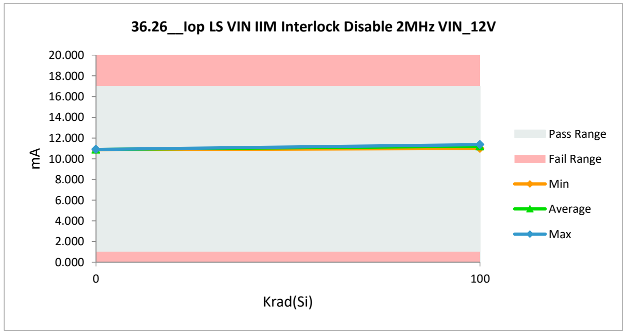


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.26__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.051	10.913	-0.138
0	2	11.002	10.860	-0.142
100	23	11.143	11.016	-0.127
100	24	11.058	11.354	0.296
100	25	11.114	11.375	0.261
100	26	10.851	11.337	0.486
100	27	11.096	11.289	0.193
100	48u	10.936	11.000	0.064
100	49u	10.997	11.085	0.088
100	50u	10.996	11.176	0.180
100	51u	11.022	11.157	0.135
100	52u	11.161	11.225	0.064
	Max	11.161	11.375	0.486
	Average	11.036	11.149	0.113
	Min	10.851	10.860	-0.142
	Std Dev	0.088	0.175	0.190

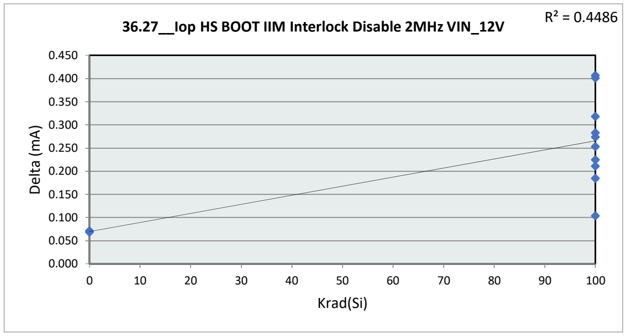


	36.26__Iop LS VIN IIM Interlock Disable 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.860	11.000
Average	10.887	11.201
Max	10.913	11.375
UL	17.000	17.000

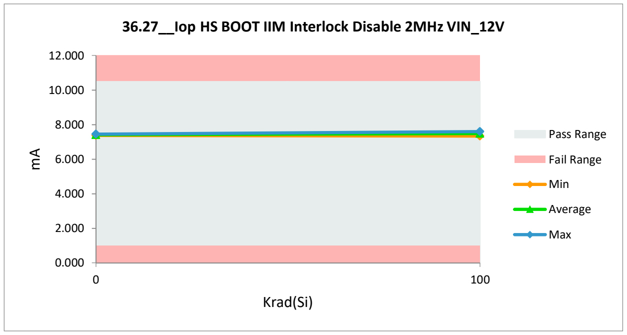


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.27__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.302	7.373	0.071
0	2	7.383	7.452	0.068
100	23	7.189	7.596	0.406
100	24	7.235	7.508	0.274
100	25	7.196	7.597	0.401
100	26	7.150	7.334	0.185
100	27	7.162	7.373	0.211
100	48u	7.370	7.595	0.225
100	49u	7.251	7.569	0.318
100	50u	7.321	7.424	0.103
100	51u	7.115	7.398	0.283
100	52u	7.204	7.457	0.253
	Max	7.383	7.597	0.406
	Average	7.240	7.473	0.233
	Min	7.115	7.334	0.068
	Std Dev	0.087	0.097	0.114

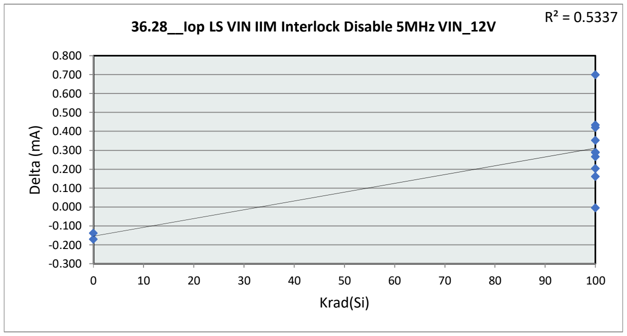


	36.27__Iop HS BOOT IIM Interlock Disable 2MHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.373	7.334
Average	7.413	7.485
Max	7.452	7.597
UL	10.500	10.500

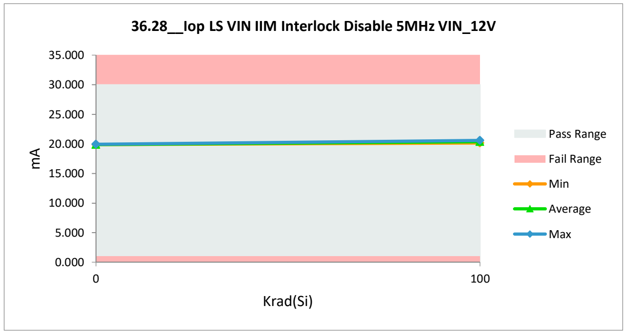


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.28__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	20.062	19.923	-0.139
0	2	20.048	19.877	-0.171
100	23	20.171	20.167	-0.004
100	24	20.082	20.502	0.420
100	25	20.147	20.581	0.434
100	26	19.868	20.568	0.700
100	27	20.125	20.413	0.289
100	48u	19.969	20.173	0.204
100	49u	20.023	20.289	0.266
100	50u	20.036	20.326	0.290
100	51u	20.046	20.398	0.352
100	52u	20.189	20.350	0.161
	Max	20.189	20.581	0.700
	Average	20.064	20.297	0.234
	Min	19.868	19.877	-0.171
	Std Dev	0.090	0.228	0.248

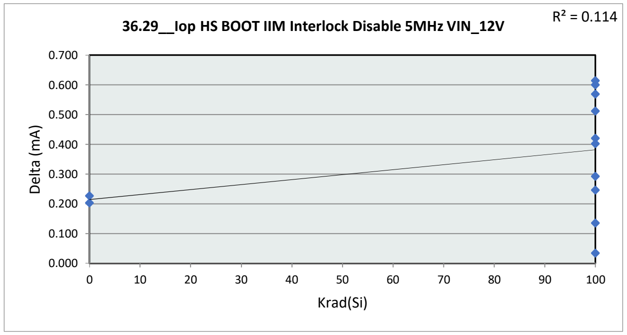


	36.28__Iop LS VIN IIM Interlock Disable 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.877	20.167
Average	19.900	20.377
Max	19.923	20.581
UL	30.000	30.000

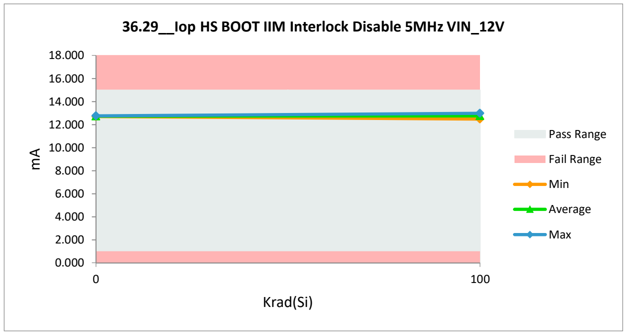


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		36.29__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		15	15	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.461	12.687	0.226
0	2	12.555	12.758	0.203
100	23	12.302	12.917	0.614
100	24	12.369	12.614	0.245
100	25	12.352	12.952	0.600
100	26	12.275	12.567	0.292
100	27	12.351	12.486	0.135
100	48u	12.565	12.967	0.402
100	49u	12.367	12.935	0.568
100	50u	12.516	12.550	0.034
100	51u	12.265	12.776	0.512
100	52u	12.359	12.779	0.420
	Max	12.565	12.967	0.614
	Average	12.395	12.749	0.354
	Min	12.265	12.486	0.034
	Std Dev	0.105	0.170	0.193

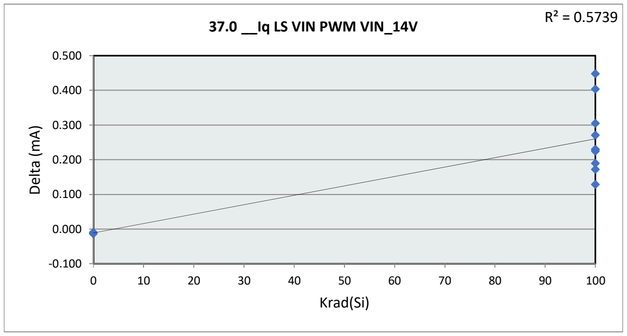


	36.29__Iop HS BOOT IIM Interlock Disable 5MHz VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.687	12.486
Average	12.723	12.754
Max	12.758	12.967
UL	15.000	15.000

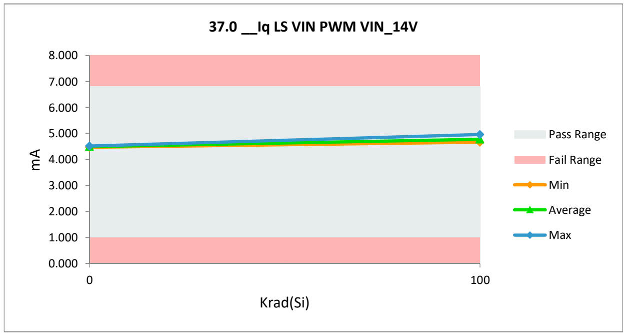


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.0 __Iq LS VIN PWM VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.8	6.8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.528	4.518	-0.010
0	2	4.479	4.466	-0.013
100	23	4.584	4.713	0.128
100	24	4.538	4.843	0.305
100	25	4.563	4.967	0.404
100	26	4.335	4.784	0.448
100	27	4.577	4.848	0.271
100	48u	4.485	4.675	0.190
100	49u	4.455	4.684	0.229
100	50u	4.492	4.664	0.172
100	51u	4.483	4.713	0.230
100	52u	4.636	4.861	0.225
	Max	4.636	4.967	0.448
	Average	4.513	4.728	0.215
	Min	4.335	4.466	-0.013
	Std Dev	0.077	0.144	0.140



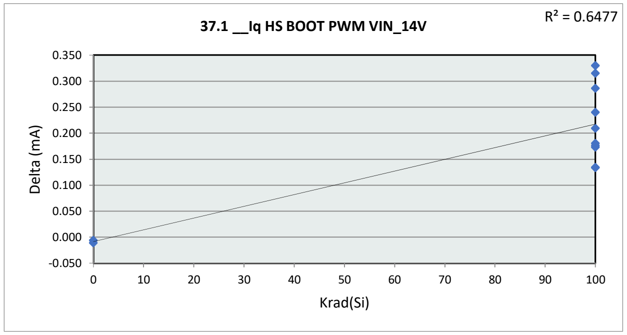
	37.0 __Iq LS VIN PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.466	4.664
Average	4.492	4.775
Max	4.518	4.967
UL	6.800	6.800



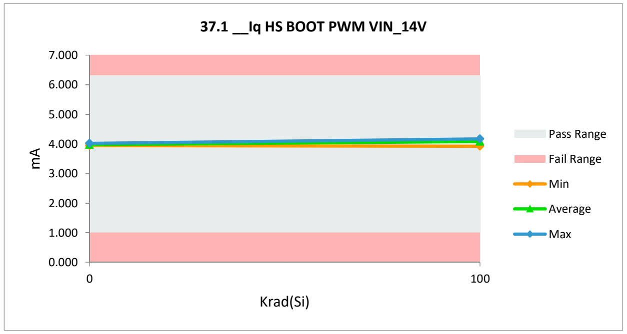
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	37.1 __Iq HS BOOT PWM VIN_14	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	6.3	6.3
Min Limit	1	1

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.949	3.943	-0.006
0	2	4.027	4.016	-0.011
100	23	3.837	4.167	0.330
100	24	3.869	4.155	0.286
100	25	3.847	4.161	0.315
100	26	3.808	3.981	0.173
100	27	3.812	4.052	0.240
100	48u	4.005	4.139	0.134
100	49u	3.905	4.114	0.209
100	50u	3.944	4.078	0.134
100	51u	3.750	3.926	0.176
100	52u	3.853	4.033	0.180
	Max	4.027	4.167	0.330
	Average	3.884	4.064	0.180
	Min	3.750	3.926	-0.011
	Std Dev	0.084	0.086	0.109

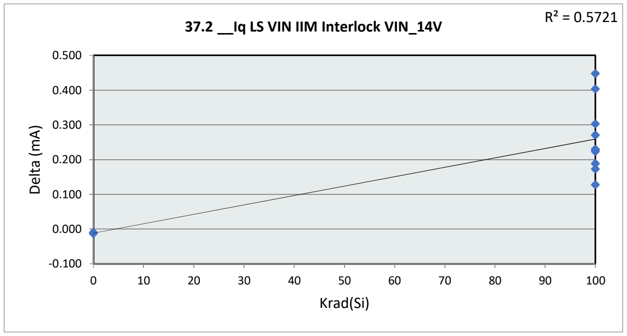


	37.1 __Iq HS BOOT PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.943	3.926
Average	3.979	4.081
Max	4.016	4.167
UL	6.300	6.300

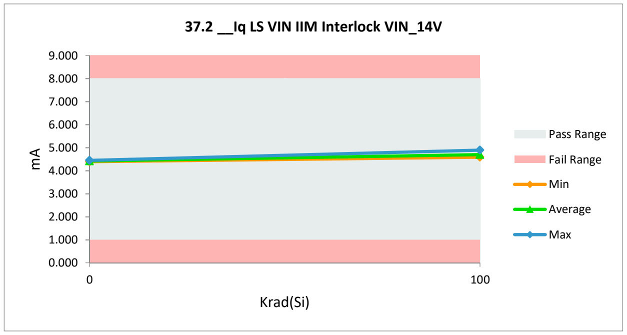


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.2 __Iq LS VIN IIM Interlock V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	8	8	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.455	4.445	-0.010
0	2	4.407	4.394	-0.013
100	23	4.512	4.639	0.127
100	24	4.466	4.769	0.303
100	25	4.491	4.894	0.403
100	26	4.264	4.711	0.447
100	27	4.506	4.776	0.270
100	48u	4.414	4.602	0.188
100	49u	4.382	4.610	0.228
100	50u	4.419	4.591	0.172
100	51u	4.412	4.641	0.230
100	52u	4.565	4.789	0.223
	Max	4.565	4.894	0.447
	Average	4.441	4.655	0.214
	Min	4.264	4.394	-0.013
	Std Dev	0.078	0.144	0.139

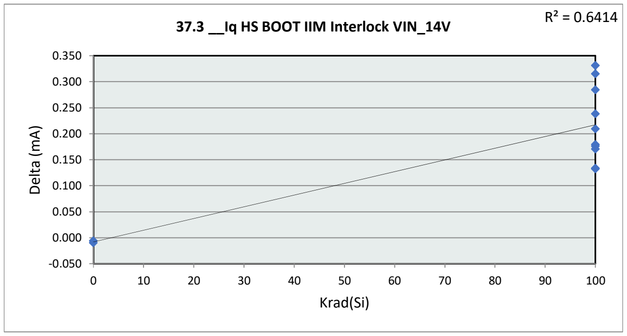


	37.2 __Iq LS VIN IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.394	4.591
Average	4.420	4.702
Max	4.445	4.895
UL	8.000	8.000

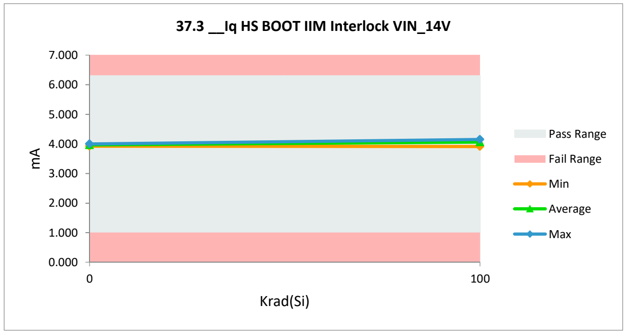


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.3 __Iq HS BOOT IIM Interloc		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.3	6.3	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.933	3.927	-0.006
0	2	4.010	4.001	-0.010
100	23	3.820	4.152	0.331
100	24	3.854	4.139	0.284
100	25	3.830	4.146	0.316
100	26	3.793	3.963	0.171
100	27	3.795	4.034	0.238
100	48u	3.989	4.123	0.134
100	49u	3.890	4.099	0.209
100	50u	3.929	4.061	0.133
100	51u	3.734	3.910	0.176
100	52u	3.838	4.017	0.179
	Max	4.010	4.152	0.331
	Average	3.868	4.048	0.180
	Min	3.734	3.910	-0.010
	Std Dev	0.084	0.086	0.109

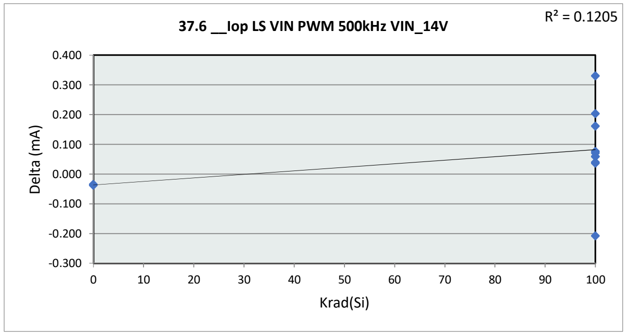


	37.3 __Iq HS BOOT IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.3	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	3.927	3.910
Average	3.964	4.064
Max	4.001	4.152
UL	6.300	6.300

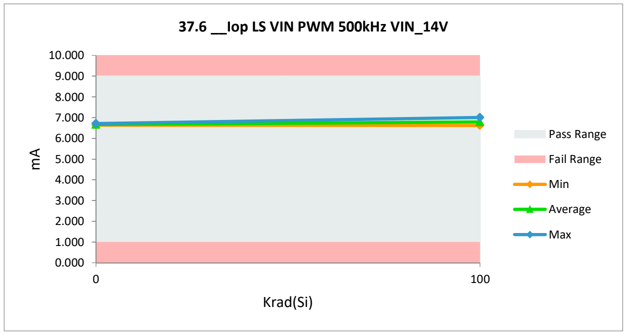


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.6 __Iop LS VIN PWM 500kHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		9	9	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.742	6.707	-0.035
0	2	6.679	6.641	-0.038
100	23	6.837	6.630	-0.208
100	24	6.738	6.899	0.161
100	25	6.802	7.005	0.203
100	26	6.525	6.854	0.330
100	27	6.766	6.825	0.059
100	48u	6.582	6.618	0.036
100	49u	6.658	6.697	0.039
100	50u	6.657	6.728	0.070
100	51u	6.717	6.792	0.076
100	52u	6.832	6.891	0.059
	Max	6.837	7.005	0.330
	Average	6.711	6.774	0.063
	Min	6.525	6.618	-0.208
	Std Dev	0.096	0.123	0.133

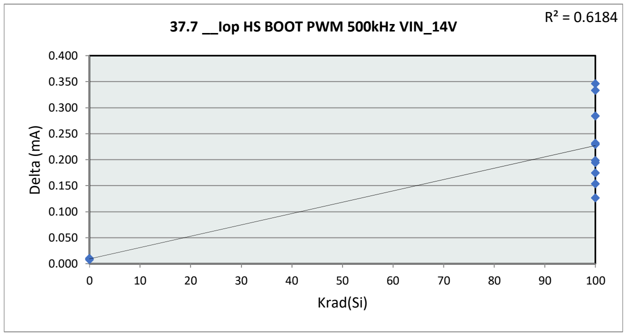


	37.6 __Iop LS VIN PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.641	6.618
Average	6.674	6.794
Max	6.707	7.005
UL	9.000	9.000

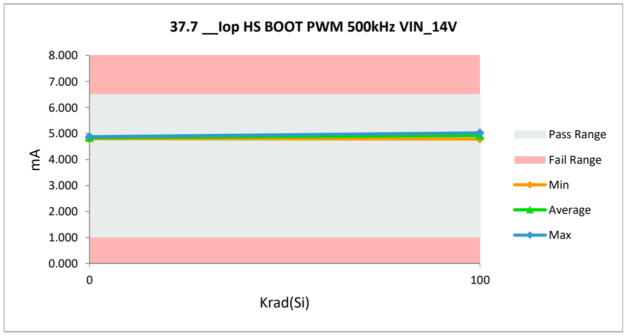


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.7 __Iop HS BOOT PWM 500kH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	6.5	6.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.787	4.798	0.010
0	2	4.865	4.873	0.008
100	23	4.673	5.019	0.346
100	24	4.706	4.991	0.284
100	25	4.684	5.017	0.333
100	26	4.642	4.817	0.174
100	27	4.650	4.879	0.230
100	48u	4.845	4.999	0.154
100	49u	4.741	4.972	0.232
100	50u	4.786	4.912	0.127
100	51u	4.592	4.790	0.198
100	52u	4.690	4.885	0.194
	Max	4.865	5.019	0.346
	Average	4.722	4.913	0.191
	Min	4.592	4.790	0.008
	Std Dev	0.084	0.085	0.108

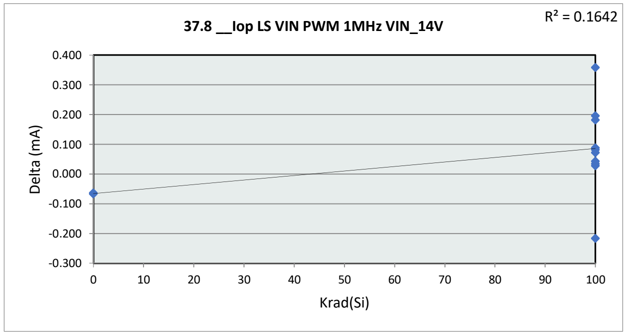


	37.7 __Iop HS BOOT PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.798	4.790
Average	4.835	4.928
Max	4.873	5.019
UL	6.500	6.500

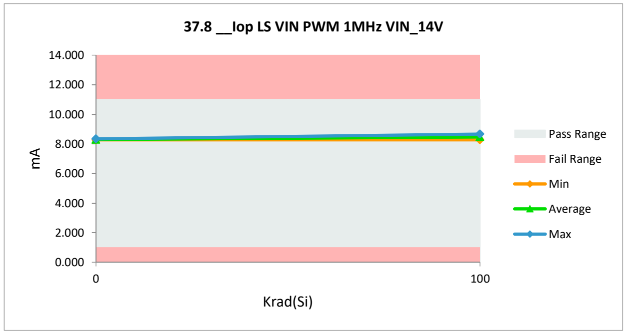


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.8 __Iop LS VIN PWM 1MHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		11	11	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.402	8.338	-0.064
0	2	8.346	8.279	-0.067
100	23	8.502	8.285	-0.217
100	24	8.399	8.580	0.181
100	25	8.471	8.666	0.195
100	26	8.191	8.549	0.358
100	27	8.431	8.503	0.072
100	48u	8.249	8.276	0.027
100	49u	8.329	8.363	0.034
100	50u	8.325	8.413	0.088
100	51u	8.381	8.463	0.082
100	52u	8.500	8.542	0.043
	Max	8.502	8.666	0.358
	Average	8.377	8.438	0.061
	Min	8.191	8.276	-0.217
	Std Dev	0.096	0.132	0.146

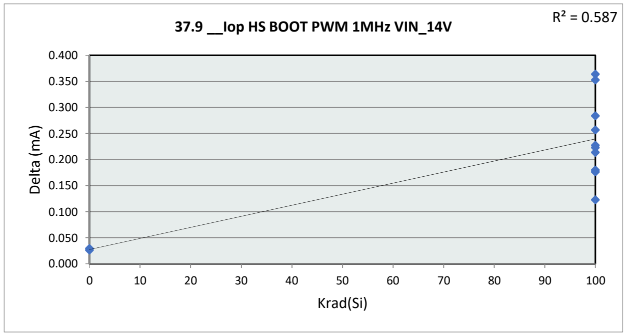


	37.8 __Iop LS VIN PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	11	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	8.279	8.276
Average	8.309	8.464
Max	8.338	8.666
UL	11.000	11.000

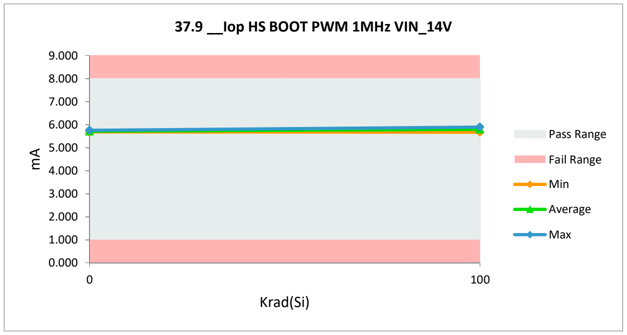


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.9 __Iop HS BOOT PWM 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.646	5.675	0.029
0	2	5.722	5.748	0.026
100	23	5.527	5.890	0.364
100	24	5.563	5.847	0.284
100	25	5.540	5.893	0.353
100	26	5.493	5.673	0.180
100	27	5.503	5.726	0.223
100	48u	5.703	5.880	0.176
100	49u	5.595	5.852	0.257
100	50u	5.644	5.766	0.122
100	51u	5.448	5.675	0.227
100	52u	5.545	5.759	0.214
	Max	5.722	5.893	0.364
	Average	5.577	5.782	0.204
	Min	5.448	5.673	0.026
	Std Dev	0.086	0.087	0.108

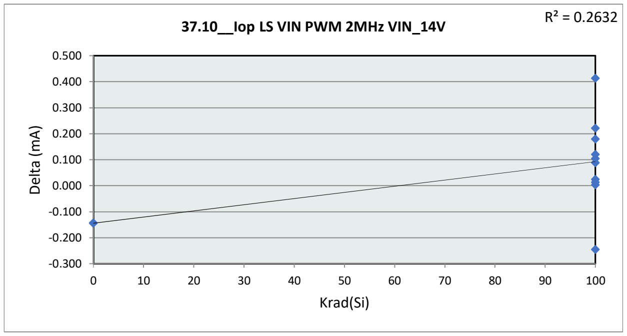


37.9 __Iop HS BOOT PWM 1MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.675	5.673
Average	5.711	5.796
Max	5.748	5.893
UL	8.000	8.000

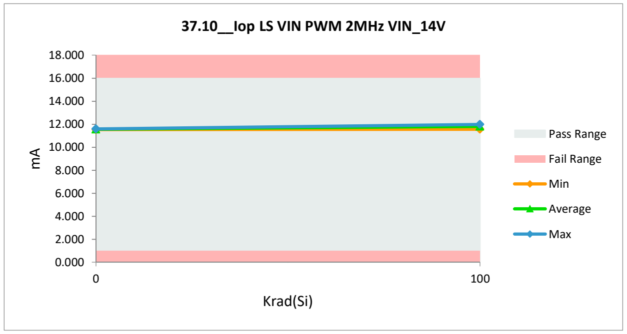


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.10__Iop LS VIN PWM 2MHz V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.720	11.577	-0.143
0	2	11.679	11.535	-0.145
100	23	11.822	11.577	-0.245
100	24	11.718	11.939	0.221
100	25	11.801	11.981	0.180
100	26	11.523	11.937	0.414
100	27	11.759	11.863	0.105
100	48u	11.567	11.570	0.004
100	49u	11.670	11.694	0.025
100	50u	11.659	11.779	0.120
100	51u	11.709	11.798	0.089
100	52u	11.837	11.851	0.014
	Max	11.837	11.981	0.414
	Average	11.705	11.758	0.053
	Min	11.523	11.535	-0.245
	Std Dev	0.095	0.163	0.179

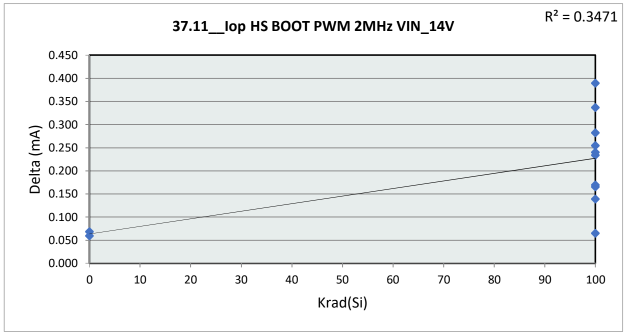


	37.10__Iop LS VIN PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	16	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	11.535	11.570
Average	11.556	11.799
Max	11.577	11.981
UL	16.000	16.000

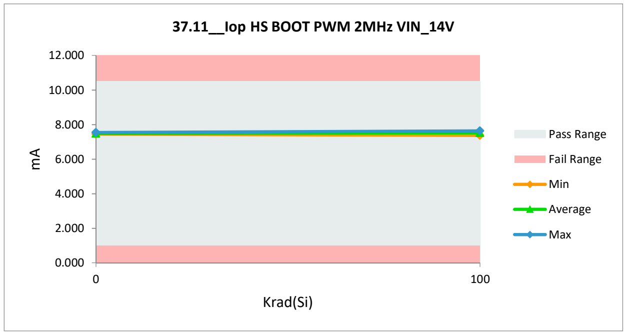


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.11__Iop HS BOOT PWM 2MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.380	7.439	0.059
0	2	7.464	7.532	0.068
100	23	7.215	7.604	0.389
100	24	7.267	7.549	0.282
100	25	7.287	7.623	0.336
100	26	7.231	7.369	0.139
100	27	7.244	7.409	0.165
100	48u	7.444	7.612	0.169
100	49u	7.331	7.585	0.254
100	50u	7.392	7.456	0.064
100	51u	7.199	7.432	0.233
100	52u	7.275	7.515	0.240
	Max	7.464	7.623	0.389
	Average	7.311	7.511	0.200
	Min	7.199	7.369	0.059
	Std Dev	0.090	0.087	0.108

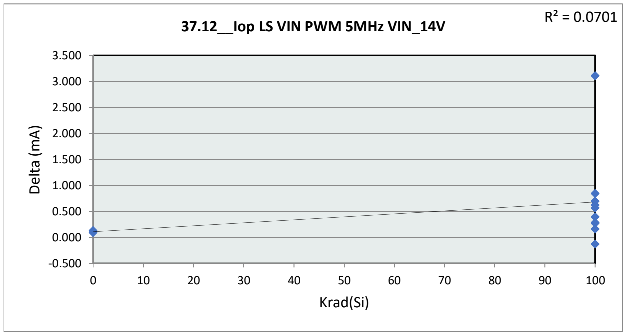


37.11__Iop HS BOOT PWM 2MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.440	7.369
Average	7.486	7.516
Max	7.532	7.623
UL	10.500	10.500

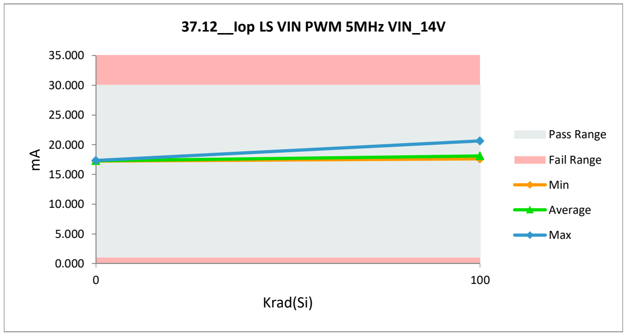


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.12__Iop LS VIN PWM 5MHz V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.196	17.326	0.130
0	2	17.132	17.226	0.094
100	23	17.771	17.646	-0.125
100	24	17.621	17.896	0.275
100	25	17.433	18.278	0.845
100	26	17.005	17.706	0.701
100	27	17.734	17.896	0.163
100	48u	17.339	17.906	0.567
100	49u	17.333	17.729	0.396
100	50u	17.332	17.620	0.288
100	51u	17.144	17.769	0.625
100	52u	17.524	20.632	3.108
	Max	17.771	20.632	3.108
	Average	17.380	17.969	0.589
	Min	17.005	17.226	-0.125
	Std Dev	0.245	0.882	0.842

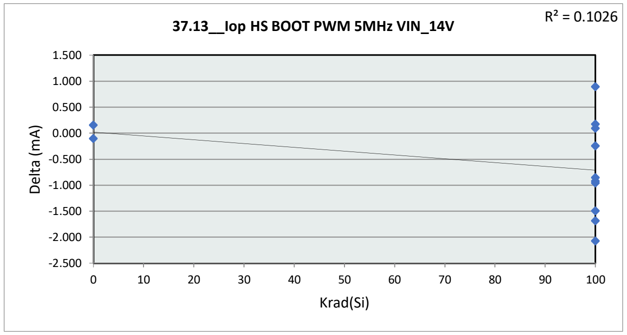


	37.12__Iop LS VIN PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	17.226	17.620
Average	17.276	18.108
Max	17.326	20.632
UL	30.000	30.000

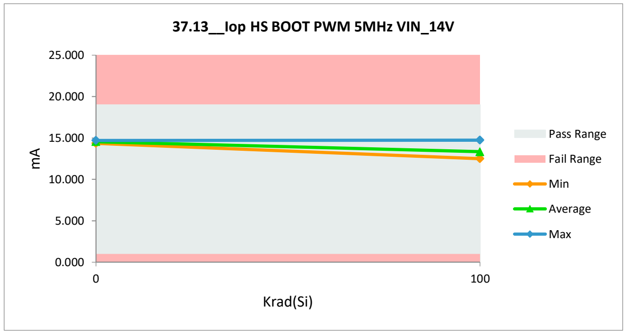


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.13__Iop HS BOOT PWM 5MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		19	19	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	14.549	14.699	0.151
0	2	14.470	14.364	-0.106
100	23	12.414	12.505	0.091
100	24	13.454	13.627	0.173
100	25	14.311	13.456	-0.856
100	26	14.240	13.277	-0.963
100	27	14.407	13.485	-0.922
100	48u	14.663	12.587	-2.076
100	49u	14.460	12.773	-1.687
100	50u	14.550	13.055	-1.495
100	51u	14.077	13.828	-0.249
100	52u	13.861	14.754	0.892
	Max	14.663	14.754	0.892
	Average	14.121	13.534	-0.587
	Min	12.414	12.505	-2.076
	Std Dev	0.636	0.767	0.889

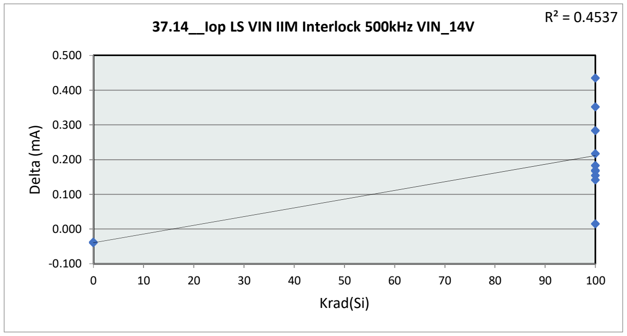


	37.13__Iop HS BOOT PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	19	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	14.364	12.505
Average	14.532	13.335
Max	14.699	14.754
UL	19.000	19.000

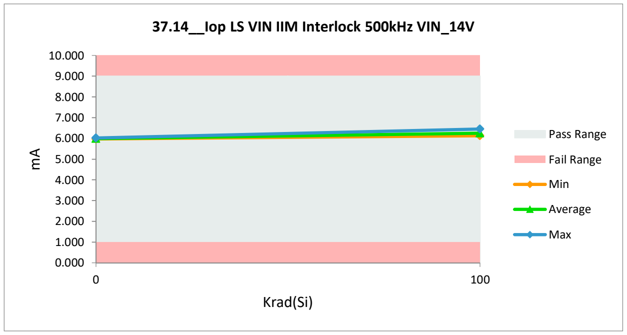


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.14__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.060	6.022	-0.038
0	2	6.009	5.969	-0.040
100	23	6.136	6.151	0.015
100	24	6.070	6.353	0.283
100	25	6.107	6.458	0.352
100	26	5.866	6.300	0.435
100	27	6.104	6.320	0.216
100	48u	5.983	6.124	0.141
100	49u	5.992	6.161	0.169
100	50u	6.015	6.169	0.154
100	51u	6.027	6.209	0.182
100	52u	6.165	6.332	0.167
	Max	6.165	6.458	0.435
	Average	6.044	6.214	0.170
	Min	5.866	5.969	-0.040
	Std Dev	0.081	0.143	0.145

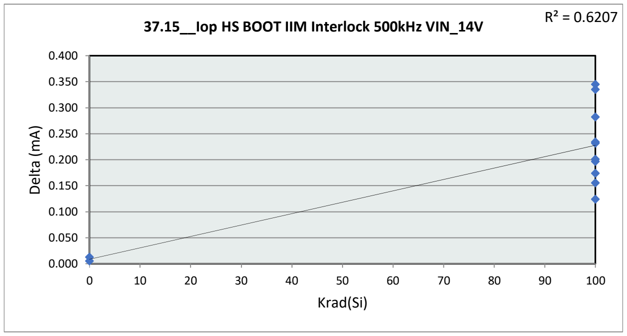


	37.14__Iop LS VIN IIM Interlock 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.969	6.124
Average	5.996	6.258
Max	6.022	6.459
UL	9.000	9.000

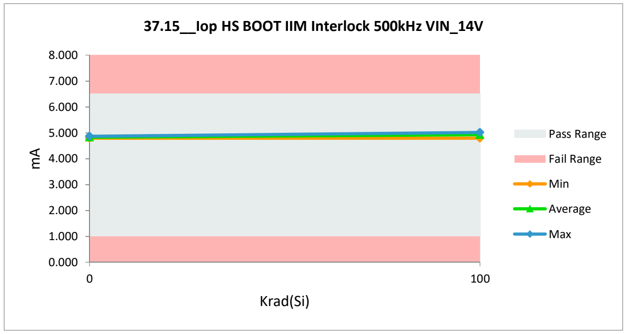


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.15__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.783	4.796	0.012
0	2	4.864	4.869	0.005
100	23	4.672	5.017	0.345
100	24	4.707	4.989	0.282
100	25	4.680	5.016	0.335
100	26	4.640	4.814	0.174
100	27	4.646	4.877	0.232
100	48u	4.843	4.998	0.155
100	49u	4.739	4.973	0.234
100	50u	4.787	4.911	0.124
100	51u	4.588	4.789	0.201
100	52u	4.688	4.885	0.197
	Max	4.864	5.017	0.345
	Average	4.720	4.911	0.191
	Min	4.588	4.789	0.005
	Std Dev	0.085	0.086	0.108

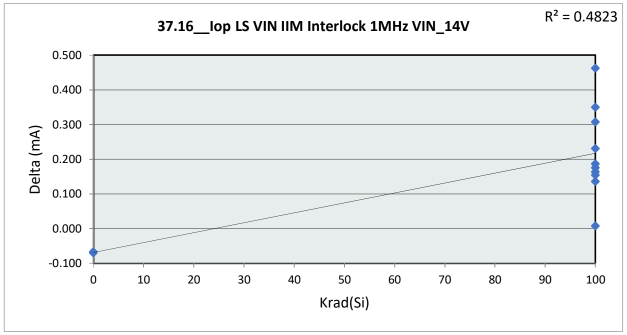


	37.15__Iop HS BOOT IIM Interlock 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.796	4.789
Average	4.832	4.927
Max	4.869	5.017
UL	6.500	6.500

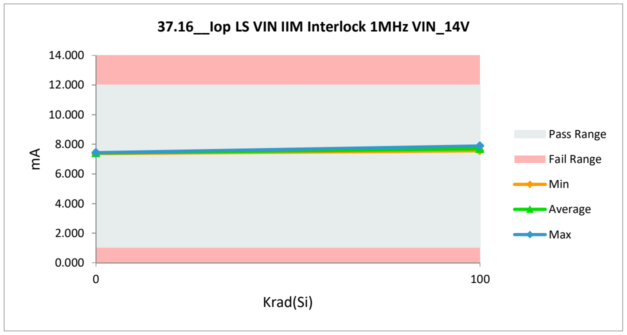


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.16__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.496	7.429	-0.067
0	2	7.448	7.378	-0.070
100	23	7.572	7.580	0.008
100	24	7.505	7.812	0.307
100	25	7.546	7.896	0.350
100	26	7.306	7.769	0.463
100	27	7.544	7.774	0.231
100	48u	7.419	7.554	0.136
100	49u	7.435	7.599	0.164
100	50u	7.453	7.628	0.175
100	51u	7.462	7.649	0.187
100	52u	7.605	7.759	0.154
	Max	7.605	7.896	0.463
	Average	7.483	7.652	0.170
	Min	7.306	7.378	-0.070
	Std Dev	0.081	0.156	0.160

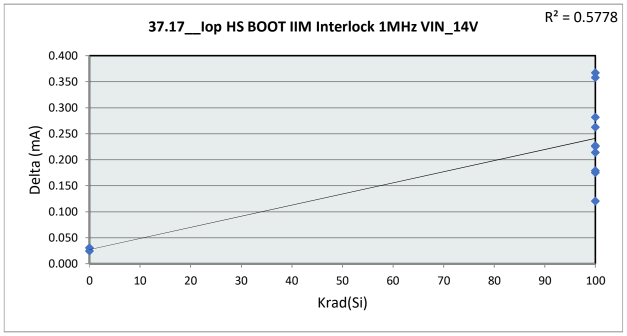


	37.16__Iop LS VIN IIM Interlock 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.378	7.554
Average	7.403	7.702
Max	7.429	7.896
UL	12.000	12.000

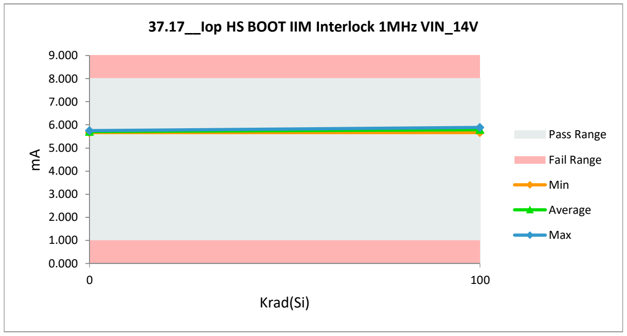


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.17__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		8	8	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.639	5.669	0.031
0	2	5.721	5.745	0.024
100	23	5.525	5.892	0.367
100	24	5.564	5.845	0.282
100	25	5.534	5.892	0.358
100	26	5.491	5.670	0.179
100	27	5.498	5.725	0.227
100	48u	5.702	5.877	0.175
100	49u	5.592	5.854	0.262
100	50u	5.645	5.766	0.120
100	51u	5.446	5.672	0.226
100	52u	5.542	5.756	0.214
	Max	5.721	5.892	0.367
	Average	5.575	5.780	0.205
	Min	5.446	5.669	0.024
	Std Dev	0.086	0.088	0.109

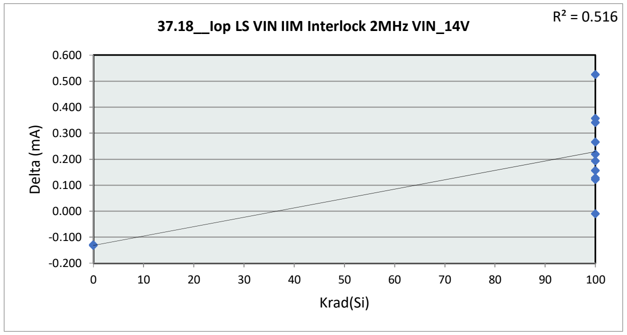


37.17__Iop HS BOOT IIM Interlock 1MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.669	5.670
Average	5.707	5.795
Max	5.745	5.892
UL	8.000	8.000

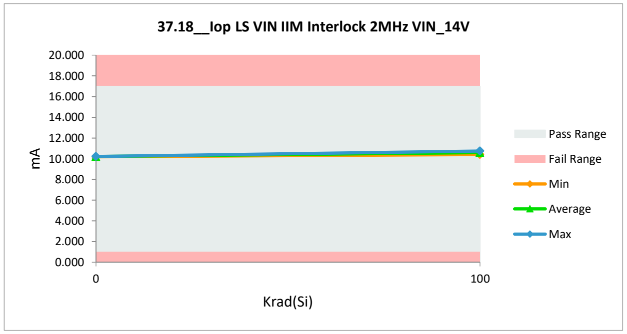


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.18__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	17	17	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	10.358	10.229	-0.130
0	2	10.314	10.181	-0.132
100	23	10.437	10.427	-0.010
100	24	10.368	10.725	0.356
100	25	10.415	10.755	0.340
100	26	10.175	10.700	0.525
100	27	10.410	10.675	0.265
100	48u	10.283	10.405	0.122
100	49u	10.311	10.467	0.156
100	50u	10.321	10.540	0.219
100	51u	10.326	10.520	0.193
100	52u	10.474	10.602	0.127
	Max	10.474	10.755	0.525
	Average	10.349	10.519	0.169
	Min	10.175	10.181	-0.132
	Std Dev	0.080	0.187	0.195

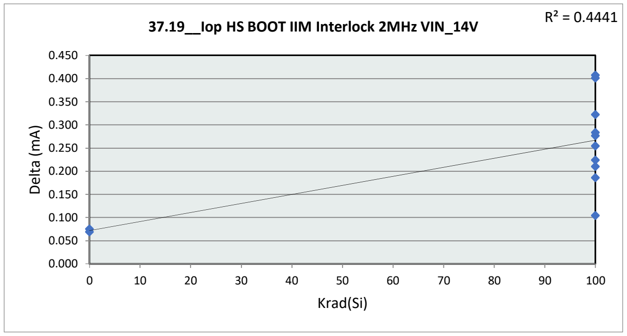


	37.18__Iop LS VIN IIM Interlock 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.181	10.405
Average	10.205	10.582
Max	10.229	10.755
UL	17.000	17.000

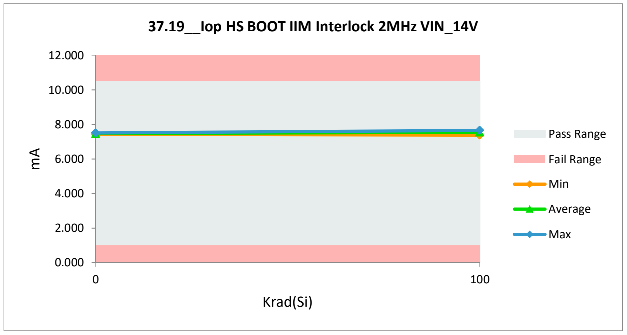


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.19__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.348	7.423	0.075
0	2	7.431	7.500	0.069
100	23	7.234	7.641	0.407
100	24	7.280	7.557	0.276
100	25	7.244	7.645	0.401
100	26	7.195	7.380	0.186
100	27	7.207	7.417	0.210
100	48u	7.418	7.642	0.224
100	49u	7.298	7.620	0.322
100	50u	7.368	7.472	0.104
100	51u	7.162	7.445	0.283
100	52u	7.251	7.505	0.254
	Max	7.431	7.645	0.407
	Average	7.286	7.521	0.234
	Min	7.162	7.380	0.069
	Std Dev	0.088	0.098	0.114

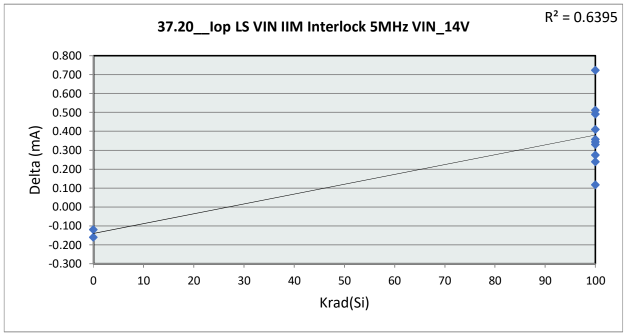


	37.19__Iop HS BOOT IIM Interlock 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.423	7.380
Average	7.461	7.532
Max	7.500	7.645
UL	10.500	10.500

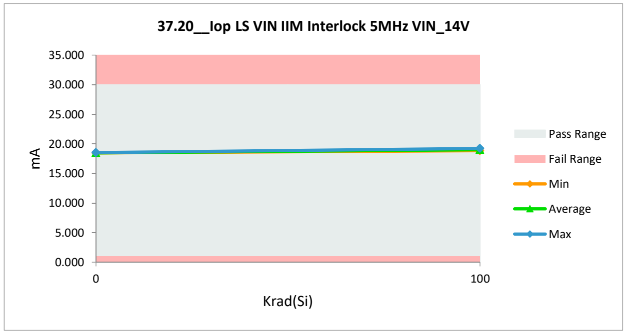


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.20__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.652	18.532	-0.120
0	2	18.636	18.476	-0.159
100	23	18.743	18.861	0.118
100	24	18.670	19.161	0.492
100	25	18.735	19.246	0.512
100	26	18.474	19.198	0.724
100	27	18.724	19.081	0.357
100	48u	18.592	18.866	0.274
100	49u	18.622	18.966	0.344
100	50u	18.643	18.974	0.331
100	51u	18.634	19.045	0.411
100	52u	18.776	19.015	0.240
	Max	18.776	19.246	0.724
	Average	18.658	18.952	0.294
	Min	18.474	18.476	-0.159
	Std Dev	0.081	0.241	0.253

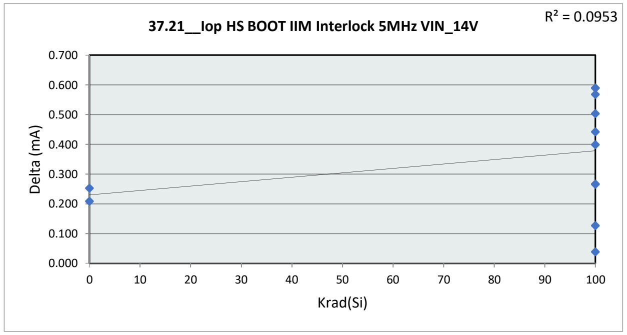


	37.20__Iop LS VIN IIM Interlock 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	18.476	18.861
Average	18.504	19.041
Max	18.532	19.246
UL	30.000	30.000

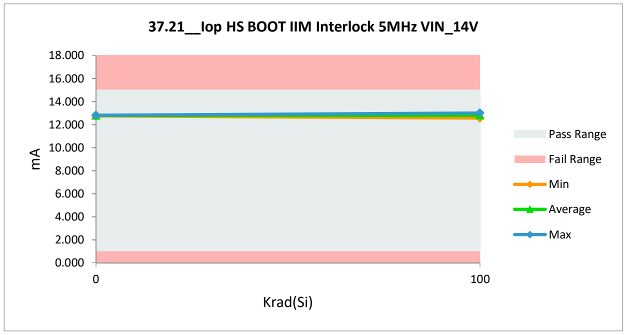


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.21__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.496	12.747	0.252
0	2	12.612	12.820	0.208
100	23	12.378	12.967	0.589
100	24	12.426	12.691	0.266
100	25	12.412	13.001	0.589
100	26	12.339	12.605	0.266
100	27	12.425	12.552	0.127
100	48u	12.613	13.012	0.399
100	49u	12.414	12.982	0.568
100	50u	12.570	12.608	0.038
100	51u	12.324	12.828	0.503
100	52u	12.388	12.829	0.441
	Max	12.613	13.012	0.589
	Average	12.450	12.803	0.354
	Min	12.324	12.552	0.038
	Std Dev	0.100	0.165	0.188

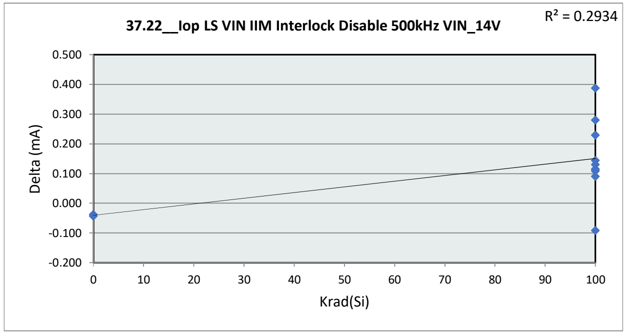


	37.21__Iop HS BOOT IIM Interlock 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.747	12.552
Average	12.784	12.807
Max	12.820	13.012
UL	15.000	15.000

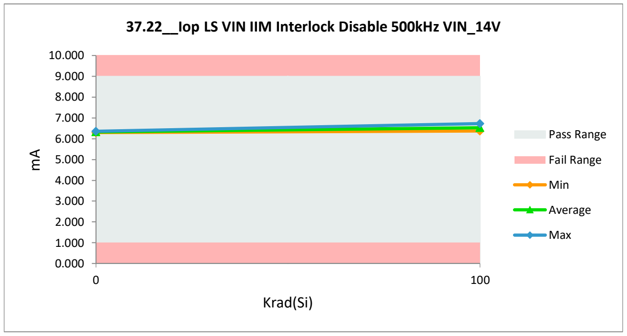


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.22__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	9	9	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.400	6.362	-0.038
0	2	6.343	6.300	-0.043
100	23	6.485	6.393	-0.092
100	24	6.403	6.632	0.229
100	25	6.452	6.732	0.280
100	26	6.193	6.581	0.388
100	27	6.435	6.580	0.144
100	48u	6.282	6.372	0.090
100	49u	6.323	6.431	0.108
100	50u	6.335	6.450	0.115
100	51u	6.370	6.499	0.130
100	52u	6.496	6.610	0.114
	Max	6.496	6.732	0.388
	Average	6.376	6.495	0.119
	Min	6.193	6.300	-0.092
	Std Dev	0.088	0.131	0.137

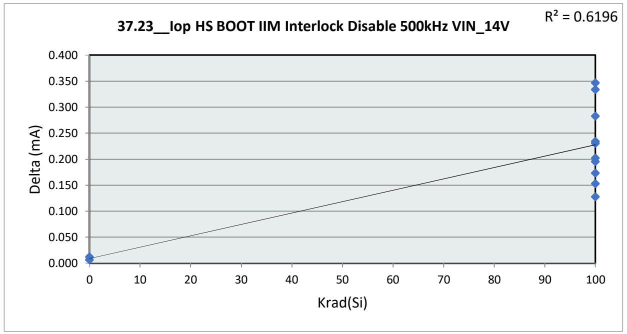


	37.22__Iop LS VIN IIM Interlock Disable 500kHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	6.300	6.373
Average	6.331	6.528
Max	6.362	6.732
UL	9.000	9.000

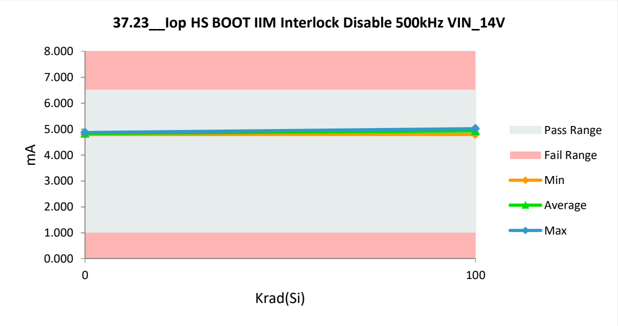


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.23__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		6.5	6.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.783	4.795	0.012
0	2	4.863	4.869	0.006
100	23	4.672	5.018	0.347
100	24	4.708	4.990	0.283
100	25	4.680	5.014	0.334
100	26	4.640	4.813	0.173
100	27	4.646	4.877	0.230
100	48u	4.842	4.995	0.153
100	49u	4.738	4.972	0.234
100	50u	4.785	4.912	0.128
100	51u	4.587	4.789	0.202
100	52u	4.687	4.882	0.195
	Max	4.863	5.018	0.347
	Average	4.719	4.910	0.191
	Min	4.587	4.789	0.006
	Std Dev	0.084	0.086	0.108

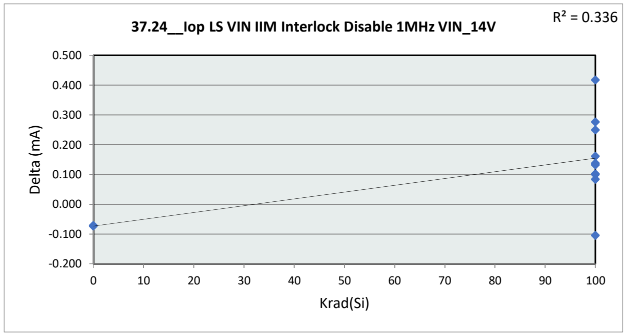


	37.23__Iop HS BOOT IIM Interlock Disable 500kHz VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	6.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	4.795	4.789
Average	4.832	4.926
Max	4.869	5.019
UL	6.500	6.500

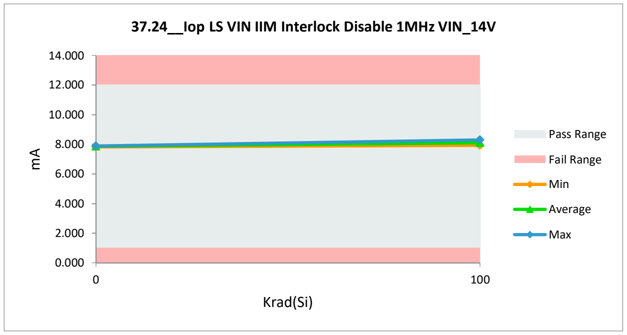


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.24__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		12	12	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.963	7.891	-0.072
0	2	7.908	7.833	-0.074
100	23	8.051	7.946	-0.105
100	24	7.967	8.217	0.249
100	25	8.018	8.294	0.276
100	26	7.759	8.177	0.417
100	27	8.001	8.161	0.160
100	48u	7.845	7.929	0.084
100	49u	7.894	7.996	0.102
100	50u	7.902	8.038	0.137
100	51u	7.933	8.065	0.132
100	52u	8.063	8.163	0.100
	Max	8.063	8.294	0.417
	Average	7.942	8.059	0.117
	Min	7.759	7.833	-0.105
	Std Dev	0.088	0.144	0.153



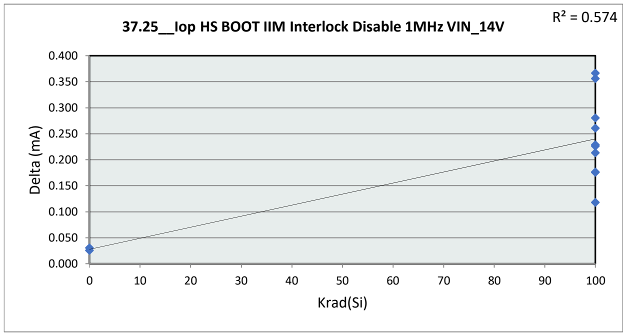
	37.24__Iop LS VIN IIM Interlock Disable 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.834	7.929
Average	7.862	8.099
Max	7.891	8.294
UL	12.000	12.000



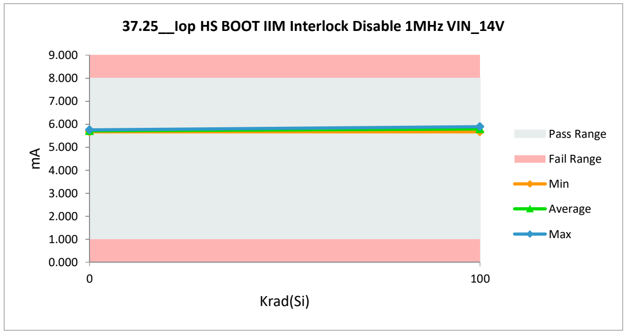
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	37.25__Iop HS BOOT IIM Interlo	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	mA	mA
Max Limit	8	8
Min Limit	1	1

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.637	5.668	0.030
0	2	5.719	5.745	0.026
100	23	5.526	5.892	0.366
100	24	5.564	5.845	0.280
100	25	5.534	5.890	0.356
100	26	5.492	5.668	0.176
100	27	5.499	5.725	0.226
100	48u	5.700	5.877	0.177
100	49u	5.591	5.851	0.260
100	50u	5.646	5.764	0.118
100	51u	5.444	5.673	0.229
100	52u	5.541	5.754	0.213
	Max	5.719	5.892	0.366
	Average	5.574	5.779	0.205
	Min	5.444	5.668	0.026
	Std Dev	0.086	0.088	0.109

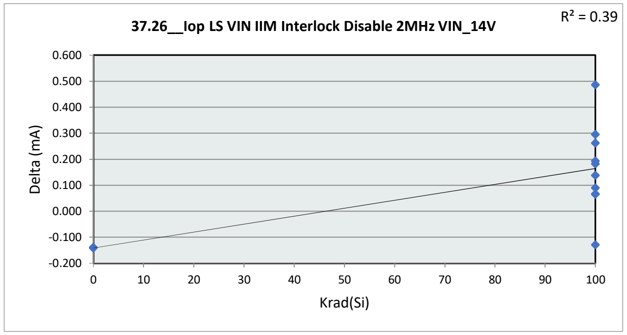


	37.25__Iop HS BOOT IIM Interlock Disable 1MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	5.668	5.668
Average	5.706	5.794
Max	5.745	5.892
UL	8.000	8.000

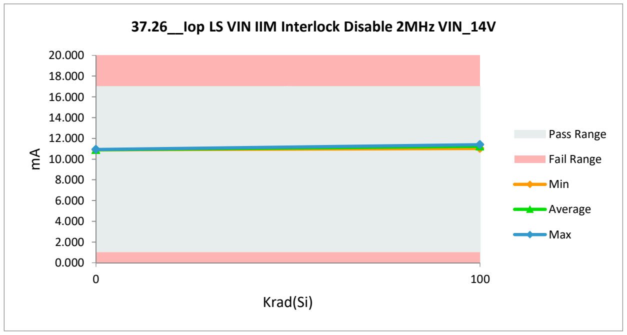


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.26__Iop LS VIN IIM Interlock		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		17	17	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	11.079	10.939	-0.139
0	2	11.028	10.886	-0.142
100	23	11.170	11.040	-0.129
100	24	11.085	11.379	0.294
100	25	11.141	11.403	0.262
100	26	10.879	11.364	0.485
100	27	11.122	11.315	0.193
100	48u	10.962	11.028	0.065
100	49u	11.023	11.112	0.089
100	50u	11.023	11.205	0.182
100	51u	11.049	11.186	0.137
100	52u	11.186	11.252	0.065
	Max	11.186	11.403	0.485
	Average	11.062	11.176	0.113
	Min	10.879	10.886	-0.142
	Std Dev	0.088	0.175	0.190

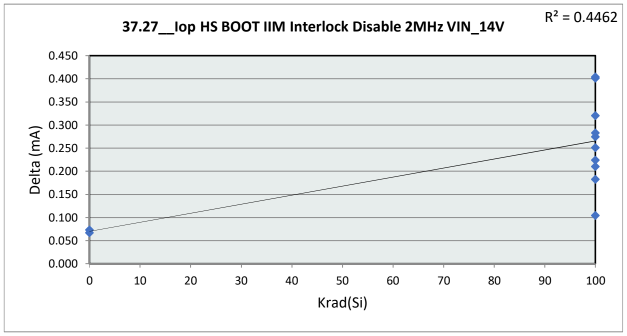


	37.26__Iop LS VIN IIM Interlock Disable 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	17	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	10.886	11.028
Average	10.913	11.228
Max	10.940	11.403
UL	17.000	17.000

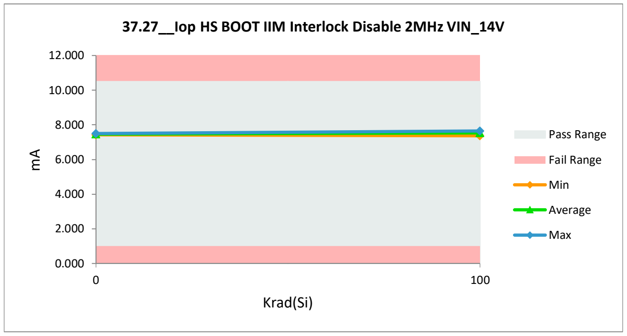


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.27__Iop HS BOOT IIM Interlo		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		mA	mA	
Max Limit		10.5	10.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.347	7.420	0.073
0	2	7.431	7.498	0.067
100	23	7.236	7.640	0.404
100	24	7.280	7.555	0.274
100	25	7.243	7.644	0.401
100	26	7.195	7.378	0.183
100	27	7.207	7.417	0.210
100	48u	7.417	7.641	0.224
100	49u	7.297	7.617	0.320
100	50u	7.367	7.471	0.104
100	51u	7.162	7.445	0.283
100	52u	7.250	7.502	0.251
	Max	7.431	7.644	0.404
	Average	7.286	7.519	0.233
	Min	7.162	7.378	0.067
	Std Dev	0.087	0.098	0.114

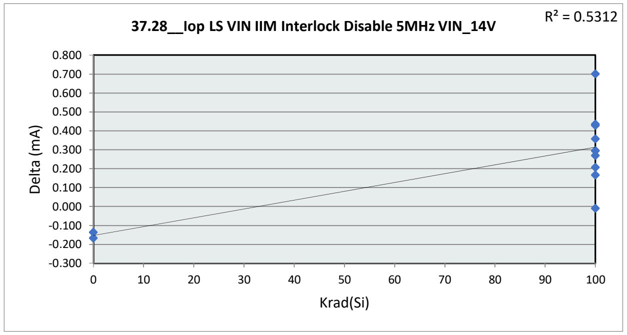


	37.27__Iop HS BOOT IIM Interlock Disable 2MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10.5	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	7.420	7.378
Average	7.459	7.531
Max	7.498	7.644
UL	10.500	10.500

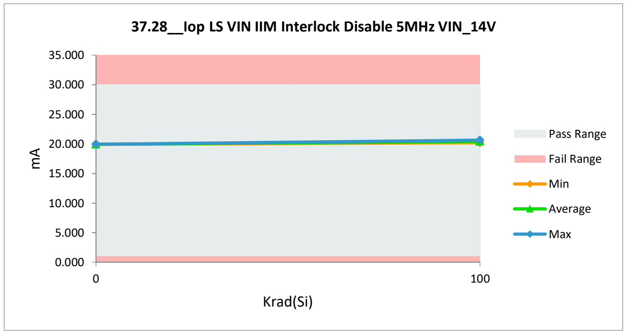


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.28__Iop LS VIN IIM Interlock		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	20.094	19.956	-0.138
0	2	20.080	19.912	-0.168
100	23	20.205	20.194	-0.010
100	24	20.115	20.542	0.427
100	25	20.182	20.617	0.434
100	26	19.903	20.603	0.699
100	27	20.157	20.451	0.294
100	48u	19.996	20.203	0.207
100	49u	20.057	20.325	0.269
100	50u	20.068	20.362	0.294
100	51u	20.078	20.435	0.357
100	52u	20.218	20.383	0.165
	Max	20.218	20.617	0.699
	Average	20.096	20.332	0.236
	Min	19.903	19.912	-0.168
	Std Dev	0.090	0.230	0.249

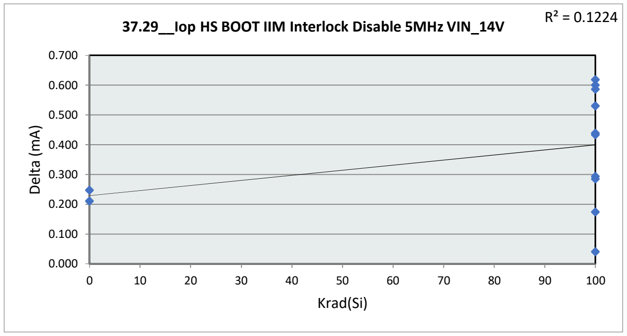


	37.28__Iop LS VIN IIM Interlock Disable 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	30	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	19.912	20.194
Average	19.934	20.412
Max	19.956	20.617
UL	30.000	30.000

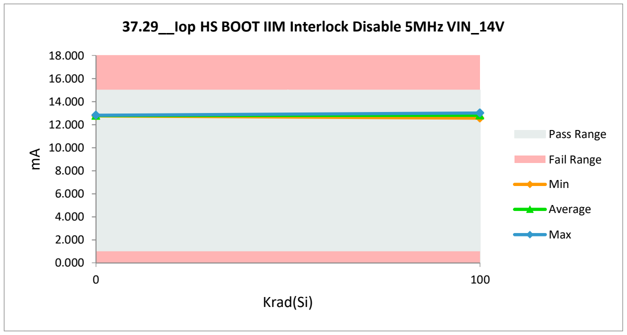


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		37.29__Iop HS BOOT IIM Interlo		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	mA	mA	
	Max Limit	15	15	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	12.498	12.746	0.247
0	2	12.597	12.807	0.211
100	23	12.349	12.967	0.618
100	24	12.403	12.687	0.284
100	25	12.400	13.000	0.600
100	26	12.314	12.607	0.294
100	27	12.383	12.557	0.174
100	48u	12.580	13.014	0.433
100	49u	12.400	12.986	0.586
100	50u	12.556	12.596	0.040
100	51u	12.294	12.824	0.530
100	52u	12.387	12.825	0.439
	Max	12.597	13.014	0.618
	Average	12.430	12.801	0.371
	Min	12.294	12.557	0.040
	Std Dev	0.103	0.166	0.190

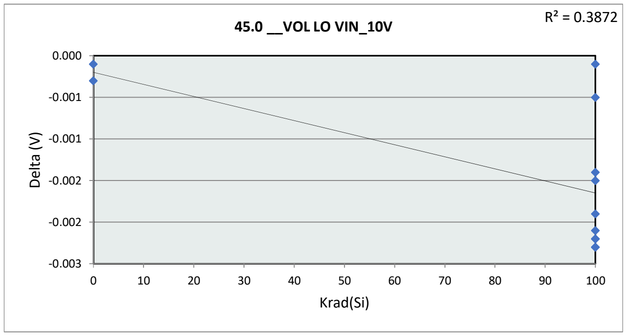


	37.29__Iop HS BOOT IIM Interlock Disable 5MHz VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	mA
Min Limit	1	mA
Krad(Si)	0	100
LL	1.000	1.000
Min	12.746	12.557
Average	12.776	12.806
Max	12.807	13.014
UL	15.000	15.000

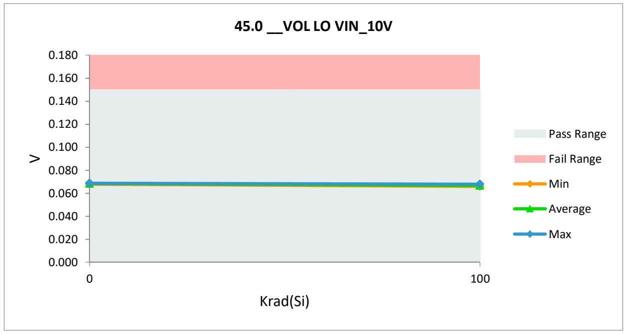


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		45.0 __VOL LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.15	0.15	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.068	0.068	0.000
0	2	0.069	0.069	0.000
100	23	0.068	0.068	-0.001
100	24	0.069	0.067	-0.002
100	25	0.068	0.067	-0.001
100	26	0.069	0.067	-0.002
100	27	0.068	0.068	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.066	-0.002
100	52u	0.069	0.067	-0.002
	Max	0.069	0.069	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.002
	Std Dev	0.000	0.001	0.001

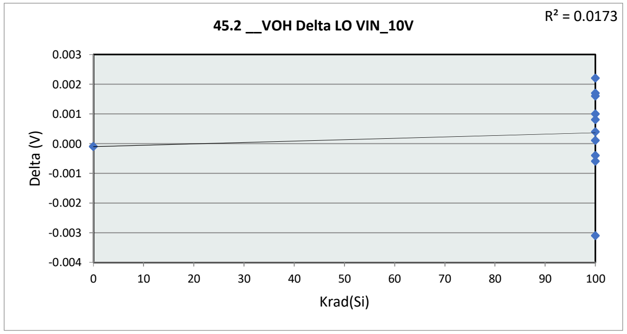


	45.0 __VOL LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.068	0.066
Average	0.068	0.067
Max	0.069	0.068
UL	0.150	0.150

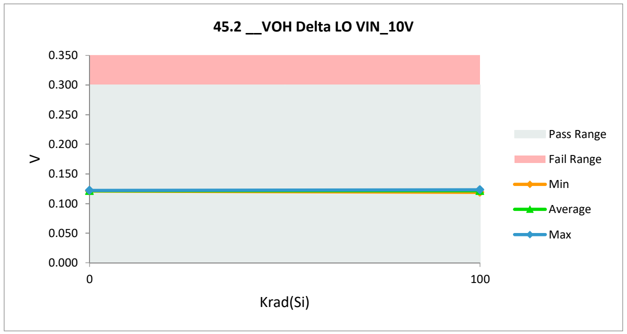


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		45.2 __VOH Delta LO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.3	0.3	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.121	0.121	0.000
0	2	0.122	0.122	0.000
100	23	0.122	0.122	-0.001
100	24	0.121	0.121	0.000
100	25	0.123	0.123	0.000
100	26	0.122	0.121	0.000
100	27	0.122	0.119	-0.003
100	48u	0.120	0.123	0.002
100	49u	0.120	0.122	0.002
100	50u	0.120	0.121	0.001
100	51u	0.122	0.123	0.001
100	52u	0.122	0.123	0.002
	Max	0.123	0.123	0.002
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.001

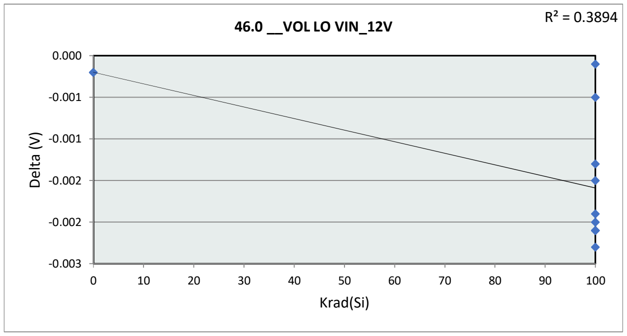


	45.2 __VOH Delta LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.122	0.122
Max	0.122	0.123
UL	0.300	0.300

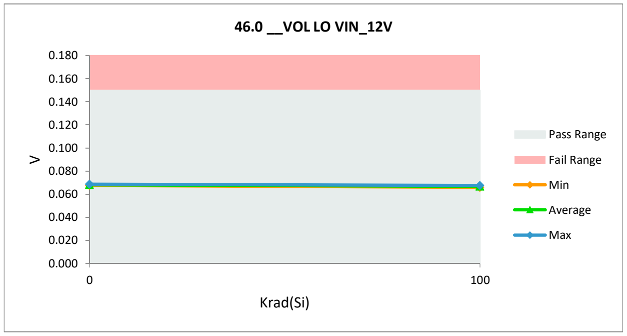


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		46.0 __VOL LO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.15	0.15	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.068	0.068	0.000
0	2	0.069	0.069	0.000
100	23	0.068	0.068	-0.001
100	24	0.069	0.067	-0.001
100	25	0.068	0.067	-0.001
100	26	0.068	0.067	-0.002
100	27	0.068	0.068	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.066	-0.002
100	52u	0.069	0.067	-0.002
	Max	0.069	0.069	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.002
	Std Dev	0.000	0.001	0.001

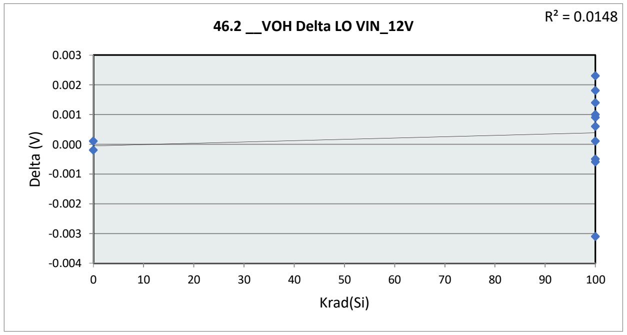


	46.0 __VOL LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.068	0.066
Average	0.068	0.067
Max	0.069	0.068
UL	0.150	0.150

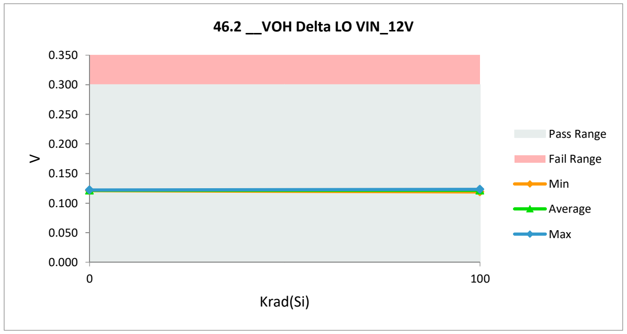


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		46.2 __VOH Delta LO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.3	0.3	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.121	0.121	0.000
0	2	0.122	0.122	0.000
100	23	0.122	0.122	-0.001
100	24	0.121	0.121	0.000
100	25	0.122	0.123	0.001
100	26	0.121	0.121	-0.001
100	27	0.122	0.119	-0.003
100	48u	0.120	0.123	0.002
100	49u	0.120	0.121	0.001
100	50u	0.120	0.121	0.001
100	51u	0.122	0.122	0.001
100	52u	0.122	0.123	0.002
	Max	0.122	0.123	0.002
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.001

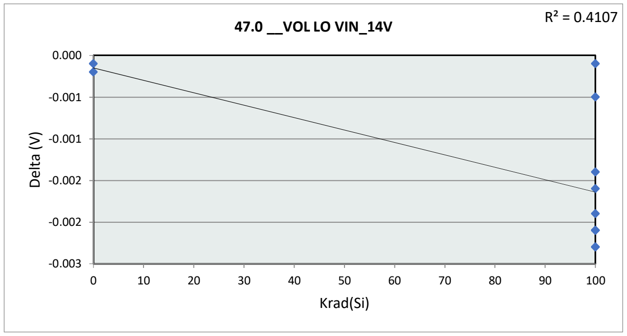


	46.2 __VOH Delta LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.122	0.122
Max	0.122	0.123
UL	0.300	0.300

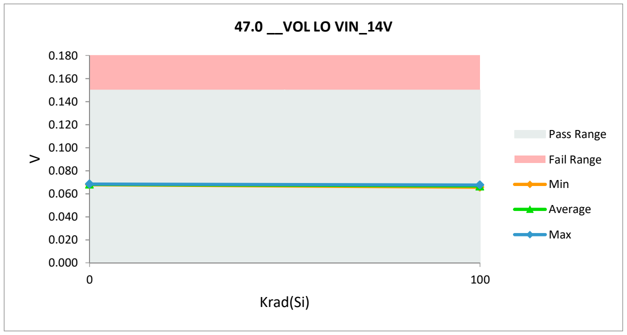


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		47.0 __VOL LO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.15	0.15	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.068	0.068	0.000
0	2	0.069	0.068	0.000
100	23	0.068	0.068	-0.001
100	24	0.069	0.067	-0.002
100	25	0.068	0.066	-0.001
100	26	0.068	0.066	-0.002
100	27	0.068	0.067	0.000
100	48u	0.069	0.067	-0.002
100	49u	0.068	0.066	-0.002
100	50u	0.068	0.066	-0.002
100	51u	0.068	0.066	-0.002
100	52u	0.069	0.067	-0.002
	Max	0.069	0.068	0.000
	Average	0.068	0.067	-0.001
	Min	0.068	0.066	-0.002
	Std Dev	0.000	0.001	0.001

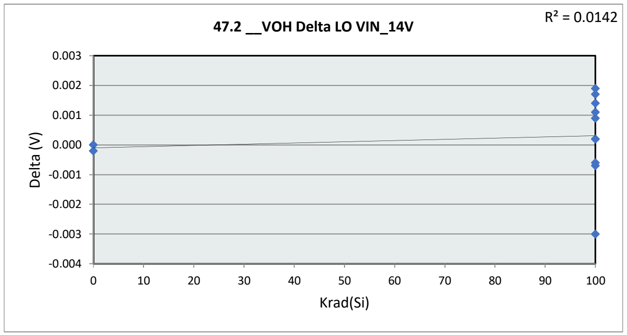


	47.0 __VOL LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.15	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.068	0.066
Average	0.068	0.067
Max	0.069	0.068
UL	0.150	0.150

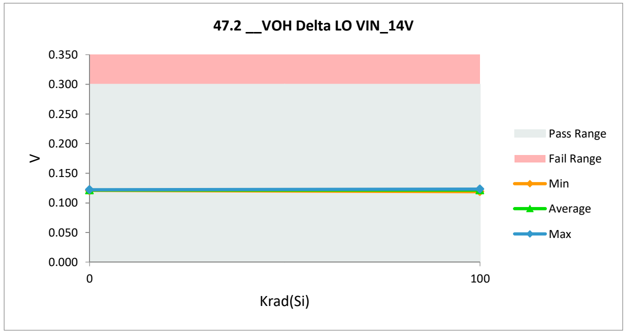


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		47.2 __VOH Delta LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.3	0.3	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.121	0.121	0.000
0	2	0.122	0.122	0.000
100	23	0.122	0.121	-0.001
100	24	0.121	0.121	0.000
100	25	0.122	0.123	0.000
100	26	0.121	0.121	-0.001
100	27	0.122	0.119	-0.003
100	48u	0.120	0.122	0.002
100	49u	0.120	0.121	0.001
100	50u	0.120	0.121	0.001
100	51u	0.122	0.123	0.001
100	52u	0.121	0.123	0.002
	Max	0.122	0.123	0.002
	Average	0.121	0.122	0.000
	Min	0.120	0.119	-0.003
	Std Dev	0.001	0.001	0.001



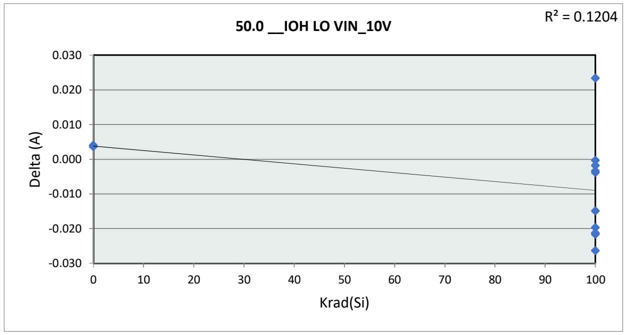
	47.2 __VOH Delta LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.3	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.121	0.119
Average	0.121	0.122
Max	0.122	0.123
UL	0.300	0.300



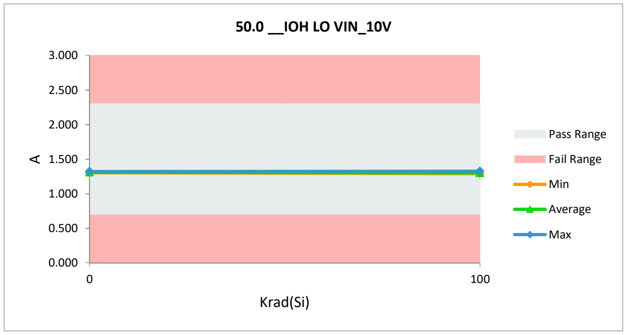
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	50.0 __IOH LO VIN_10V	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	A	A
Max Limit	2.3	2.3
Min Limit	0.7	0.7

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.318	1.322	0.004
0	2	1.300	1.303	0.004
100	23	1.304	1.303	0.000
100	24	1.306	1.305	-0.002
100	25	1.299	1.295	-0.004
100	26	1.310	1.307	-0.003
100	27	1.303	1.326	0.023
100	48u	1.313	1.291	-0.022
100	49u	1.324	1.297	-0.026
100	50u	1.316	1.301	-0.015
100	51u	1.309	1.288	-0.021
100	52u	1.310	1.290	-0.020
	Max	1.324	1.326	0.023
	Average	1.309	1.302	-0.007
	Min	1.299	1.288	-0.026
	Std Dev	0.007	0.012	0.014

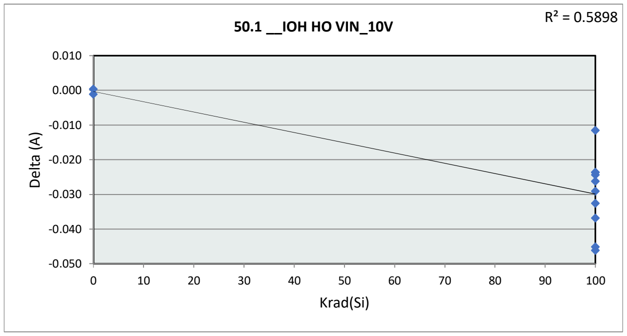


	50.0 __IOH LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.303	1.288
Average	1.313	1.300
Max	1.322	1.326
UL	2.300	2.300

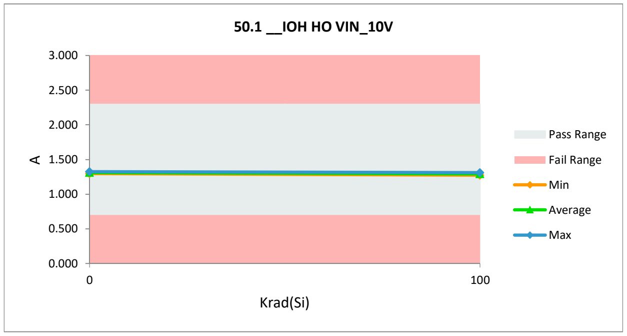


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		50.1 __IOH HO VIN_10V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	A	A	
	Max Limit	2.3	2.3	
	Min Limit	0.7	0.7	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.324	1.323	-0.001
0	2	1.299	1.299	0.000
100	23	1.321	1.275	-0.046
100	24	1.334	1.289	-0.045
100	25	1.320	1.291	-0.029
100	26	1.337	1.311	-0.026
100	27	1.337	1.301	-0.037
100	48u	1.306	1.281	-0.024
100	49u	1.324	1.291	-0.033
100	50u	1.313	1.302	-0.012
100	51u	1.311	1.287	-0.024
100	52u	1.321	1.297	-0.024
	Max	1.337	1.323	0.000
	Average	1.321	1.296	-0.025
	Min	1.299	1.275	-0.046
	Std Dev	0.012	0.013	0.015

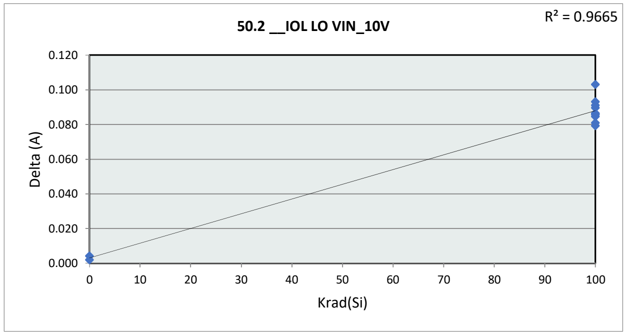


	50.1 __IOH HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.299	1.275
Average	1.311	1.293
Max	1.323	1.311
UL	2.300	2.300

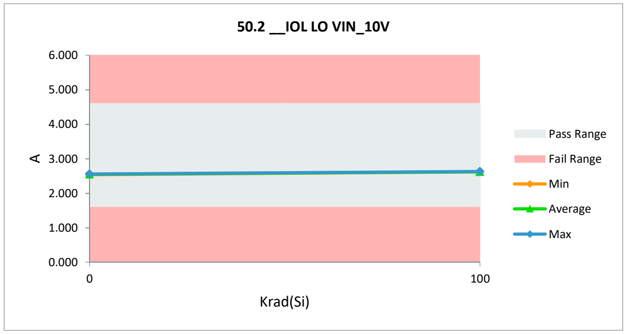


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		50.2 __IOL LO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		4.6	4.6	
Min Limit		1.6	1.6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.551	2.553	0.002
0	2	2.536	2.541	0.004
100	23	2.519	2.622	0.103
100	24	2.533	2.619	0.086
100	25	2.538	2.618	0.081
100	26	2.526	2.619	0.093
100	27	2.549	2.629	0.079
100	48u	2.540	2.625	0.085
100	49u	2.545	2.631	0.086
100	50u	2.541	2.632	0.091
100	51u	2.542	2.632	0.090
100	52u	2.542	2.628	0.086
	Max	2.551	2.632	0.103
	Average	2.539	2.612	0.074
	Min	2.519	2.541	0.002
	Std Dev	0.009	0.031	0.034

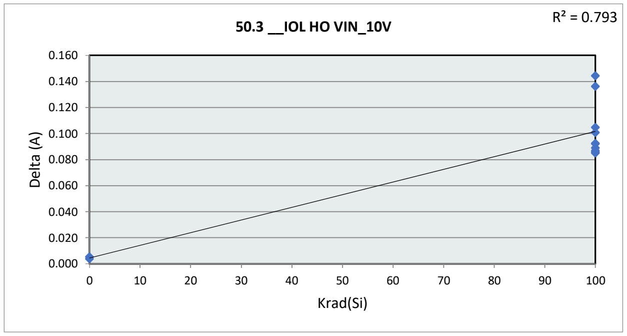


	50.2 __IOL LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4.6	A
Min Limit	1.6	A
Krad(Si)	0	100
LL	1.600	1.600
Min	2.541	2.619
Average	2.547	2.626
Max	2.553	2.632
UL	4.600	4.600

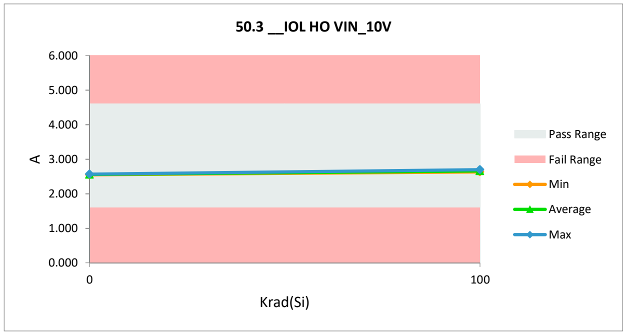


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		50.3 __IOL HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		4.6	4.6	
Min Limit		1.6	1.6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.565	2.569	0.004
0	2	2.545	2.550	0.005
100	23	2.562	2.663	0.101
100	24	2.558	2.694	0.136
100	25	2.548	2.692	0.144
100	26	2.548	2.641	0.092
100	27	2.581	2.686	0.105
100	48u	2.548	2.635	0.087
100	49u	2.553	2.639	0.086
100	50u	2.547	2.639	0.092
100	51u	2.546	2.635	0.089
100	52u	2.574	2.659	0.085
	Max	2.581	2.694	0.144
	Average	2.556	2.642	0.085
	Min	2.545	2.550	0.004
	Std Dev	0.012	0.044	0.042

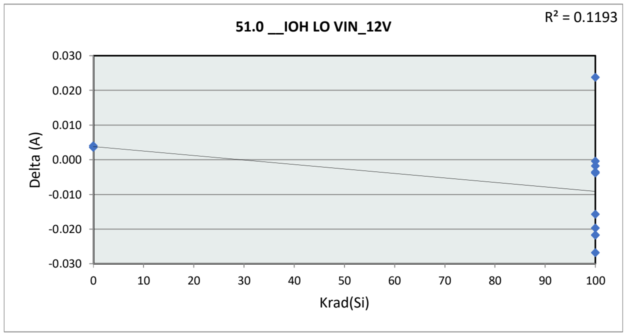


	50.3 __IOL HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4.6	A
Min Limit	1.6	A
Krad(Si)	0	100
LL	1.600	1.600
Min	2.551	2.635
Average	2.560	2.658
Max	2.569	2.695
UL	4.600	4.600

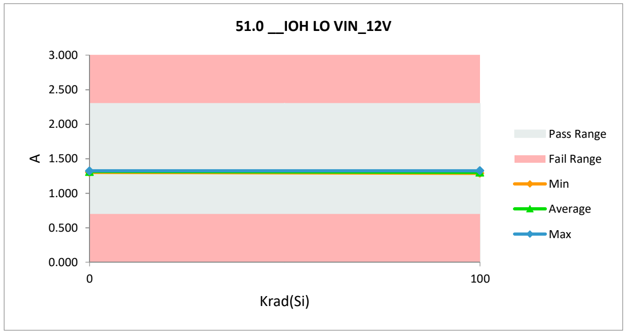


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		51.0 __IOH LO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		A	A	
Max Limit		2.3	2.3	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.318	1.322	0.004
0	2	1.300	1.304	0.004
100	23	1.304	1.304	0.000
100	24	1.307	1.305	-0.002
100	25	1.299	1.296	-0.003
100	26	1.311	1.307	-0.004
100	27	1.303	1.327	0.024
100	48u	1.313	1.291	-0.022
100	49u	1.324	1.298	-0.027
100	50u	1.317	1.301	-0.016
100	51u	1.310	1.288	-0.022
100	52u	1.311	1.291	-0.020
	Max	1.324	1.327	0.024
	Average	1.310	1.303	-0.007
	Min	1.299	1.288	-0.027
	Std Dev	0.008	0.012	0.015



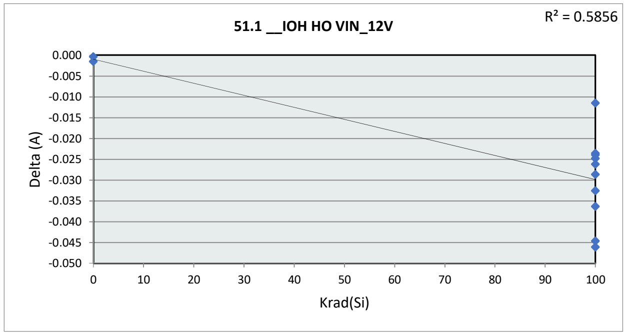
	51.0 __IOH LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.304	1.288
Average	1.313	1.301
Max	1.322	1.327
UL	2.300	2.300



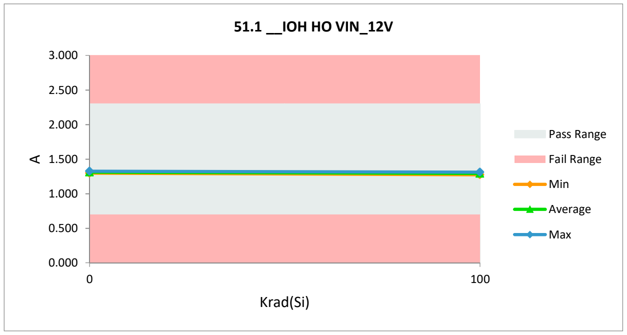
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	51.1 __IOH HO VIN_12V	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	A	A
Max Limit	2.3	2.3
Min Limit	0.7	0.7

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.324	1.323	-0.001
0	2	1.300	1.299	0.000
100	23	1.321	1.275	-0.046
100	24	1.334	1.290	-0.045
100	25	1.320	1.291	-0.029
100	26	1.337	1.311	-0.026
100	27	1.338	1.301	-0.036
100	48u	1.306	1.281	-0.025
100	49u	1.324	1.291	-0.033
100	50u	1.314	1.302	-0.012
100	51u	1.311	1.287	-0.024
100	52u	1.321	1.298	-0.024
	Max	1.338	1.323	0.000
	Average	1.321	1.296	-0.025
	Min	1.300	1.275	-0.046
	Std Dev	0.012	0.013	0.015

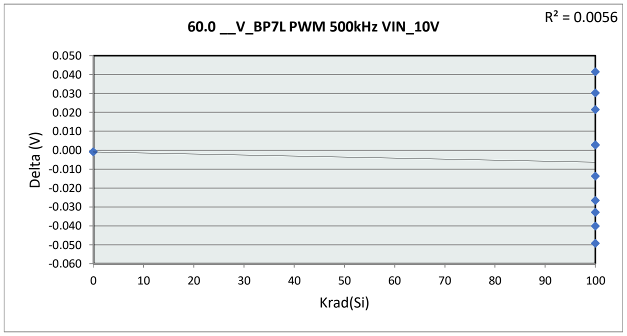


	51.1 __IOH HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.3	A
Min Limit	0.7	A
Krad(Si)	0	100
LL	0.700	0.700
Min	1.299	1.275
Average	1.311	1.293
Max	1.323	1.311
UL	2.300	2.300

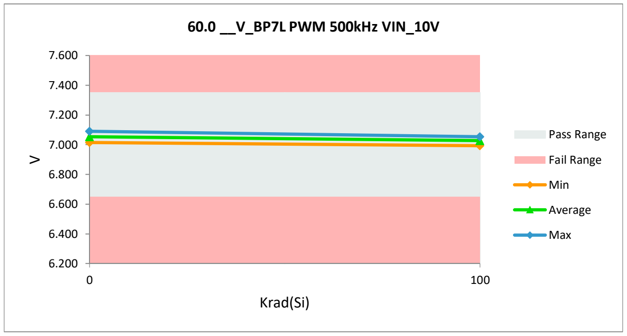


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.0 __V_BP7L PWM 500kHz VI		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.042
100	27	7.016	7.019	0.003
100	48u	7.020	6.994	-0.026
100	49u	7.056	7.007	-0.049
100	50u	7.027	7.049	0.022
100	51u	7.045	7.031	-0.014
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.042
	Average	7.036	7.031	-0.005
	Min	7.001	6.994	-0.049
	Std Dev	0.027	0.026	0.028

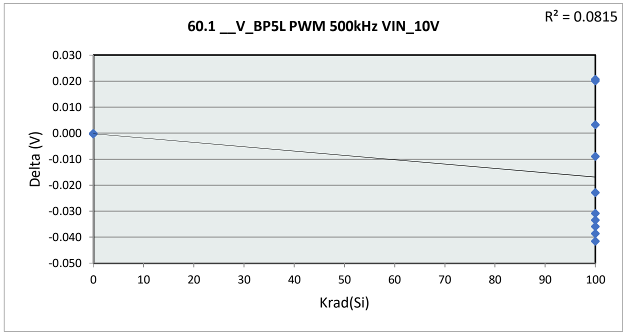


	60.0 __V_BP7L PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.994
Average	7.052	7.026
Max	7.090	7.054
UL	7.350	7.350

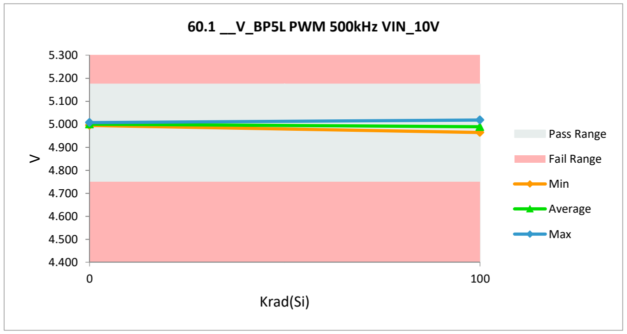


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.1 __V_BP5L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.995	4.994	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.033
100	25	5.003	4.995	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.039
100	48u	5.023	4.982	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.021	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.005	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023

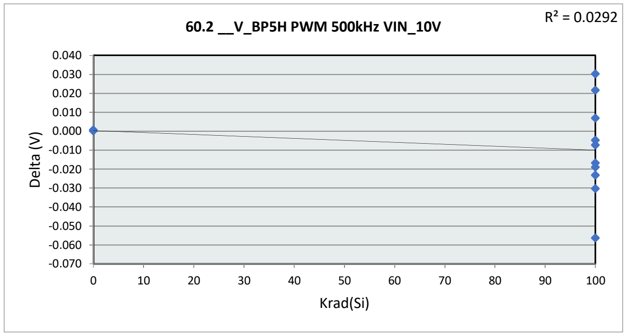


	60.1 __V_BP5L PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.994	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175

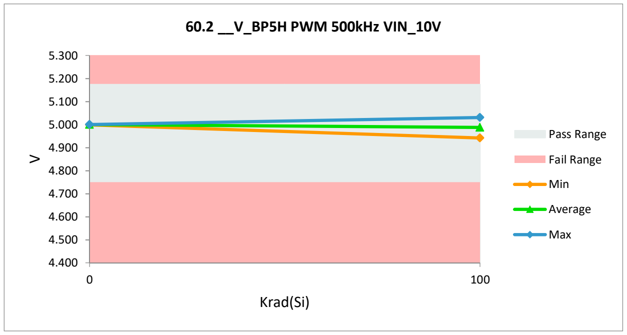


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.2 __V_BP5H PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.942	-0.056
100	48u	4.996	5.003	0.007
100	49u	4.990	5.011	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.000	5.030	0.030
100	52u	4.992	4.976	-0.017
	Max	5.015	5.030	0.030
	Average	4.998	4.990	-0.008
	Min	4.988	4.942	-0.056
	Std Dev	0.008	0.023	0.023

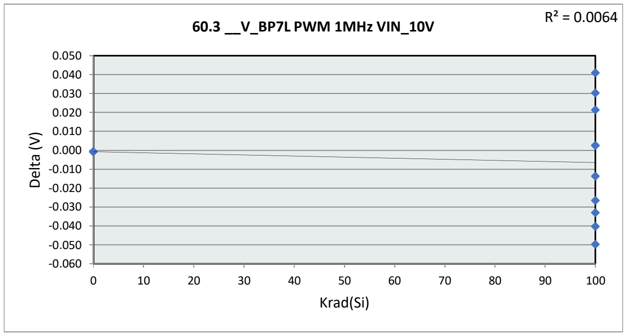


	60.2 __V_BP5H PWM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.988
Max	5.000	5.030
UL	5.175	5.175

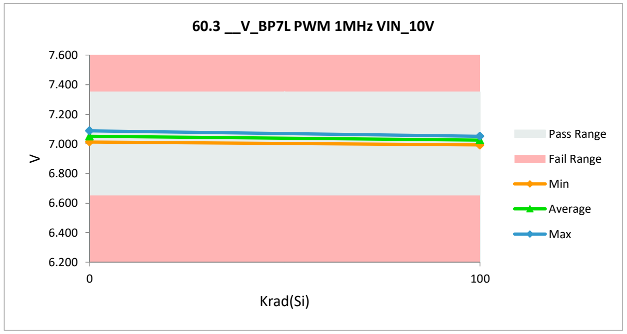


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.3 __V_BP7L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.018	0.003
100	48u	7.019	6.992	-0.027
100	49u	7.055	7.005	-0.050
100	50u	7.026	7.047	0.021
100	51u	7.044	7.030	-0.014
100	52u	7.074	7.041	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.029	-0.006
	Min	6.999	6.992	-0.050
	Std Dev	0.027	0.026	0.028

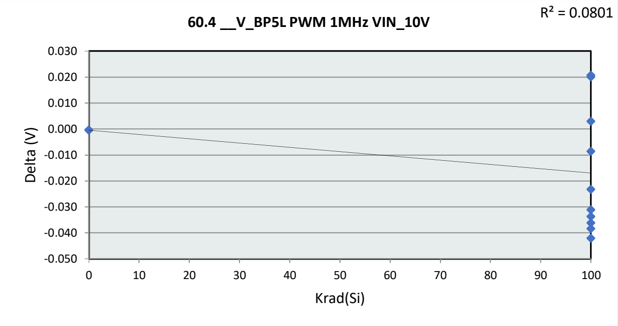


	60.3 __V_BP7L PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.992
Average	7.051	7.025
Max	7.089	7.052
UL	7.350	7.350

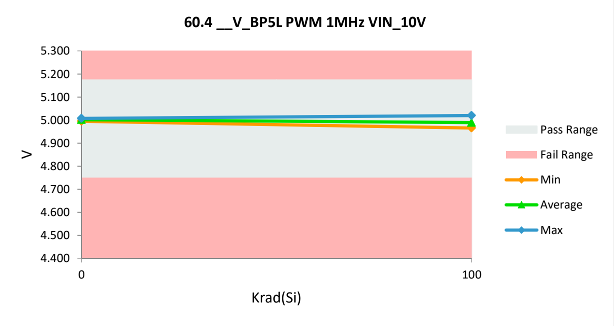


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.4 __V_BP5L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.996	4.995	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.996	-0.009
100	26	4.985	5.005	0.020
100	27	5.004	4.965	-0.038
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.990	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.005	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

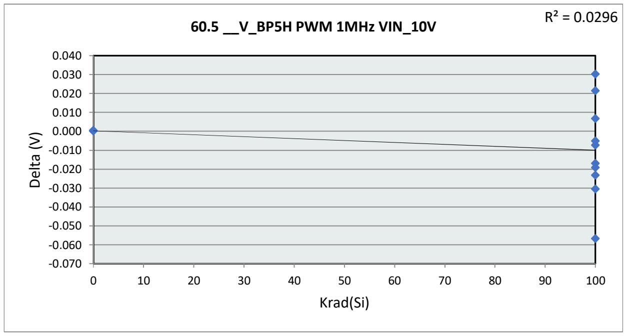


	60.4 __V_BP5L PWM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.001	4.989
Max	5.008	5.019
UL	5.175	5.175

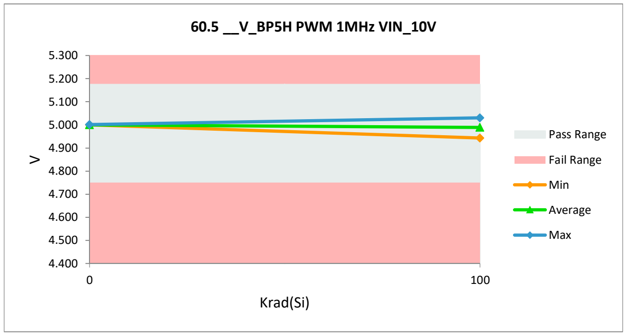


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.5 __V_BP5H PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.012	4.993	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.057
100	48u	4.997	5.003	0.007
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.001	5.031	0.030
100	52u	4.993	4.976	-0.017
	Max	5.015	5.031	0.030
	Average	4.999	4.991	-0.008
	Min	4.988	4.943	-0.057
	Std Dev	0.008	0.023	0.023

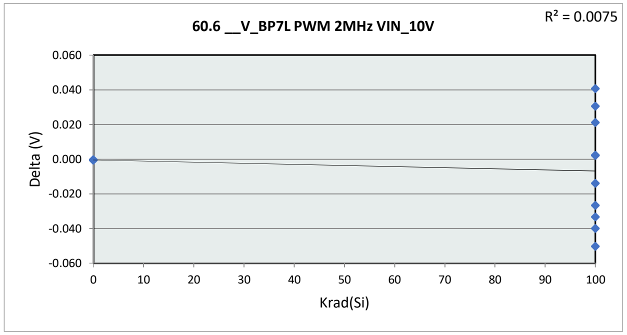


	60.5 __V_BP5H PWM 1MHz VIN_10V		
Test Site	DAL-FL		
Tester	ETS364		
Test Number	EB937004		
Max Limit	5.175		V
Min Limit	4.75		V
Krad(Si)	0		100
LL	4.750		4.750
Min	4.999		4.943
Average	5.000		4.989
Max	5.001		5.031
UL	5.175		5.175

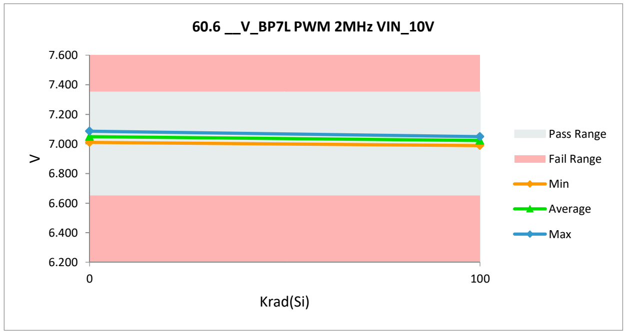


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.6 __V_BP7L PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.011	-0.001
0	2	7.087	7.087	0.000
100	23	6.997	7.028	0.030
100	24	7.045	7.005	-0.040
100	25	7.022	7.024	0.002
100	26	7.009	7.050	0.041
100	27	7.013	7.015	0.002
100	48u	7.016	6.990	-0.027
100	49u	7.053	7.002	-0.050
100	50u	7.023	7.045	0.021
100	51u	7.042	7.028	-0.014
100	52u	7.071	7.038	-0.033
	Max	7.087	7.087	0.041
	Average	7.033	7.027	-0.006
	Min	6.997	6.990	-0.050
	Std Dev	0.027	0.026	0.028

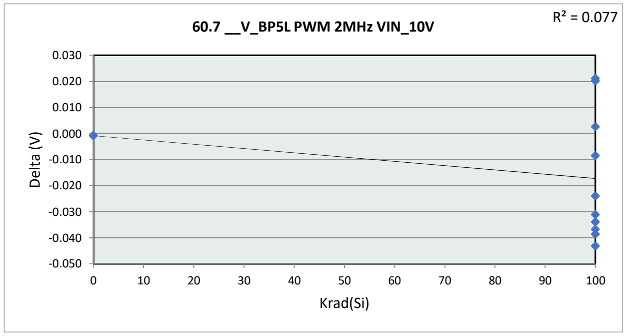


	60.6 __V_BP7L PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.990
Average	7.049	7.022
Max	7.087	7.050
UL	7.350	7.350

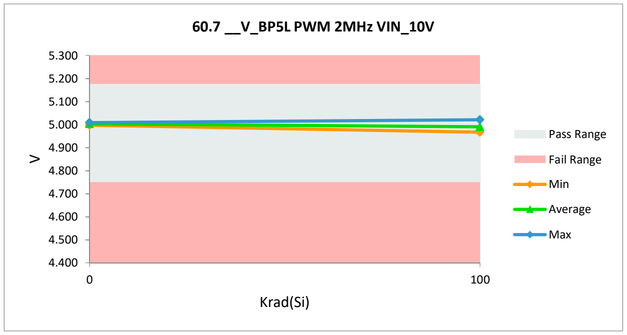


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.7 __V_BP5L PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.009	-0.001
100	23	5.014	4.977	-0.037
100	24	5.015	4.981	-0.034
100	25	5.006	4.998	-0.008
100	26	4.987	5.007	0.020
100	27	5.005	4.967	-0.039
100	48u	5.026	4.983	-0.043
100	49u	5.012	5.015	0.003
100	50u	5.023	4.992	-0.031
100	51u	5.001	5.022	0.021
100	52u	4.992	4.968	-0.024
	Max	5.026	5.022	0.021
	Average	5.007	4.993	-0.015
	Min	4.987	4.967	-0.043
	Std Dev	0.012	0.018	0.023

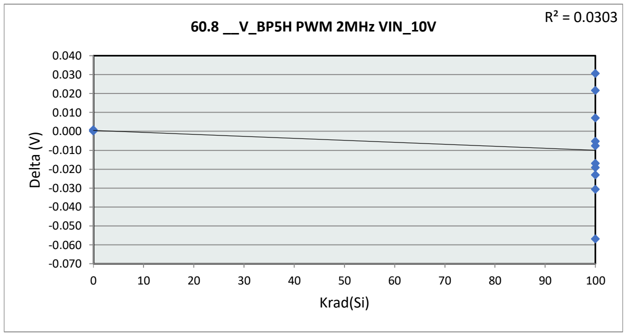


60.7 __V_BP5L PWM 2MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.967
Average	5.003	4.991
Max	5.009	5.022
UL	5.175	5.175

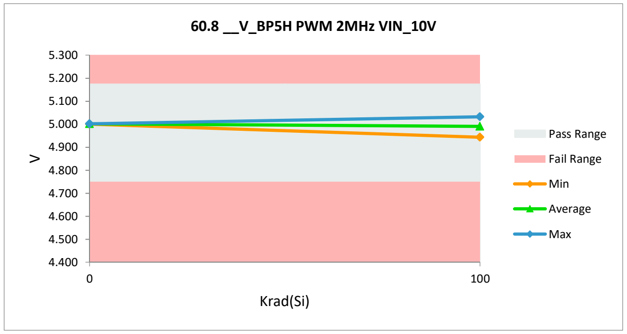


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.8 __V_BP5H PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.031
100	24	5.013	4.994	-0.019
100	25	4.993	4.985	-0.008
100	26	5.001	4.995	-0.005
100	27	5.001	4.944	-0.057
100	48u	4.998	5.005	0.007
100	49u	4.991	5.013	0.022
100	50u	5.016	4.993	-0.023
100	51u	5.002	5.033	0.031
100	52u	4.994	4.977	-0.017
	Max	5.016	5.033	0.031
	Average	5.000	4.992	-0.008
	Min	4.990	4.944	-0.057
	Std Dev	0.008	0.024	0.024

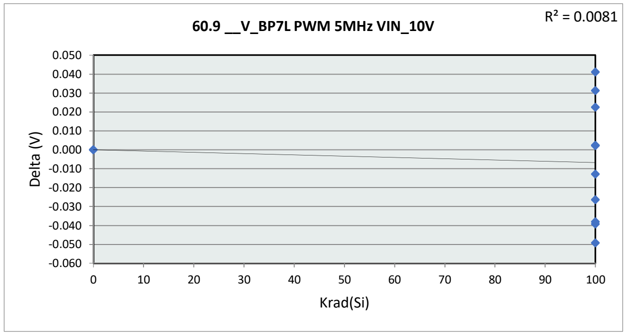


	60.8 __V_BP5H PWM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.944
Average	5.001	4.990
Max	5.002	5.033
UL	5.175	5.175

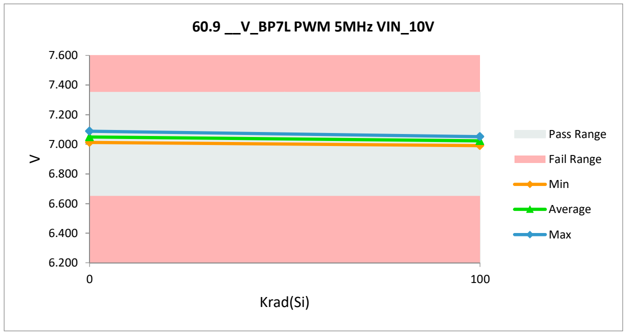


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.9 __V_BP7L PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.012	0.000
0	2	7.088	7.088	0.000
100	23	6.998	7.029	0.031
100	24	7.046	7.006	-0.039
100	25	7.023	7.025	0.002
100	26	7.010	7.051	0.041
100	27	7.013	7.016	0.002
100	48u	7.017	6.990	-0.026
100	49u	7.053	7.004	-0.049
100	50u	7.024	7.046	0.022
100	51u	7.042	7.029	-0.013
100	52u	7.072	7.034	-0.038
	Max	7.088	7.088	0.041
	Average	7.033	7.028	-0.006
	Min	6.998	6.990	-0.049
	Std Dev	0.027	0.026	0.029

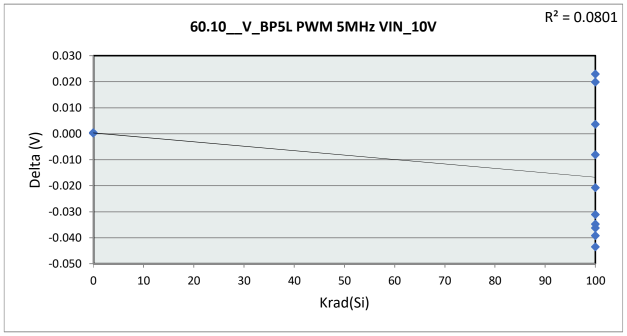


	60.9 __V_BP7L PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.991
Average	7.050	7.023
Max	7.088	7.051
UL	7.350	7.350

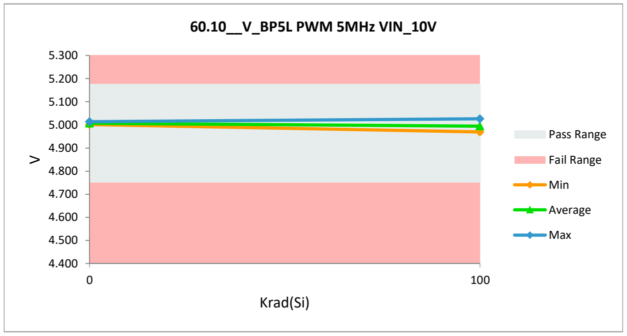


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.10__V_BP5L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.001	5.001	0.000
0	2	5.013	5.013	0.000
100	23	5.017	4.981	-0.036
100	24	5.017	4.983	-0.035
100	25	5.009	5.001	-0.008
100	26	4.990	5.010	0.020
100	27	5.008	4.969	-0.039
100	48u	5.029	4.985	-0.043
100	49u	5.015	5.019	0.004
100	50u	5.026	4.995	-0.031
100	51u	5.003	5.026	0.023
100	52u	4.995	4.974	-0.021
	Max	5.029	5.026	0.023
	Average	5.010	4.996	-0.014
	Min	4.990	4.969	-0.043
	Std Dev	0.012	0.018	0.023

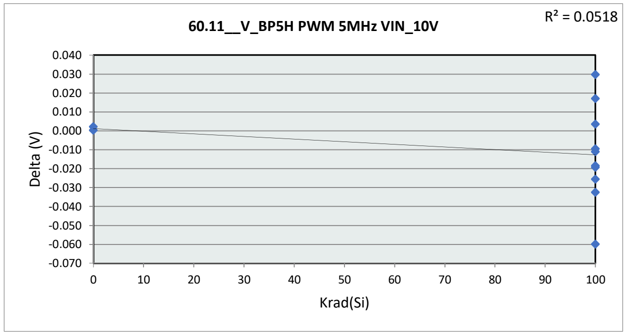


	60.10__V_BP5L PWM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.969
Average	5.007	4.994
Max	5.013	5.026
UL	5.175	5.175

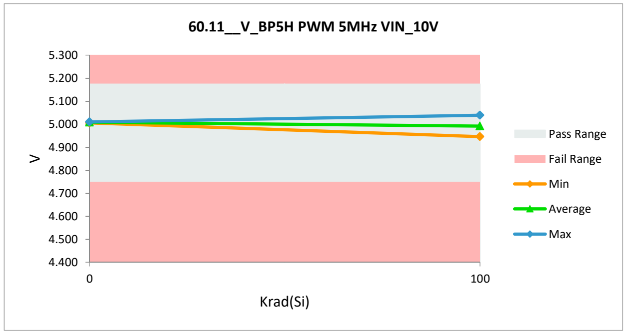


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.11__V_BP5H PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.006	5.006	0.000
0	2	5.008	5.010	0.002
100	23	4.991	4.958	-0.032
100	24	5.016	4.997	-0.019
100	25	4.998	4.987	-0.011
100	26	5.006	4.997	-0.010
100	27	5.006	4.946	-0.060
100	48u	5.003	5.006	0.003
100	49u	4.997	5.014	0.017
100	50u	5.022	4.996	-0.026
100	51u	5.009	5.039	0.030
100	52u	5.002	4.983	-0.019
	Max	5.022	5.039	0.030
	Average	5.005	4.995	-0.010
	Min	4.991	4.946	-0.060
	Std Dev	0.008	0.025	0.024

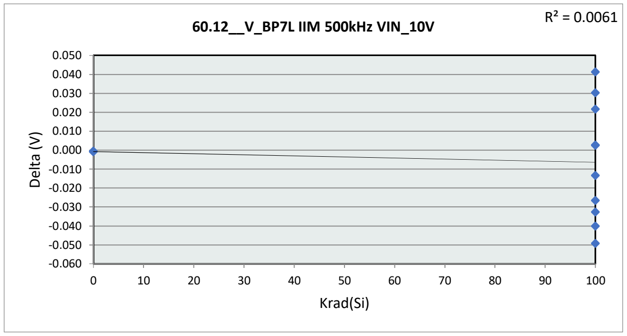


60.11__V_BP5H PWM 5MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.006	4.946
Average	5.008	4.992
Max	5.010	5.039
UL	5.175	5.175

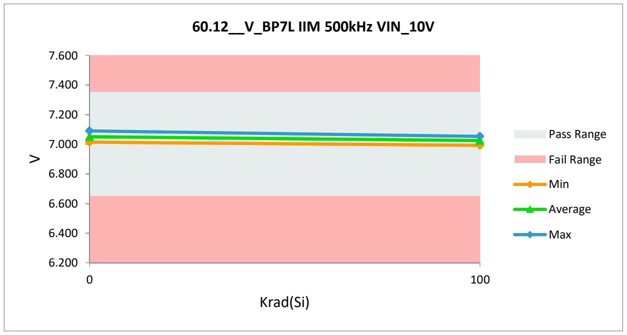


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.12__V_BP7L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.012	7.054	0.041
100	27	7.016	7.019	0.003
100	48u	7.020	6.993	-0.027
100	49u	7.056	7.007	-0.049
100	50u	7.027	7.049	0.022
100	51u	7.045	7.032	-0.014
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.041
	Average	7.036	7.031	-0.005
	Min	7.001	6.993	-0.049
	Std Dev	0.027	0.026	0.028

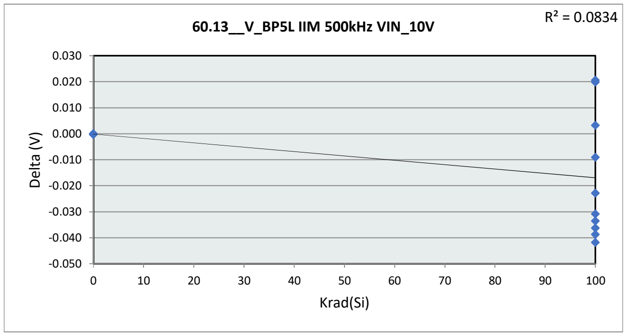


	60.12__V_BP7L IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.993
Average	7.052	7.026
Max	7.090	7.054
UL	7.350	7.350

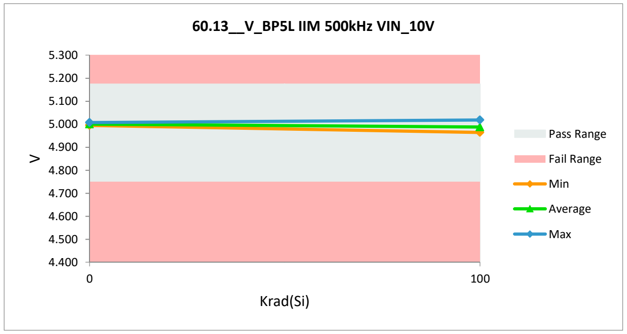


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.13__V_BP5L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.994	4.995	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.034
100	25	5.004	4.995	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.021	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.004	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023

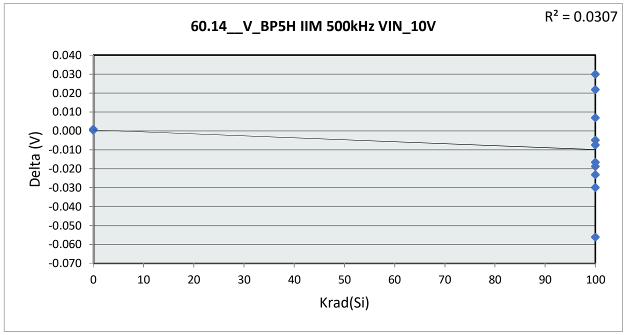


	60.13__V_BP5L IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175

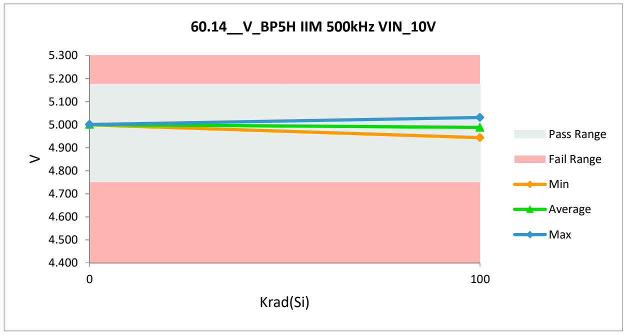


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.14__V_BP5H IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.008
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.996	5.003	0.007
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.000	5.030	0.030
100	52u	4.992	4.976	-0.017
	Max	5.015	5.030	0.030
	Average	4.998	4.990	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

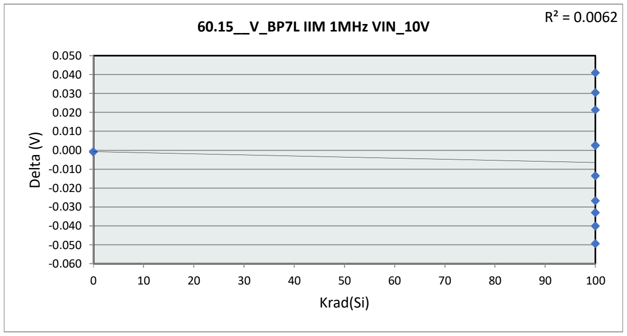


	60.14__V_BP5H IIM 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.988
Max	5.001	5.030
UL	5.175	5.175

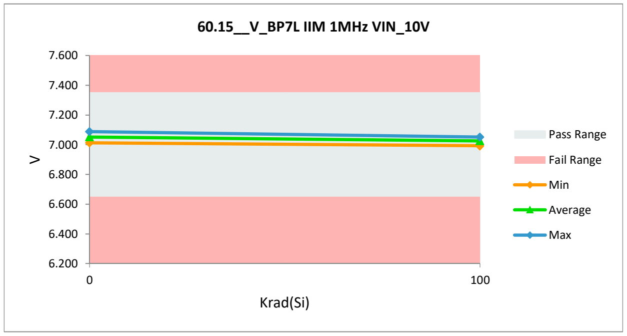


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.15__V_BP7L IIM 1MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.018	0.003
100	48u	7.019	6.992	-0.027
100	49u	7.055	7.005	-0.049
100	50u	7.026	7.047	0.021
100	51u	7.044	7.030	-0.014
100	52u	7.074	7.041	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.029	-0.006
	Min	6.999	6.992	-0.049
	Std Dev	0.027	0.026	0.028

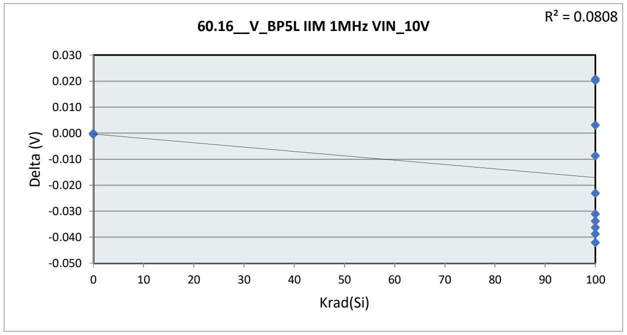


	60.15__V_BP7L IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.992
Average	7.051	7.025
Max	7.089	7.052
UL	7.350	7.350

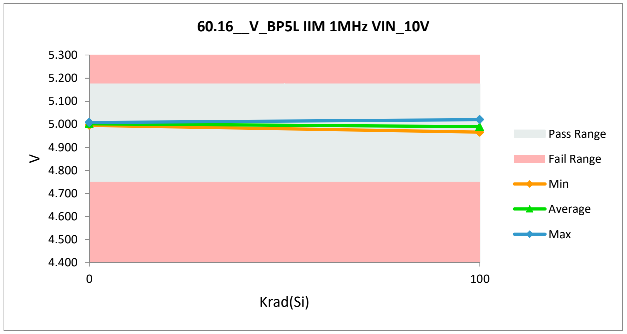


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.16__V_BP5L IIM 1MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.995	4.995	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.996	-0.009
100	26	4.985	5.005	0.020
100	27	5.003	4.965	-0.039
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.990	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.005	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

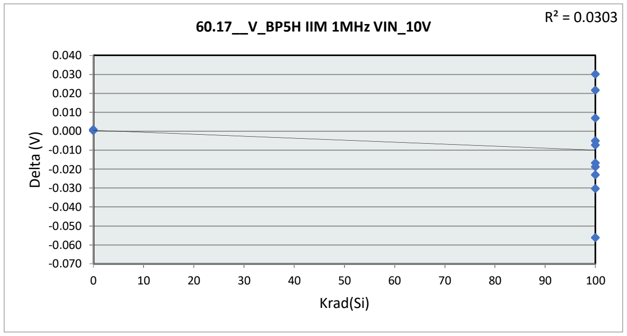


	60.16__V_BP5L IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.001	4.989
Max	5.008	5.019
UL	5.175	5.175

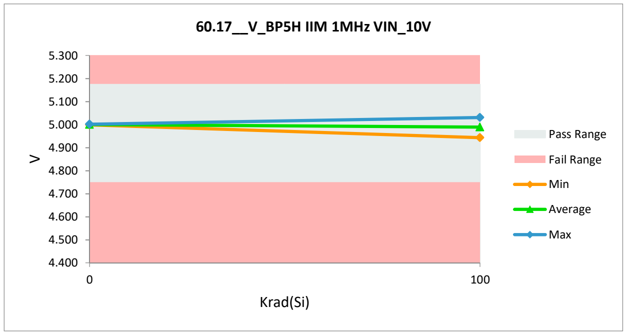


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.17__V_BP5H IIM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.012	4.993	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.997	5.004	0.007
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.001	5.031	0.030
100	52u	4.993	4.976	-0.017
	Max	5.015	5.031	0.030
	Average	4.999	4.991	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

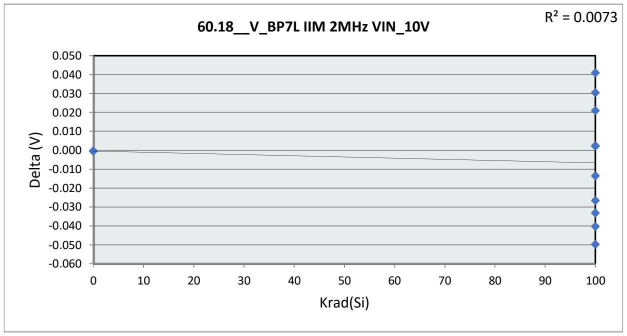


	60.17__V_BP5H IIM 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.989
Max	5.001	5.031
UL	5.175	5.175

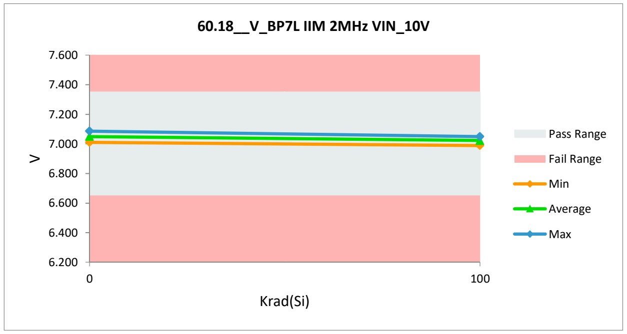


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.18__V_BP7L IIM 2MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.011	7.011	0.000
0	2	7.087	7.087	0.000
100	23	6.997	7.028	0.030
100	24	7.045	7.005	-0.040
100	25	7.022	7.024	0.002
100	26	7.009	7.050	0.041
100	27	7.013	7.015	0.002
100	48u	7.016	6.990	-0.027
100	49u	7.052	7.002	-0.050
100	50u	7.023	7.044	0.021
100	51u	7.041	7.028	-0.014
100	52u	7.071	7.038	-0.033
	Max	7.087	7.087	0.041
	Average	7.032	7.027	-0.006
	Min	6.997	6.990	-0.050
	Std Dev	0.027	0.026	0.028

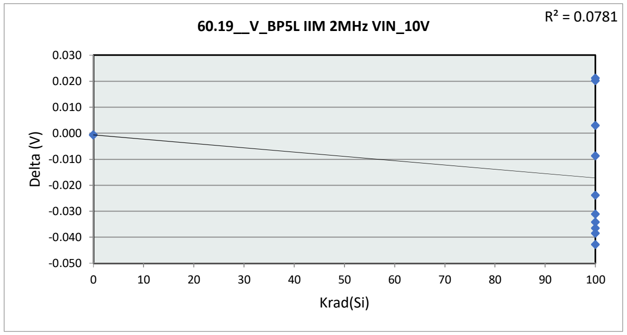


	60.18__V_BP7L IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.990
Average	7.049	7.022
Max	7.087	7.050
UL	7.350	7.350

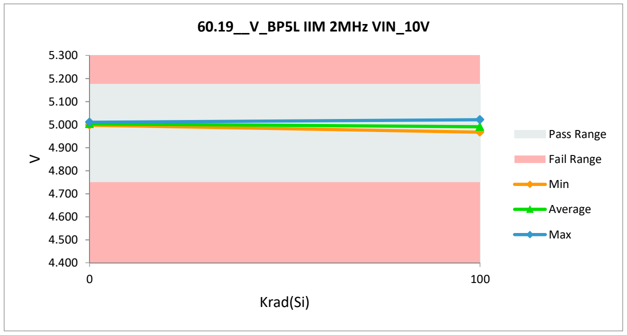


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.19__V_BP5L IIM 2MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.997	4.997	-0.001
0	2	5.010	5.009	-0.001
100	23	5.014	4.977	-0.037
100	24	5.015	4.981	-0.034
100	25	5.006	4.997	-0.009
100	26	4.987	5.007	0.020
100	27	5.005	4.967	-0.038
100	48u	5.026	4.983	-0.043
100	49u	5.012	5.015	0.003
100	50u	5.023	4.992	-0.031
100	51u	5.000	5.022	0.021
100	52u	4.992	4.968	-0.024
	Max	5.026	5.022	0.021
	Average	5.007	4.993	-0.014
	Min	4.987	4.967	-0.043
	Std Dev	0.012	0.018	0.023

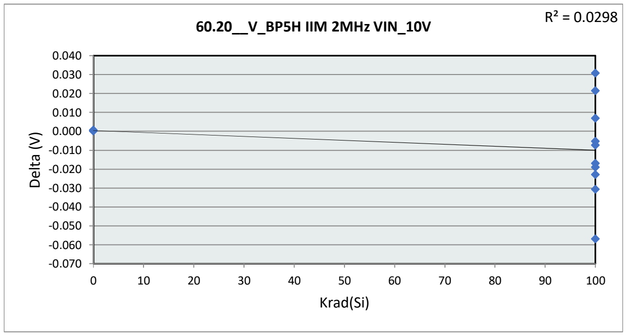


	60.19__V_BP5L IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.967
Average	5.003	4.991
Max	5.009	5.022
UL	5.175	5.175

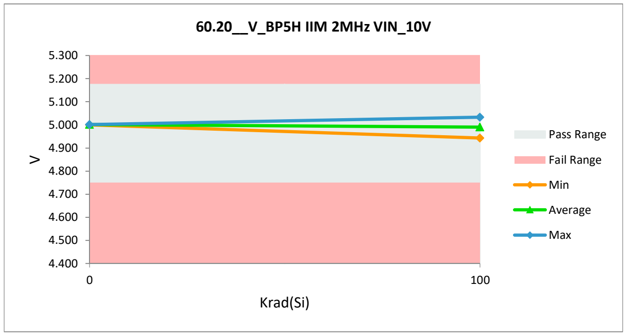


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.20__V_BP5H IIM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.031
100	24	5.013	4.994	-0.019
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.005
100	27	5.000	4.944	-0.057
100	48u	4.998	5.005	0.007
100	49u	4.991	5.013	0.022
100	50u	5.016	4.994	-0.023
100	51u	5.002	5.033	0.031
100	52u	4.994	4.977	-0.017
	Max	5.016	5.033	0.031
	Average	5.000	4.992	-0.008
	Min	4.990	4.944	-0.057
	Std Dev	0.008	0.024	0.023

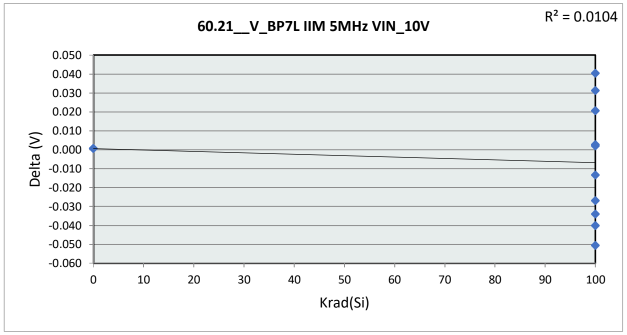


	60.20__V_BP5H IIM 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.944
Average	5.001	4.990
Max	5.002	5.033
UL	5.175	5.175

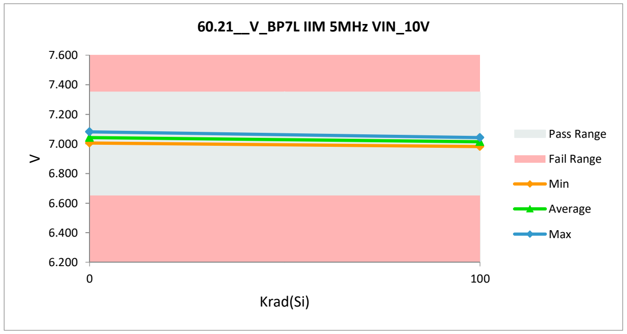


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.21__V_BP7L IIM 5MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.005	7.006	0.001
0	2	7.081	7.082	0.001
100	23	6.991	7.022	0.031
100	24	7.039	6.999	-0.040
100	25	7.016	7.018	0.003
100	26	7.002	7.043	0.040
100	27	7.006	7.008	0.002
100	48u	7.010	6.983	-0.027
100	49u	7.046	6.996	-0.051
100	50u	7.016	7.037	0.021
100	51u	7.035	7.021	-0.014
100	52u	7.065	7.031	-0.034
	Max	7.081	7.082	0.040
	Average	7.026	7.020	-0.006
	Min	6.991	6.983	-0.051
	Std Dev	0.027	0.026	0.028

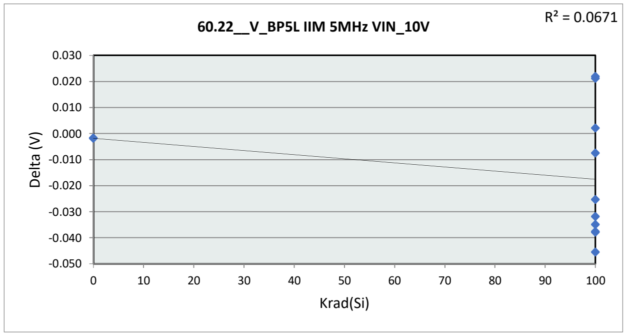


	60.21__V_BP7L IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.006	6.983
Average	7.044	7.016
Max	7.082	7.043
UL	7.350	7.350

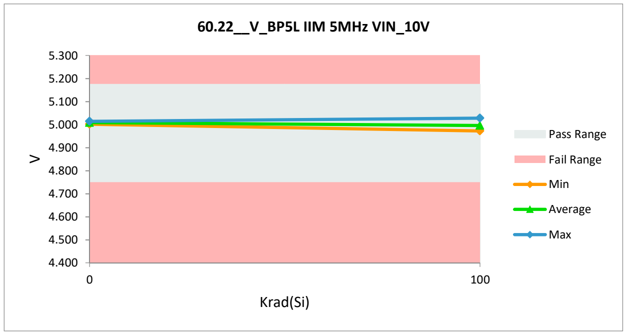


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.22__V_BP5L IIM 5MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.004	5.002	-0.002
0	2	5.016	5.014	-0.002
100	23	5.020	4.982	-0.038
100	24	5.021	4.986	-0.035
100	25	5.011	5.004	-0.008
100	26	4.992	5.014	0.021
100	27	5.011	4.973	-0.038
100	48u	5.032	4.986	-0.045
100	49u	5.017	5.019	0.002
100	50u	5.029	4.997	-0.032
100	51u	5.006	5.028	0.022
100	52u	4.997	4.972	-0.025
	Max	5.032	5.028	0.022
	Average	5.013	4.998	-0.015
	Min	4.992	4.972	-0.045
	Std Dev	0.012	0.019	0.024

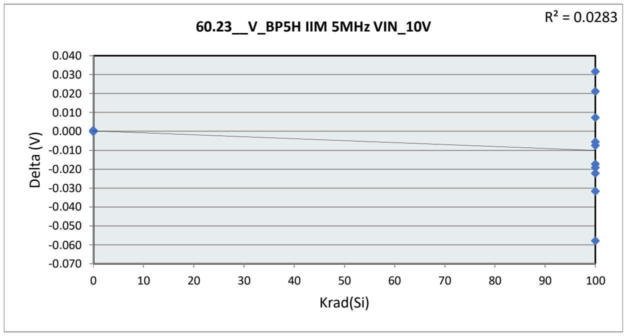


	60.22__V_BP5L IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.002	4.972
Average	5.008	4.996
Max	5.014	5.028
UL	5.175	5.175

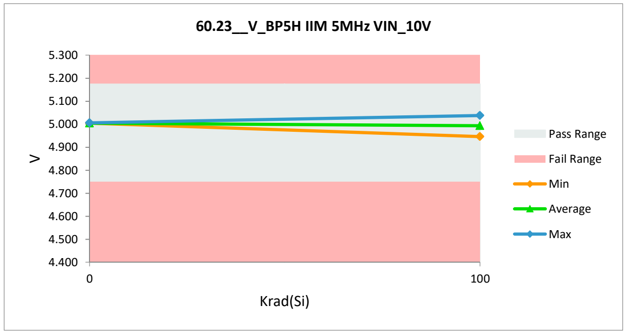


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		60.23__V_BP5H IIM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.003	5.004	0.000
0	2	5.005	5.005	0.000
100	23	4.993	4.961	-0.032
100	24	5.016	4.997	-0.019
100	25	4.996	4.989	-0.008
100	26	5.004	4.998	-0.006
100	27	5.004	4.946	-0.058
100	48u	5.001	5.008	0.007
100	49u	4.995	5.016	0.021
100	50u	5.019	4.997	-0.022
100	51u	5.006	5.037	0.032
100	52u	4.997	4.980	-0.017
	Max	5.019	5.037	0.032
	Average	5.003	4.995	-0.008
	Min	4.993	4.946	-0.058
	Std Dev	0.008	0.024	0.024

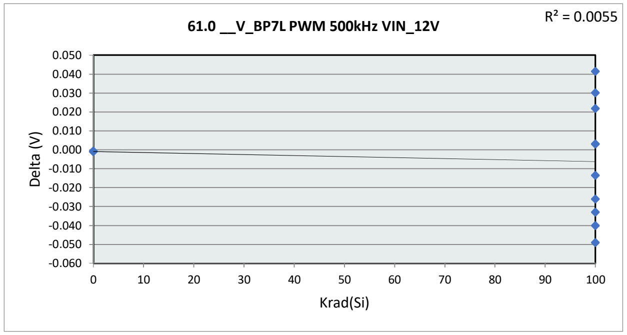


	60.23__V_BP5H IIM 5MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.004	4.946
Average	5.004	4.993
Max	5.005	5.037
UL	5.175	5.175

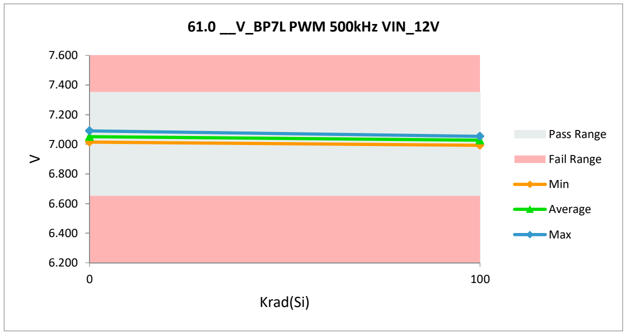


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.0 __V_BP7L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.016	7.015	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.029	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.020	0.003
100	48u	7.020	6.994	-0.026
100	49u	7.056	7.007	-0.049
100	50u	7.027	7.049	0.022
100	51u	7.045	7.032	-0.014
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.041
	Average	7.036	7.031	-0.005
	Min	7.001	6.994	-0.049
	Std Dev	0.027	0.026	0.028

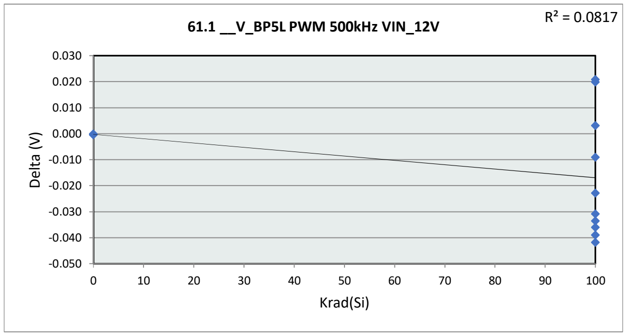


	61.0 __V_BP7L PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.015	6.994
Average	7.052	7.027
Max	7.090	7.054
UL	7.350	7.350

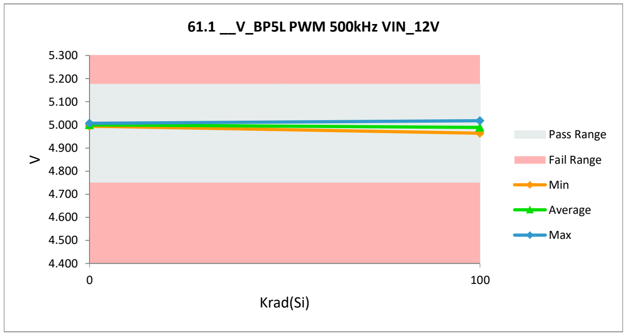


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.1 __V_BP5L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.995	4.994	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.034
100	25	5.004	4.995	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.021	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.005	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023



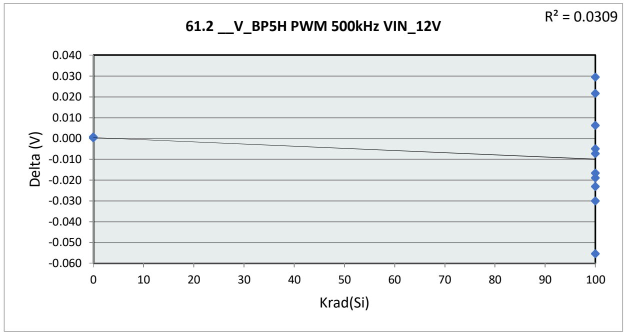
	61.1 __V_BP5L PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.994	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175



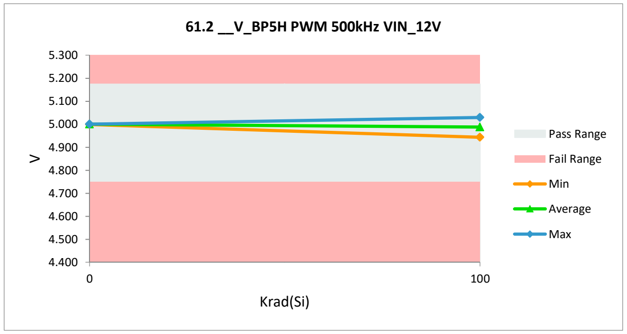
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	61.2 __V_BP5H PWM 500kHz VI	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.996	5.002	0.006
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.000	5.030	0.029
100	52u	4.992	4.975	-0.017
	Max	5.015	5.030	0.029
	Average	4.998	4.990	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

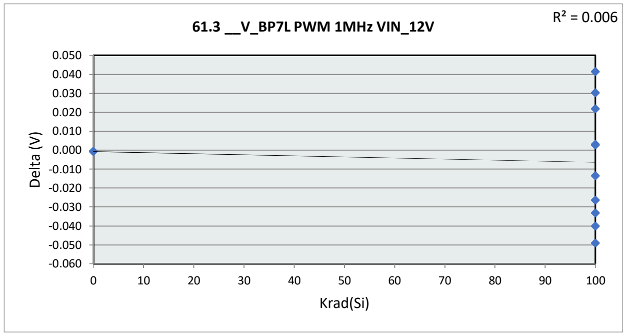


	61.2 __V_BP5H PWM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.988
Max	5.000	5.030
UL	5.175	5.175

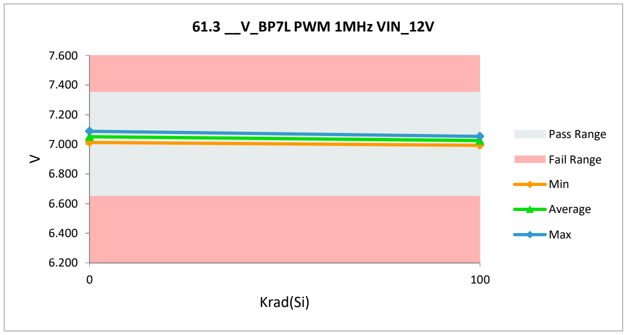


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.3 __V_BP7L PWM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.014	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.053	0.041
100	27	7.016	7.018	0.003
100	48u	7.019	6.992	-0.026
100	49u	7.055	7.006	-0.049
100	50u	7.026	7.048	0.022
100	51u	7.044	7.030	-0.014
100	52u	7.074	7.041	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.030	-0.005
	Min	7.000	6.992	-0.049
	Std Dev	0.027	0.026	0.028

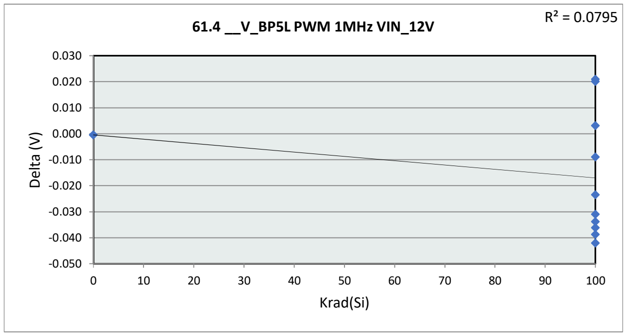


	61.3 __V_BP7L PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.992
Average	7.051	7.025
Max	7.089	7.053
UL	7.350	7.350

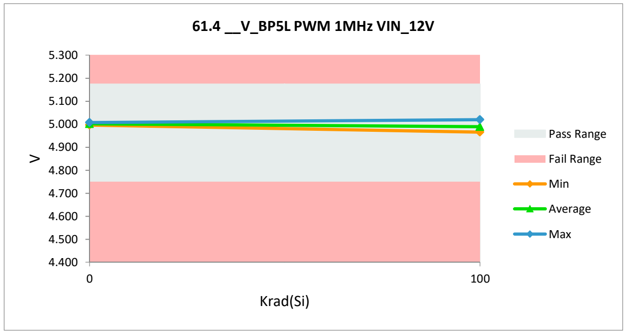


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.4 __V_BP5L PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.996	4.995	0.000
0	2	5.008	5.008	-0.001
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.996	-0.009
100	26	4.985	5.005	0.020
100	27	5.004	4.965	-0.039
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.991	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.006	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

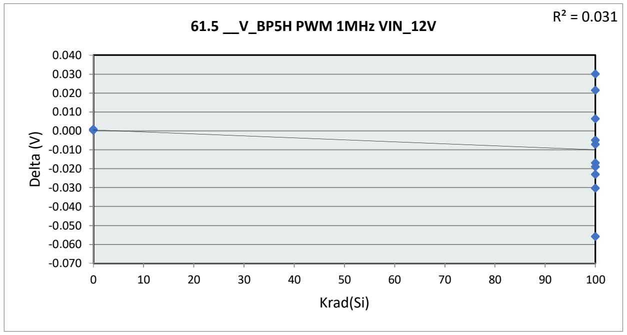


61.4 __V_BP5L PWM 1MHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.001	4.989
Max	5.008	5.020
UL	5.175	5.175

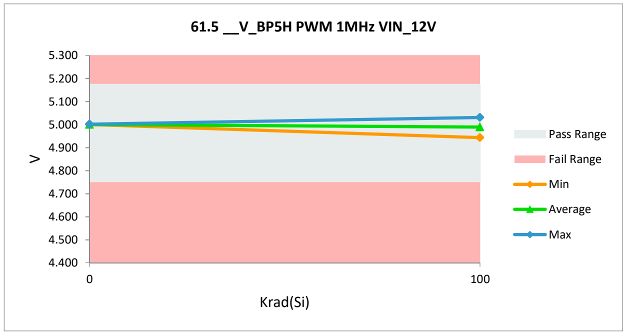


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.5 __V_BP5H PWM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.989	4.958	-0.030
100	24	5.012	4.993	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.997	5.003	0.006
100	49u	4.990	5.012	0.021
100	50u	5.015	4.992	-0.023
100	51u	5.001	5.031	0.030
100	52u	4.993	4.976	-0.017
	Max	5.015	5.031	0.030
	Average	4.999	4.991	-0.008
	Min	4.989	4.943	-0.056
	Std Dev	0.008	0.023	0.023

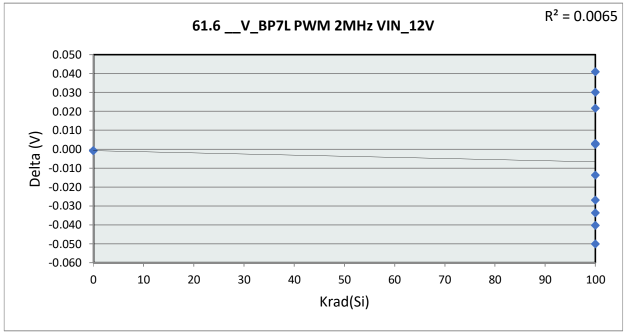


	61.5 __V_BP5H PWM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.000	4.943
Average	5.000	4.989
Max	5.001	5.031
UL	5.175	5.175

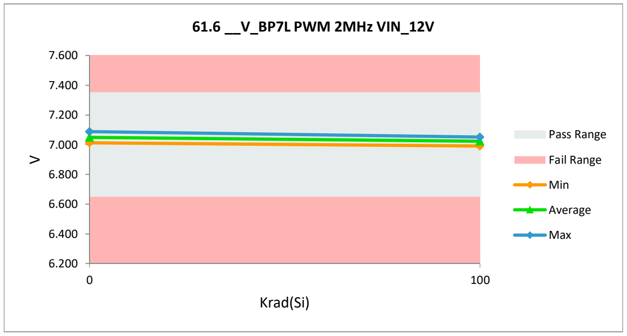


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.6 __V_BP7L PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.022	7.025	0.003
100	26	7.010	7.050	0.041
100	27	7.013	7.016	0.003
100	48u	7.017	6.990	-0.027
100	49u	7.053	7.003	-0.050
100	50u	7.024	7.045	0.022
100	51u	7.042	7.028	-0.014
100	52u	7.072	7.038	-0.034
	Max	7.088	7.087	0.041
	Average	7.033	7.027	-0.006
	Min	6.998	6.990	-0.050
	Std Dev	0.027	0.026	0.028

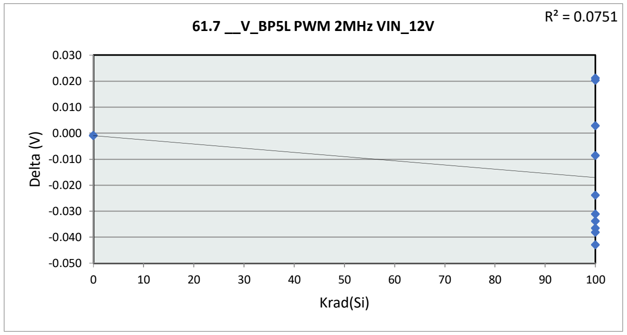


	61.6 __V_BP7L PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.990
Average	7.049	7.023
Max	7.087	7.050
UL	7.350	7.350

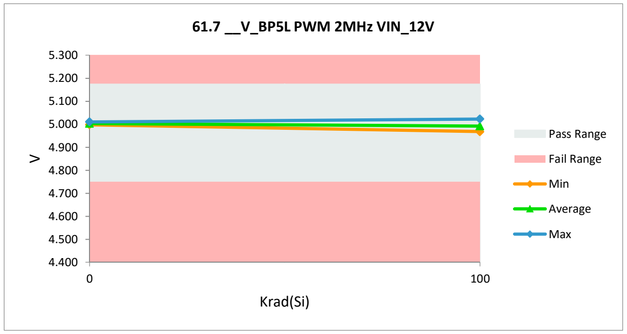


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.7 __V_BP5L PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.009	-0.001
100	23	5.014	4.978	-0.037
100	24	5.015	4.981	-0.034
100	25	5.006	4.998	-0.009
100	26	4.987	5.008	0.020
100	27	5.006	4.968	-0.038
100	48u	5.026	4.983	-0.043
100	49u	5.012	5.015	0.003
100	50u	5.024	4.993	-0.031
100	51u	5.001	5.022	0.021
100	52u	4.992	4.968	-0.024
	Max	5.026	5.022	0.021
	Average	5.008	4.993	-0.014
	Min	4.987	4.968	-0.043
	Std Dev	0.012	0.018	0.023

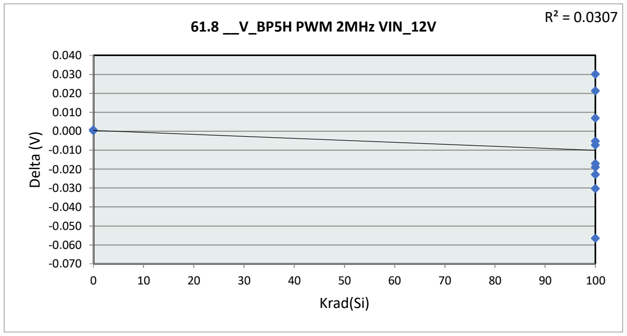


	61.7 __V_BP5L PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.968
Average	5.003	4.991
Max	5.009	5.022
UL	5.175	5.175

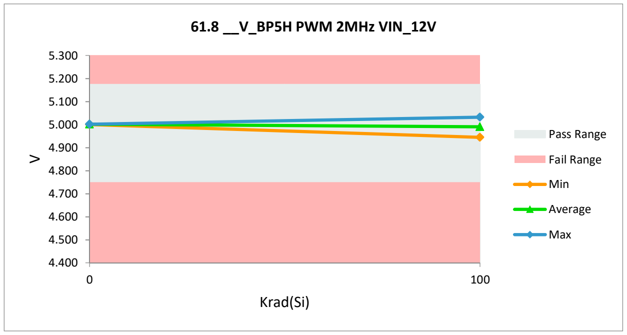


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.8 __V_BP5H PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.030
100	24	5.013	4.994	-0.019
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.005
100	27	5.001	4.944	-0.057
100	48u	4.998	5.005	0.007
100	49u	4.992	5.013	0.021
100	50u	5.016	4.994	-0.023
100	51u	5.002	5.032	0.030
100	52u	4.994	4.977	-0.017
	Max	5.016	5.032	0.030
	Average	5.000	4.992	-0.008
	Min	4.990	4.944	-0.057
	Std Dev	0.008	0.023	0.023

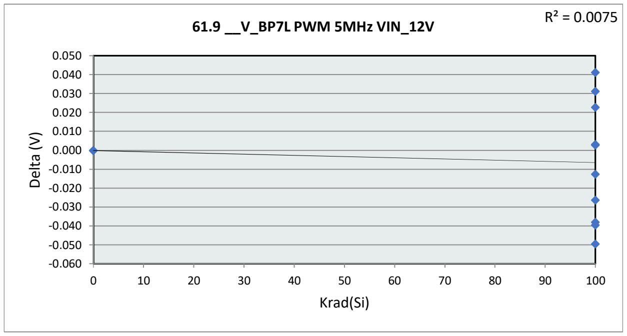


	61.8 __V_BP5H PWM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.944
Average	5.001	4.990
Max	5.002	5.032
UL	5.175	5.175

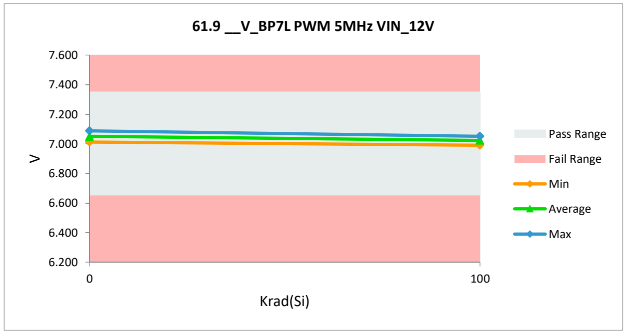


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.9 __V_BP7L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.013	7.012	0.000
0	2	7.089	7.088	0.000
100	23	6.998	7.029	0.031
100	24	7.046	7.007	-0.040
100	25	7.023	7.025	0.003
100	26	7.010	7.051	0.041
100	27	7.014	7.017	0.003
100	48u	7.017	6.991	-0.026
100	49u	7.053	7.004	-0.049
100	50u	7.024	7.047	0.023
100	51u	7.042	7.030	-0.013
100	52u	7.072	7.034	-0.038
	Max	7.089	7.088	0.041
	Average	7.033	7.028	-0.005
	Min	6.998	6.991	-0.049
	Std Dev	0.027	0.026	0.029

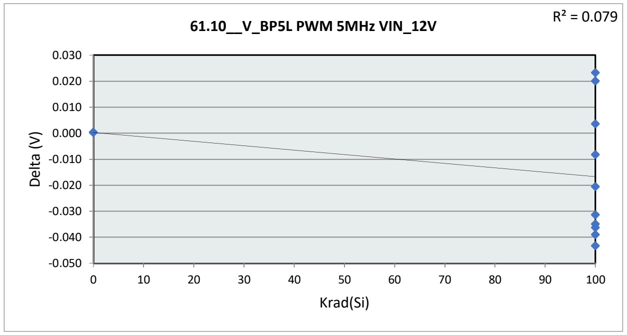


	61.9 __V_BP7L PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.991
Average	7.050	7.023
Max	7.088	7.051
UL	7.350	7.350

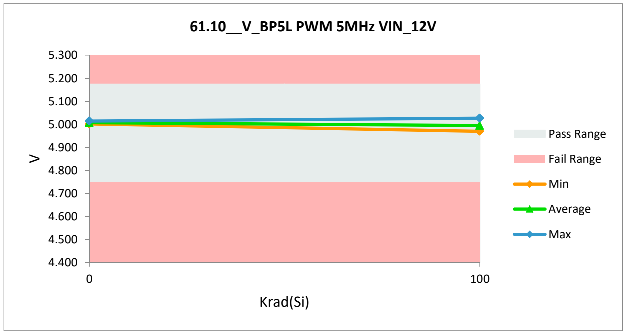


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.10__V_BP5L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.001	5.001	0.000
0	2	5.013	5.014	0.000
100	23	5.017	4.981	-0.036
100	24	5.018	4.983	-0.035
100	25	5.009	5.001	-0.008
100	26	4.990	5.010	0.020
100	27	5.008	4.969	-0.039
100	48u	5.029	4.986	-0.043
100	49u	5.015	5.019	0.004
100	50u	5.027	4.995	-0.031
100	51u	5.004	5.027	0.023
100	52u	4.995	4.975	-0.021
	Max	5.029	5.027	0.023
	Average	5.011	4.997	-0.014
	Min	4.990	4.969	-0.043
	Std Dev	0.012	0.018	0.023

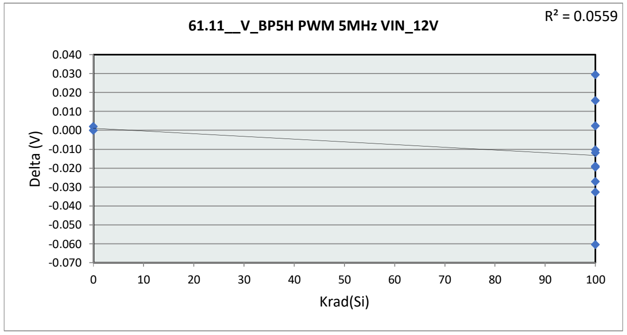


	61.10__V_BP5L PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.969
Average	5.007	4.995
Max	5.014	5.027
UL	5.175	5.175

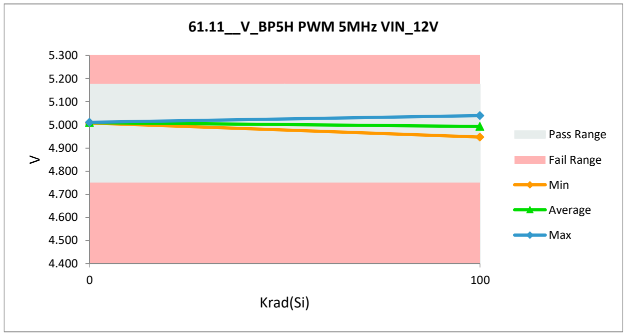


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.11__V_BP5H PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.008	5.008	0.000
0	2	5.009	5.011	0.002
100	23	4.991	4.959	-0.033
100	24	5.017	4.998	-0.019
100	25	5.000	4.988	-0.012
100	26	5.008	4.998	-0.010
100	27	5.007	4.947	-0.060
100	48u	5.004	5.006	0.002
100	49u	4.998	5.014	0.016
100	50u	5.023	4.996	-0.027
100	51u	5.010	5.040	0.030
100	52u	5.003	4.984	-0.019
	Max	5.023	5.040	0.030
	Average	5.007	4.996	-0.011
	Min	4.991	4.947	-0.060
	Std Dev	0.008	0.025	0.024

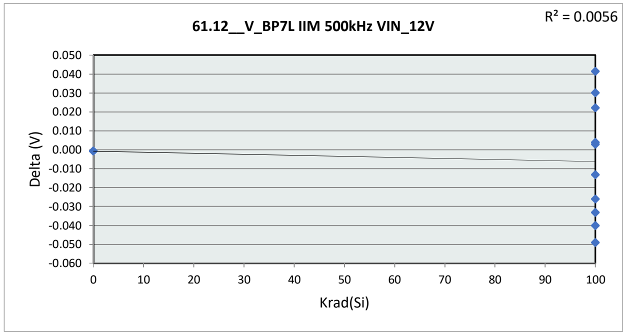


	61.11__V_BP5H PWM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.008	4.947
Average	5.010	4.993
Max	5.011	5.040
UL	5.175	5.175

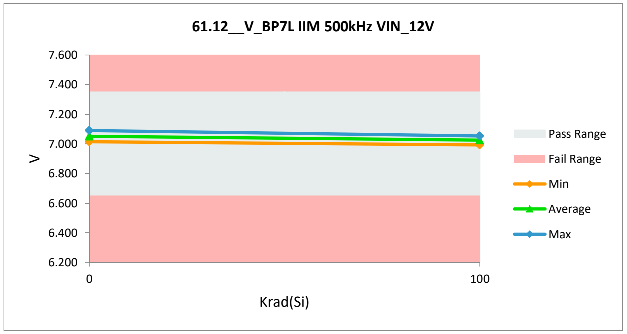


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.12__V_BP7L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.015	7.014	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.016	7.020	0.004
100	48u	7.020	6.994	-0.026
100	49u	7.056	7.007	-0.049
100	50u	7.027	7.049	0.022
100	51u	7.045	7.032	-0.013
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.041
	Average	7.036	7.031	-0.005
	Min	7.001	6.994	-0.049
	Std Dev	0.027	0.026	0.028

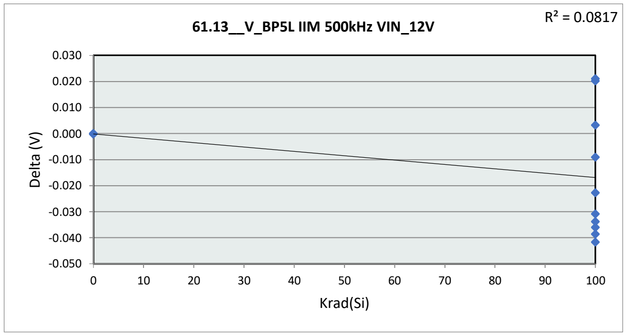


	61.12__V_BP7L IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.994
Average	7.052	7.027
Max	7.090	7.054
UL	7.350	7.350

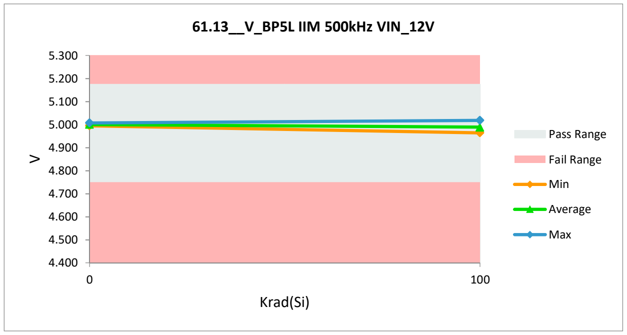


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.13__V_BP5L IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.994	4.994	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.034
100	25	5.003	4.994	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.020	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.004	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023

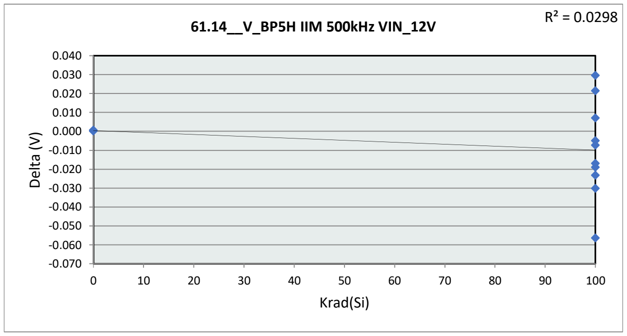


	61.13__V_BP5L IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.994	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175

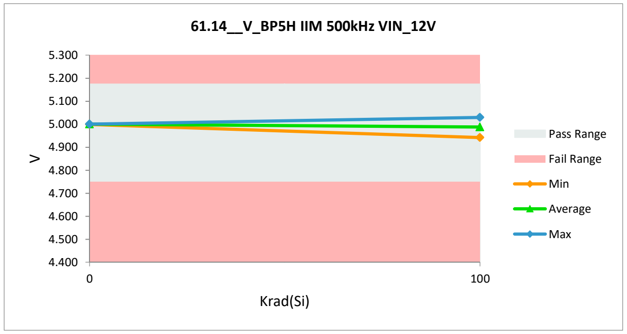


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.14__V_BP5H IIM 500kHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.942	-0.056
100	48u	4.996	5.003	0.007
100	49u	4.990	5.011	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.000	5.030	0.030
100	52u	4.992	4.975	-0.017
	Max	5.015	5.030	0.030
	Average	4.998	4.990	-0.008
	Min	4.988	4.942	-0.056
	Std Dev	0.008	0.023	0.023

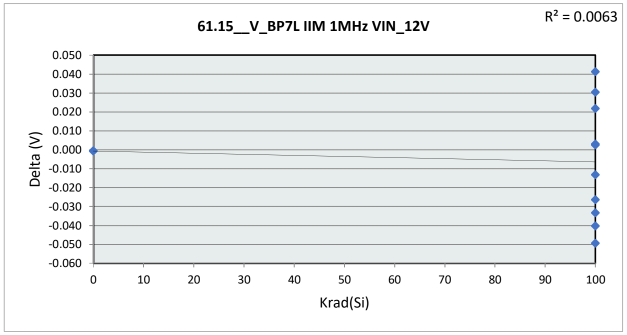


	61.14__V_BP5H IIM 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.942
Average	5.000	4.988
Max	5.000	5.030
UL	5.175	5.175

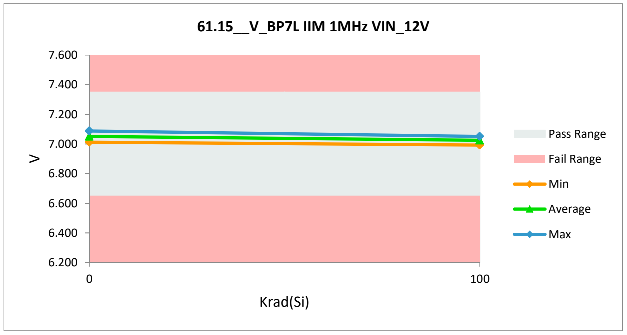


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.15__V_BP7L IIM 1MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.013	-0.001
0	2	7.090	7.089	-0.001
100	23	6.999	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.052	0.041
100	27	7.015	7.018	0.002
100	48u	7.019	6.992	-0.026
100	49u	7.055	7.005	-0.049
100	50u	7.026	7.048	0.022
100	51u	7.044	7.031	-0.013
100	52u	7.074	7.040	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.029	-0.005
	Min	6.999	6.992	-0.049
	Std Dev	0.027	0.026	0.028

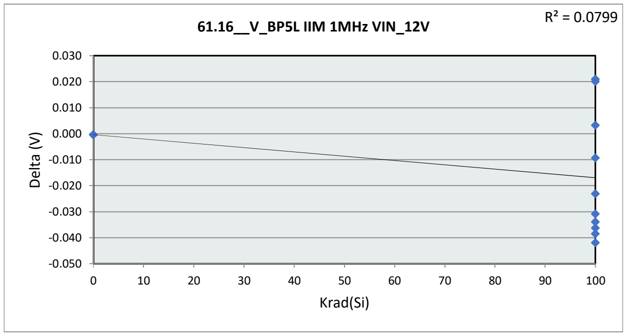


	61.15__V_BP7L IIM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.992
Average	7.051	7.025
Max	7.089	7.053
UL	7.350	7.350

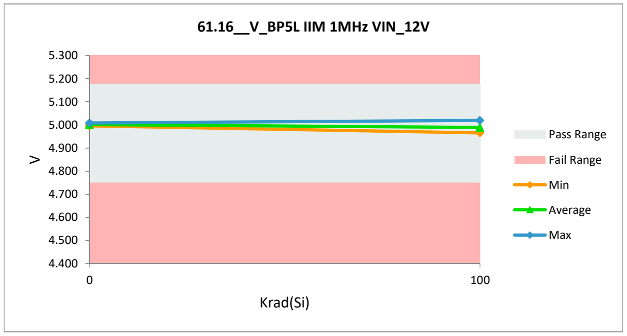


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.16__V_BP5L IIM 1MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.996	4.995	0.000
0	2	5.008	5.008	-0.001
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.995	-0.009
100	26	4.985	5.005	0.020
100	27	5.003	4.965	-0.038
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.991	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.006	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

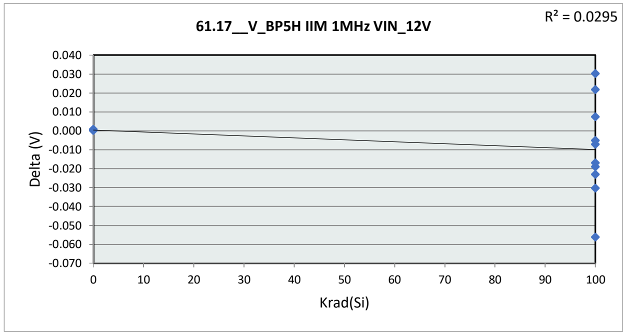


	61.16__V_BP5L IIM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.001	4.989
Max	5.008	5.020
UL	5.175	5.175

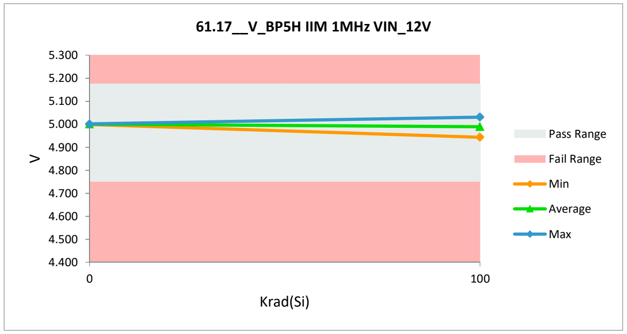


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.17__V_BP5H IIM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.989	4.958	-0.030
100	24	5.012	4.993	-0.019
100	25	4.992	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.997	5.004	0.007
100	49u	4.990	5.012	0.022
100	50u	5.016	4.992	-0.023
100	51u	5.001	5.031	0.030
100	52u	4.993	4.976	-0.017
	Max	5.016	5.031	0.030
	Average	4.999	4.991	-0.008
	Min	4.989	4.943	-0.056
	Std Dev	0.008	0.023	0.023



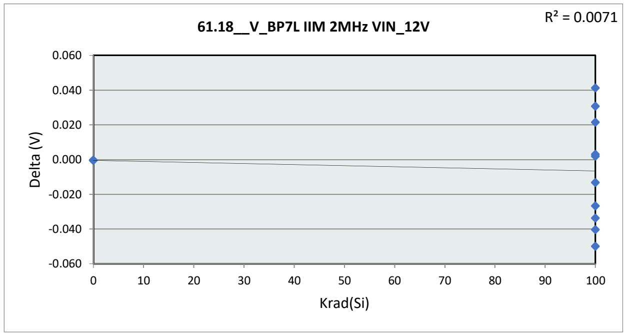
	61.17__V_BP5H IIM 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.989
Max	5.001	5.031
UL	5.175	5.175



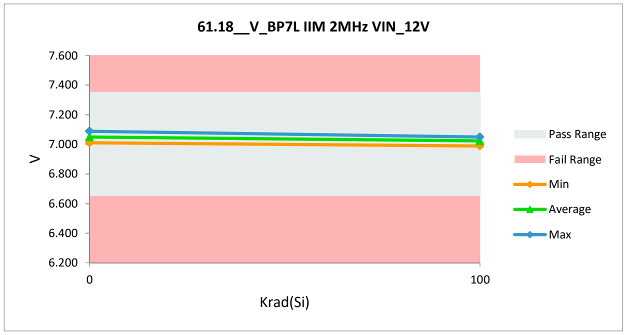
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	61.18__V_BP7L IIM 2MHz VIN_1	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	7.35	7.35
Min Limit	6.65	6.65

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.011	-0.001
0	2	7.088	7.087	0.000
100	23	6.997	7.028	0.031
100	24	7.046	7.005	-0.040
100	25	7.022	7.025	0.003
100	26	7.009	7.050	0.041
100	27	7.013	7.015	0.002
100	48u	7.016	6.990	-0.027
100	49u	7.053	7.003	-0.050
100	50u	7.024	7.045	0.022
100	51u	7.042	7.028	-0.013
100	52u	7.072	7.038	-0.034
	Max	7.088	7.087	0.041
	Average	7.033	7.027	-0.006
	Min	6.997	6.990	-0.050
	Std Dev	0.027	0.026	0.028

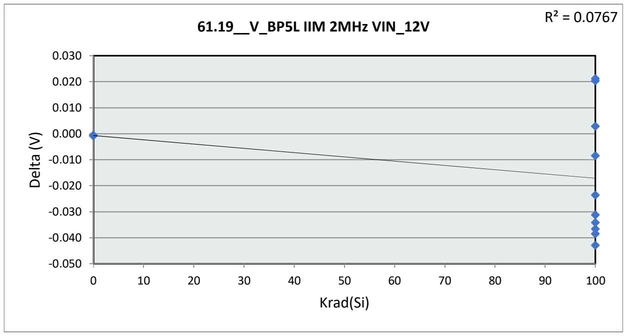


	61.18__V_BP7L IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.011	6.990
Average	7.049	7.023
Max	7.087	7.050
UL	7.350	7.350

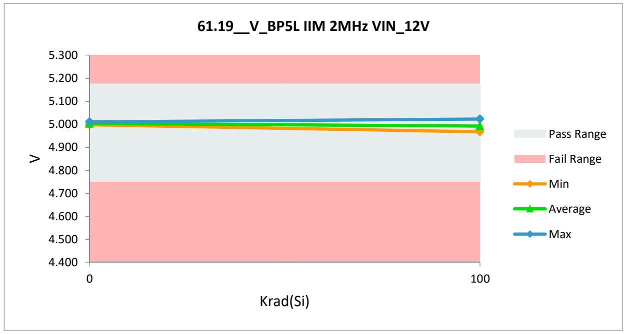


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.19__V_BP5L IIM 2MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.010	-0.001
100	23	5.014	4.978	-0.037
100	24	5.015	4.981	-0.034
100	25	5.006	4.998	-0.008
100	26	4.987	5.007	0.020
100	27	5.005	4.967	-0.038
100	48u	5.026	4.983	-0.043
100	49u	5.012	5.015	0.003
100	50u	5.024	4.992	-0.031
100	51u	5.001	5.022	0.021
100	52u	4.992	4.968	-0.024
	Max	5.026	5.022	0.021
	Average	5.008	4.993	-0.014
	Min	4.987	4.967	-0.043
	Std Dev	0.012	0.018	0.023

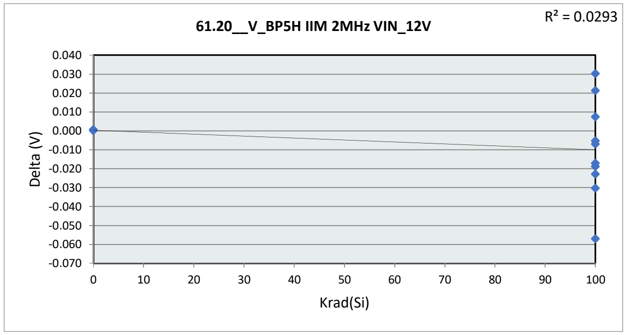


	61.19__V_BP5L IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.967
Average	5.003	4.991
Max	5.010	5.022
UL	5.175	5.175

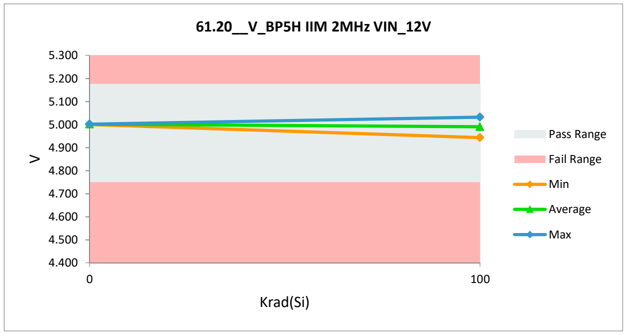


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.20__V_BP5H IIM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.030
100	24	5.013	4.994	-0.019
100	25	4.993	4.986	-0.007
100	26	5.001	4.995	-0.005
100	27	5.000	4.943	-0.057
100	48u	4.998	5.005	0.007
100	49u	4.991	5.013	0.021
100	50u	5.016	4.994	-0.023
100	51u	5.002	5.032	0.030
100	52u	4.994	4.977	-0.017
	Max	5.016	5.032	0.030
	Average	5.000	4.992	-0.008
	Min	4.990	4.943	-0.057
	Std Dev	0.008	0.024	0.023

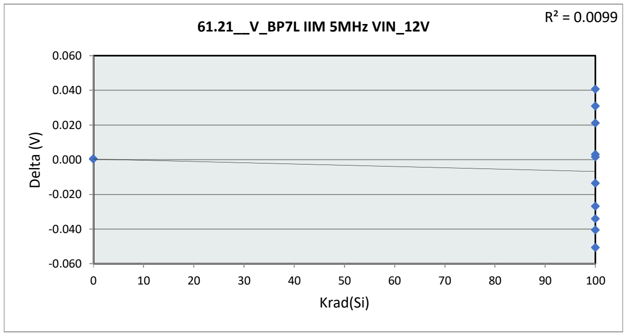


	61.20__V_BP5H IIM 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.943
Average	5.001	4.990
Max	5.002	5.032
UL	5.175	5.175

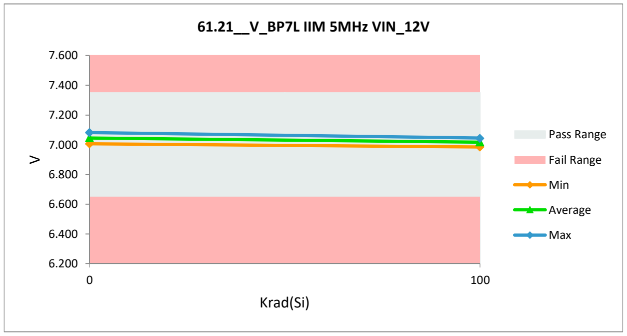


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.21__V_BP7L IIM 5MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.006	7.006	0.000
0	2	7.082	7.082	0.000
100	23	6.992	7.023	0.031
100	24	7.040	6.999	-0.041
100	25	7.017	7.020	0.003
100	26	7.003	7.044	0.041
100	27	7.007	7.009	0.002
100	48u	7.011	6.984	-0.027
100	49u	7.047	6.996	-0.051
100	50u	7.018	7.039	0.021
100	51u	7.036	7.022	-0.014
100	52u	7.066	7.032	-0.034
	Max	7.082	7.082	0.041
	Average	7.027	7.021	-0.006
	Min	6.992	6.984	-0.051
	Std Dev	0.027	0.026	0.029



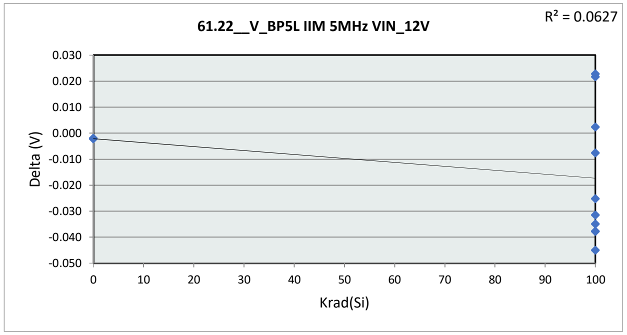
	61.21__V_BP7L IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.007	6.984
Average	7.044	7.017
Max	7.082	7.044
UL	7.350	7.350



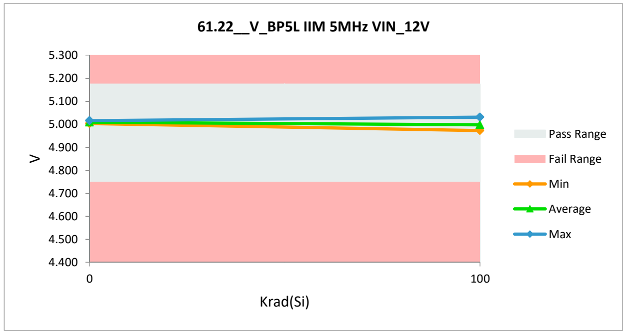
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	61.22__V_BP5L IIM 5MHz VIN_	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.005	5.003	-0.002
0	2	5.017	5.015	-0.002
100	23	5.021	4.983	-0.038
100	24	5.022	4.986	-0.035
100	25	5.012	5.004	-0.008
100	26	4.993	5.015	0.022
100	27	5.011	4.974	-0.038
100	48u	5.033	4.988	-0.045
100	49u	5.018	5.021	0.002
100	50u	5.030	4.999	-0.031
100	51u	5.007	5.030	0.023
100	52u	4.998	4.973	-0.025
	Max	5.033	5.030	0.023
	Average	5.014	4.999	-0.015
	Min	4.993	4.973	-0.045
	Std Dev	0.012	0.019	0.024

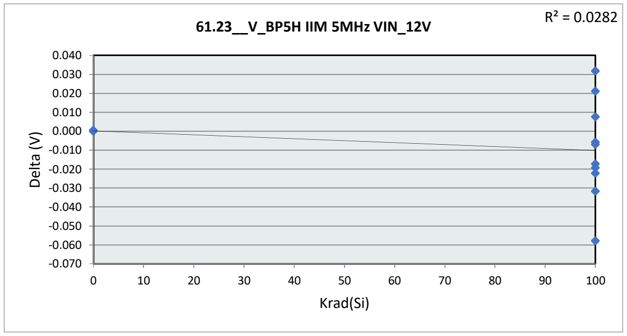


	61.22__V_BP5L IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.003	4.973
Average	5.009	4.997
Max	5.015	5.030
UL	5.175	5.175

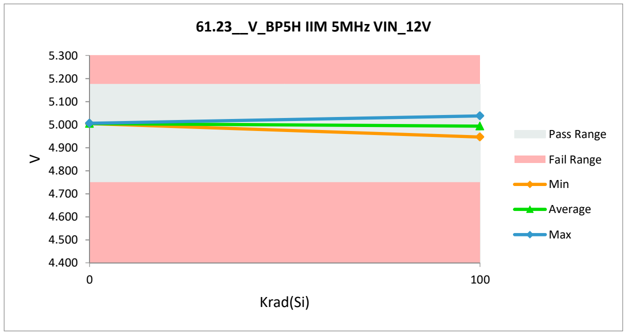


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		61.23__V_BP5H IIM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.004	5.004	0.001
0	2	5.006	5.005	0.000
100	23	4.993	4.962	-0.032
100	24	5.017	4.997	-0.019
100	25	4.996	4.989	-0.007
100	26	5.004	4.999	-0.006
100	27	5.004	4.946	-0.058
100	48u	5.002	5.009	0.008
100	49u	4.995	5.016	0.021
100	50u	5.020	4.998	-0.022
100	51u	5.006	5.038	0.032
100	52u	4.998	4.980	-0.017
	Max	5.020	5.038	0.032
	Average	5.004	4.995	-0.008
	Min	4.993	4.946	-0.058
	Std Dev	0.008	0.024	0.024

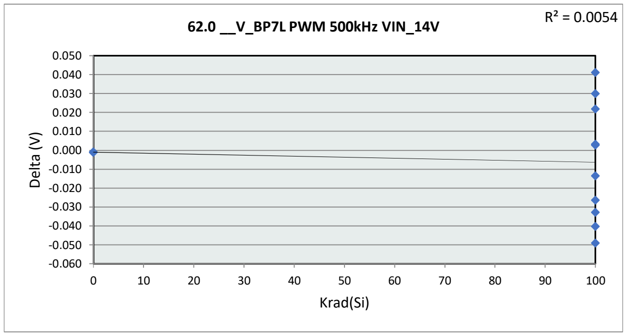


	61.23__V_BP5H IIM 5MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.004	4.946
Average	5.005	4.993
Max	5.006	5.038
UL	5.175	5.175

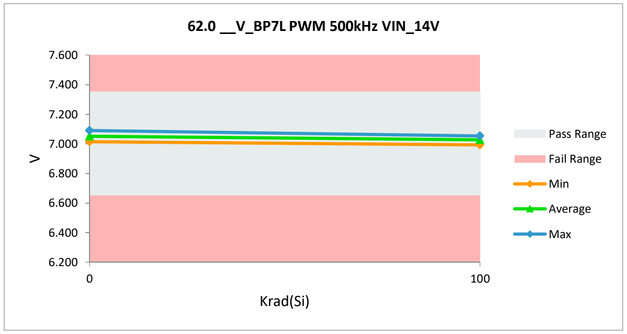


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.0 __V_BP7L PWM 500kHz VI		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.016	7.015	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.026	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.020	0.003
100	48u	7.020	6.994	-0.026
100	49u	7.056	7.007	-0.049
100	50u	7.028	7.049	0.022
100	51u	7.045	7.032	-0.014
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.041
	Average	7.036	7.031	-0.005
	Min	7.001	6.994	-0.049
	Std Dev	0.027	0.026	0.028

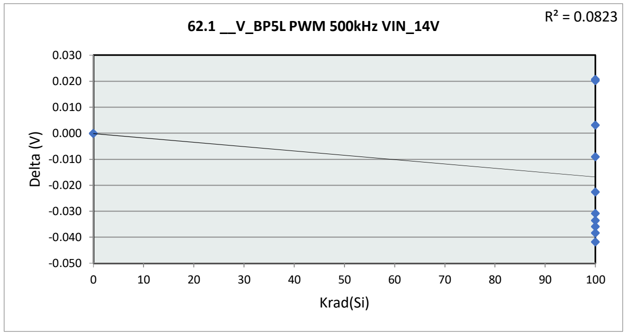


	62.0 __V_BP7L PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.015	6.994
Average	7.052	7.027
Max	7.090	7.054
UL	7.350	7.350

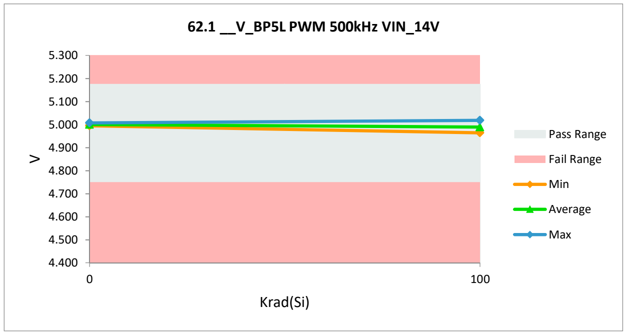


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.1 __V_BP5L PWM 500kHz VI		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.995	4.994	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.034
100	25	5.003	4.994	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.038
100	48u	5.023	4.981	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.021	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.004	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023



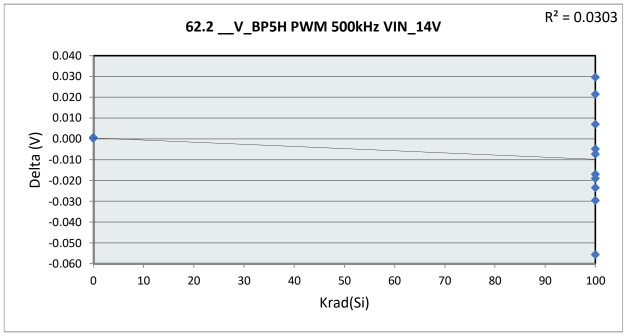
	62.1 __V_BP5L PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.994	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175



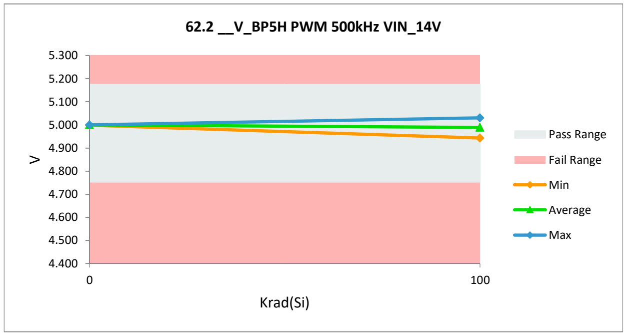
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	62.2 __V_BP5H PWM 500kHz VI	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.996	5.003	0.007
100	49u	4.990	5.011	0.022
100	50u	5.015	4.991	-0.024
100	51u	5.000	5.030	0.030
100	52u	4.992	4.975	-0.017
	Max	5.015	5.030	0.030
	Average	4.998	4.990	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

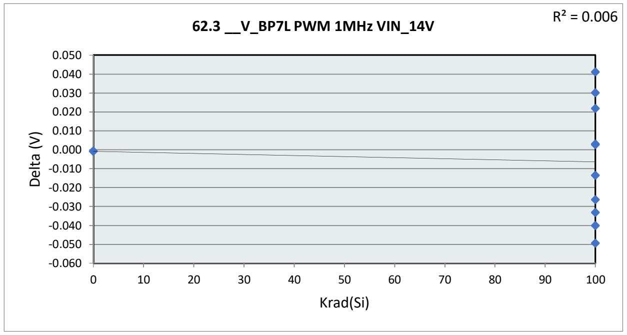


	62.2 __V_BP5H PWM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.988
Max	5.000	5.030
UL	5.175	5.175

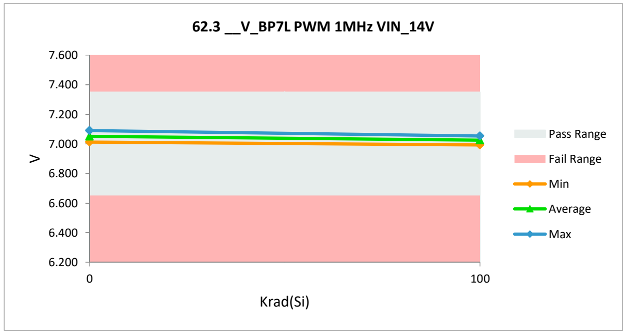


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.3 __V_BP7L PWM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.014	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.012	7.053	0.041
100	27	7.016	7.019	0.003
100	48u	7.019	6.993	-0.026
100	49u	7.055	7.006	-0.049
100	50u	7.026	7.048	0.022
100	51u	7.044	7.031	-0.014
100	52u	7.074	7.041	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.030	-0.006
	Min	7.000	6.993	-0.049
	Std Dev	0.027	0.026	0.028

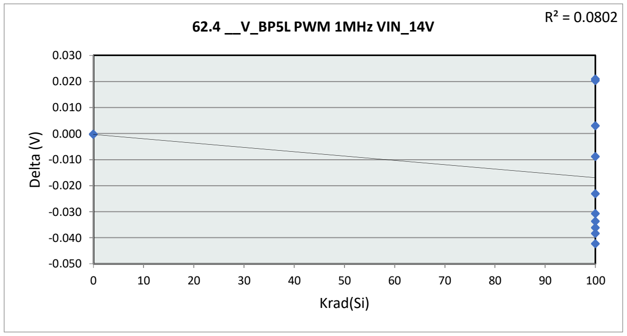


62.3 __V_BP7L PWM 1MHz VIN_14V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.993
Average	7.051	7.025
Max	7.089	7.053
UL	7.350	7.350

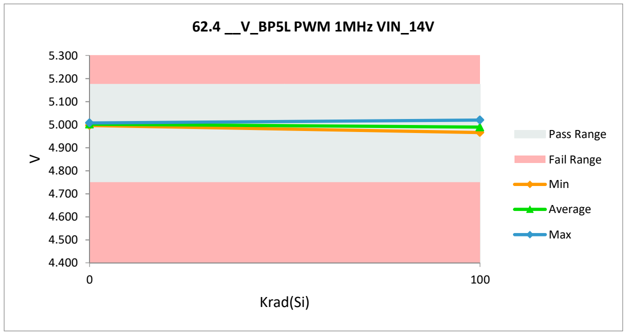


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.4 __V_BP5L PWM 1MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.996	4.995	0.000
0	2	5.008	5.008	0.000
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.996	-0.009
100	26	4.985	5.005	0.020
100	27	5.004	4.965	-0.038
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.991	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.006	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

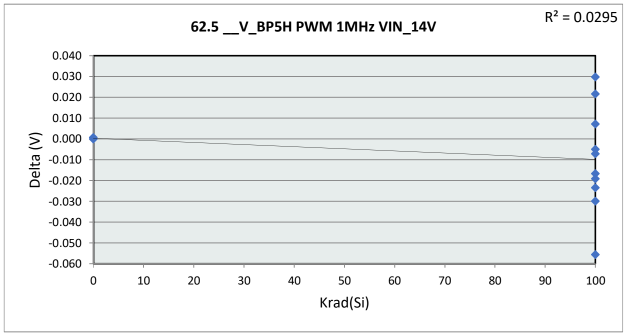


	62.4 __V_BP5L PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.002	4.989
Max	5.008	5.019
UL	5.175	5.175

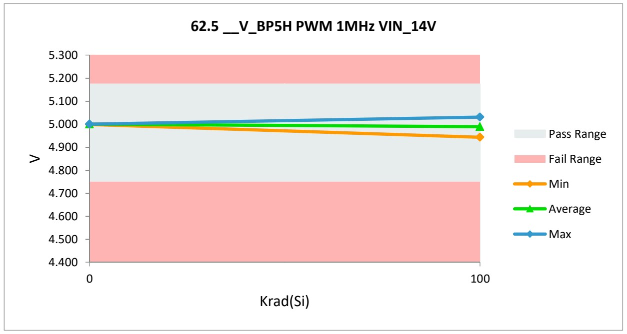


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.5 __V_BP5H PWM 1MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.012	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.944	-0.056
100	48u	4.997	5.004	0.007
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.001	5.030	0.030
100	52u	4.993	4.976	-0.017
	Max	5.015	5.030	0.030
	Average	4.999	4.991	-0.008
	Min	4.988	4.944	-0.056
	Std Dev	0.008	0.023	0.023

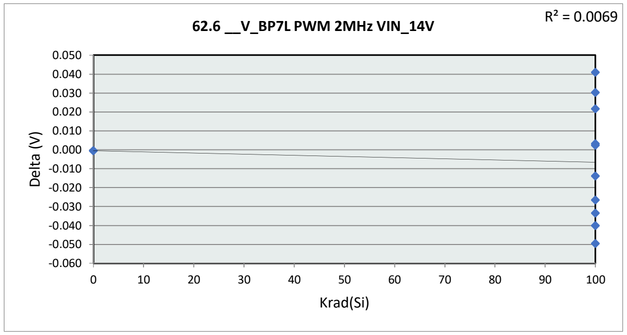


	62.5 __V_BP5H PWM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.944
Average	5.000	4.989
Max	5.001	5.031
UL	5.175	5.175

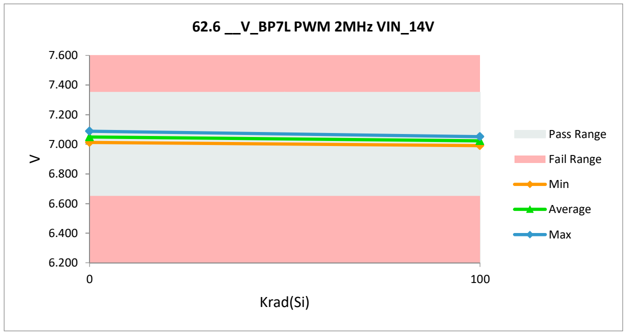


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.6 __V_BP7L PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.012	-0.001
0	2	7.088	7.088	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.023	7.025	0.002
100	26	7.010	7.051	0.041
100	27	7.014	7.017	0.003
100	48u	7.017	6.990	-0.027
100	49u	7.053	7.003	-0.050
100	50u	7.024	7.046	0.022
100	51u	7.042	7.028	-0.014
100	52u	7.072	7.038	-0.034
	Max	7.088	7.088	0.041
	Average	7.033	7.028	-0.006
	Min	6.998	6.990	-0.050
	Std Dev	0.027	0.026	0.028

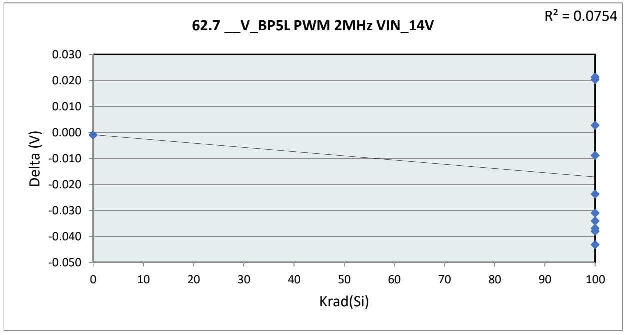


	62.6 __V_BP7L PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.990
Average	7.050	7.023
Max	7.088	7.051
UL	7.350	7.350

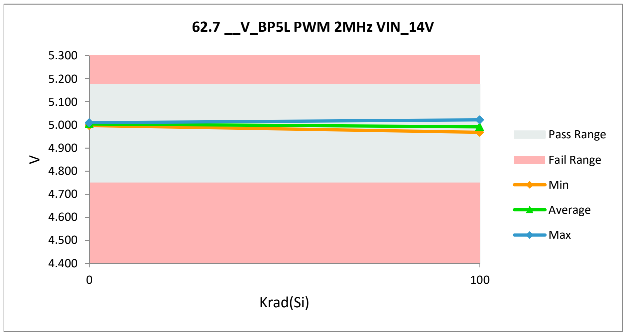


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.7 __V_BP5L PWM 2MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.997	-0.001
0	2	5.010	5.010	-0.001
100	23	5.015	4.978	-0.037
100	24	5.015	4.981	-0.034
100	25	5.007	4.998	-0.009
100	26	4.987	5.008	0.020
100	27	5.006	4.968	-0.038
100	48u	5.027	4.983	-0.043
100	49u	5.013	5.015	0.003
100	50u	5.024	4.993	-0.031
100	51u	5.001	5.022	0.021
100	52u	4.992	4.969	-0.024
	Max	5.027	5.022	0.021
	Average	5.008	4.994	-0.014
	Min	4.987	4.968	-0.043
	Std Dev	0.012	0.018	0.023

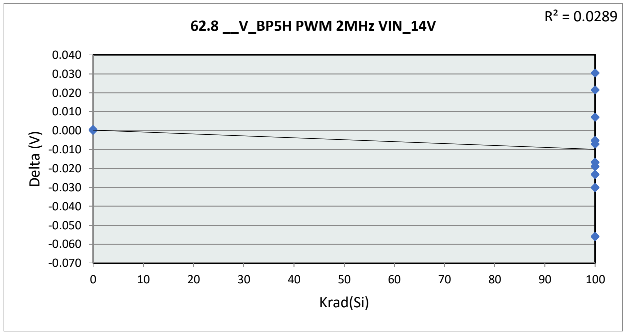


	62.7 __V_BP5L PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.997	4.968
Average	5.004	4.992
Max	5.010	5.022
UL	5.175	5.175

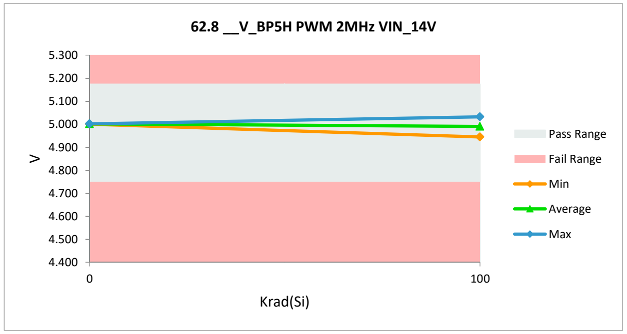


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.8 __V_BP5H PWM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.030
100	24	5.013	4.994	-0.019
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.005
100	27	5.001	4.944	-0.056
100	48u	4.998	5.005	0.007
100	49u	4.992	5.013	0.021
100	50u	5.017	4.993	-0.023
100	51u	5.002	5.033	0.030
100	52u	4.994	4.977	-0.017
	Max	5.017	5.033	0.030
	Average	5.000	4.992	-0.008
	Min	4.990	4.944	-0.056
	Std Dev	0.008	0.023	0.023

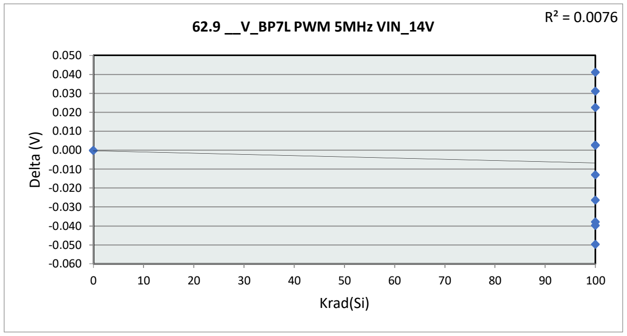


	62.8 __V_BP5H PWM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.945
Average	5.001	4.990
Max	5.002	5.033
UL	5.175	5.175

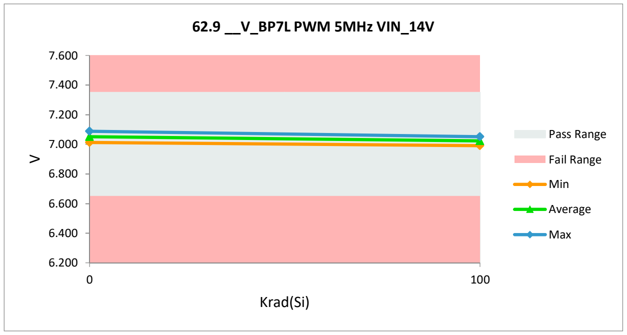


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.9 __V_BP7L PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.013	7.013	0.000
0	2	7.089	7.088	0.000
100	23	6.998	7.029	0.031
100	24	7.047	7.007	-0.040
100	25	7.023	7.025	0.002
100	26	7.010	7.051	0.041
100	27	7.014	7.017	0.003
100	48u	7.017	6.991	-0.027
100	49u	7.054	7.004	-0.050
100	50u	7.024	7.047	0.022
100	51u	7.042	7.029	-0.013
100	52u	7.073	7.035	-0.038
	Max	7.089	7.088	0.041
	Average	7.034	7.028	-0.006
	Min	6.998	6.991	-0.050
	Std Dev	0.027	0.026	0.029

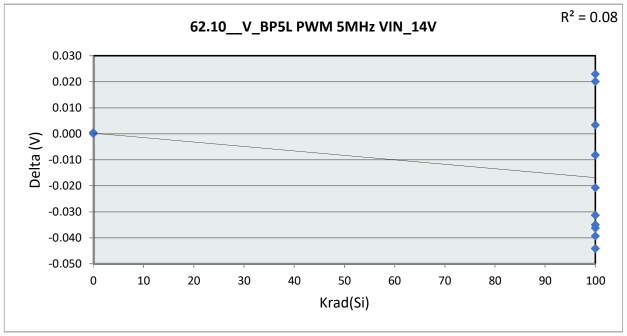


	62.9 __V_BP7L PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.013	6.991
Average	7.051	7.023
Max	7.088	7.051
UL	7.350	7.350

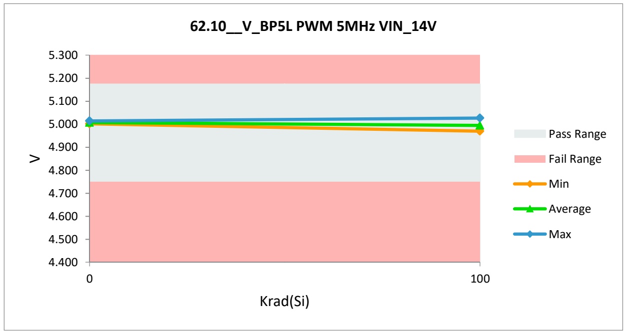


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.10__V_BP5L PWM 5MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.001	5.002	0.000
0	2	5.014	5.014	0.000
100	23	5.017	4.981	-0.036
100	24	5.018	4.983	-0.035
100	25	5.010	5.001	-0.008
100	26	4.990	5.011	0.020
100	27	5.009	4.969	-0.039
100	48u	5.030	4.986	-0.044
100	49u	5.016	5.019	0.003
100	50u	5.027	4.996	-0.031
100	51u	5.004	5.027	0.023
100	52u	4.996	4.975	-0.021
	Max	5.030	5.027	0.023
	Average	5.011	4.997	-0.014
	Min	4.990	4.969	-0.044
	Std Dev	0.012	0.018	0.024

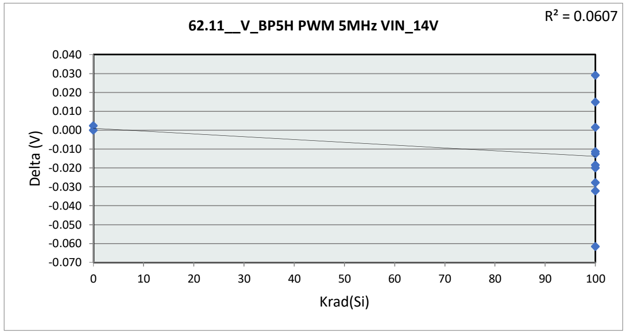


	62.10__V_BP5L PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.002	4.969
Average	5.008	4.995
Max	5.014	5.027
UL	5.175	5.175

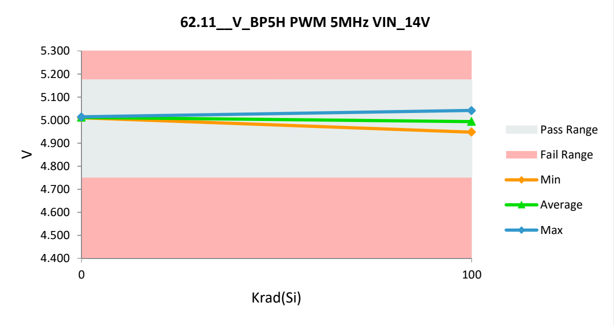


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.11__V_BP5H PWM 5MHz VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.010	5.010	0.000
0	2	5.011	5.013	0.002
100	23	4.992	4.959	-0.032
100	24	5.018	4.998	-0.020
100	25	5.001	4.989	-0.013
100	26	5.010	4.998	-0.011
100	27	5.009	4.948	-0.062
100	48u	5.006	5.007	0.002
100	49u	5.000	5.015	0.015
100	50u	5.025	4.997	-0.028
100	51u	5.012	5.041	0.029
100	52u	5.005	4.986	-0.019
	Max	5.025	5.041	0.029
	Average	5.008	4.997	-0.011
	Min	4.992	4.948	-0.062
	Std Dev	0.009	0.025	0.024

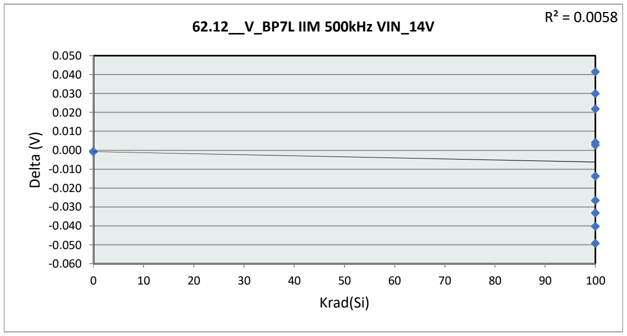


	62.11__V_BP5H PWM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.010	4.948
Average	5.011	4.994
Max	5.013	5.041
UL	5.175	5.175

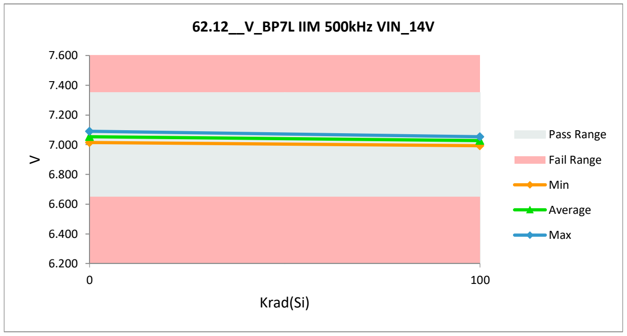


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.12__V_BP7L IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.015	7.015	-0.001
0	2	7.091	7.090	-0.001
100	23	7.001	7.031	0.030
100	24	7.049	7.009	-0.040
100	25	7.025	7.028	0.003
100	26	7.013	7.054	0.041
100	27	7.017	7.021	0.004
100	48u	7.020	6.994	-0.027
100	49u	7.056	7.007	-0.049
100	50u	7.027	7.049	0.022
100	51u	7.045	7.032	-0.014
100	52u	7.075	7.042	-0.033
	Max	7.091	7.090	0.041
	Average	7.036	7.031	-0.005
	Min	7.001	6.994	-0.049
	Std Dev	0.027	0.026	0.028

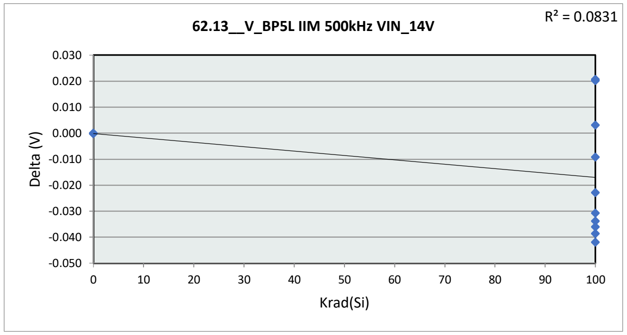


	62.12__V_BP7L IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.015	6.994
Average	7.052	7.027
Max	7.090	7.054
UL	7.350	7.350

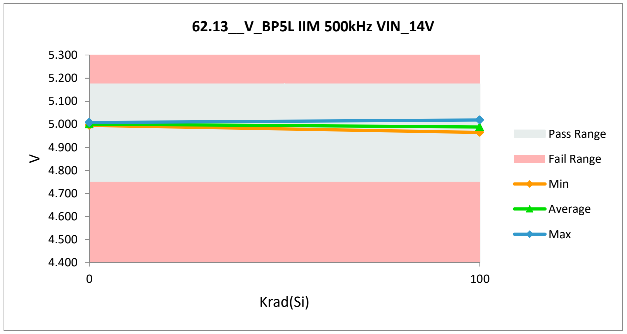


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.13__V_BP5L IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.994	4.994	0.000
0	2	5.007	5.007	0.000
100	23	5.011	4.975	-0.036
100	24	5.012	4.978	-0.034
100	25	5.003	4.994	-0.009
100	26	4.984	5.004	0.020
100	27	5.003	4.964	-0.039
100	48u	5.023	4.981	-0.042
100	49u	5.009	5.012	0.003
100	50u	5.020	4.990	-0.031
100	51u	4.997	5.018	0.021
100	52u	4.989	4.966	-0.023
	Max	5.023	5.018	0.021
	Average	5.004	4.990	-0.014
	Min	4.984	4.964	-0.042
	Std Dev	0.012	0.018	0.023

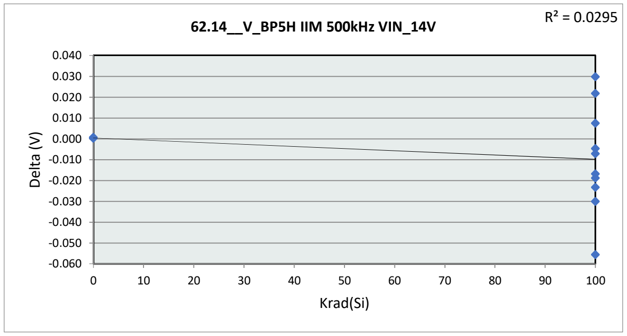


	62.13__V_BP5L IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.994	4.964
Average	5.001	4.988
Max	5.007	5.018
UL	5.175	5.175

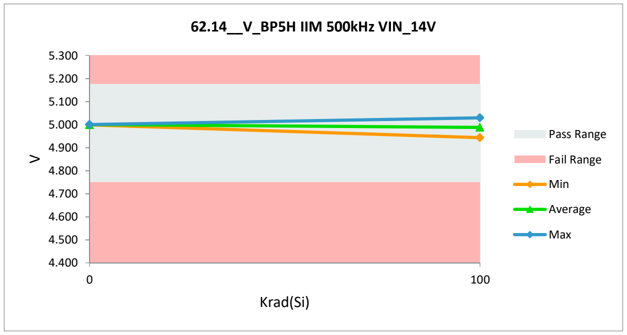


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.14__V_BP5H IIM 500kHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.999	0.001
0	2	5.000	5.000	0.000
100	23	4.988	4.958	-0.030
100	24	5.011	4.992	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.996	5.003	0.007
100	49u	4.990	5.011	0.022
100	50u	5.015	4.991	-0.023
100	51u	5.000	5.030	0.030
100	52u	4.992	4.975	-0.017
	Max	5.015	5.030	0.030
	Average	4.998	4.990	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

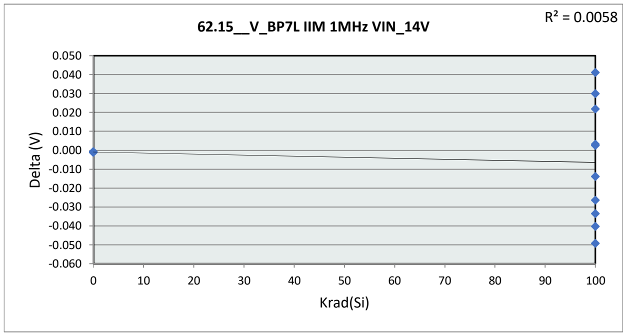


	62.14__V_BP5H IIM 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	4.999	4.988
Max	5.000	5.030
UL	5.175	5.175

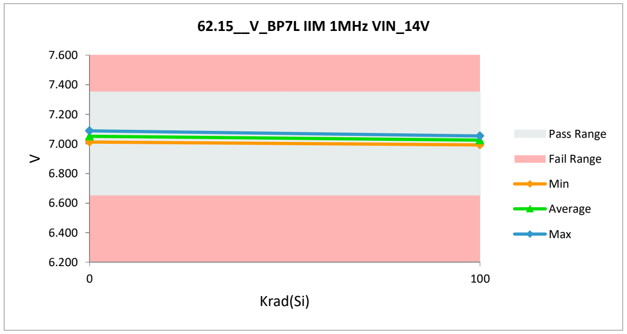


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.15__V_BP7L IIM 1MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.014	7.014	-0.001
0	2	7.090	7.089	-0.001
100	23	7.000	7.030	0.030
100	24	7.048	7.008	-0.040
100	25	7.024	7.027	0.003
100	26	7.011	7.053	0.041
100	27	7.016	7.019	0.003
100	48u	7.019	6.992	-0.026
100	49u	7.055	7.006	-0.049
100	50u	7.026	7.048	0.022
100	51u	7.044	7.030	-0.014
100	52u	7.074	7.040	-0.033
	Max	7.090	7.089	0.041
	Average	7.035	7.030	-0.005
	Min	7.000	6.992	-0.049
	Std Dev	0.027	0.026	0.028

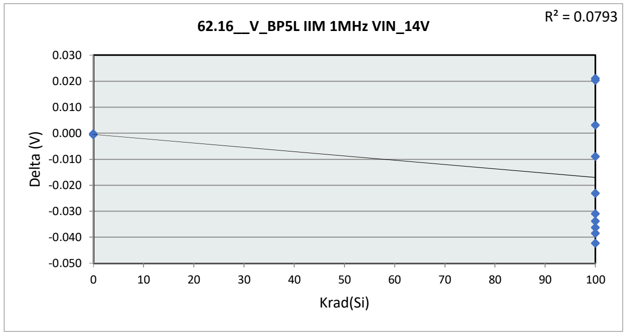


	62.15__V_BP7L IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.014	6.993
Average	7.051	7.025
Max	7.089	7.053
UL	7.350	7.350

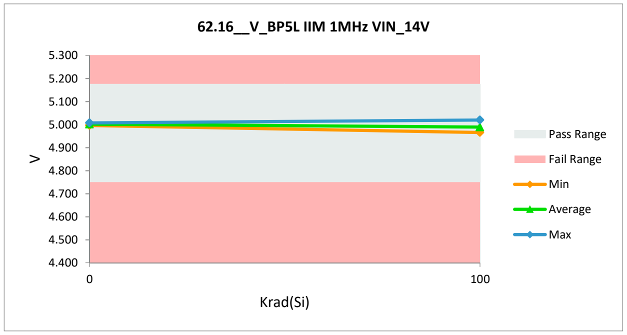


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.16__V_BP5L IIM 1MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.996	4.995	0.000
0	2	5.008	5.008	-0.001
100	23	5.012	4.976	-0.036
100	24	5.013	4.979	-0.034
100	25	5.004	4.996	-0.009
100	26	4.985	5.005	0.020
100	27	5.004	4.965	-0.039
100	48u	5.024	4.982	-0.042
100	49u	5.010	5.013	0.003
100	50u	5.022	4.991	-0.031
100	51u	4.998	5.019	0.021
100	52u	4.990	4.967	-0.023
	Max	5.024	5.019	0.021
	Average	5.006	4.991	-0.014
	Min	4.985	4.965	-0.042
	Std Dev	0.012	0.018	0.023

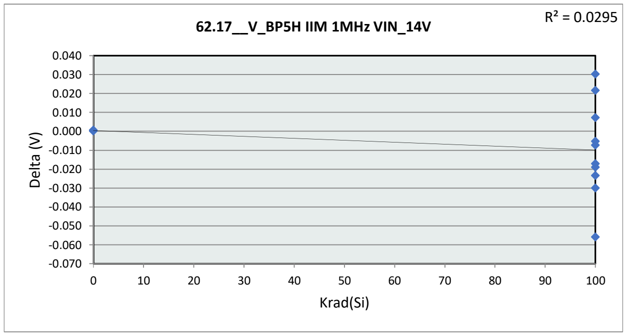


	62.16__V_BP5L IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.995	4.965
Average	5.002	4.989
Max	5.008	5.020
UL	5.175	5.175

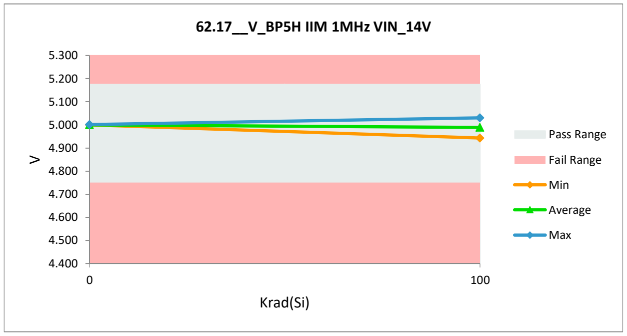


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.17__V_BP5H IIM 1MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.999	4.999	0.001
0	2	5.001	5.001	0.000
100	23	4.988	4.958	-0.030
100	24	5.012	4.993	-0.019
100	25	4.991	4.984	-0.007
100	26	4.999	4.994	-0.005
100	27	4.999	4.943	-0.056
100	48u	4.997	5.004	0.007
100	49u	4.990	5.012	0.022
100	50u	5.015	4.992	-0.023
100	51u	5.001	5.031	0.030
100	52u	4.993	4.976	-0.017
	Max	5.015	5.031	0.030
	Average	4.999	4.991	-0.008
	Min	4.988	4.943	-0.056
	Std Dev	0.008	0.023	0.023

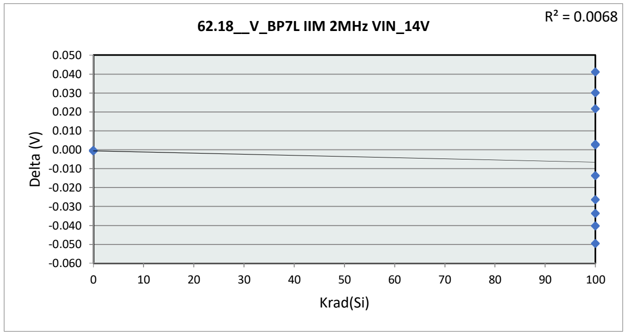


	62.17__V_BP5H IIM 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.999	4.943
Average	5.000	4.989
Max	5.001	5.031
UL	5.175	5.175

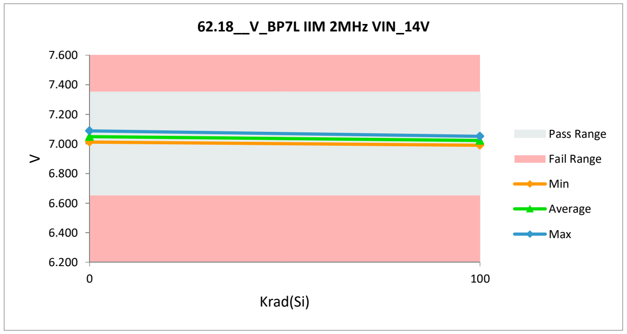


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.18__V_BP7L IIM 2MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.35	7.35	
	Min Limit	6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.012	7.012	0.000
0	2	7.088	7.087	-0.001
100	23	6.998	7.028	0.030
100	24	7.046	7.006	-0.040
100	25	7.022	7.025	0.003
100	26	7.009	7.050	0.041
100	27	7.014	7.016	0.003
100	48u	7.017	6.990	-0.026
100	49u	7.053	7.003	-0.050
100	50u	7.024	7.046	0.022
100	51u	7.042	7.028	-0.014
100	52u	7.072	7.038	-0.034
	Max	7.088	7.087	0.041
	Average	7.033	7.028	-0.006
	Min	6.998	6.990	-0.050
	Std Dev	0.027	0.026	0.028

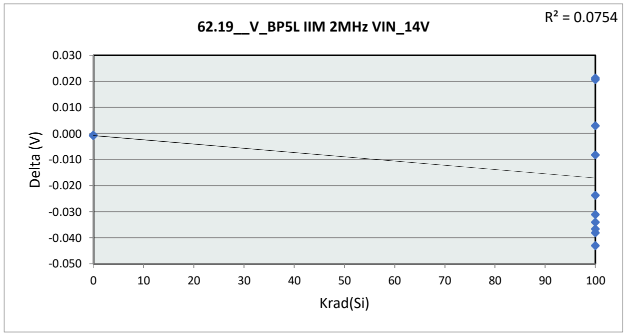


	62.18__V_BP7L IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.012	6.991
Average	7.050	7.023
Max	7.087	7.051
UL	7.350	7.350

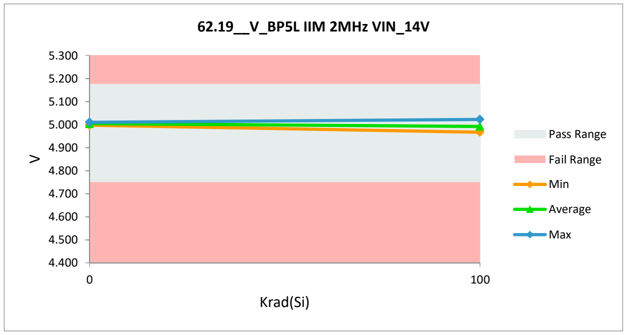


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.19__V_BP5L IIM 2MHz VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.998	4.998	-0.001
0	2	5.010	5.010	-0.001
100	23	5.015	4.978	-0.037
100	24	5.015	4.981	-0.034
100	25	5.006	4.998	-0.008
100	26	4.987	5.008	0.021
100	27	5.006	4.967	-0.038
100	48u	5.027	4.983	-0.043
100	49u	5.012	5.015	0.003
100	50u	5.024	4.993	-0.031
100	51u	5.001	5.022	0.021
100	52u	4.992	4.969	-0.024
	Max	5.027	5.022	0.021
	Average	5.008	4.994	-0.014
	Min	4.987	4.967	-0.043
	Std Dev	0.012	0.018	0.023

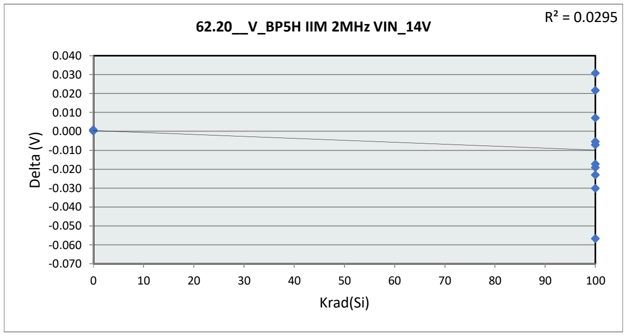


	62.19__V_BP5L IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	4.998	4.967
Average	5.004	4.991
Max	5.010	5.022
UL	5.175	5.175

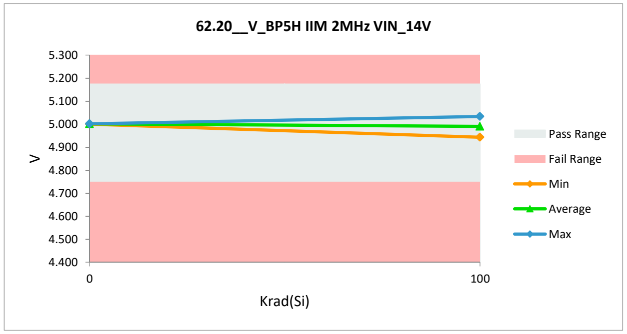


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.20__V_BP5H IIM 2MHz VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	5.175	5.175	
	Min Limit	4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.000	5.001	0.001
0	2	5.002	5.002	0.000
100	23	4.990	4.959	-0.030
100	24	5.013	4.994	-0.019
100	25	4.993	4.985	-0.007
100	26	5.001	4.995	-0.005
100	27	5.000	4.944	-0.057
100	48u	4.998	5.005	0.007
100	49u	4.992	5.013	0.022
100	50u	5.016	4.994	-0.023
100	51u	5.002	5.033	0.031
100	52u	4.994	4.977	-0.017
	Max	5.016	5.033	0.031
	Average	5.000	4.992	-0.008
	Min	4.990	4.944	-0.057
	Std Dev	0.008	0.024	0.023

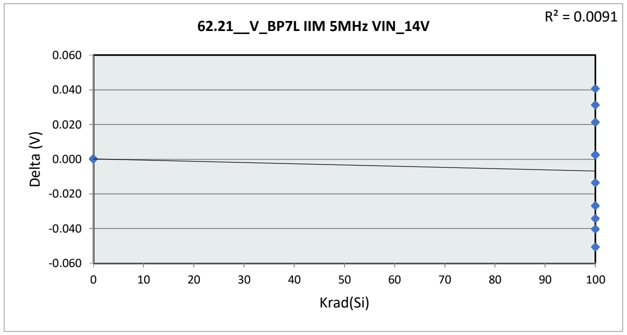


	62.20__V_BP5H IIM 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.001	4.944
Average	5.001	4.990
Max	5.002	5.033
UL	5.175	5.175

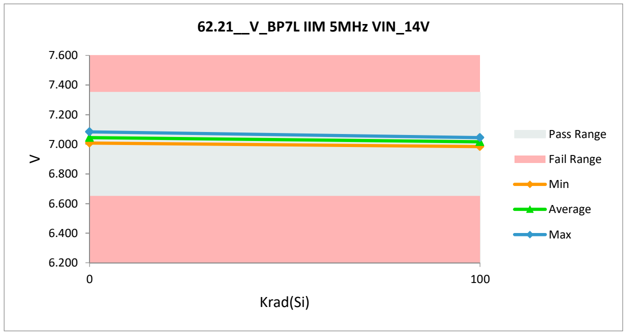


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.21__V_BP7L IIM 5MHz VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7.35	7.35	
Min Limit		6.65	6.65	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.007	7.007	0.000
0	2	7.083	7.083	0.000
100	23	6.992	7.024	0.031
100	24	7.041	7.000	-0.040
100	25	7.017	7.020	0.002
100	26	7.004	7.044	0.041
100	27	7.008	7.011	0.003
100	48u	7.012	6.985	-0.027
100	49u	7.048	6.997	-0.051
100	50u	7.018	7.040	0.021
100	51u	7.037	7.023	-0.014
100	52u	7.067	7.032	-0.034
	Max	7.083	7.083	0.041
	Average	7.028	7.022	-0.006
	Min	6.992	6.985	-0.051
	Std Dev	0.027	0.026	0.029

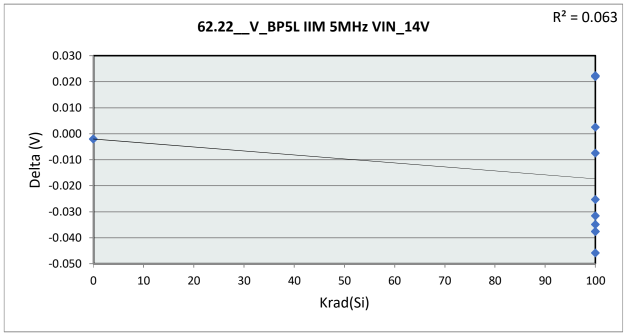


	62.21__V_BP7L IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.35	V
Min Limit	6.65	V
Krad(Si)	0	100
LL	6.650	6.650
Min	7.007	6.985
Average	7.045	7.018
Max	7.083	7.045
UL	7.350	7.350

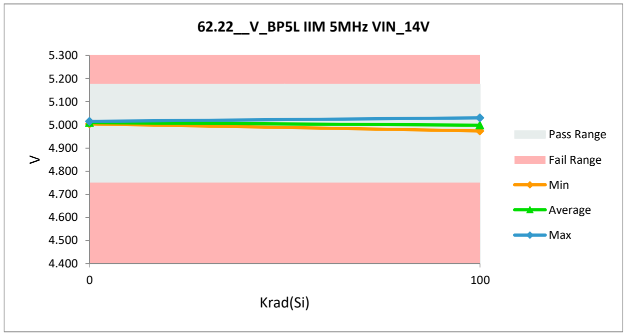


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		62.22__V_BP5L IIM 5MHz VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		5.175	5.175	
Min Limit		4.75	4.75	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.005	5.003	-0.002
0	2	5.017	5.015	-0.002
100	23	5.022	4.984	-0.038
100	24	5.022	4.987	-0.035
100	25	5.013	5.005	-0.007
100	26	4.994	5.016	0.022
100	27	5.012	4.975	-0.038
100	48u	5.033	4.988	-0.046
100	49u	5.019	5.022	0.003
100	50u	5.031	4.999	-0.032
100	51u	5.008	5.030	0.022
100	52u	4.999	4.973	-0.025
	Max	5.033	5.030	0.022
	Average	5.015	5.000	-0.015
	Min	4.994	4.973	-0.046
	Std Dev	0.012	0.019	0.024



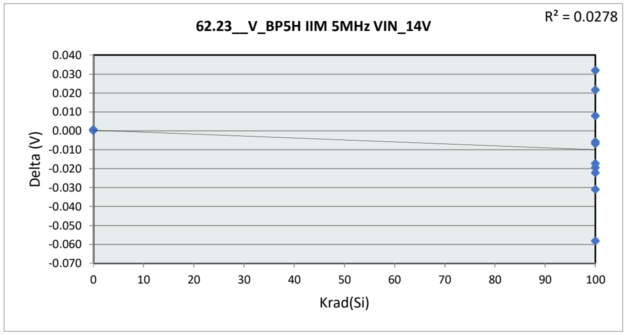
	62.22__V_BP5L IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.003	4.974
Average	5.009	4.998
Max	5.015	5.030
UL	5.175	5.175



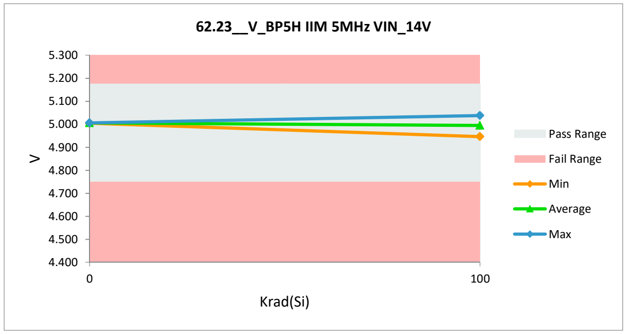
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	62.23__V_BP5H IIM 5MHz VIN	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	V	V
Max Limit	5.175	5.175
Min Limit	4.75	4.75

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	5.004	5.005	0.001
0	2	5.006	5.006	0.000
100	23	4.994	4.963	-0.031
100	24	5.017	4.997	-0.020
100	25	4.997	4.990	-0.007
100	26	5.005	4.999	-0.006
100	27	5.005	4.946	-0.058
100	48u	5.002	5.010	0.008
100	49u	4.996	5.017	0.022
100	50u	5.020	4.998	-0.022
100	51u	5.006	5.038	0.032
100	52u	4.998	4.981	-0.017
	Max	5.020	5.038	0.032
	Average	5.004	4.996	-0.008
	Min	4.994	4.946	-0.058
	Std Dev	0.008	0.024	0.024

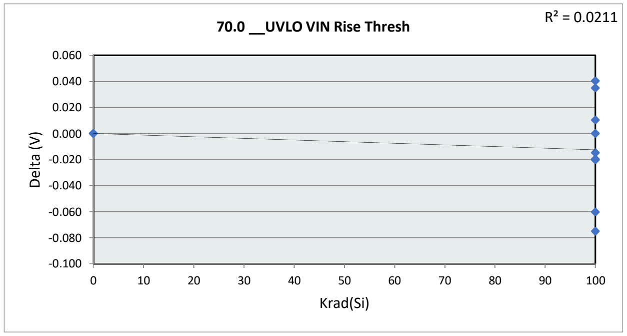


	62.23__V_BP5H IIM 5MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.175	V
Min Limit	4.75	V
Krad(Si)	0	100
LL	4.750	4.750
Min	5.005	4.947
Average	5.005	4.994
Max	5.006	5.038
UL	5.175	5.175

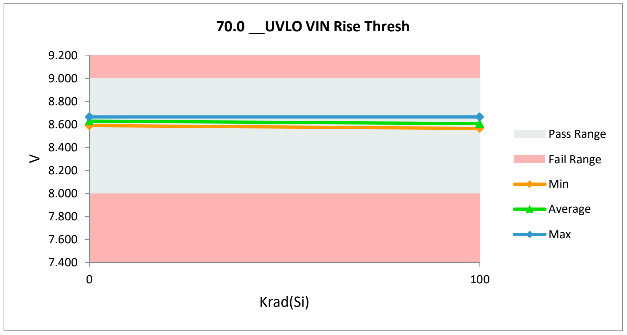


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		70.0 __UVLO VIN Rise Thresh		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		9	9	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.590	8.590	0.000
0	2	8.665	8.665	0.000
100	23	8.550	8.590	0.040
100	24	8.580	8.565	-0.015
100	25	8.650	8.575	-0.075
100	26	8.620	8.600	-0.020
100	27	8.645	8.655	0.010
100	48u	8.610	8.590	-0.020
100	49u	8.675	8.615	-0.060
100	50u	8.630	8.665	0.035
100	51u	8.635	8.615	-0.020
100	52u	8.595	8.595	0.000
	Max	8.675	8.665	0.040
	Average	8.620	8.610	-0.010
	Min	8.550	8.565	-0.075
	Std Dev	0.037	0.034	0.033

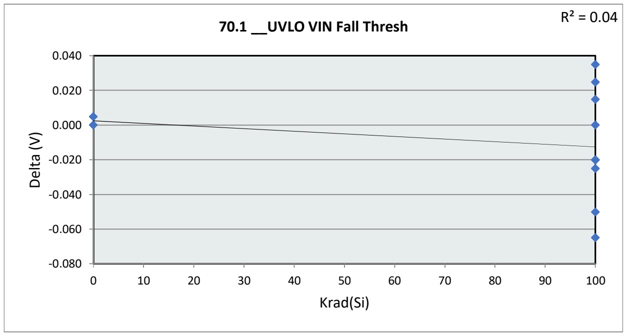


	70.0 __UVLO VIN Rise Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	9	V
Min Limit	8	V
Krad(Si)	0	100
LL	8.000	8.000
Min	8.590	8.565
Average	8.628	8.607
Max	8.665	8.665
UL	9.000	9.000

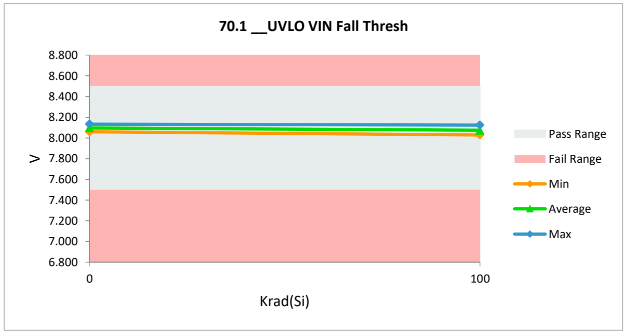


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		70.1 __UVLO VIN Fall Thresh		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		8.5	8.5	
Min Limit		7.5	7.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.055	8.060	0.005
0	2	8.135	8.135	0.000
100	23	8.020	8.055	0.035
100	24	8.050	8.030	-0.020
100	25	8.115	8.050	-0.065
100	26	8.085	8.065	-0.020
100	27	8.105	8.120	0.015
100	48u	8.080	8.055	-0.025
100	49u	8.135	8.085	-0.050
100	50u	8.100	8.125	0.025
100	51u	8.105	8.085	-0.020
100	52u	8.065	8.065	0.000
	Max	8.135	8.135	0.035
	Average	8.088	8.077	-0.010
	Min	8.020	8.030	-0.065
	Std Dev	0.035	0.033	0.029

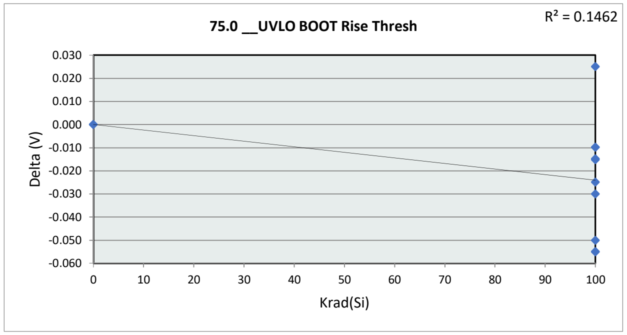


	70.1 __UVLO VIN Fall Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8.5	V
Min Limit	7.5	V
Krad(Si)	0	100
LL	7.500	7.500
Min	8.060	8.030
Average	8.098	8.073
Max	8.135	8.125
UL	8.500	8.500

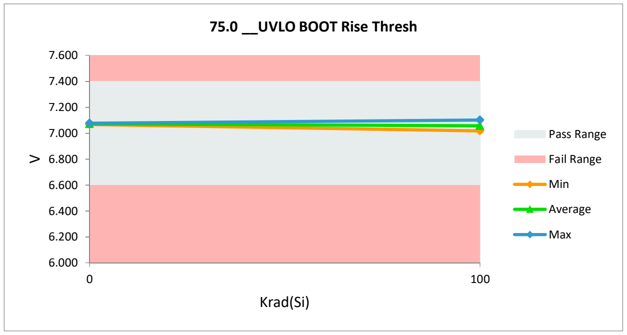


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		75.0 __UVLO BOOT Rise Thresh		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	7.4	7.4	
	Min Limit	6.6	6.6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	7.068	7.068	0.000
0	2	7.077	7.077	0.000
100	23	7.098	7.043	-0.055
100	24	7.082	7.027	-0.055
100	25	7.102	7.093	-0.010
100	26	7.048	7.038	-0.010
100	27	6.992	7.017	0.025
100	48u	7.082	7.068	-0.015
100	49u	7.068	7.052	-0.015
100	50u	7.102	7.052	-0.050
100	51u	7.093	7.068	-0.025
100	52u	7.133	7.102	-0.030
	Max	7.133	7.102	0.025
	Average	7.079	7.059	-0.020
	Min	6.992	7.017	-0.055
	Std Dev	0.035	0.025	0.024

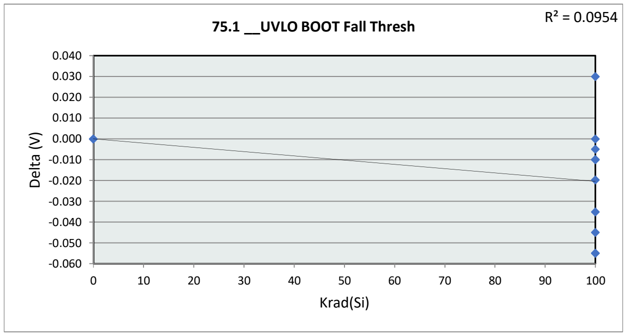


	75.0 __UVLO BOOT Rise Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.4	V
Min Limit	6.6	V
Krad(Si)	0	100
LL	6.600	6.600
Min	7.068	7.018
Average	7.073	7.056
Max	7.078	7.103
UL	7.400	7.400

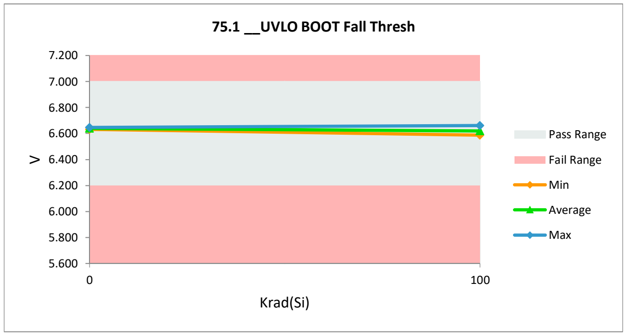


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		75.1 __UVLO BOOT Fall Thresh		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		7	7	
Min Limit		6.2	6.2	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.633	6.633	0.000
0	2	6.648	6.648	0.000
100	23	6.663	6.608	-0.055
100	24	6.642	6.588	-0.055
100	25	6.663	6.663	0.000
100	26	6.608	6.603	-0.005
100	27	6.557	6.588	0.030
100	48u	6.642	6.633	-0.010
100	49u	6.628	6.617	-0.010
100	50u	6.657	6.613	-0.045
100	51u	6.652	6.633	-0.020
100	52u	6.693	6.657	-0.035
	Max	6.693	6.663	0.030
	Average	6.640	6.623	-0.017
	Min	6.557	6.588	-0.055
	Std Dev	0.034	0.025	0.026

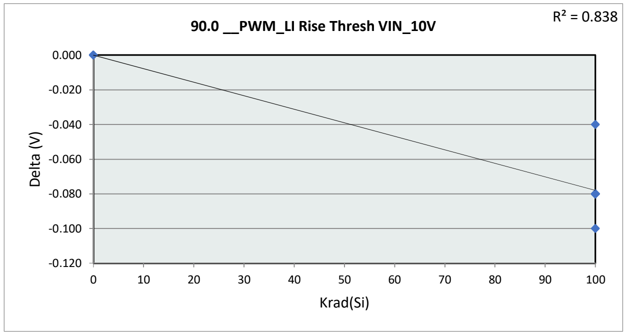


	75.1 __UVLO BOOT Fall Thresh	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7	V
Min Limit	6.2	V
Krad(Si)	0	100
LL	6.200	6.200
Min	6.633	6.588
Average	6.640	6.620
Max	6.648	6.663
UL	7.000	7.000

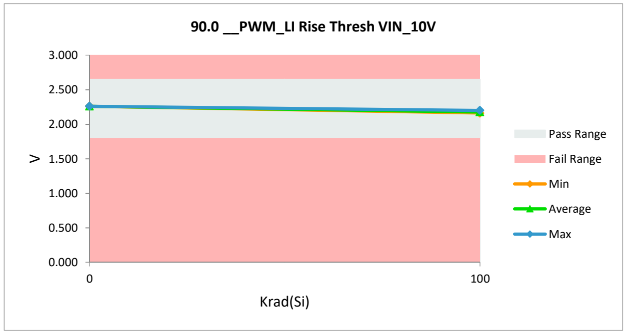


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		90.0 __PWM_LI Rise Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.180	-0.080
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.260	2.180	-0.080
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.260	2.260	0.000
	Average	2.257	2.192	-0.065
	Min	2.240	2.160	-0.100
	Std Dev	0.008	0.034	0.033

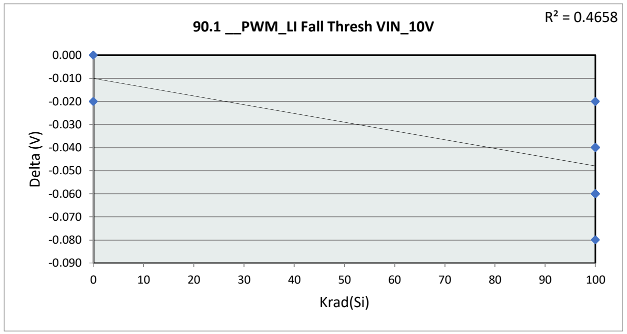


90.0 __PWM_LI Rise Thresh VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.178
Max	2.260	2.200
UL	2.650	2.650

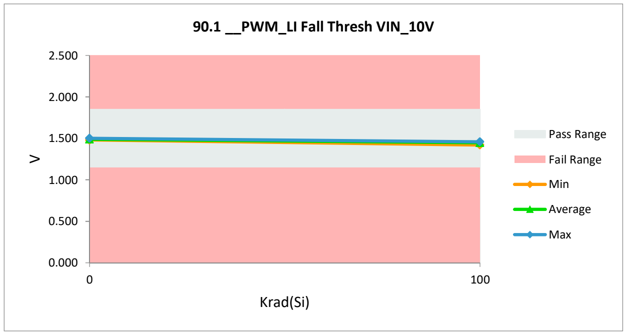


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		90.1 __PWM_LI Fall Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.500	0.000
100	23	1.500	1.460	-0.040
100	24	1.500	1.460	-0.040
100	25	1.500	1.460	-0.040
100	26	1.480	1.460	-0.020
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.480	1.440	-0.040
100	52u	1.500	1.420	-0.080
	Max	1.500	1.500	0.000
	Average	1.497	1.455	-0.042
	Min	1.480	1.420	-0.080
	Std Dev	0.008	0.021	0.022

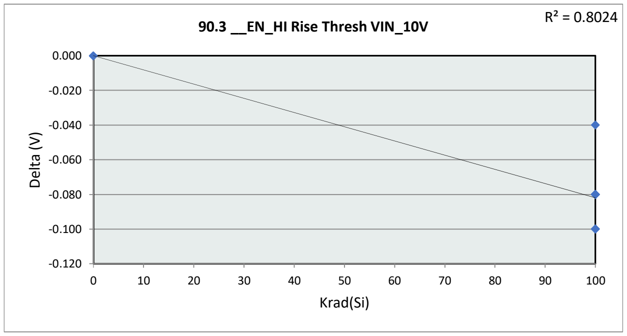


	90.1 __PWM_LI Fall Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.420
Average	1.490	1.448
Max	1.500	1.460
UL	1.850	1.850

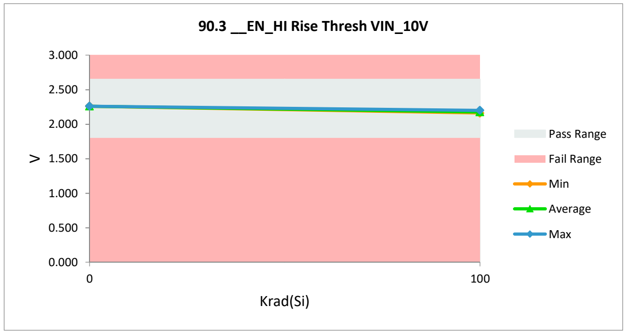


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		90.3 __EN_HI Rise Thresh VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.65	2.65	
	Min Limit	1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.160	-0.100
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.280	2.260	0.000
	Average	2.258	2.190	-0.068
	Min	2.240	2.160	-0.100
	Std Dev	0.010	0.035	0.036

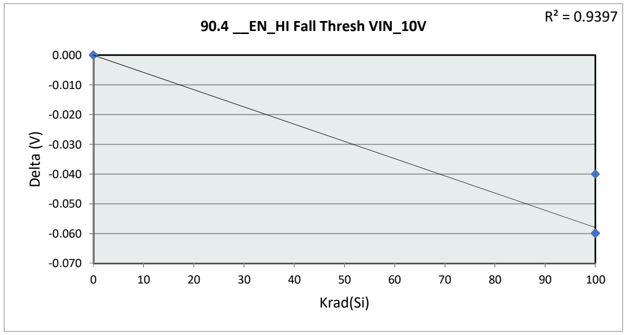


90.3 __EN_HI Rise Thresh VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.176
Max	2.260	2.200
UL	2.650	2.650

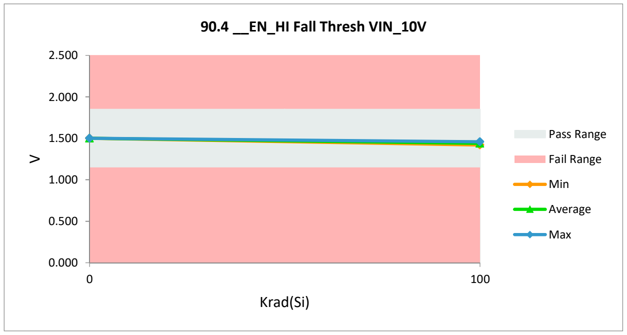


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		90.4 __EN_HI Fall Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.500	0.000
0	2	1.500	1.500	0.000
100	23	1.500	1.440	-0.060
100	24	1.500	1.440	-0.060
100	25	1.500	1.440	-0.060
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.480	1.420	-0.060
	Max	1.500	1.500	0.000
	Average	1.498	1.450	-0.048
	Min	1.480	1.420	-0.060
	Std Dev	0.006	0.025	0.023



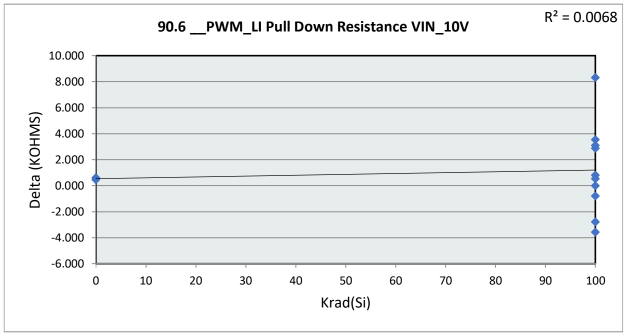
	90.4 __EN_HI Fall Thresh VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.500	1.420
Average	1.500	1.440
Max	1.500	1.460
UL	1.850	1.850



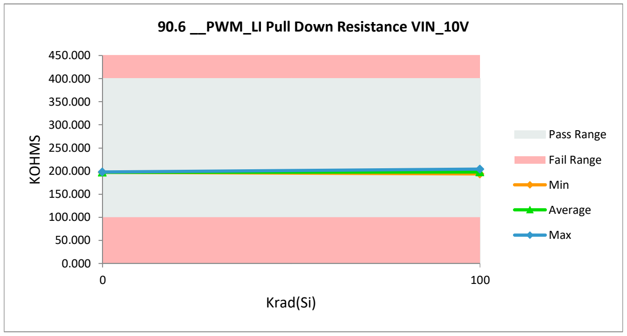
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	90.6 __PWM_LI Pull Down Resis	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit	KOHMS	KOHMS
Max Limit	400	400
Min Limit	100	100

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	197.680	198.146	0.465
0	2	196.427	197.043	0.616
100	23	196.178	204.493	8.315
100	24	193.983	196.865	2.882
100	25	196.510	193.739	-2.771
100	26	195.693	195.698	0.005
100	27	198.073	201.168	3.095
100	48u	201.100	201.630	0.530
100	49u	198.697	195.124	-3.573
100	50u	195.764	199.314	3.549
100	51u	196.685	195.907	-0.778
100	52u	195.240	196.045	0.805
	Max	201.100	204.493	8.315
	Average	196.836	197.931	1.095
	Min	193.983	193.739	-3.573
	Std Dev	1.853	3.151	3.130

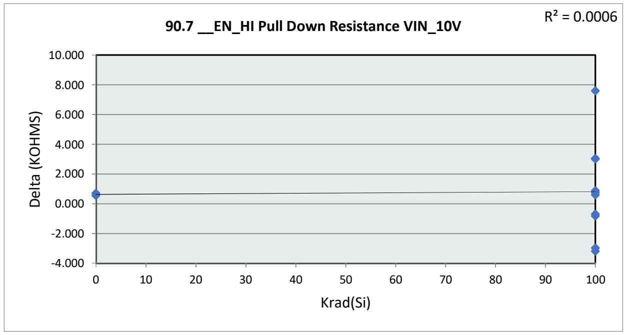


	90.6 __PWM_LI Pull Down Resistance VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	197.043	193.739
Average	197.594	197.998
Max	198.146	204.493
UL	400.000	400.000

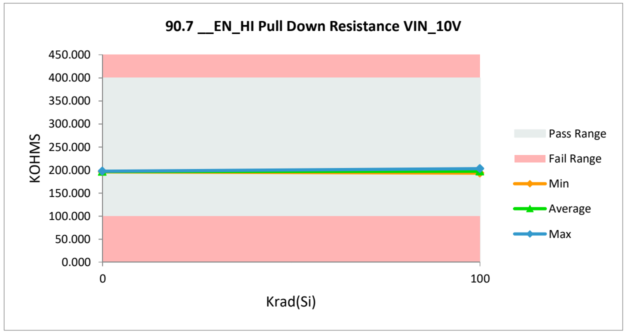


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		90.7 __EN_HI Pull Down Resista		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	KOHMS	KOHMS	
	Max Limit	400	400	
	Min Limit	100	100	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	196.734	197.292	0.558
0	2	195.529	196.237	0.708
100	23	195.550	203.138	7.587
100	24	193.495	196.491	2.996
100	25	195.996	193.008	-2.988
100	26	195.063	194.232	-0.831
100	27	199.004	199.743	0.740
100	48u	199.724	200.314	0.589
100	49u	197.805	194.606	-3.199
100	50u	195.148	198.195	3.047
100	51u	195.576	194.881	-0.695
100	52u	194.675	195.554	0.880
	Max	199.724	203.138	7.587
	Average	196.192	196.974	0.783
	Min	193.495	193.008	-3.199
	Std Dev	1.821	2.930	2.881

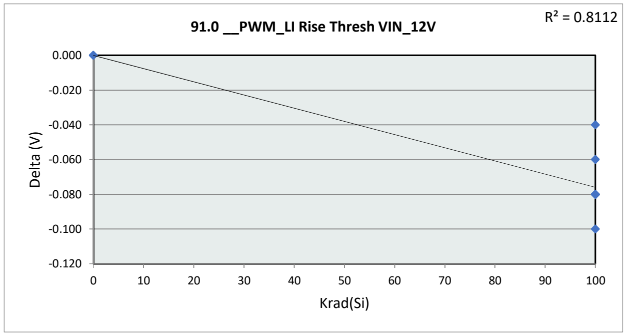


	90.7 __EN_HI Pull Down Resistance VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	196.237	193.009
Average	196.764	197.016
Max	197.292	203.138
UL	400.000	400.000

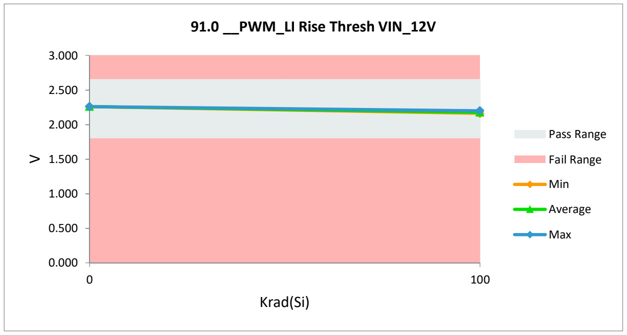


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		91.0 __PWM_LI Rise Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.65	2.65	
	Min Limit	1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.240	2.180	-0.060
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.260	2.180	-0.080
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.260	2.260	0.000
	Average	2.255	2.192	-0.063
	Min	2.240	2.160	-0.100
	Std Dev	0.009	0.034	0.033

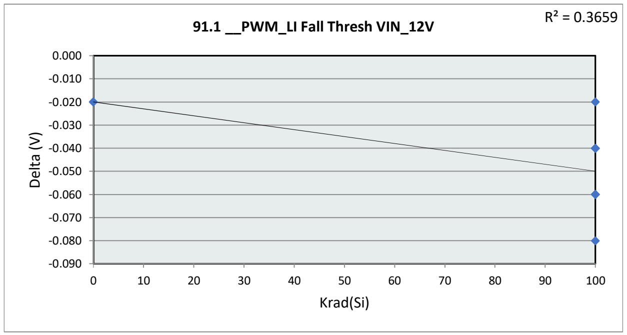


	91.0 __PWM_LI Rise Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.178
Max	2.260	2.200
UL	2.650	2.650

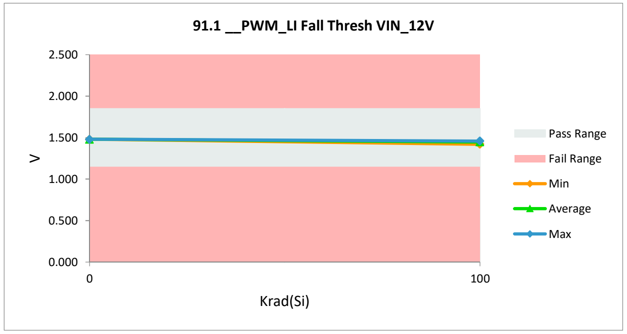


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		91.1 __PWM_LI Fall Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	1.85	1.85	
	Min Limit	1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.480	-0.020
100	23	1.500	1.460	-0.040
100	24	1.500	1.460	-0.040
100	25	1.500	1.460	-0.040
100	26	1.480	1.460	-0.020
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.500	1.420	-0.080
	Max	1.500	1.480	-0.020
	Average	1.498	1.453	-0.045
	Min	1.480	1.420	-0.080
	Std Dev	0.006	0.018	0.019

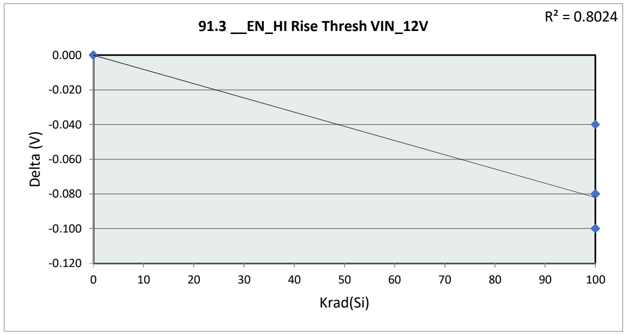


	91.1 __PWM_LI Fall Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.420
Average	1.480	1.448
Max	1.480	1.460
UL	1.850	1.850

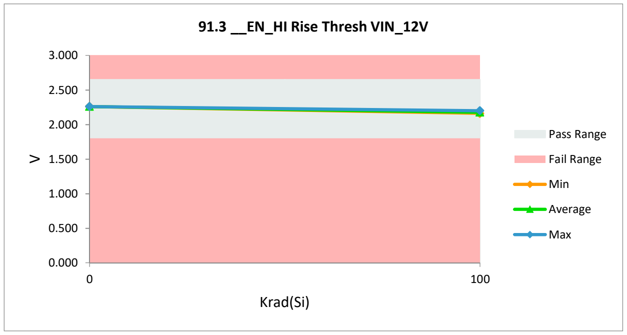


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		91.3 __EN_HI Rise Thresh VIN_		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.160	-0.100
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.280	2.260	0.000
	Average	2.258	2.190	-0.068
	Min	2.240	2.160	-0.100
	Std Dev	0.010	0.035	0.036

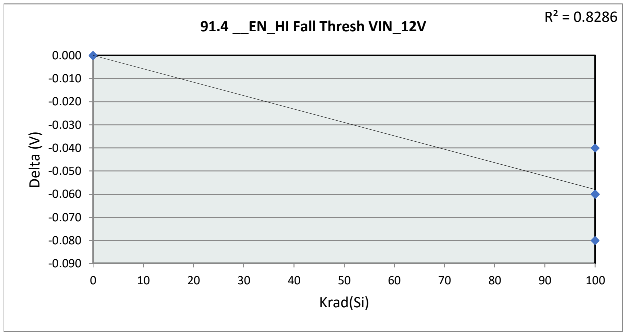


	91.3 __EN_HI Rise Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.176
Max	2.260	2.200
UL	2.650	2.650

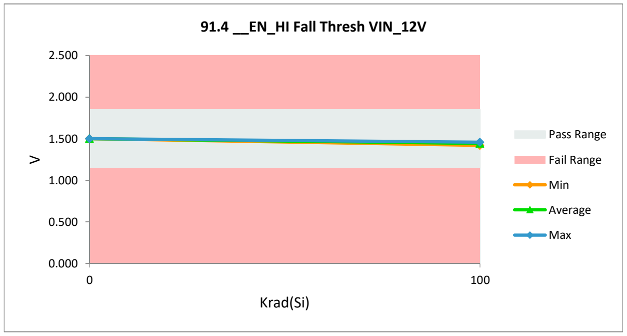


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		91.4 __EN_HI Fall Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.500	0.000
0	2	1.500	1.500	0.000
100	23	1.500	1.440	-0.060
100	24	1.500	1.460	-0.040
100	25	1.500	1.440	-0.060
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.500	1.420	-0.080
	Max	1.500	1.500	0.000
	Average	1.500	1.452	-0.048
	Min	1.500	1.420	-0.080
	Std Dev	0.000	0.025	0.025

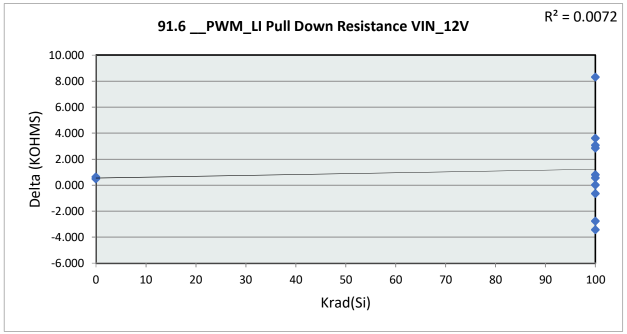


	91.4 __EN_HI Fall Thresh VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.500	1.420
Average	1.500	1.442
Max	1.500	1.460
UL	1.850	1.850

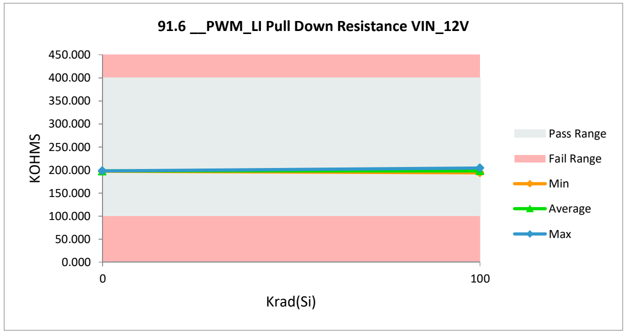


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		91.6 __PWM_LI Pull Down Resis		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		400	400	
Min Limit		100	100	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	197.728	198.216	0.487
0	2	196.484	197.104	0.620
100	23	196.249	204.553	8.304
100	24	194.040	196.886	2.846
100	25	196.566	193.794	-2.771
100	26	195.767	195.765	-0.002
100	27	198.150	201.200	3.051
100	48u	201.151	201.695	0.544
100	49u	198.754	195.317	-3.437
100	50u	195.819	199.425	3.605
100	51u	196.746	196.088	-0.657
100	52u	195.305	196.105	0.800
	Max	201.151	204.553	8.304
	Average	196.897	198.012	1.116
	Min	194.040	193.794	-3.437
	Std Dev	1.850	3.135	3.103



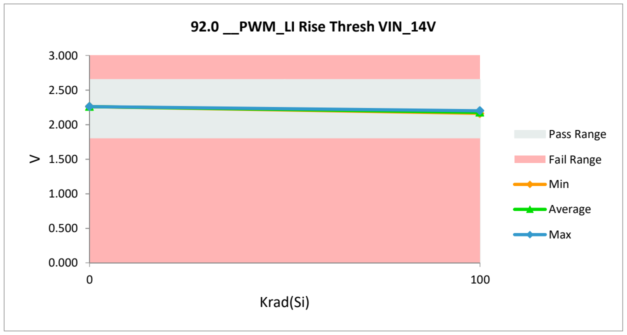
	91.6 __PWM_LI Pull Down Resistance VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	197.104	193.795
Average	197.660	198.083
Max	198.216	204.553
UL	400.000	400.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

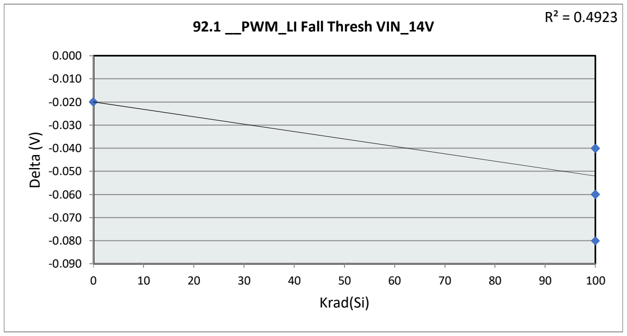
		92.0 __PWM_LI Rise Thresh VIN		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.65	2.65	
Min Limit		1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.180	-0.080
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.260	2.180	-0.080
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.280	2.260	0.000
	Average	2.258	2.192	-0.067
	Min	2.240	2.160	-0.100
	Std Dev	0.010	0.034	0.034

	92.0 __PWM_LI Rise Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.178
Max	2.260	2.200
UL	2.650	2.650

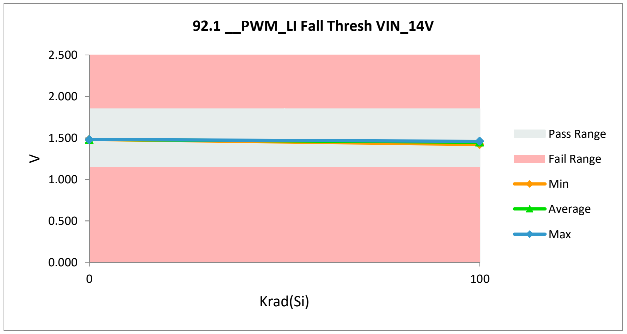


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		92.1 __PWM_LI Fall Thresh VIN		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	1.85	1.85	
	Min Limit	1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.480	-0.020
100	23	1.500	1.460	-0.040
100	24	1.500	1.460	-0.040
100	25	1.500	1.460	-0.040
100	26	1.500	1.460	-0.040
100	27	1.500	1.460	-0.040
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.500	1.420	-0.080
	Max	1.500	1.480	-0.020
	Average	1.500	1.453	-0.047
	Min	1.500	1.420	-0.080
	Std Dev	0.000	0.018	0.018

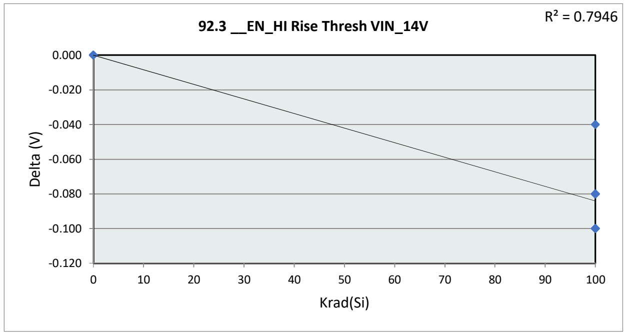


	92.1 __PWM_LI Fall Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.420
Average	1.480	1.448
Max	1.480	1.460
UL	1.850	1.850

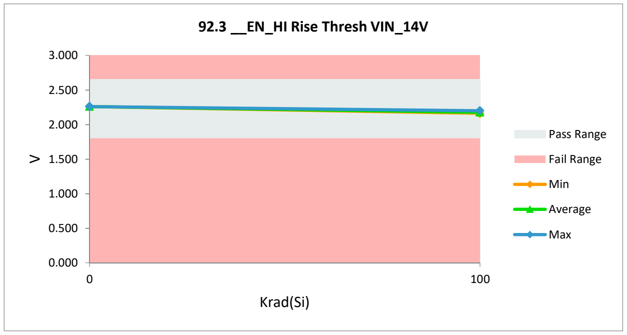


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		92.3 __EN_HI Rise Thresh VIN_		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.65	2.65	
	Min Limit	1.8	1.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.260	2.260	0.000
0	2	2.260	2.260	0.000
100	23	2.260	2.160	-0.100
100	24	2.260	2.180	-0.080
100	25	2.260	2.180	-0.080
100	26	2.240	2.200	-0.040
100	27	2.260	2.180	-0.080
100	48u	2.260	2.160	-0.100
100	49u	2.280	2.180	-0.100
100	50u	2.280	2.180	-0.100
100	51u	2.260	2.180	-0.080
100	52u	2.240	2.160	-0.080
	Max	2.280	2.260	0.000
	Average	2.260	2.190	-0.070
	Min	2.240	2.160	-0.100
	Std Dev	0.012	0.035	0.037

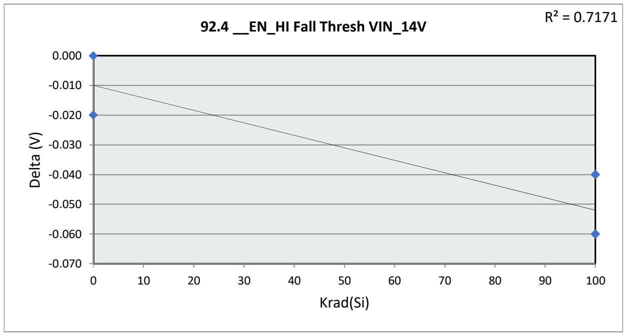


	92.3 __EN_HI Rise Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.65	V
Min Limit	1.8	V
Krad(Si)	0	100
LL	1.800	1.800
Min	2.260	2.160
Average	2.260	2.176
Max	2.260	2.200
UL	2.650	2.650

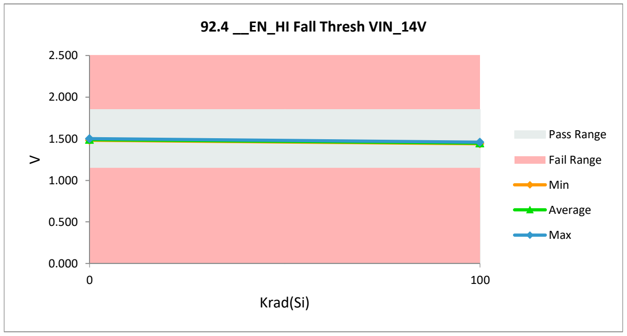


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		92.4 __EN_HI Fall Thresh VIN_1		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		1.85	1.85	
Min Limit		1.15	1.15	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.500	1.480	-0.020
0	2	1.500	1.500	0.000
100	23	1.500	1.460	-0.040
100	24	1.500	1.460	-0.040
100	25	1.500	1.440	-0.060
100	26	1.500	1.460	-0.040
100	27	1.500	1.440	-0.060
100	48u	1.500	1.440	-0.060
100	49u	1.500	1.440	-0.060
100	50u	1.500	1.440	-0.060
100	51u	1.500	1.440	-0.060
100	52u	1.480	1.440	-0.040
	Max	1.500	1.500	0.000
	Average	1.498	1.453	-0.045
	Min	1.480	1.440	-0.060
	Std Dev	0.006	0.020	0.019

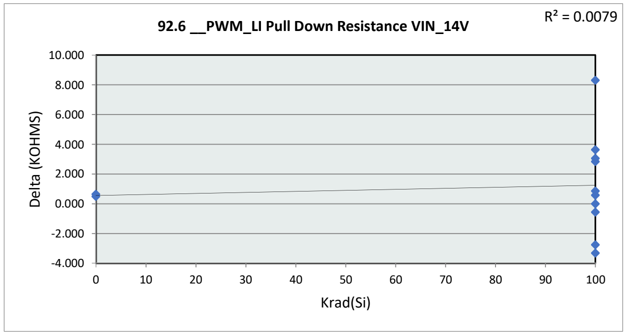


	92.4 __EN_HI Fall Thresh VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.85	V
Min Limit	1.15	V
Krad(Si)	0	100
LL	1.150	1.150
Min	1.480	1.440
Average	1.490	1.446
Max	1.500	1.460
UL	1.850	1.850

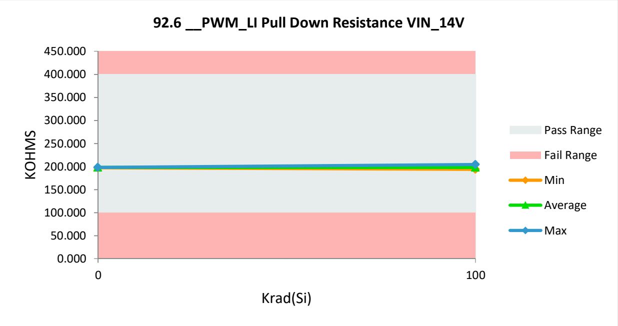


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		92.6 __PWM_LI Pull Down Resis		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	KOHMS	KOHMS	
	Max Limit	400	400	
	Min Limit	100	100	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	197.791	198.265	0.474
0	2	196.529	197.158	0.629
100	23	196.275	204.584	8.309
100	24	194.077	196.906	2.829
100	25	196.617	193.849	-2.768
100	26	195.816	195.801	-0.014
100	27	198.177	201.222	3.045
100	48u	201.196	201.766	0.570
100	49u	198.808	195.476	-3.332
100	50u	195.876	199.505	3.629
100	51u	196.810	196.242	-0.568
100	52u	195.329	196.184	0.855
	Max	201.196	204.584	8.309
	Average	196.942	198.080	1.138
	Min	194.077	193.849	-3.332
	Std Dev	1.853	3.117	3.085

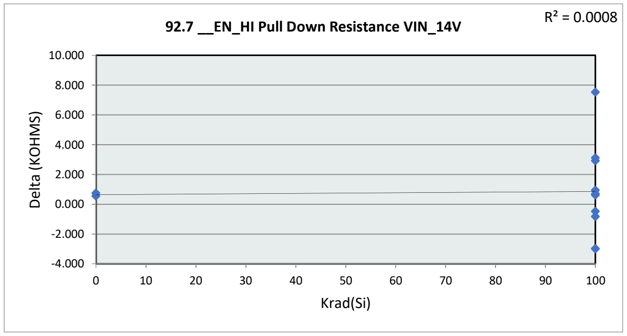


	92.6 __PWM_LI Pull Down Resistance VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	197.158	193.849
Average	197.712	198.154
Max	198.265	204.584
UL	400.000	400.000

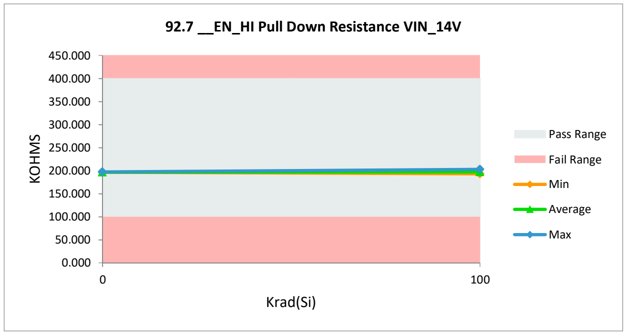


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		92.7 __EN_HI Pull Down Resista		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		400	400	
Min Limit		100	100	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	196.848	197.400	0.551
0	2	195.619	196.360	0.741
100	23	195.651	203.184	7.533
100	24	193.620	196.547	2.927
100	25	196.121	193.125	-2.996
100	26	195.178	194.359	-0.819
100	27	199.107	199.804	0.698
100	48u	199.809	200.418	0.609
100	49u	197.936	194.950	-2.986
100	50u	195.268	198.389	3.121
100	51u	195.684	195.198	-0.486
100	52u	194.768	195.704	0.937
	Max	199.809	203.184	7.533
	Average	196.301	197.120	0.819
	Min	193.620	193.125	-2.996
	Std Dev	1.817	2.883	2.835

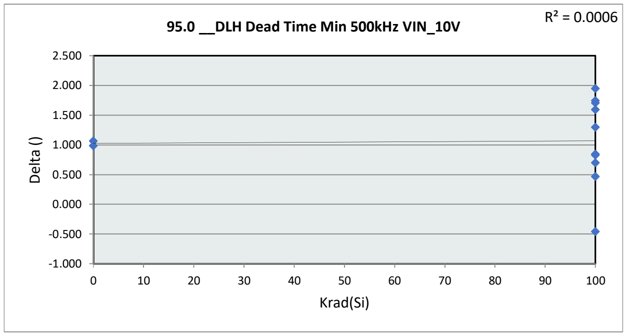


	92.7 __EN_HI Pull Down Resistance VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	400	KOHMS
Min Limit	100	KOHMS
Krad(Si)	0	100
LL	100.000	100.000
Min	196.360	193.125
Average	196.880	197.168
Max	197.400	203.185
UL	400.000	400.000

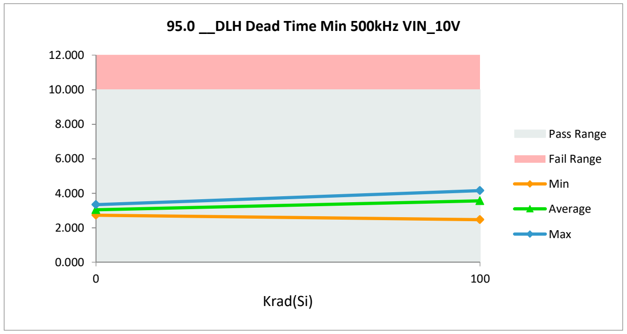


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.0 __DLH Dead Time Min 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.356	3.341	0.985
0	2	1.668	2.734	1.065
100	23	2.944	3.772	0.828
100	24	3.407	2.947	-0.460
100	25	2.452	4.046	1.593
100	26	1.992	2.460	0.467
100	27	2.542	3.388	0.845
100	48u	2.411	4.156	1.745
100	49u	2.358	4.064	1.706
100	50u	2.349	3.051	0.702
100	51u	2.504	3.800	1.296
100	52u	1.902	3.853	1.951
	Max	3.407	4.156	1.951
	Average	2.407	3.468	1.060
	Min	1.668	2.460	-0.460
	Std Dev	0.457	0.567	0.668

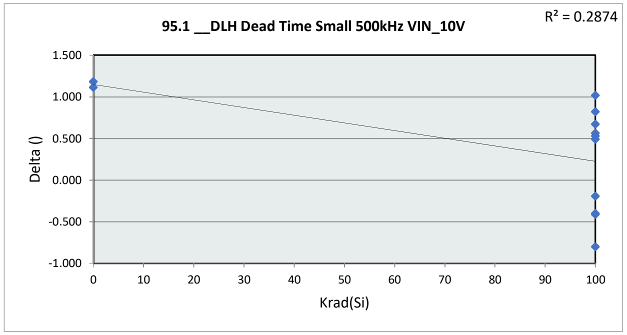


	95.0 __DLH Dead Time Min 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.734	2.460
Average	3.038	3.554
Max	3.341	4.156
UL	10.000	10.000

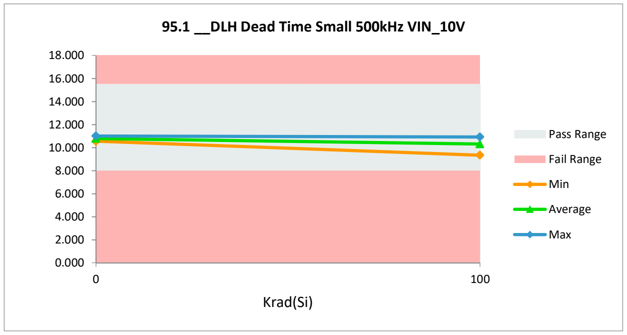


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.1 __DLH Dead Time Small 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.813	10.995	1.182
0	2	9.433	10.545	1.112
100	23	10.075	10.565	0.489
100	24	10.578	9.774	-0.805
100	25	10.104	10.925	0.821
100	26	9.740	9.324	-0.416
100	27	10.381	10.187	-0.194
100	48u	10.106	10.666	0.561
100	49u	10.099	10.771	0.671
100	50u	10.016	9.611	-0.405
100	51u	10.014	10.543	0.529
100	52u	9.738	10.753	1.015
	Max	10.578	10.995	1.182
	Average	10.008	10.388	0.380
	Min	9.433	9.324	-0.805
	Std Dev	0.303	0.543	0.668

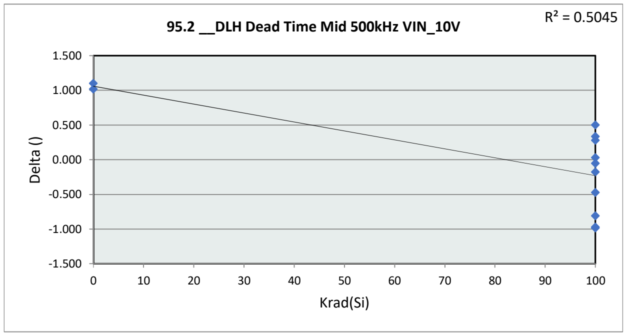


	95.1 __DLH Dead Time Small 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.545	9.324
Average	10.770	10.312
Max	10.995	10.925
UL	15.500	15.500

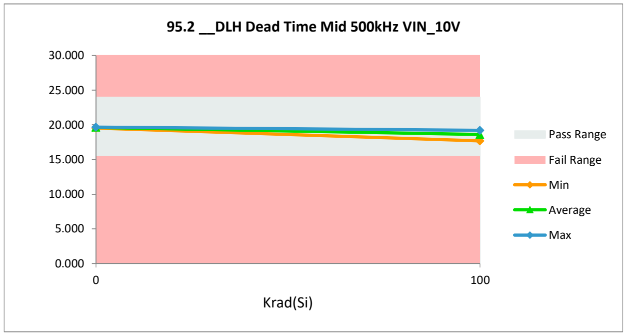


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.2 __DLH Dead Time Mid 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.581	19.682	1.101
0	2	18.521	19.539	1.018
100	23	18.282	18.782	0.500
100	24	18.861	17.889	-0.973
100	25	19.112	19.059	-0.052
100	26	18.662	17.678	-0.984
100	27	19.136	18.666	-0.471
100	48u	18.721	18.753	0.032
100	49u	18.734	19.071	0.336
100	50u	18.695	17.888	-0.807
100	51u	19.063	18.887	-0.176
100	52u	18.913	19.192	0.279
	Max	19.136	19.682	1.101
	Average	18.773	18.757	-0.016
	Min	18.282	17.678	-0.984
	Std Dev	0.256	0.643	0.708

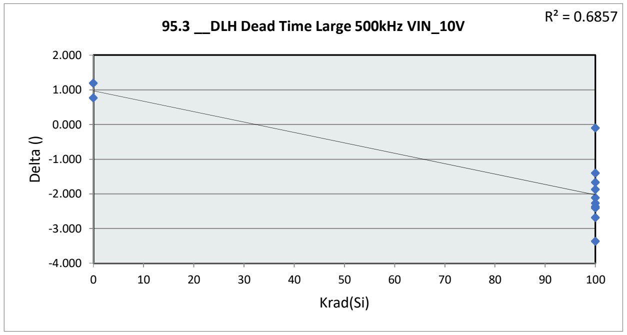


	95.2 __DLH Dead Time Mid 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.540	17.678
Average	19.611	18.586
Max	19.682	19.192
UL	24.000	24.000

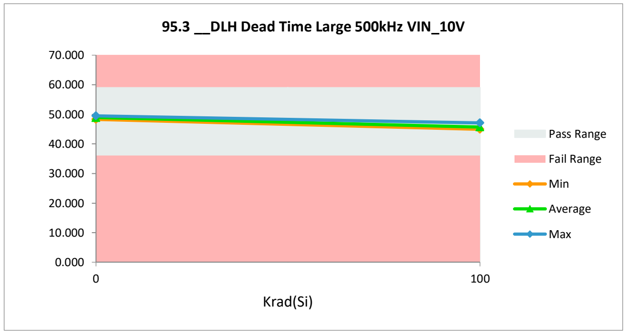


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.3 __DLH Dead Time Large 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	47.520	48.281	0.760
0	2	48.312	49.497	1.185
100	23	45.560	45.453	-0.107
100	24	46.424	45.017	-1.407
100	25	48.523	46.116	-2.407
100	26	48.461	45.091	-3.370
100	27	48.294	45.923	-2.371
100	48u	47.391	45.121	-2.270
100	49u	47.605	45.728	-1.877
100	50u	47.677	44.988	-2.689
100	51u	48.352	46.242	-2.111
100	52u	48.730	47.056	-1.674
	Max	48.730	49.497	1.185
	Average	47.737	46.209	-1.528
	Min	45.560	44.988	-3.370
	Std Dev	0.944	1.416	1.411

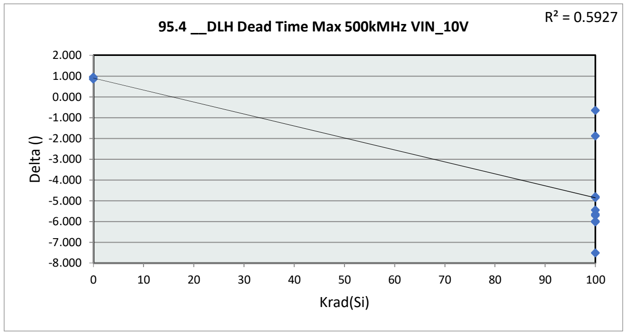


	95.3 __DLH Dead Time Large 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.281	44.988
Average	48.889	45.674
Max	49.497	47.056
UL	59.000	59.000

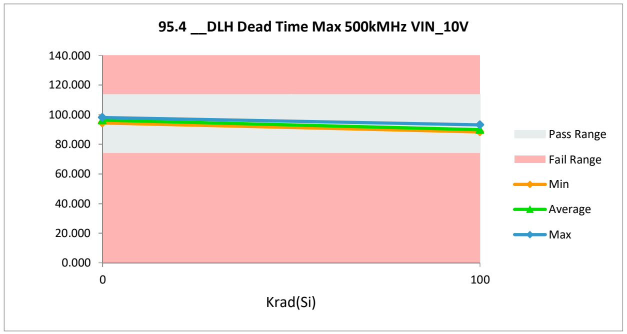


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.4 __DLH Dead Time Max 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	93.582	94.429	0.847
0	2	97.197	98.141	0.943
100	23	89.442	88.780	-0.662
100	24	91.022	89.138	-1.884
100	25	96.344	90.314	-6.030
100	26	96.950	89.430	-7.520
100	27	95.330	90.468	-4.862
100	48u	94.143	88.423	-5.720
100	49u	94.795	88.802	-5.994
100	50u	94.306	88.646	-5.660
100	51u	96.298	90.844	-5.454
100	52u	97.949	93.131	-4.817
	Max	97.949	98.141	0.943
	Average	94.780	90.879	-3.901
	Min	89.442	88.423	-7.520
	Std Dev	2.528	2.951	2.910

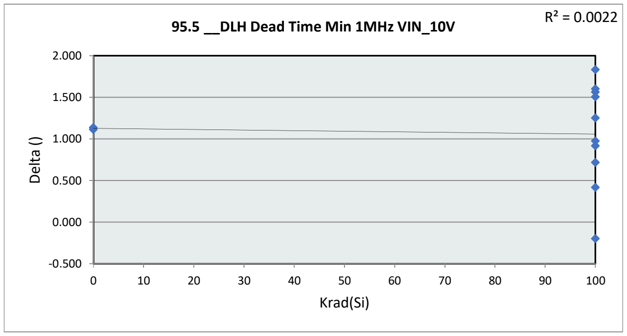


	95.4 __DLH Dead Time Max 500kMHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.429	88.423
Average	96.285	89.798
Max	98.141	93.131
UL	113.500	113.500

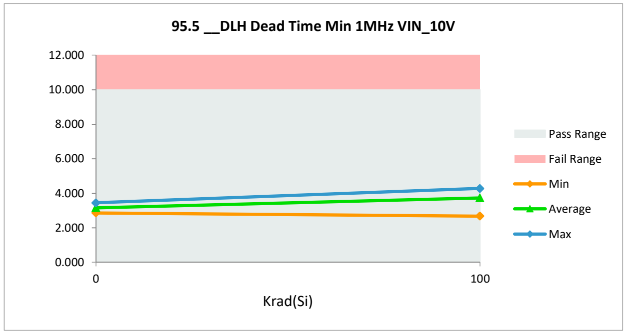


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.5 __DLH Dead Time Min 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.300	3.438	1.139
0	2	1.736	2.851	1.116
100	23	2.994	3.969	0.975
100	24	3.457	3.258	-0.198
100	25	2.649	4.251	1.602
100	26	2.253	2.670	0.417
100	27	2.804	3.721	0.917
100	48u	2.691	4.199	1.508
100	49u	2.709	4.272	1.563
100	50u	2.527	3.243	0.716
100	51u	2.525	3.778	1.253
100	52u	2.141	3.975	1.834
	Max	3.457	4.272	1.834
	Average	2.565	3.636	1.070
	Min	1.736	2.670	-0.198
	Std Dev	0.439	0.542	0.567

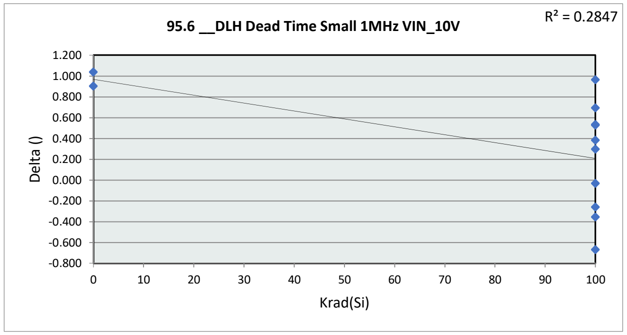


	95.5 __DLH Dead Time Min 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.851	2.670
Average	3.145	3.734
Max	3.439	4.272
UL	10.000	10.000

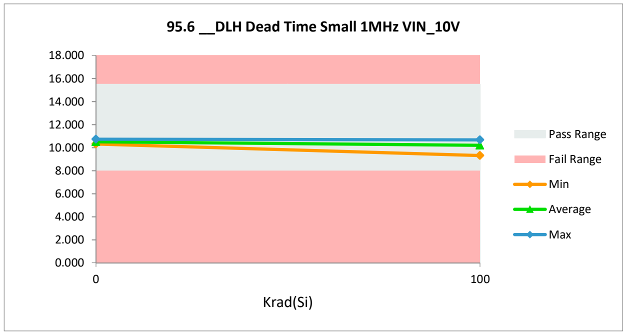


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.6 __DLH Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.691	10.728	1.037
0	2	9.401	10.301	0.900
100	23	10.034	10.331	0.297
100	24	10.283	9.613	-0.671
100	25	10.114	10.646	0.531
100	26	9.561	9.300	-0.261
100	27	10.273	10.241	-0.033
100	48u	10.034	10.561	0.527
100	49u	9.964	10.657	0.693
100	50u	9.956	9.599	-0.357
100	51u	9.898	10.279	0.381
100	52u	9.716	10.680	0.964
	Max	10.283	10.728	1.037
	Average	9.910	10.245	0.334
	Min	9.401	9.300	-0.671
	Std Dev	0.272	0.484	0.556

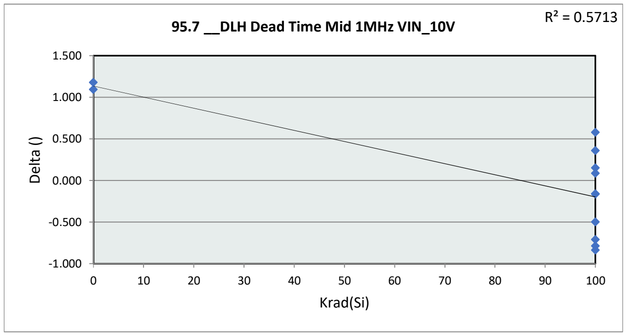


	95.6 __DLH Dead Time Small 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.301	9.300
Average	10.514	10.191
Max	10.728	10.680
UL	15.500	15.500

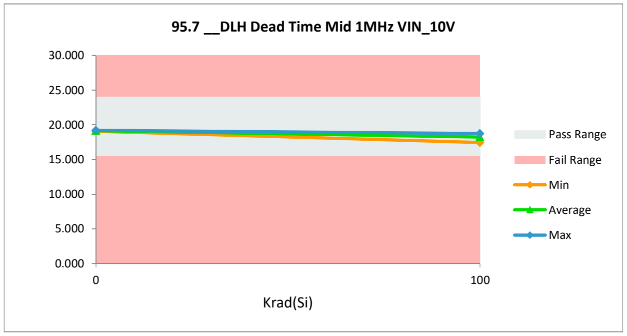


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.7 __DLH Dead Time Mid 1MHz		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.993	19.086	1.093
0	2	18.025	19.203	1.179
100	23	17.892	18.470	0.578
100	24	18.229	17.733	-0.497
100	25	18.618	18.769	0.151
100	26	18.220	17.435	-0.785
100	27	18.882	18.175	-0.707
100	48u	18.430	18.271	-0.159
100	49u	18.487	18.574	0.087
100	50u	18.443	17.606	-0.837
100	51u	18.565	18.403	-0.161
100	52u	18.396	18.755	0.359
	Max	18.882	19.203	1.179
	Average	18.348	18.373	0.025
	Min	17.892	17.435	-0.837
	Std Dev	0.288	0.562	0.687

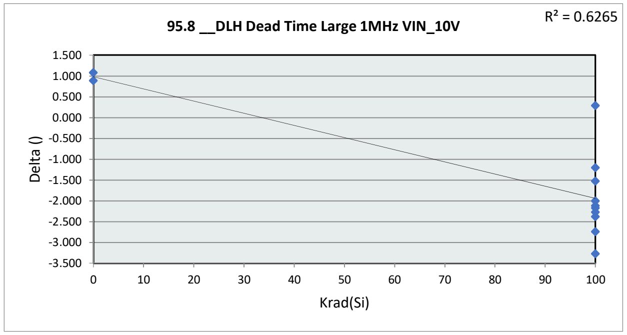


	95.7 __DLH Dead Time Mid 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.086	17.435
Average	19.145	18.219
Max	19.203	18.769
UL	24.000	24.000

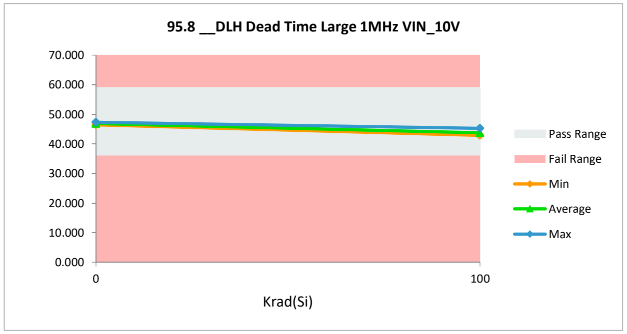


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.8 __DLH Dead Time Large 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.620	46.508	0.888
0	2	46.210	47.287	1.078
100	23	43.327	43.614	0.287
100	24	44.369	43.160	-1.209
100	25	46.471	44.350	-2.120
100	26	46.412	43.134	-3.278
100	27	46.374	43.994	-2.379
100	48u	45.489	43.211	-2.278
100	49u	45.688	43.683	-2.005
100	50u	45.648	42.907	-2.741
100	51u	46.301	44.125	-2.176
100	52u	46.796	45.265	-1.531
	Max	46.796	47.287	1.078
	Average	45.725	44.270	-1.455
	Min	43.327	42.907	-3.278
	Std Dev	0.992	1.397	1.439

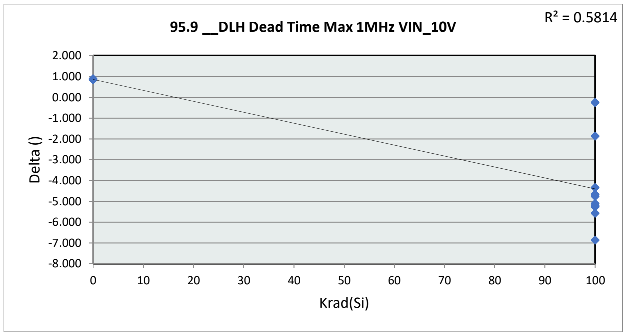


	95.8 __DLH Dead Time Large 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.508	42.907
Average	46.898	43.744
Max	47.287	45.265
UL	59.000	59.000

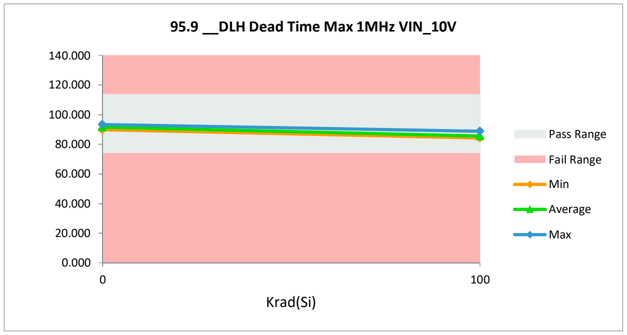


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.9 __DLH Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	89.098	89.934	0.836
0	2	92.386	93.268	0.882
100	23	84.904	84.643	-0.261
100	24	86.695	84.820	-1.875
100	25	91.745	86.157	-5.588
100	26	91.869	85.004	-6.866
100	27	90.618	85.948	-4.671
100	48u	89.444	84.318	-5.126
100	49u	89.915	84.637	-5.278
100	50u	89.598	84.377	-5.221
100	51u	91.497	86.734	-4.763
100	52u	93.076	88.728	-4.347
	Max	93.076	93.268	0.882
	Average	90.070	86.547	-3.523
	Min	84.904	84.318	-6.866
	Std Dev	2.382	2.768	2.684

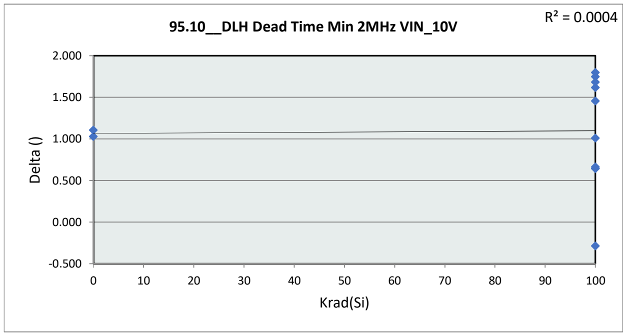


	95.9 __DLH Dead Time Max 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	89.934	84.318
Average	91.601	85.537
Max	93.268	88.728
UL	113.500	113.500

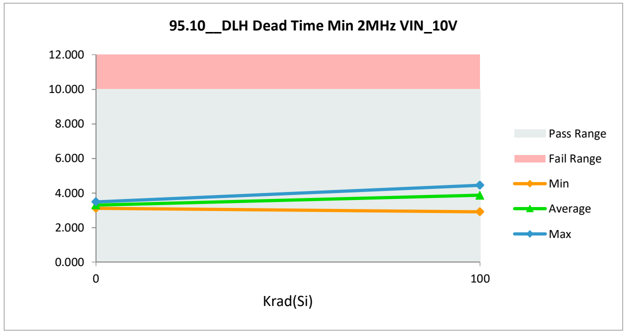


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.10__DLH Dead Time Min 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.383	3.489	1.106
0	2	2.085	3.113	1.028
100	23	3.265	3.909	0.644
100	24	3.609	3.323	-0.286
100	25	2.651	4.398	1.747
100	26	2.247	2.912	0.664
100	27	2.768	3.778	1.010
100	48u	2.821	4.440	1.619
100	49u	2.626	4.310	1.684
100	50u	2.646	3.289	0.643
100	51u	2.690	4.145	1.455
100	52u	2.342	4.141	1.799
	Max	3.609	4.440	1.799
	Average	2.678	3.771	1.093
	Min	2.085	2.912	-0.286
	Std Dev	0.424	0.532	0.617

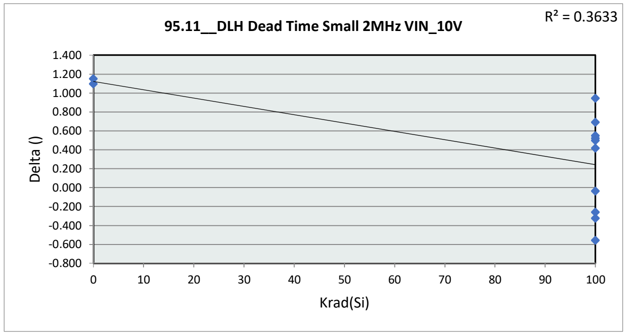


	95.10__DLH Dead Time Min 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.113	2.912
Average	3.301	3.865
Max	3.489	4.440
UL	10.000	10.000

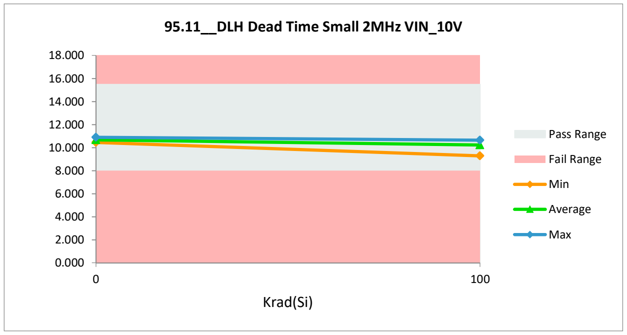


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.11__DLH Dead Time Small 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.753	10.903	1.150
0	2	9.357	10.452	1.095
100	23	9.948	10.445	0.496
100	24	10.340	9.781	-0.559
100	25	10.114	10.635	0.520
100	26	9.532	9.270	-0.263
100	27	10.316	10.278	-0.038
100	48u	9.934	10.623	0.689
100	49u	10.056	10.605	0.549
100	50u	9.981	9.655	-0.326
100	51u	9.951	10.367	0.416
100	52u	9.681	10.625	0.945
	Max	10.340	10.903	1.150
	Average	9.914	10.303	0.390
	Min	9.357	9.270	-0.559
	Std Dev	0.293	0.484	0.568

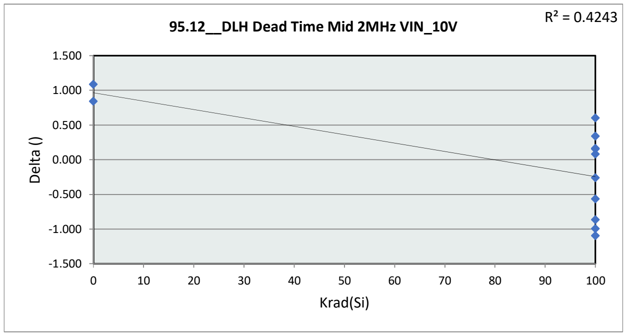


	95.11__DLH Dead Time Small 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.452	9.270
Average	10.677	10.228
Max	10.903	10.635
UL	15.500	15.500

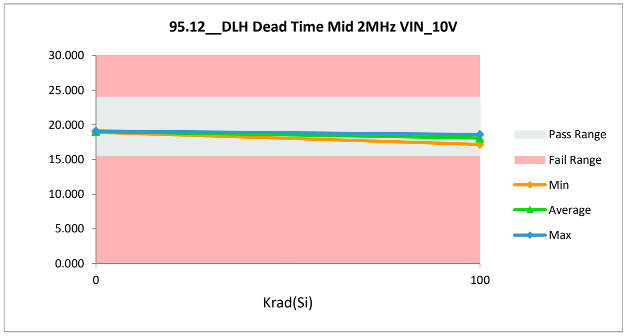


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.12__DLH Dead Time Mid 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.051	19.137	1.085
0	2	18.076	18.918	0.843
100	23	17.764	18.367	0.603
100	24	18.427	17.565	-0.863
100	25	18.427	18.507	0.080
100	26	18.269	17.174	-1.095
100	27	18.654	18.088	-0.566
100	48u	18.183	18.339	0.155
100	49u	18.307	18.473	0.166
100	50u	18.360	17.365	-0.995
100	51u	18.547	18.289	-0.258
100	52u	18.282	18.622	0.341
	Max	18.654	19.137	1.085
	Average	18.279	18.237	-0.042
	Min	17.764	17.174	-1.095
	Std Dev	0.240	0.599	0.721



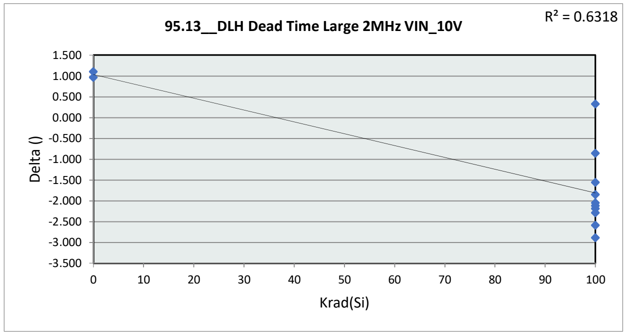
	95.12__DLH Dead Time Mid 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	18.918	17.174
Average	19.027	18.079
Max	19.137	18.622
UL	24.000	24.000



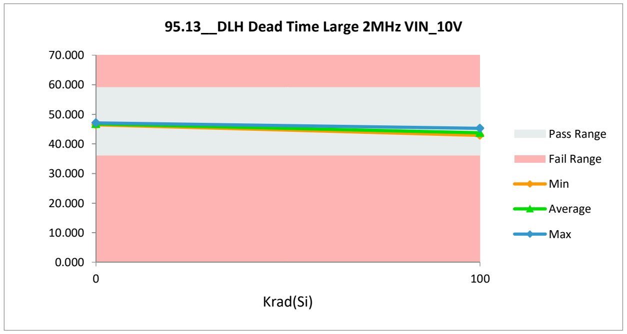
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	95.13__DLH Dead Time Large 2	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	59	59
Min Limit	36	36

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.322	46.426	1.104
0	2	46.138	47.100	0.962
100	23	43.381	43.705	0.324
100	24	44.106	43.247	-0.860
100	25	46.307	44.257	-2.050
100	26	46.175	43.285	-2.890
100	27	46.205	44.084	-2.121
100	48u	45.535	43.343	-2.192
100	49u	45.573	43.724	-1.849
100	50u	45.529	42.939	-2.590
100	51u	46.111	43.818	-2.294
100	52u	46.794	45.233	-1.561
	Max	46.794	47.100	1.104
	Average	45.598	44.263	-1.335
	Min	43.381	42.939	-2.890
	Std Dev	0.973	1.317	1.391

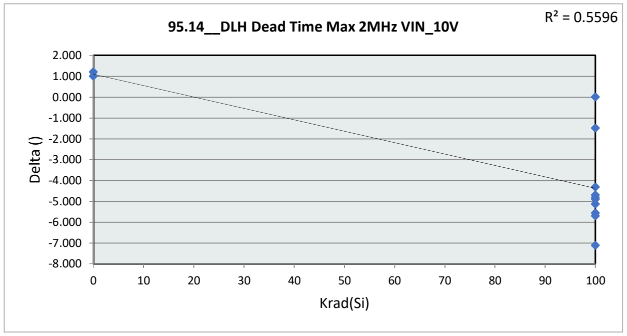


	95.13__DLH Dead Time Large 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.426	42.939
Average	46.763	43.763
Max	47.101	45.233
UL	59.000	59.000

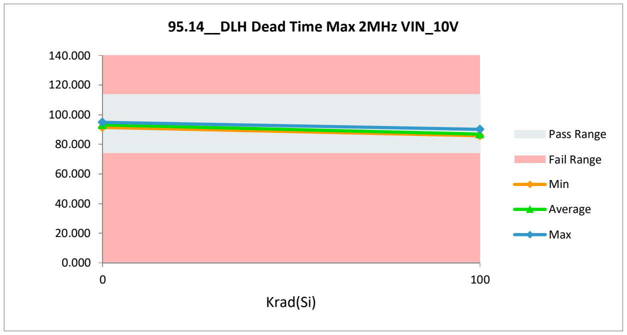


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.14__DLH Dead Time Max 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	90.349	91.354	1.005
0	2	93.761	94.963	1.203
100	23	85.967	85.971	0.004
100	24	87.640	86.150	-1.489
100	25	93.028	87.325	-5.703
100	26	93.347	86.229	-7.118
100	27	92.036	87.329	-4.707
100	48u	90.663	85.764	-4.898
100	49u	91.391	85.821	-5.570
100	50u	90.868	85.729	-5.139
100	51u	92.766	87.941	-4.825
100	52u	94.466	90.141	-4.326
	Max	94.466	94.963	1.203
	Average	91.357	87.893	-3.464
	Min	85.967	85.729	-7.118
	Std Dev	2.509	2.871	2.852

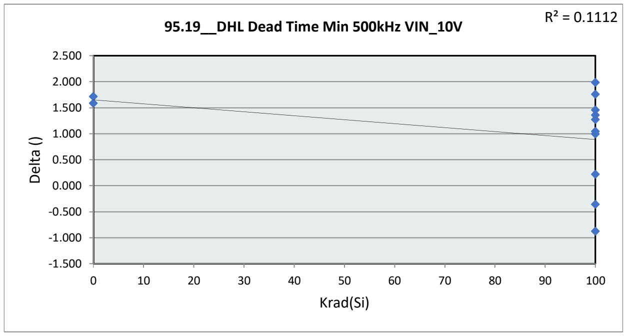


	95.14__DLH Dead Time Max 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.354	85.729
Average	93.159	86.840
Max	94.963	90.141
UL	113.500	113.500

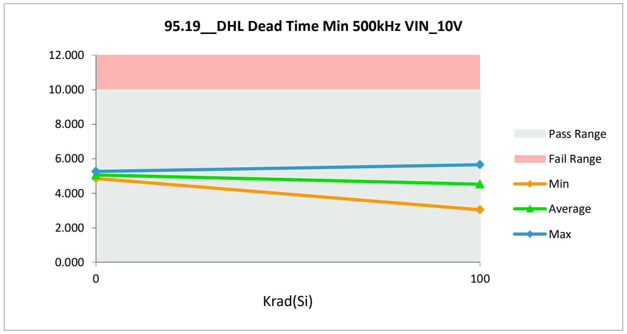


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.19__DHL Dead Time Min 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.257	4.847	1.590
0	2	3.540	5.253	1.713
100	23	3.126	5.111	1.986
100	24	3.059	4.107	1.048
100	25	3.806	4.800	0.994
100	26	3.914	3.040	-0.873
100	27	3.849	3.493	-0.357
100	48u	3.510	5.268	1.758
100	49u	3.569	4.925	1.356
100	50u	3.521	3.745	0.223
100	51u	3.602	5.057	1.455
100	52u	4.378	5.653	1.275
	Max	4.378	5.653	1.986
	Average	3.594	4.608	1.014
	Min	3.059	3.040	-0.873
	Std Dev	0.364	0.814	0.893

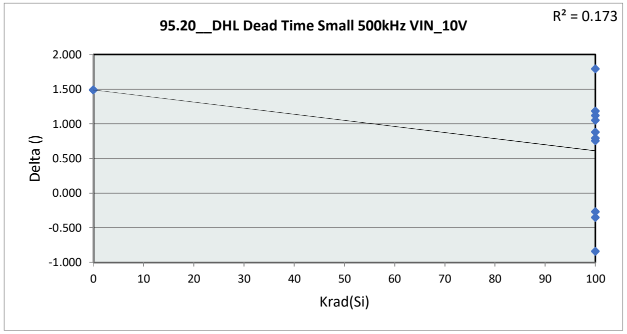


	95.19__DHL Dead Time Min 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.847	3.040
Average	5.050	4.520
Max	5.253	5.653
UL	10.000	10.000

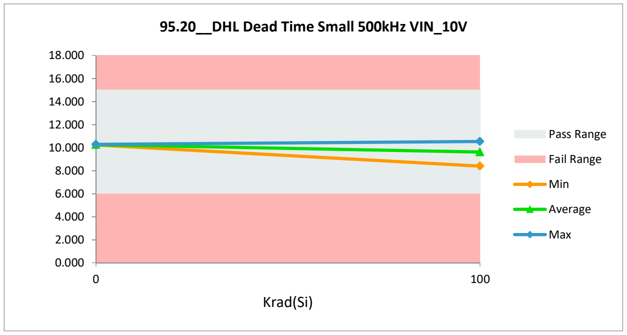


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.20__DHL Dead Time Small 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15	15	
	Min Limit	6	6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.726	10.214	1.488
0	2	8.780	10.269	1.490
100	23	8.547	10.341	1.794
100	24	8.409	9.288	0.879
100	25	9.300	10.057	0.757
100	26	9.233	8.390	-0.842
100	27	9.196	8.844	-0.351
100	48u	9.178	10.363	1.184
100	49u	8.939	9.732	0.793
100	50u	8.840	8.570	-0.269
100	51u	8.797	9.918	1.121
100	52u	9.469	10.520	1.051
	Max	9.469	10.520	1.794
	Average	8.951	9.709	0.758
	Min	8.409	8.390	-0.842
	Std Dev	0.324	0.750	0.820

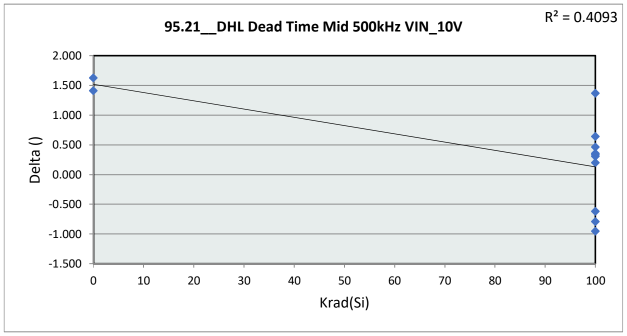


	95.20__DHL Dead Time Small 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.214	8.390
Average	10.242	9.602
Max	10.270	10.520
UL	15.000	15.000

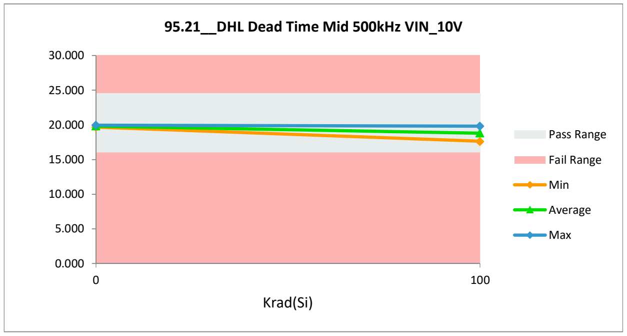


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
		95.21__DHL Dead Time Mid 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24.5	24.5	
	Min Limit	16	16	
0	1	18.306	19.933	1.627
0	2	18.280	19.688	1.409
100	23	18.200	19.568	1.367
100	24	18.044	18.399	0.354
100	25	18.973	19.172	0.199
100	26	18.571	17.617	-0.953
100	27	18.882	18.264	-0.618
100	48u	19.189	19.828	0.639
100	49u	18.348	18.681	0.333
100	50u	18.533	17.742	-0.792
100	51u	18.659	18.965	0.306
100	52u	19.091	19.553	0.462
	Max	19.189	19.933	1.627
	Average	18.590	18.951	0.361
	Min	18.044	17.617	-0.953
	Std Dev	0.374	0.807	0.845



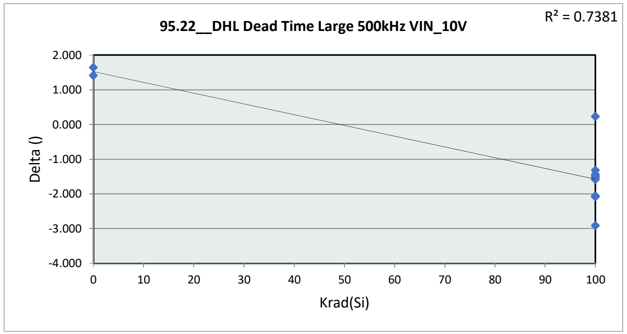
	95.21__DHL Dead Time Mid 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.689	17.617
Average	19.811	18.779
Max	19.933	19.828
UL	24.500	24.500



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

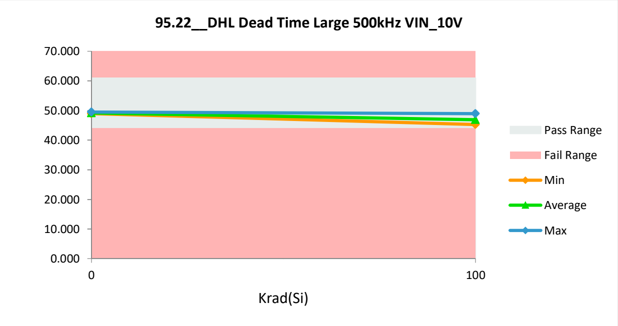
95.22__DHL Dead Time Large 50

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.050	49.461	1.411
0	2	47.298	48.934	1.637
100	23	48.180	48.409	0.229
100	24	48.099	46.508	-1.591
100	25	49.071	47.011	-2.061
100	26	47.816	45.730	-2.086
100	27	48.503	47.022	-1.480
100	48u	50.441	48.916	-1.524
100	49u	47.844	46.307	-1.537
100	50u	48.171	45.256	-2.916
100	51u	48.207	46.889	-1.318
100	52u	48.243	46.798	-1.445
	Max	50.441	49.461	1.637
	Average	48.327	47.270	-1.057
	Min	47.298	45.256	-2.916
	Std Dev	0.786	1.349	1.403



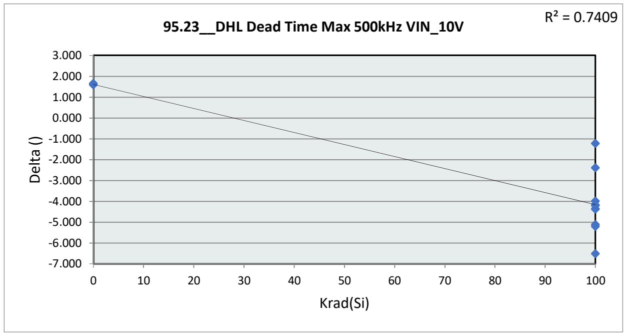
95.22__DHL Dead Time Large 500kHz VIN_10V

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.934	45.256
Average	49.198	46.885
Max	49.461	48.916
UL	61.000	61.000

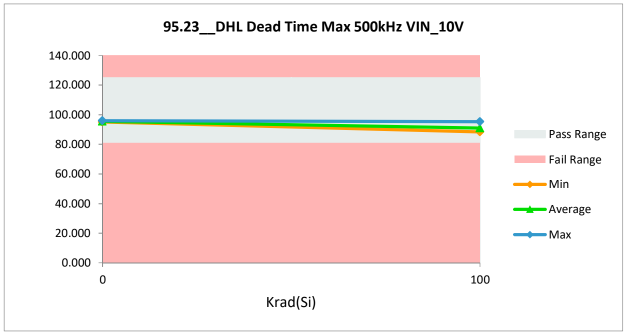


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.23__DHL Dead Time Max 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	94.307	95.892	1.584
0	2	93.453	95.093	1.640
100	23	94.902	93.676	-1.226
100	24	95.285	90.164	-5.120
100	25	96.200	90.986	-5.214
100	26	93.676	89.674	-4.002
100	27	95.024	92.624	-2.400
100	48u	99.722	95.354	-4.367
100	49u	94.009	89.791	-4.218
100	50u	94.888	88.365	-6.523
100	51u	94.724	90.538	-4.186
100	52u	93.978	89.600	-4.378
	Max	99.722	95.892	1.640
	Average	95.014	91.813	-3.201
	Min	93.453	88.365	-6.523
	Std Dev	1.667	2.603	2.612

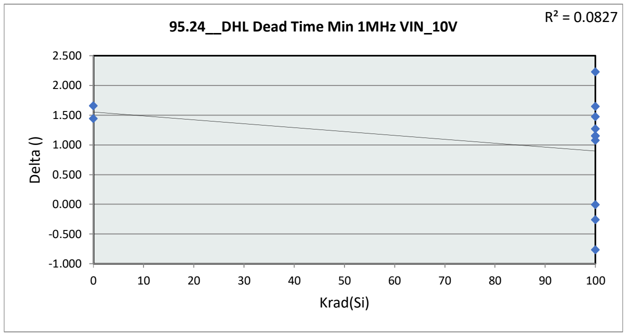


	95.23__DHL Dead Time Max 500kHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	95.093	88.365
Average	95.493	91.077
Max	95.892	95.354
UL	125.000	125.000

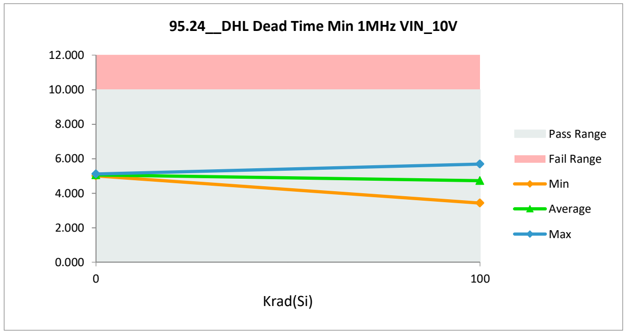


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.24__DHL Dead Time Min 1MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.351	5.009	1.658
0	2	3.678	5.122	1.444
100	23	3.167	5.396	2.229
100	24	3.356	4.507	1.151
100	25	3.954	5.104	1.151
100	26	4.186	3.424	-0.762
100	27	3.985	3.726	-0.259
100	48u	3.868	5.344	1.475
100	49u	3.736	4.811	1.076
100	50u	3.821	3.815	-0.006
100	51u	3.748	5.396	1.647
100	52u	4.424	5.693	1.268
	Max	4.424	5.693	2.229
	Average	3.773	4.779	1.006
	Min	3.167	3.424	-0.762
	Std Dev	0.358	0.747	0.885



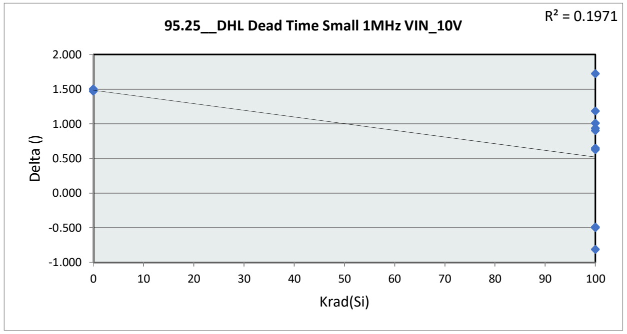
95.24__DHL Dead Time Min 1MHz VIN_10V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.009	3.424
Average	5.065	4.722
Max	5.122	5.693
UL	10.000	10.000



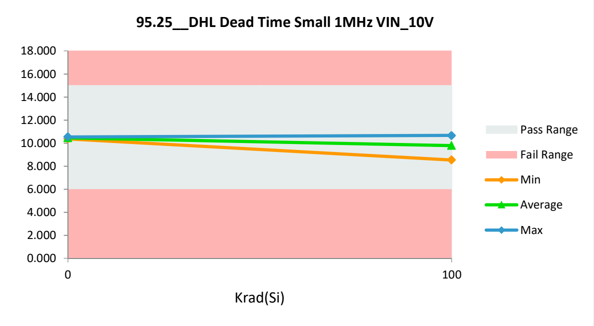
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	95.25__DHL Dead Time Small 1M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.883	10.352	1.469
0	2	9.016	10.519	1.504
100	23	8.744	10.468	1.724
100	24	8.741	9.389	0.648
100	25	9.502	10.125	0.623
100	26	9.337	8.521	-0.816
100	27	9.443	8.951	-0.492
100	48u	9.422	10.606	1.183
100	49u	9.071	10.007	0.936
100	50u	9.298	8.799	-0.499
100	51u	9.234	10.240	1.006
100	52u	9.754	10.656	0.902
	Max	9.754	10.656	1.724
	Average	9.204	9.886	0.682
	Min	8.741	8.521	-0.816
	Std Dev	0.317	0.765	0.846

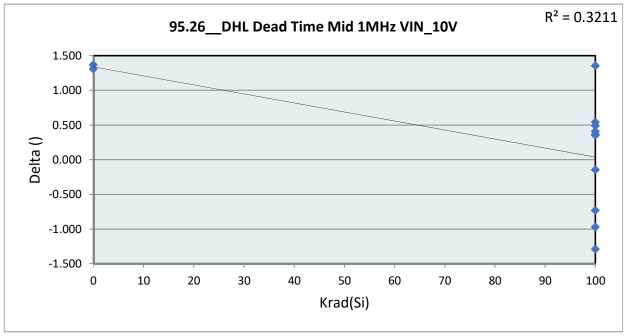


	95.25__DHL Dead Time Small 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.352	8.521
Average	10.436	9.776
Max	10.519	10.656
UL	15.000	15.000

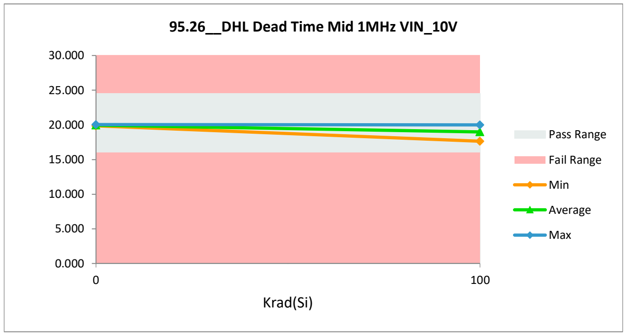


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.743	20.050	1.307
0	2	18.496	19.864	1.367
100	23	18.476	19.830	1.355
100	24	18.313	18.722	0.409
100	25	19.263	19.117	-0.146
100	26	18.945	17.658	-1.287
100	27	19.202	18.472	-0.730
100	48u	19.622	19.989	0.367
100	49u	18.613	18.968	0.355
100	50u	18.799	17.829	-0.970
100	51u	18.866	19.359	0.493
100	52u	19.167	19.711	0.544
	Max	19.622	20.050	1.367
	Average	18.875	19.131	0.255
	Min	18.313	17.658	-1.287
	Std Dev	0.383	0.825	0.892

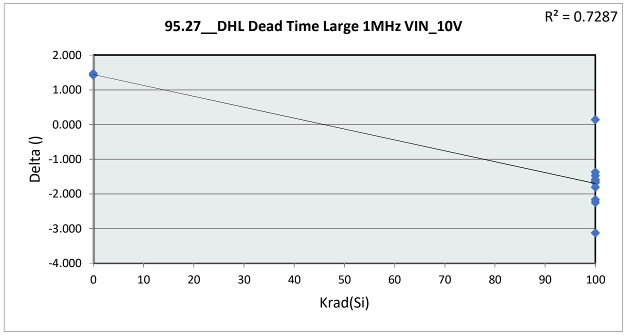


	95.26__DHL Dead Time Mid 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.864	17.658
Average	19.957	18.966
Max	20.050	19.989
UL	24.500	24.500

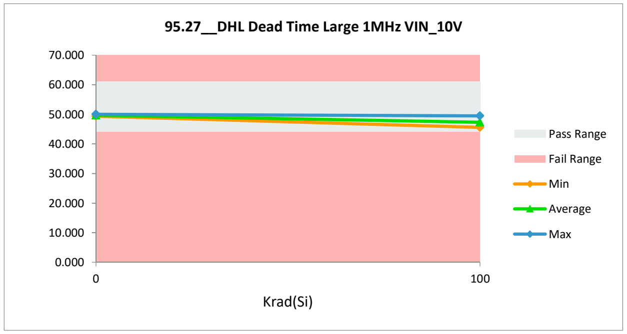


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.27__DHL Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.635	50.053	1.418
0	2	47.960	49.428	1.467
100	23	48.797	48.931	0.134
100	24	48.609	46.924	-1.685
100	25	49.563	47.308	-2.255
100	26	48.353	46.178	-2.175
100	27	48.998	47.620	-1.378
100	48u	51.033	49.443	-1.590
100	49u	48.411	46.778	-1.632
100	50u	48.724	45.593	-3.130
100	51u	48.811	47.002	-1.809
100	52u	48.767	47.293	-1.474
	Max	51.033	50.053	1.467
	Average	48.888	47.713	-1.176
	Min	47.960	45.593	-3.130
	Std Dev	0.777	1.417	1.433

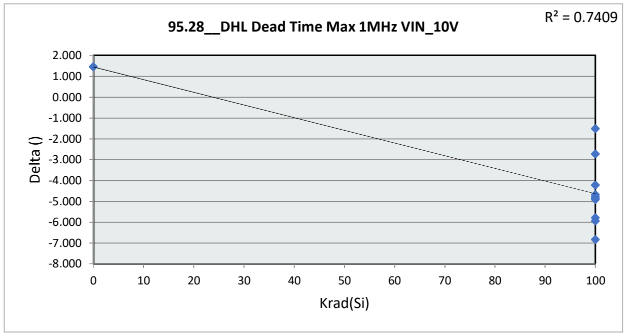


	95.27__DHL Dead Time Large 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.428	45.593
Average	49.740	47.307
Max	50.053	49.443
UL	61.000	61.000

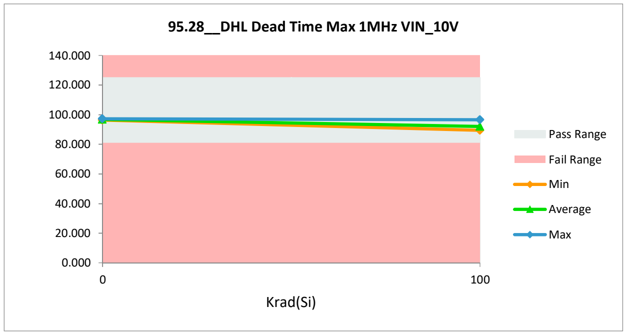


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.28__DHL Dead Time Max 1MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	95.817	97.256	1.439
0	2	94.870	96.323	1.453
100	23	96.229	94.706	-1.522
100	24	96.840	91.040	-5.800
100	25	97.842	91.887	-5.954
100	26	94.984	90.761	-4.223
100	27	96.541	93.798	-2.743
100	48u	101.290	96.602	-4.688
100	49u	95.555	90.702	-4.853
100	50u	96.348	89.509	-6.839
100	51u	96.223	91.427	-4.796
100	52u	95.647	90.728	-4.919
	Max	101.290	97.256	1.453
	Average	96.515	92.895	-3.620
	Min	94.870	89.509	-6.839
	Std Dev	1.708	2.709	2.750

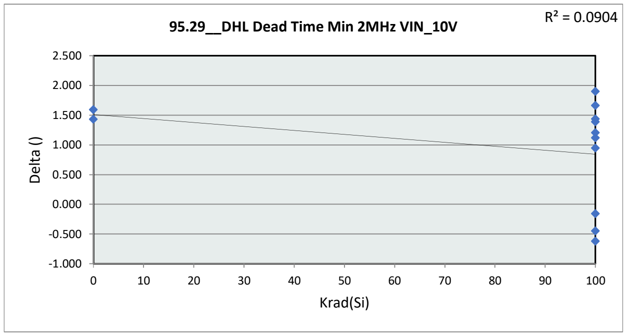


	95.28__DHL Dead Time Max 1MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.323	89.509
Average	96.789	92.116
Max	97.256	96.602
UL	125.000	125.000

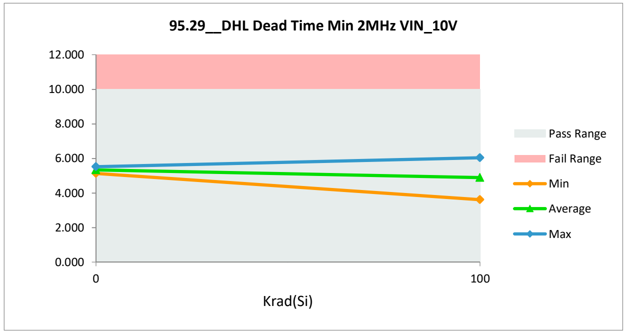


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.29__DHL Dead Time Min 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.711	5.141	1.430
0	2	3.926	5.518	1.592
100	23	3.594	5.492	1.898
100	24	3.561	4.682	1.120
100	25	4.320	5.268	0.947
100	26	4.240	3.621	-0.619
100	27	4.207	3.759	-0.448
100	48u	3.913	5.576	1.662
100	49u	3.972	5.175	1.203
100	50u	4.044	3.890	-0.154
100	51u	3.953	5.391	1.438
100	52u	4.643	6.034	1.391
	Max	4.643	6.034	1.898
	Average	4.007	4.962	0.955
	Min	3.561	3.621	-0.619
	Std Dev	0.313	0.795	0.864



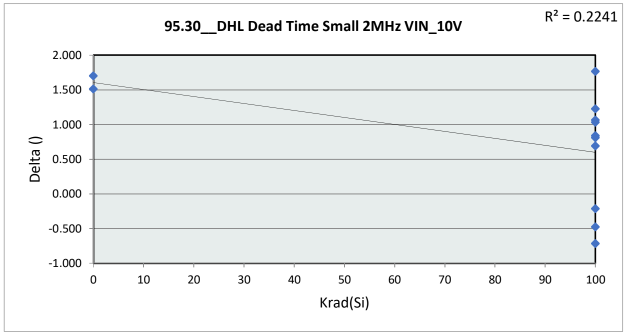
	95.29__DHL Dead Time Min 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.141	3.621
Average	5.329	4.889
Max	5.518	6.034
UL	10.000	10.000



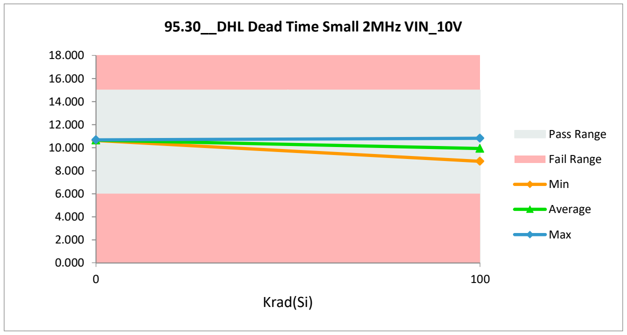
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	95.30__DHL Dead Time Small 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.924	10.625	1.702
0	2	9.149	10.661	1.512
100	23	8.803	10.569	1.766
100	24	8.851	9.539	0.688
100	25	9.528	10.364	0.836
100	26	9.514	8.796	-0.719
100	27	9.586	9.110	-0.476
100	48u	9.479	10.705	1.226
100	49u	9.164	9.972	0.808
100	50u	9.194	8.981	-0.213
100	51u	9.352	10.383	1.031
100	52u	9.733	10.798	1.066
	Max	9.733	10.798	1.766
	Average	9.273	10.042	0.769
	Min	8.803	8.796	-0.719
	Std Dev	0.307	0.741	0.827

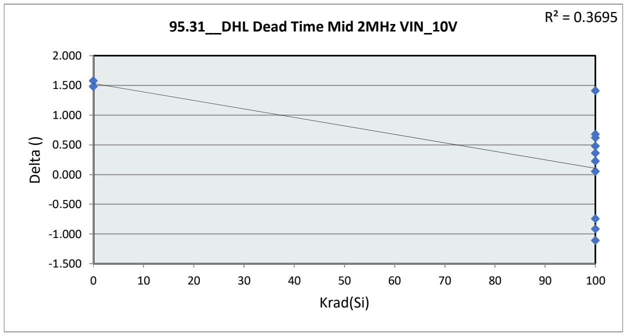


	95.30__DHL Dead Time Small 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.625	8.796
Average	10.643	9.922
Max	10.661	10.798
UL	15.000	15.000

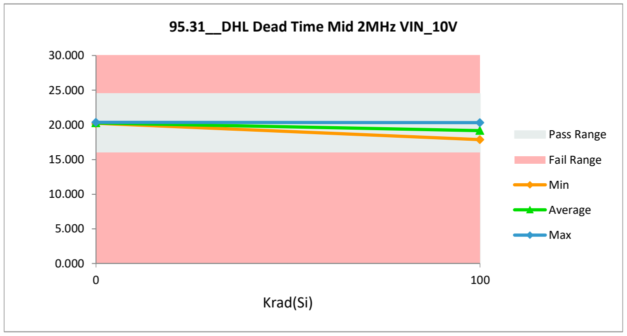


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.31__DHL Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.724	20.204	1.480
0	2	18.790	20.369	1.579
100	23	18.617	20.031	1.413
100	24	18.525	18.885	0.360
100	25	19.261	19.315	0.054
100	26	18.982	17.873	-1.109
100	27	19.454	18.541	-0.913
100	48u	19.679	20.301	0.622
100	49u	18.858	19.087	0.228
100	50u	18.865	18.123	-0.742
100	51u	19.023	19.502	0.479
100	52u	19.376	20.052	0.676
	Max	19.679	20.369	1.579
	Average	19.013	19.357	0.344
	Min	18.525	17.873	-1.109
	Std Dev	0.357	0.868	0.911

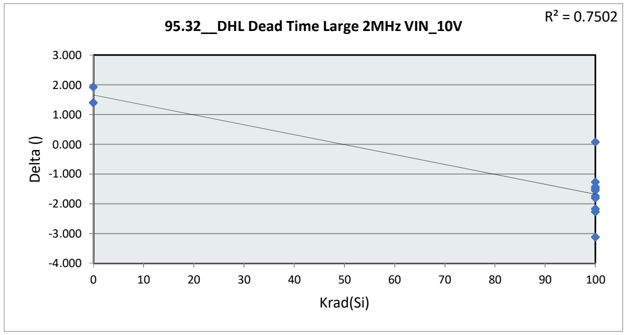


	95.31__DHL Dead Time Mid 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.204	17.873
Average	20.287	19.171
Max	20.369	20.301
UL	24.500	24.500

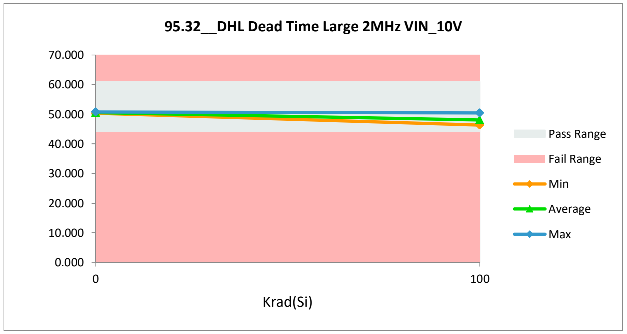


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.32__DHL Dead Time Large 2M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	49.382	50.779	1.397
0	2	48.448	50.375	1.928
100	23	49.611	49.683	0.072
100	24	49.343	47.527	-1.816
100	25	50.375	48.100	-2.275
100	26	49.103	46.927	-2.176
100	27	49.677	48.406	-1.271
100	48u	51.891	50.461	-1.430
100	49u	49.266	47.515	-1.752
100	50u	49.464	46.340	-3.123
100	51u	49.367	47.883	-1.484
100	52u	49.553	48.004	-1.549
	Max	51.891	50.779	1.928
	Average	49.623	48.500	-1.123
	Min	48.448	46.340	-3.123
	Std Dev	0.838	1.471	1.502

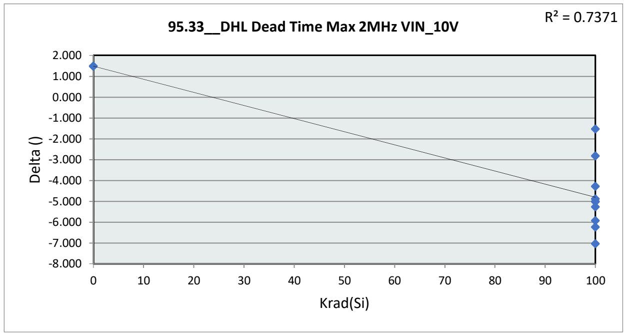


	95.32__DHL Dead Time Large 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.375	46.340
Average	50.577	48.085
Max	50.779	50.461
UL	61.000	61.000

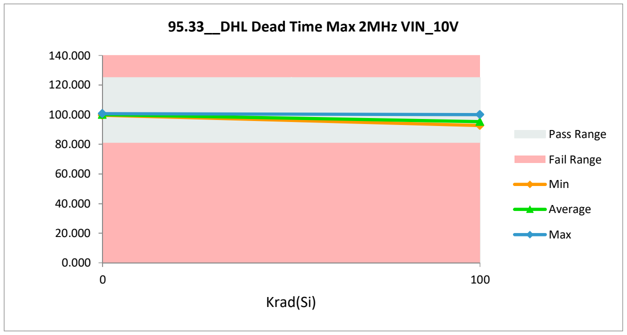


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		95.33__DHL Dead Time Max 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	99.172	100.651	1.479
0	2	98.032	99.517	1.485
100	23	99.648	98.108	-1.539
100	24	100.234	94.303	-5.931
100	25	101.318	95.082	-6.236
100	26	98.187	93.896	-4.291
100	27	99.883	97.061	-2.822
100	48u	104.972	99.963	-5.009
100	49u	98.803	93.914	-4.889
100	50u	99.711	92.668	-7.044
100	51u	99.634	94.600	-5.035
100	52u	98.814	93.539	-5.275
	Max	104.972	100.651	1.485
	Average	99.867	96.109	-3.759
	Min	98.032	92.668	-7.044
	Std Dev	1.842	2.808	2.851

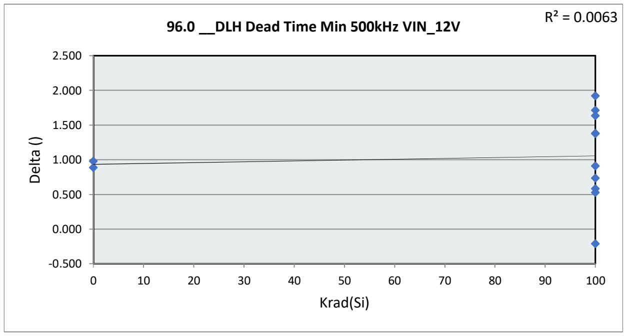


	95.33__DHL Dead Time Max 2MHz VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.517	92.668
Average	100.084	95.313
Max	100.651	99.963
UL	125.000	125.000

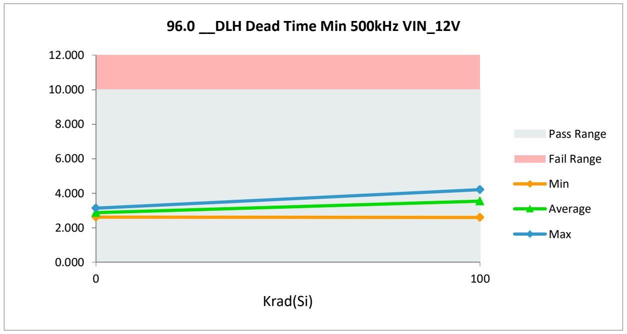


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.0 __DLH Dead Time Min 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.146	3.124	0.978
0	2	1.722	2.611	0.890
100	23	3.003	3.738	0.735
100	24	3.207	2.995	-0.212
100	25	2.567	4.204	1.637
100	26	2.066	2.592	0.526
100	27	2.588	3.497	0.909
100	48u	2.526	3.906	1.380
100	49u	2.308	4.022	1.714
100	50u	2.428	3.012	0.583
100	51u	2.416	3.790	1.375
100	52u	1.807	3.729	1.922
	Max	3.207	4.204	1.922
	Average	2.399	3.435	1.036
	Min	1.722	2.592	-0.212
	Std Dev	0.436	0.550	0.602

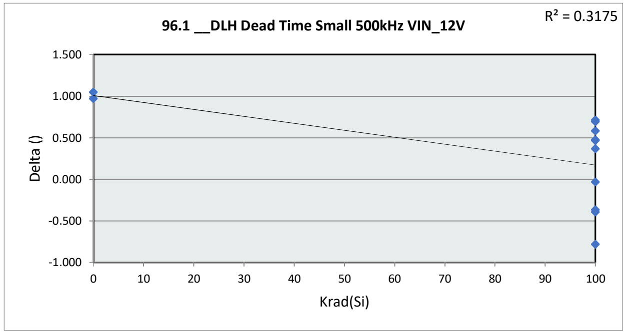


	96.0 __DLH Dead Time Min 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.611	2.592
Average	2.868	3.549
Max	3.124	4.204
UL	10.000	10.000

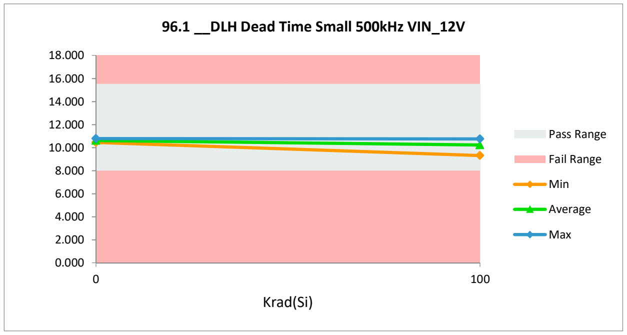


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.1 __DLH Dead Time Small 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.801	10.771	0.970
0	2	9.406	10.451	1.045
100	23	10.037	10.503	0.466
100	24	10.488	9.706	-0.782
100	25	10.162	10.742	0.580
100	26	9.708	9.314	-0.394
100	27	10.246	10.212	-0.034
100	48u	9.989	10.462	0.473
100	49u	10.046	10.759	0.713
100	50u	10.020	9.653	-0.367
100	51u	10.024	10.389	0.365
100	52u	9.787	10.478	0.691
	Max	10.488	10.771	1.045
	Average	9.976	10.287	0.310
	Min	9.406	9.314	-0.782
	Std Dev	0.277	0.477	0.578

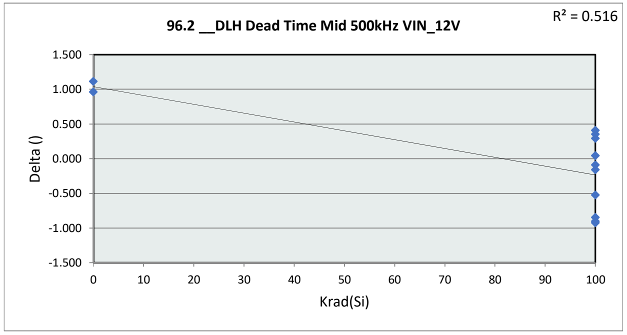


	96.1 __DLH Dead Time Small 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.451	9.314
Average	10.611	10.222
Max	10.771	10.759
UL	15.500	15.500

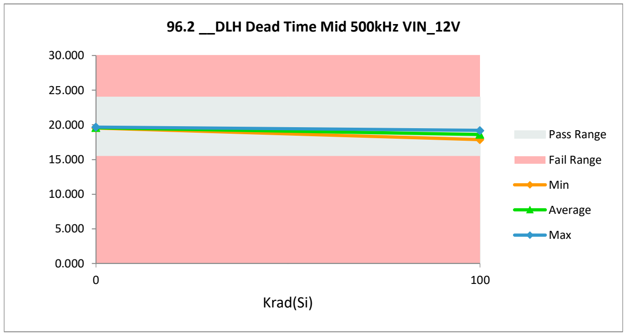


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.2 __DLH Dead Time Mid 500k		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.540	19.653	1.114
0	2	18.586	19.546	0.961
100	23	18.310	18.717	0.407
100	24	18.791	17.945	-0.846
100	25	19.146	19.188	0.043
100	26	18.811	17.886	-0.925
100	27	19.121	18.596	-0.525
100	48u	18.825	18.667	-0.158
100	49u	18.686	19.038	0.352
100	50u	18.913	18.013	-0.900
100	51u	18.893	18.802	-0.092
100	52u	18.750	19.045	0.295
	Max	19.146	19.653	1.114
	Average	18.781	18.758	-0.023
	Min	18.310	17.886	-0.925
	Std Dev	0.235	0.586	0.689

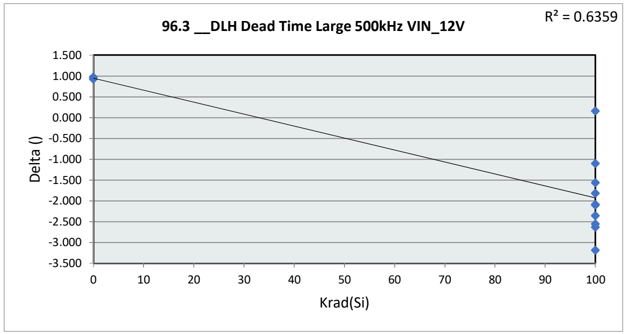


	96.2 __DLH Dead Time Mid 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.546	17.886
Average	19.600	18.590
Max	19.653	19.188
UL	24.000	24.000

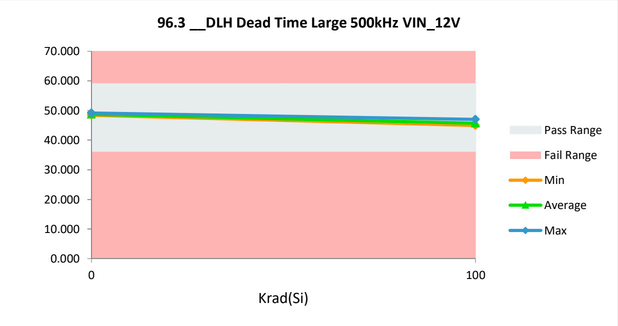


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.3 __DLH Dead Time Large 50		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	59	59	
	Min Limit	36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	47.434	48.359	0.925
0	2	48.174	49.140	0.966
100	23	45.474	45.626	0.151
100	24	46.353	45.245	-1.108
100	25	48.531	46.168	-2.363
100	26	48.336	45.142	-3.194
100	27	48.438	45.878	-2.560
100	48u	47.354	45.260	-2.094
100	49u	47.553	45.732	-1.821
100	50u	47.549	44.909	-2.640
100	51u	48.256	46.152	-2.104
100	52u	48.572	47.002	-1.570
	Max	48.572	49.140	0.966
	Average	47.669	46.218	-1.451
	Min	45.474	44.909	-3.194
	Std Dev	0.950	1.320	1.404

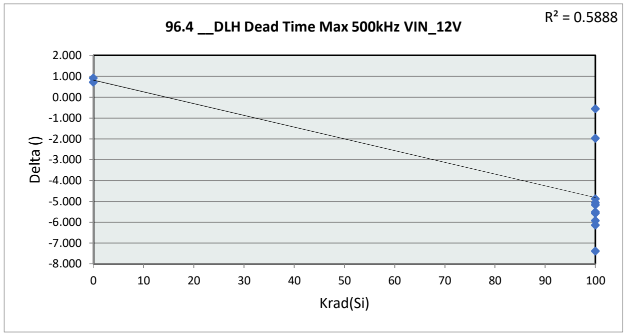


	96.3 __DLH Dead Time Large 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.359	44.909
Average	48.749	45.711
Max	49.140	47.002
UL	59.000	59.000

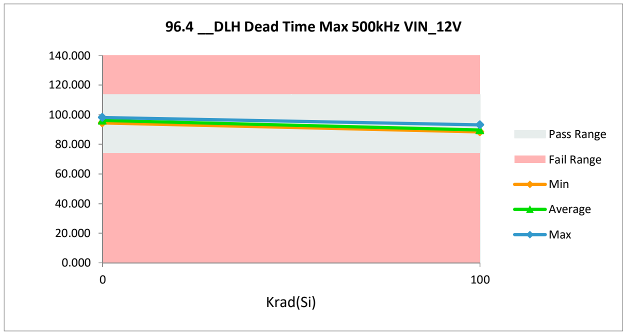


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.4 __DLH Dead Time Max 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	93.669	94.383	0.714
0	2	97.090	98.004	0.914
100	23	89.300	88.726	-0.574
100	24	91.169	89.192	-1.978
100	25	96.399	90.255	-6.145
100	26	96.778	89.377	-7.401
100	27	95.179	90.107	-5.071
100	48u	93.921	88.346	-5.575
100	49u	94.705	88.772	-5.933
100	50u	94.202	88.688	-5.515
100	51u	96.174	90.985	-5.188
100	52u	97.927	93.042	-4.886
	Max	97.927	98.004	0.914
	Average	94.709	90.823	-3.886
	Min	89.300	88.346	-7.401
	Std Dev	2.509	2.924	2.861

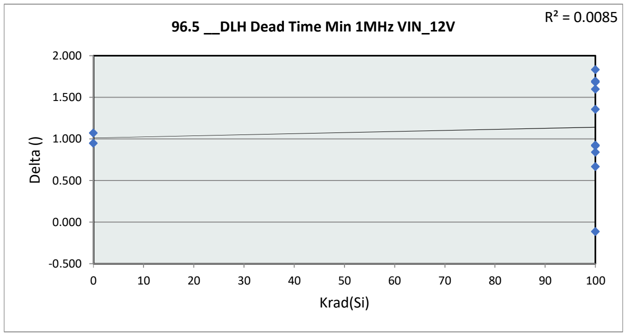


	96.4 __DLH Dead Time Max 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.383	88.346
Average	96.193	89.749
Max	98.004	93.042
UL	113.500	113.500

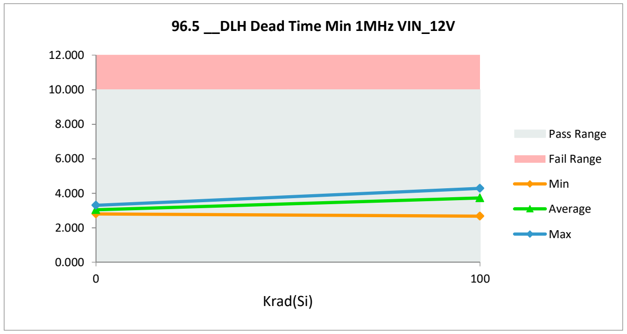


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.5 __DLH Dead Time Min 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.348	3.298	0.950
0	2	1.722	2.792	1.071
100	23	3.009	3.850	0.841
100	24	3.354	3.243	-0.111
100	25	2.585	4.281	1.696
100	26	1.998	2.668	0.669
100	27	2.730	3.646	0.917
100	48u	2.575	4.259	1.684
100	49u	2.658	4.255	1.597
100	50u	2.392	3.317	0.925
100	51u	2.372	3.730	1.358
100	52u	2.170	4.003	1.833
	Max	3.354	4.281	1.833
	Average	2.493	3.612	1.119
	Min	1.722	2.668	-0.111
	Std Dev	0.437	0.555	0.552

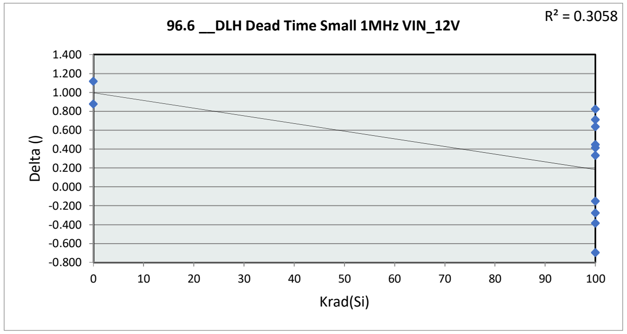


	96.5 __DLH Dead Time Min 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.792	2.668
Average	3.045	3.725
Max	3.298	4.281
UL	10.000	10.000

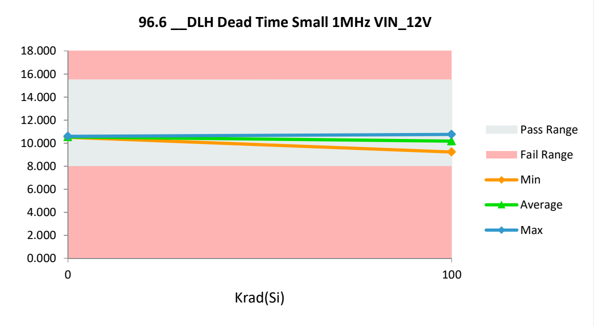


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.6 __DLH Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15.5	15.5	
Min Limit		8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.703	10.579	0.875
0	2	9.383	10.498	1.116
100	23	9.979	10.312	0.333
100	24	10.382	9.686	-0.696
100	25	10.039	10.748	0.709
100	26	9.601	9.215	-0.386
100	27	10.257	10.104	-0.152
100	48u	9.969	10.416	0.447
100	49u	10.016	10.653	0.637
100	50u	9.913	9.635	-0.278
100	51u	9.921	10.333	0.411
100	52u	9.688	10.510	0.823
	Max	10.382	10.748	1.116
	Average	9.904	10.224	0.320
	Min	9.383	9.215	-0.696
	Std Dev	0.277	0.474	0.571

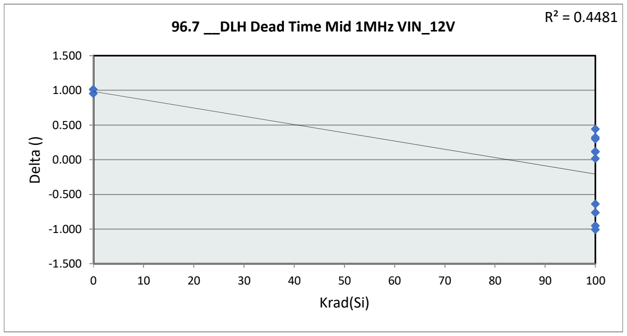


	96.6 __DLH Dead Time Small 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.499	9.215
Average	10.539	10.161
Max	10.579	10.748
UL	15.500	15.500

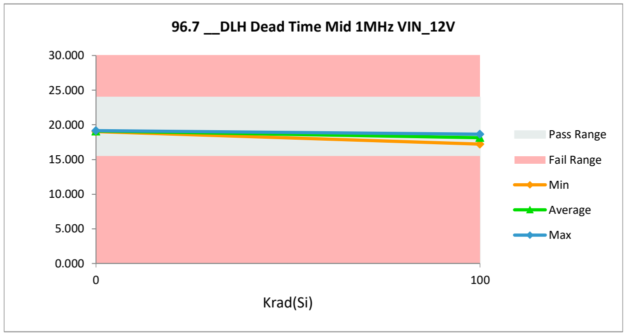


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.7 __DLH Dead Time Mid 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.209	19.163	0.954
0	2	18.013	19.028	1.015
100	23	17.854	18.295	0.441
100	24	18.377	17.613	-0.764
100	25	18.549	18.667	0.118
100	26	18.232	17.223	-1.010
100	27	18.760	18.123	-0.637
100	48u	18.279	18.394	0.115
100	49u	18.348	18.667	0.319
100	50u	18.436	17.483	-0.953
100	51u	18.347	18.364	0.017
100	52u	18.359	18.656	0.297
	Max	18.760	19.163	1.015
	Average	18.314	18.306	-0.007
	Min	17.854	17.223	-1.010
	Std Dev	0.233	0.604	0.692

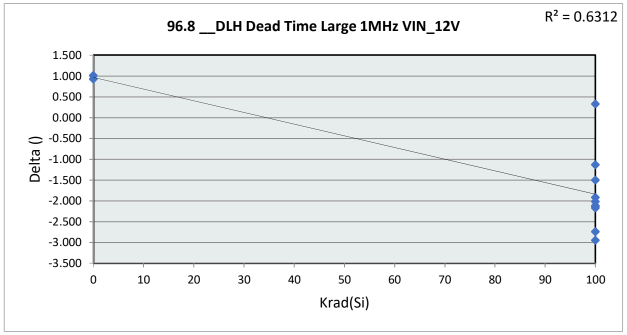


	96.7 __DLH Dead Time Mid 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.028	17.223
Average	19.096	18.149
Max	19.163	18.667
UL	24.000	24.000

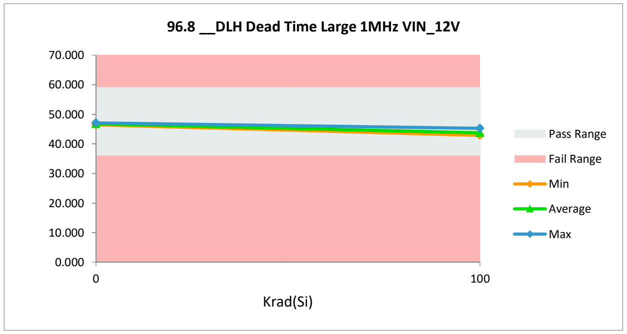


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.8 __DLH Dead Time Large 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.515	46.442	0.927
0	2	46.127	47.137	1.010
100	23	43.321	43.646	0.325
100	24	44.230	43.096	-1.134
100	25	46.370	44.446	-1.924
100	26	46.243	43.293	-2.949
100	27	46.215	44.040	-2.176
100	48u	45.548	43.409	-2.139
100	49u	45.835	43.716	-2.120
100	50u	45.600	42.852	-2.748
100	51u	46.191	44.167	-2.023
100	52u	46.800	45.294	-1.505
	Max	46.800	47.137	1.010
	Average	45.666	44.295	-1.371
	Min	43.321	42.852	-2.949
	Std Dev	0.979	1.343	1.376



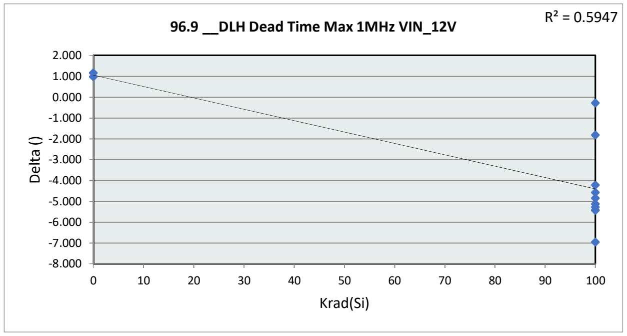
	96.8 __DLH Dead Time Large 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.442	42.852
Average	46.789	43.796
Max	47.137	45.294
UL	59.000	59.000



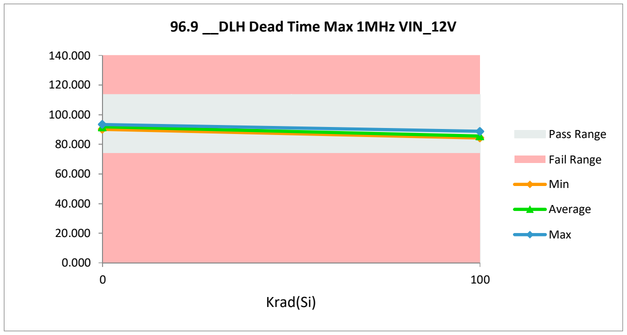
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	96.9 __DLH Dead Time Max 1MH	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	113.5	113.5
Min Limit	74	74

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	89.049	90.200	1.150
0	2	92.298	93.264	0.966
100	23	84.857	84.568	-0.289
100	24	86.527	84.699	-1.828
100	25	91.617	86.195	-5.421
100	26	92.010	85.038	-6.973
100	27	90.605	86.027	-4.578
100	48u	89.447	84.319	-5.128
100	49u	89.958	84.661	-5.296
100	50u	89.665	84.215	-5.449
100	51u	91.518	86.666	-4.851
100	52u	92.939	88.709	-4.230
	Max	92.939	93.264	1.150
	Average	90.041	86.547	-3.494
	Min	84.857	84.215	-6.973
	Std Dev	2.394	2.814	2.757

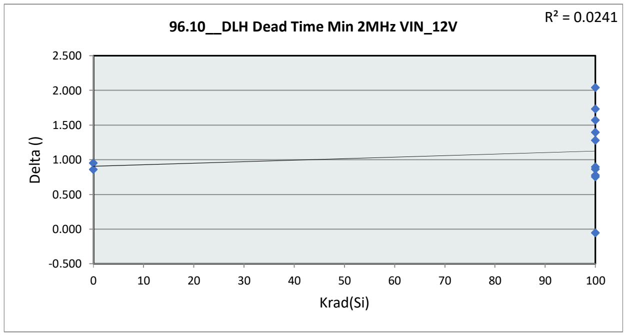


	96.9 __DLH Dead Time Max 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	90.200	84.215
Average	91.732	85.510
Max	93.264	88.709
UL	113.500	113.500

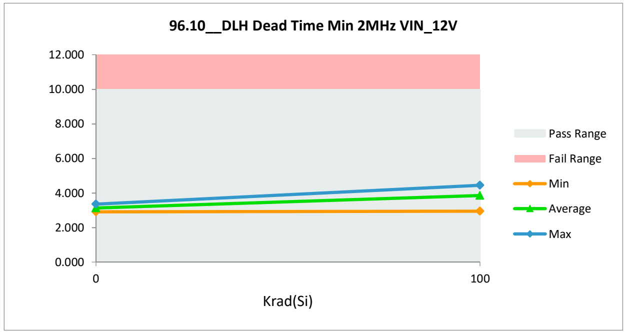


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.10__DLH Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.411	3.363	0.952
0	2	2.044	2.905	0.861
100	23	3.053	3.918	0.865
100	24	3.391	3.340	-0.051
100	25	2.718	4.449	1.731
100	26	2.167	2.944	0.777
100	27	2.970	3.868	0.898
100	48u	2.679	4.251	1.572
100	49u	2.910	4.308	1.397
100	50u	2.628	3.381	0.753
100	51u	2.645	3.925	1.281
100	52u	2.183	4.223	2.040
	Max	3.391	4.449	2.040
	Average	2.650	3.740	1.090
	Min	2.044	2.905	-0.051
	Std Dev	0.400	0.536	0.552

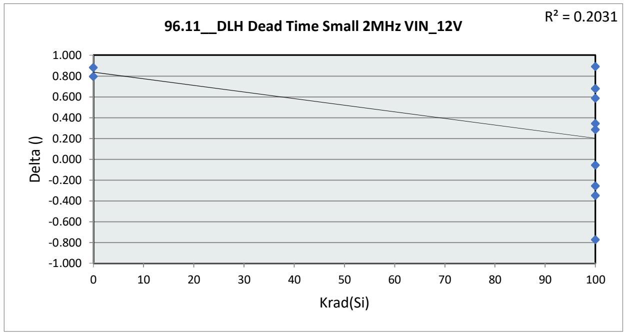


	96.10__DLH Dead Time Min 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.905	2.944
Average	3.134	3.861
Max	3.363	4.449
UL	10.000	10.000

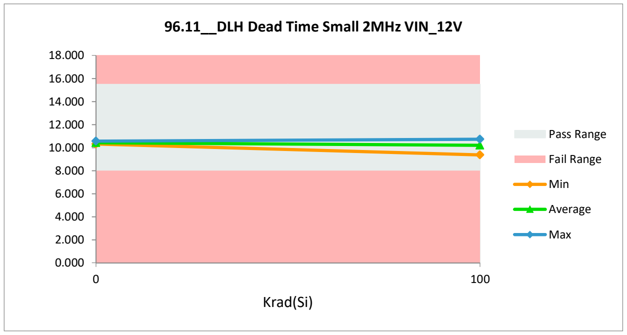


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.11__DLH Dead Time Small 2M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.758	10.552	0.794
0	2	9.427	10.306	0.880
100	23	10.017	10.301	0.284
100	24	10.405	9.629	-0.775
100	25	10.086	10.672	0.586
100	26	9.631	9.374	-0.257
100	27	10.248	10.191	-0.057
100	48u	10.039	10.716	0.677
100	49u	9.934	10.612	0.678
100	50u	9.999	9.651	-0.349
100	51u	9.948	10.290	0.342
100	52u	9.742	10.630	0.888
	Max	10.405	10.716	0.888
	Average	9.936	10.244	0.308
	Min	9.427	9.374	-0.775
	Std Dev	0.267	0.456	0.548

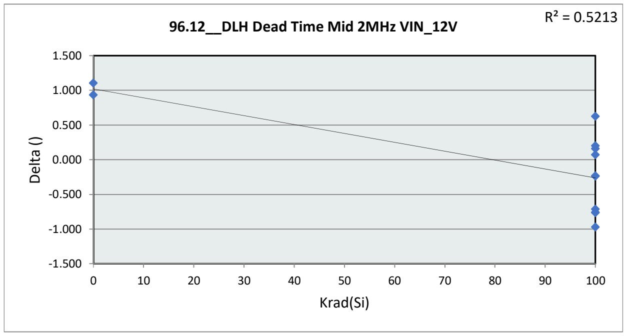


	96.11__DLH Dead Time Small 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.306	9.374
Average	10.429	10.207
Max	10.552	10.716
UL	15.500	15.500

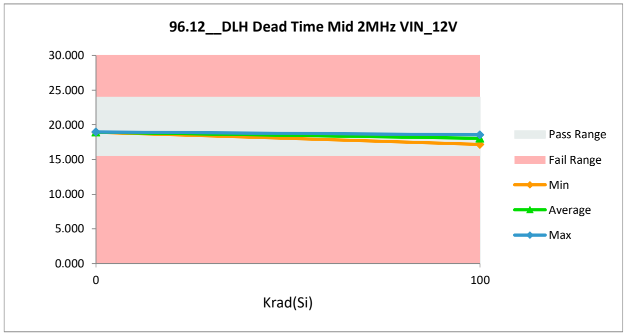


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.12__DLH Dead Time Mid 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24	24	
	Min Limit	15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.997	18.932	0.935
0	2	17.874	18.978	1.104
100	23	17.830	18.455	0.625
100	24	18.367	17.603	-0.763
100	25	18.405	18.565	0.160
100	26	18.151	17.178	-0.972
100	27	18.806	18.095	-0.712
100	48u	18.293	18.062	-0.230
100	49u	18.407	18.481	0.074
100	50u	18.260	17.501	-0.759
100	51u	18.452	18.215	-0.237
100	52u	18.367	18.567	0.200
	Max	18.806	18.978	1.104
	Average	18.267	18.219	-0.048
	Min	17.830	17.178	-0.972
	Std Dev	0.273	0.561	0.691

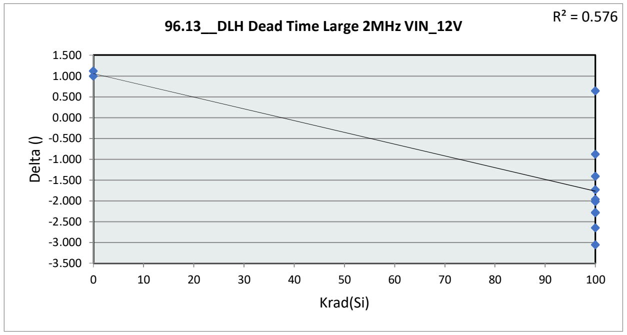


	96.12__DLH Dead Time Mid 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	18.932	17.179
Average	18.955	18.072
Max	18.978	18.567
UL	24.000	24.000

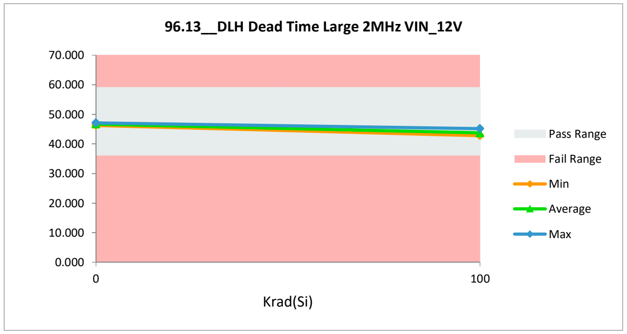


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.13__DLH Dead Time Large 2		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.264	46.259	0.995
0	2	46.014	47.133	1.119
100	23	42.935	43.571	0.636
100	24	44.050	43.164	-0.886
100	25	46.448	44.165	-2.283
100	26	46.102	43.039	-3.063
100	27	46.172	43.881	-2.291
100	48u	45.362	43.341	-2.021
100	49u	45.532	43.793	-1.739
100	50u	45.426	42.776	-2.650
100	51u	46.117	44.147	-1.970
100	52u	46.604	45.192	-1.412
	Max	46.604	47.133	1.119
	Average	45.502	44.205	-1.297
	Min	42.935	42.776	-3.063
	Std Dev	1.059	1.337	1.449

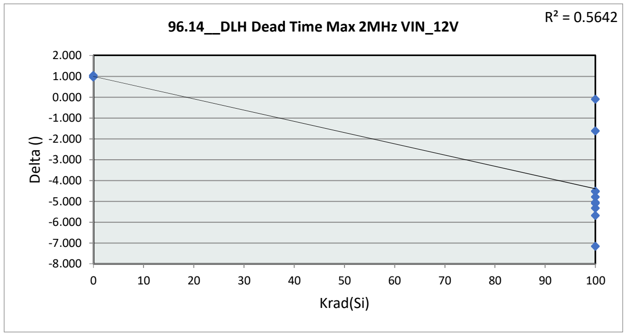


	96.13__DLH Dead Time Large 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.259	42.776
Average	46.696	43.707
Max	47.133	45.192
UL	59.000	59.000

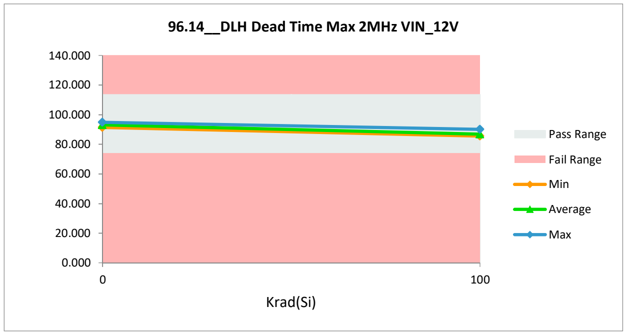


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.14__DLH Dead Time Max 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	90.385	91.336	0.951
0	2	93.837	94.875	1.038
100	23	85.950	85.840	-0.109
100	24	87.660	86.035	-1.625
100	25	92.996	87.303	-5.693
100	26	93.413	86.253	-7.160
100	27	91.810	87.282	-4.528
100	48u	90.633	85.569	-5.065
100	49u	91.099	85.991	-5.107
100	50u	90.819	85.487	-5.332
100	51u	92.822	88.021	-4.801
100	52u	94.595	90.052	-4.542
	Max	94.595	94.875	1.038
	Average	91.335	87.837	-3.498
	Min	85.950	85.487	-7.160
	Std Dev	2.534	2.878	2.793

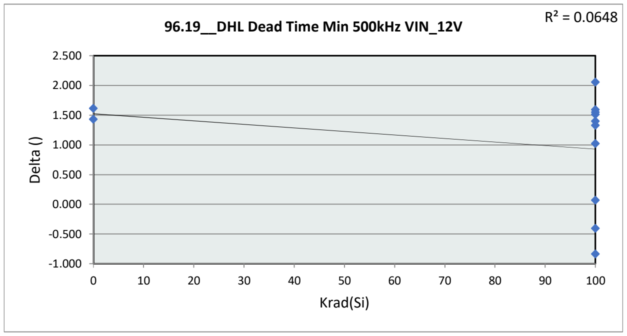


	96.14__DLH Dead Time Max 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.336	85.487
Average	93.105	86.783
Max	94.875	90.052
UL	113.500	113.500

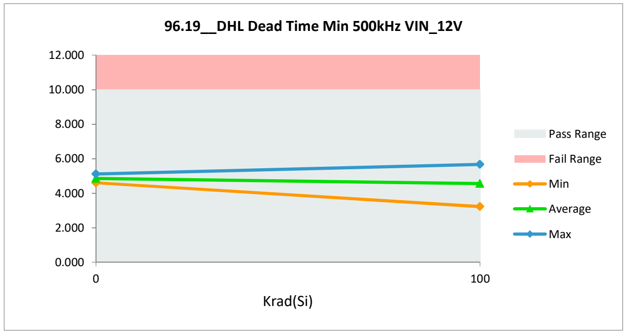


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.19__DHL Dead Time Min 500		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.173	4.604	1.431
0	2	3.504	5.118	1.614
100	23	3.118	5.175	2.057
100	24	2.972	4.372	1.400
100	25	3.897	4.921	1.024
100	26	4.060	3.227	-0.833
100	27	3.876	3.473	-0.403
100	48u	3.529	5.123	1.594
100	49u	3.405	4.732	1.327
100	50u	3.592	3.662	0.070
100	51u	3.625	5.173	1.548
100	52u	4.150	5.661	1.512
	Max	4.150	5.661	2.057
	Average	3.575	4.603	1.028
	Min	2.972	3.227	-0.833
	Std Dev	0.373	0.771	0.907

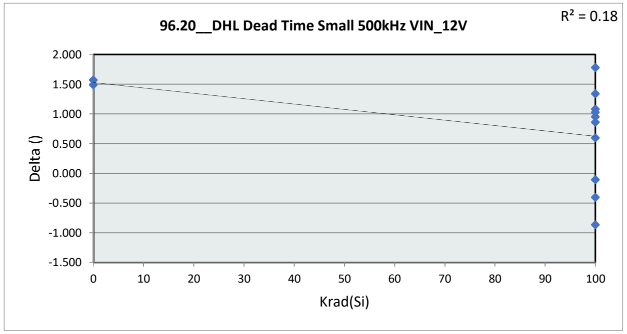


	96.19__DHL Dead Time Min 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.605	3.227
Average	4.861	4.552
Max	5.118	5.662
UL	10.000	10.000

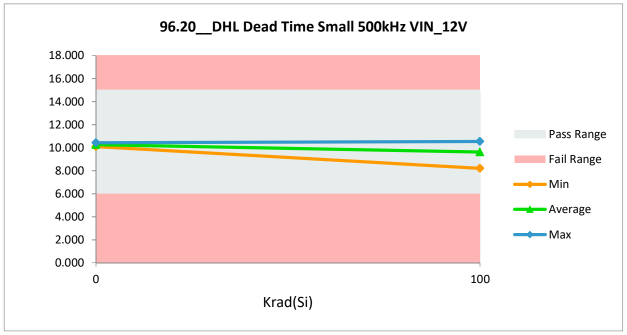


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.20__DHL Dead Time Small 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.606	10.095	1.489
0	2	8.840	10.410	1.570
100	23	8.600	10.378	1.779
100	24	8.370	9.397	1.028
100	25	9.342	9.939	0.597
100	26	9.070	8.200	-0.870
100	27	9.211	8.804	-0.407
100	48u	9.119	10.458	1.339
100	49u	8.818	9.678	0.860
100	50u	8.798	8.689	-0.109
100	51u	9.009	10.088	1.079
100	52u	9.566	10.518	0.952
	Max	9.566	10.518	1.779
	Average	8.946	9.721	0.776
	Min	8.370	8.200	-0.870
	Std Dev	0.341	0.782	0.830



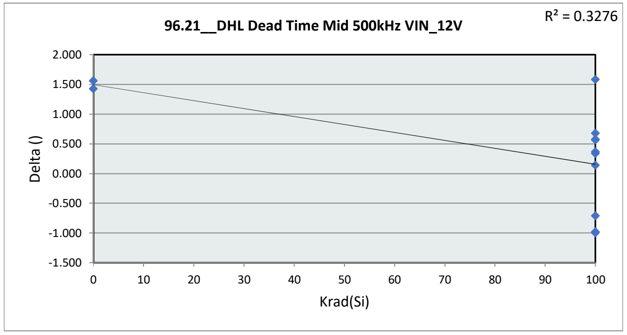
	96.20__DHL Dead Time Small 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.095	8.200
Average	10.252	9.615
Max	10.410	10.518
UL	15.000	15.000



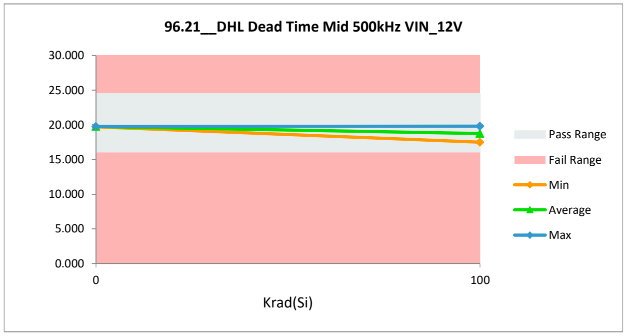
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	96.21__DHL Dead Time Mid 500	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	24.5	24.5
Min Limit	16	16

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.315	19.740	1.425
0	2	18.206	19.767	1.561
100	23	18.150	19.732	1.582
100	24	18.017	18.383	0.366
100	25	18.968	19.108	0.140
100	26	18.497	17.518	-0.979
100	27	18.756	18.047	-0.709
100	48u	19.147	19.823	0.676
100	49u	18.429	18.771	0.342
100	50u	18.545	17.550	-0.995
100	51u	18.463	19.031	0.568
100	52u	18.991	19.570	0.579
	Max	19.147	19.823	1.582
	Average	18.540	18.920	0.380
	Min	18.017	17.518	-0.995
	Std Dev	0.358	0.866	0.909

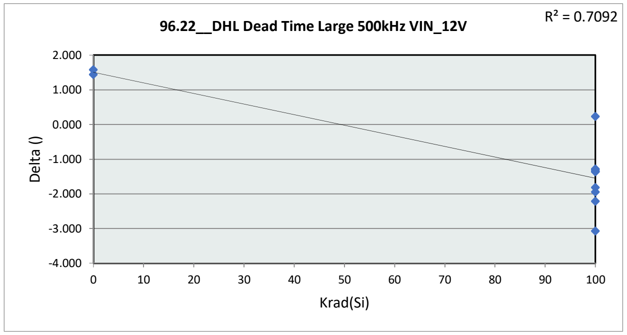


	96.21__DHL Dead Time Mid 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.740	17.518
Average	19.753	18.753
Max	19.767	19.823
UL	24.500	24.500

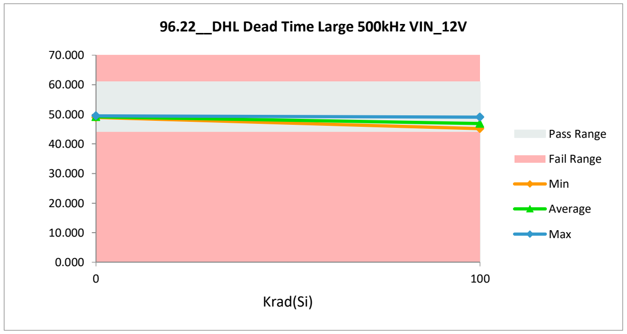


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.22__DHL Dead Time Large 50		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		61	61	
Min Limit		44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.017	49.457	1.440
0	2	47.343	48.920	1.577
100	23	48.176	48.401	0.225
100	24	48.031	46.213	-1.818
100	25	48.977	47.027	-1.949
100	26	47.883	45.663	-2.220
100	27	48.465	47.099	-1.366
100	48u	50.387	49.023	-1.363
100	49u	47.703	46.423	-1.280
100	50u	48.215	45.141	-3.074
100	51u	48.190	46.835	-1.355
100	52u	48.227	46.917	-1.310
	Max	50.387	49.457	1.577
	Average	48.301	47.260	-1.041
	Min	47.343	45.141	-3.074
	Std Dev	0.767	1.389	1.414

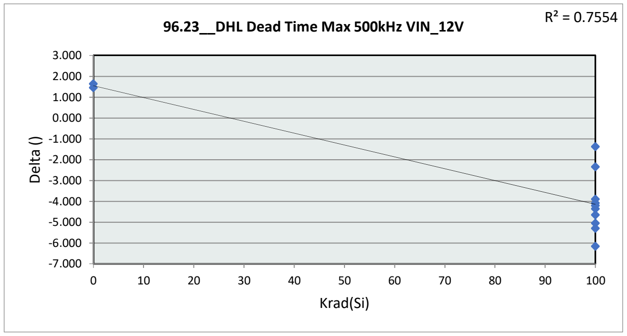


	96.22__DHL Dead Time Large 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.920	45.141
Average	49.189	46.874
Max	49.457	49.024
UL	61.000	61.000

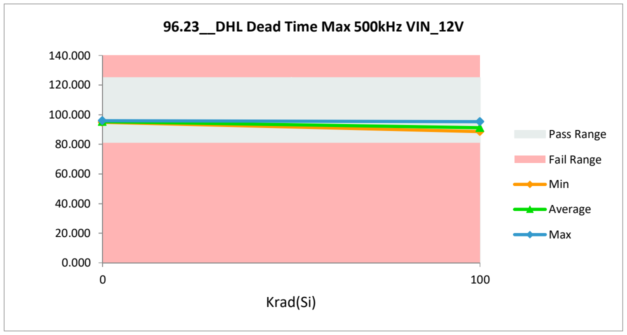


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.23__DHL Dead Time Max 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	94.247	95.886	1.639
0	2	93.406	94.857	1.451
100	23	94.858	93.482	-1.377
100	24	95.239	90.185	-5.054
100	25	96.268	90.970	-5.298
100	26	93.661	89.580	-4.082
100	27	95.033	92.677	-2.356
100	48u	99.614	95.400	-4.214
100	49u	93.923	90.025	-3.898
100	50u	94.781	88.621	-6.160
100	51u	94.840	90.469	-4.371
100	52u	94.199	89.533	-4.665
	Max	99.614	95.886	1.639
	Average	95.006	91.807	-3.199
	Min	93.406	88.621	-6.160
	Std Dev	1.645	2.540	2.549

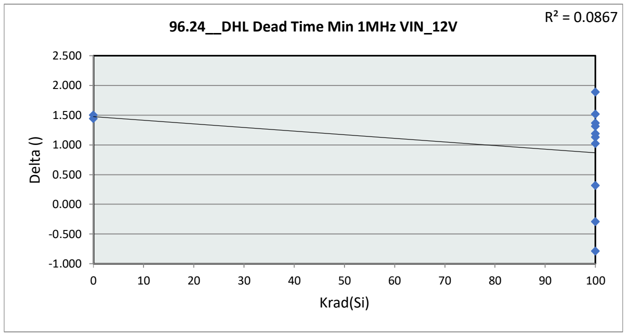


	96.23__DHL Dead Time Max 500kHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	94.857	88.621
Average	95.371	91.094
Max	95.886	95.400
UL	125.000	125.000

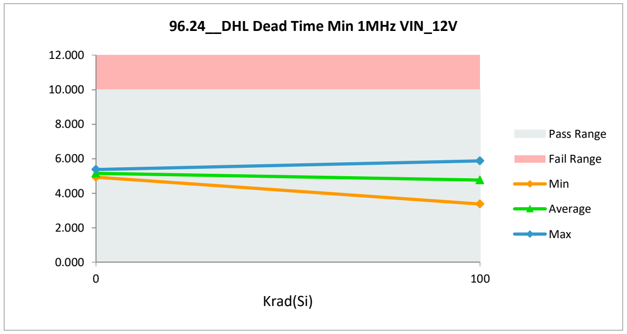


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.24__DHL Dead Time Min 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.431	4.935	1.504
0	2	3.931	5.376	1.445
100	23	3.534	5.422	1.888
100	24	3.283	4.414	1.131
100	25	4.169	5.191	1.022
100	26	4.150	3.367	-0.784
100	27	4.042	3.752	-0.289
100	48u	3.993	5.508	1.515
100	49u	3.705	5.070	1.364
100	50u	3.639	3.955	0.316
100	51u	3.913	5.105	1.192
100	52u	4.555	5.869	1.313
	Max	4.555	5.869	1.888
	Average	3.862	4.830	0.968
	Min	3.283	3.367	-0.784
	Std Dev	0.359	0.781	0.803

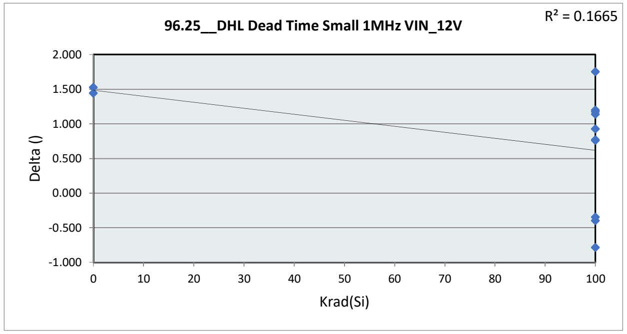


	96.24__DHL Dead Time Min 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.935	3.367
Average	5.155	4.765
Max	5.376	5.869
UL	10.000	10.000

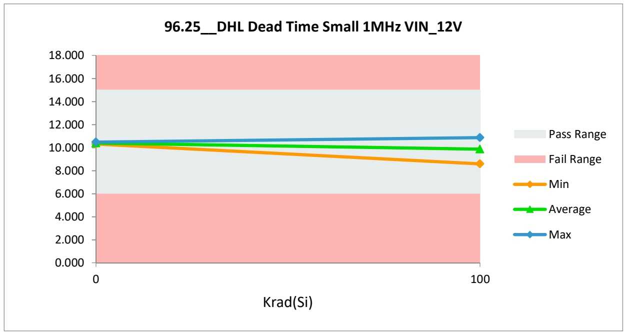


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.25__DHL Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.856	10.299	1.443
0	2	8.940	10.467	1.526
100	23	8.770	10.519	1.749
100	24	8.603	9.527	0.925
100	25	9.452	10.212	0.760
100	26	9.362	8.578	-0.784
100	27	9.439	9.040	-0.399
100	48u	9.473	10.670	1.197
100	49u	9.133	9.901	0.768
100	50u	9.352	9.004	-0.347
100	51u	9.073	10.248	1.175
100	52u	9.725	10.862	1.137
	Max	9.725	10.862	1.749
	Average	9.182	9.944	0.762
	Min	8.603	8.578	-0.784
	Std Dev	0.339	0.739	0.827

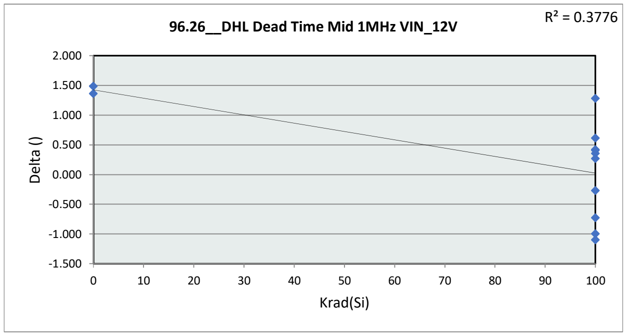


	96.25__DHL Dead Time Small 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.299	8.578
Average	10.383	9.856
Max	10.467	10.862
UL	15.000	15.000

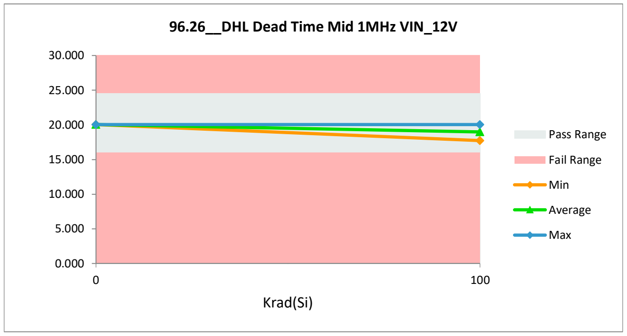


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.673	20.034	1.361
0	2	18.553	20.041	1.487
100	23	18.540	19.822	1.283
100	24	18.352	18.620	0.268
100	25	19.360	19.093	-0.266
100	26	18.834	17.736	-1.098
100	27	19.150	18.421	-0.729
100	48u	19.650	20.062	0.412
100	49u	18.712	19.067	0.355
100	50u	18.849	17.854	-0.996
100	51u	18.840	19.452	0.612
100	52u	19.313	19.736	0.423
	Max	19.650	20.062	1.487
	Average	18.902	19.162	0.259
	Min	18.352	17.736	-1.098
	Std Dev	0.388	0.842	0.885

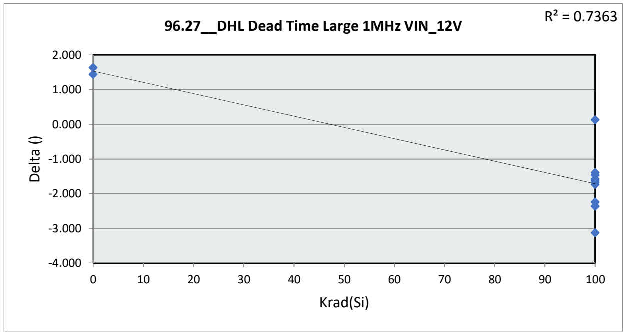


	96.26__DHL Dead Time Mid 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.034	17.736
Average	20.037	18.986
Max	20.041	20.062
UL	24.500	24.500

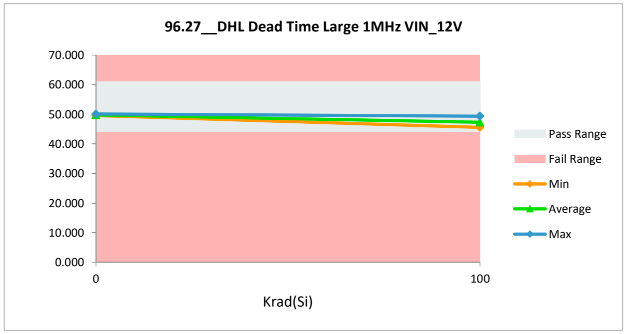


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.27__DHL Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.640	50.079	1.439
0	2	47.945	49.572	1.627
100	23	48.635	48.760	0.125
100	24	48.647	46.912	-1.735
100	25	49.680	47.312	-2.368
100	26	48.377	46.129	-2.248
100	27	48.986	47.588	-1.399
100	48u	50.995	49.411	-1.584
100	49u	48.425	46.789	-1.636
100	50u	48.740	45.613	-3.127
100	51u	48.744	47.272	-1.472
100	52u	48.901	47.217	-1.684
	Max	50.995	50.079	1.627
	Average	48.893	47.721	-1.172
	Min	47.945	45.613	-3.127
	Std Dev	0.779	1.416	1.473

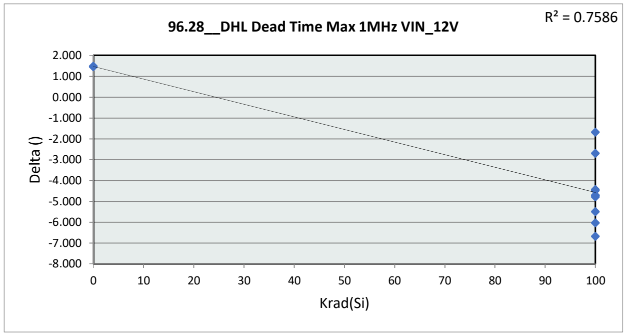


	96.27__DHL Dead Time Large 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.573	45.613
Average	49.826	47.300
Max	50.079	49.411
UL	61.000	61.000

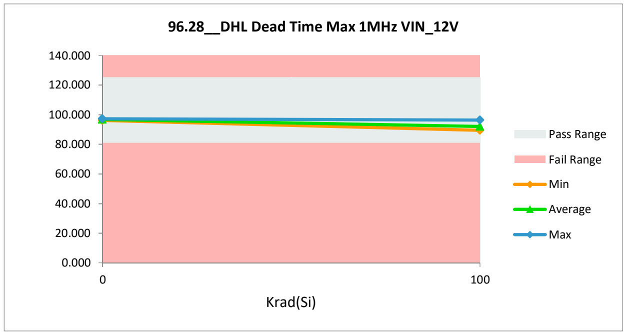


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.28__DHL Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	95.794	97.273	1.479
0	2	94.775	96.226	1.451
100	23	96.371	94.675	-1.697
100	24	96.733	91.231	-5.502
100	25	97.758	91.721	-6.037
100	26	95.072	90.627	-4.445
100	27	96.509	93.803	-2.706
100	48u	101.174	96.461	-4.713
100	49u	95.381	90.899	-4.482
100	50u	96.191	89.498	-6.693
100	51u	96.192	91.467	-4.725
100	52u	95.410	90.607	-4.804
	Max	101.174	97.273	1.479
	Average	96.447	92.874	-3.573
	Min	94.775	89.498	-6.693
	Std Dev	1.695	2.681	2.702

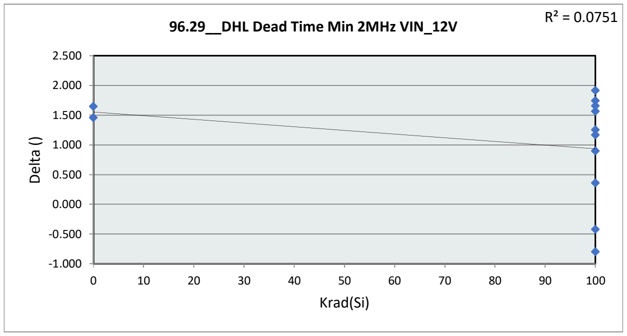


	96.28__DHL Dead Time Max 1MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.226	89.498
Average	96.750	92.099
Max	97.273	96.461
UL	125.000	125.000

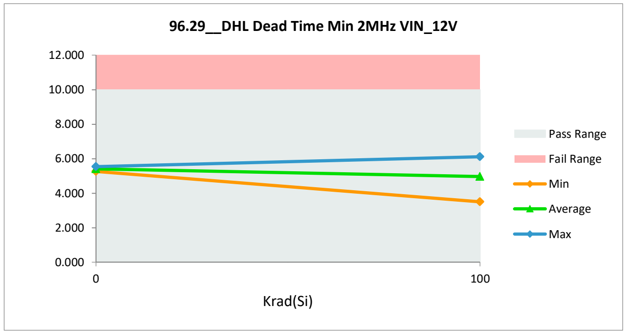


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.29__DHL Dead Time Min 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.811	5.269	1.458
0	2	3.890	5.538	1.648
100	23	3.700	5.614	1.914
100	24	3.463	4.629	1.166
100	25	4.226	5.122	0.897
100	26	4.295	3.496	-0.799
100	27	4.286	3.868	-0.417
100	48u	3.970	5.628	1.658
100	49u	3.977	5.232	1.255
100	50u	3.816	4.177	0.361
100	51u	3.947	5.688	1.741
100	52u	4.556	6.122	1.566
	Max	4.556	6.122	1.914
	Average	3.995	5.032	1.037
	Min	3.463	3.496	-0.799
	Std Dev	0.300	0.813	0.879

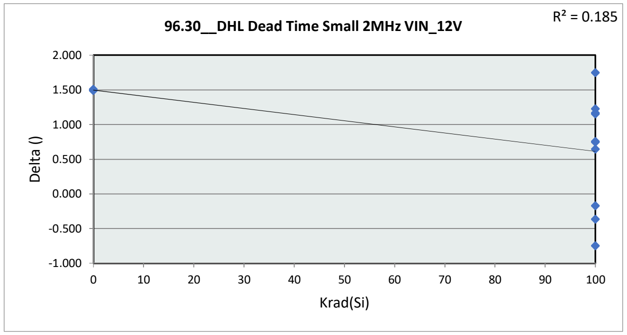


96.29__DHL Dead Time Min 2MHz VIN_12V		
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.269	3.496
Average	5.404	4.958
Max	5.538	6.122
UL	10.000	10.000

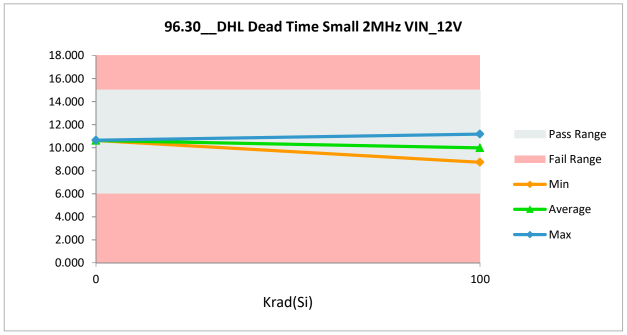


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.30__DHL Dead Time Small 2M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15	15	
	Min Limit	6	6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.102	10.610	1.508
0	2	9.143	10.629	1.486
100	23	8.904	10.651	1.747
100	24	8.878	9.523	0.645
100	25	9.615	10.360	0.746
100	26	9.479	8.731	-0.748
100	27	9.475	9.300	-0.174
100	48u	9.622	10.785	1.163
100	49u	9.138	9.892	0.754
100	50u	9.321	8.955	-0.366
100	51u	9.279	10.430	1.151
100	52u	9.955	11.179	1.224
	Max	9.955	11.179	1.747
	Average	9.326	10.087	0.761
	Min	8.878	8.731	-0.748
	Std Dev	0.318	0.789	0.799

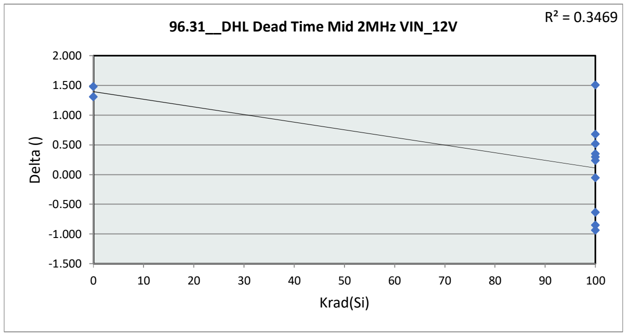


	96.30__DHL Dead Time Small 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.610	8.731
Average	10.619	9.981
Max	10.629	11.179
UL	15.000	15.000

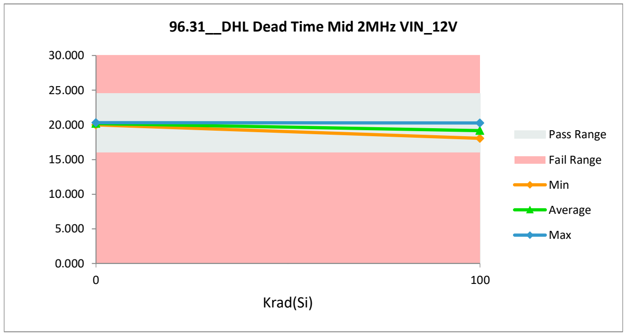


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.31__DHL Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.842	20.322	1.481
0	2	18.704	20.012	1.309
100	23	18.624	20.130	1.506
100	24	18.476	18.771	0.295
100	25	19.527	19.476	-0.051
100	26	18.923	18.070	-0.852
100	27	19.344	18.712	-0.633
100	48u	19.607	20.287	0.680
100	49u	18.768	19.005	0.237
100	50u	19.093	18.157	-0.936
100	51u	18.962	19.314	0.352
100	52u	19.393	19.912	0.520
	Max	19.607	20.322	1.506
	Average	19.022	19.347	0.326
	Min	18.476	18.070	-0.936
	Std Dev	0.371	0.805	0.848

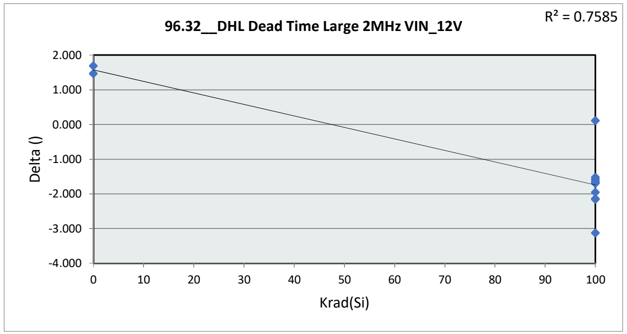


	96.31__DHL Dead Time Mid 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.012	18.070
Average	20.167	19.183
Max	20.322	20.287
UL	24.500	24.500

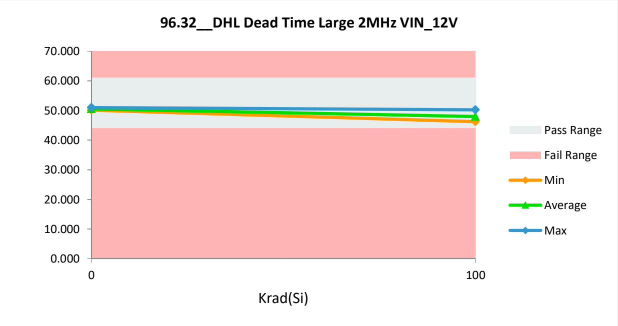


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.32__DHL Dead Time Large 2		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	49.299	50.986	1.687
0	2	48.679	50.144	1.464
100	23	49.405	49.512	0.106
100	24	49.367	47.408	-1.959
100	25	50.269	48.104	-2.165
100	26	49.028	46.888	-2.140
100	27	49.840	48.168	-1.672
100	48u	51.879	50.244	-1.635
100	49u	49.084	47.386	-1.698
100	50u	49.392	46.264	-3.128
100	51u	49.433	47.906	-1.527
100	52u	49.456	47.872	-1.584
	Max	51.879	50.986	1.687
	Average	49.594	48.407	-1.188
	Min	48.679	46.264	-3.128
	Std Dev	0.821	1.474	1.482

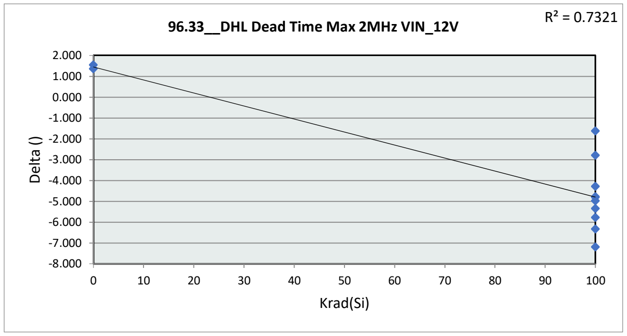


	96.32__DHL Dead Time Large 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.144	46.264
Average	50.565	47.975
Max	50.986	50.244
UL	61.000	61.000

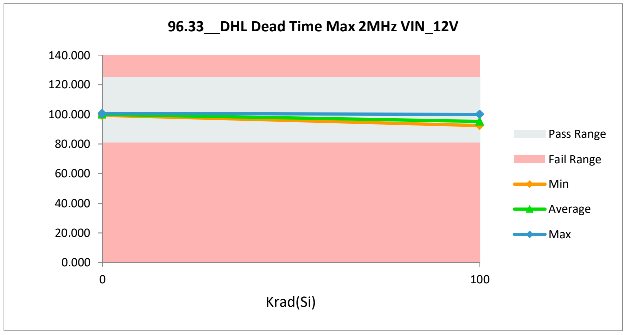


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		96.33__DHL Dead Time Max 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	99.048	100.590	1.542
0	2	98.127	99.480	1.353
100	23	99.598	97.964	-1.635
100	24	100.159	94.370	-5.788
100	25	101.286	94.944	-6.343
100	26	98.224	93.941	-4.283
100	27	99.839	97.043	-2.796
100	48u	105.020	100.034	-4.986
100	49u	98.557	93.776	-4.781
100	50u	99.642	92.442	-7.201
100	51u	99.447	94.640	-4.807
100	52u	98.850	93.497	-5.353
	Max	105.020	100.590	1.542
	Average	99.816	96.060	-3.756
	Min	98.127	92.442	-7.201
	Std Dev	1.860	2.830	2.841



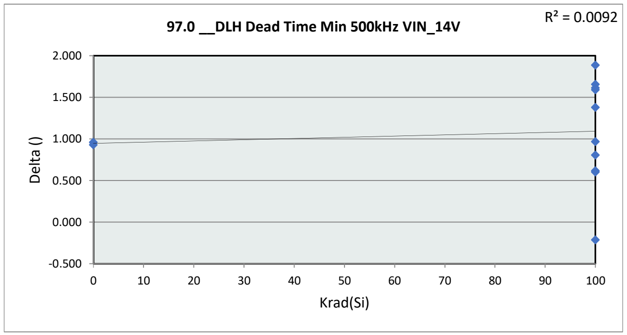
	96.33__DHL Dead Time Max 2MHz VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.480	92.442
Average	100.035	95.265
Max	100.590	100.034
UL	125.000	125.000



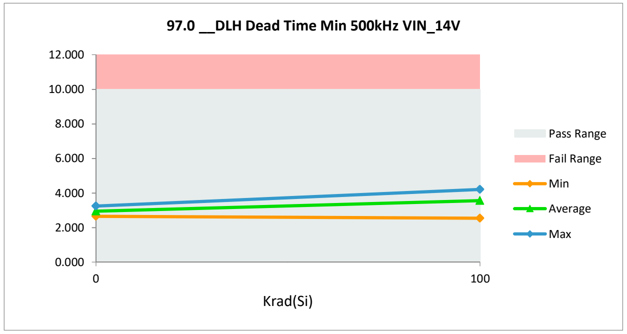
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.0 __DLH Dead Time Min 500k	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	10	10
Min Limit	0	0

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.283	3.244	0.961
0	2	1.717	2.648	0.931
100	23	2.968	3.572	0.604
100	24	3.246	3.035	-0.211
100	25	2.553	4.208	1.655
100	26	1.919	2.537	0.618
100	27	2.549	3.517	0.968
100	48u	2.451	4.065	1.615
100	49u	2.462	4.054	1.592
100	50u	2.271	3.078	0.808
100	51u	2.393	3.771	1.378
100	52u	1.839	3.728	1.888
	Max	3.246	4.208	1.888
	Average	2.388	3.455	1.067
	Min	1.717	2.537	-0.211
	Std Dev	0.440	0.552	0.592

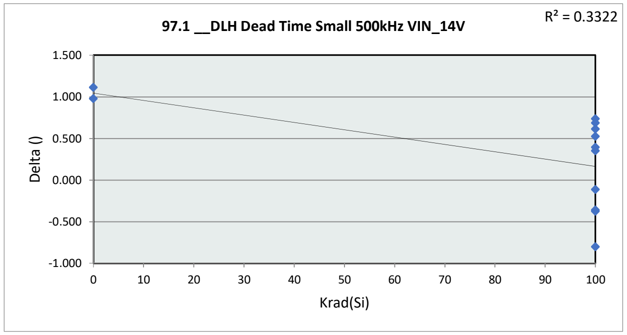


	97.0 __DLH Dead Time Min 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.648	2.537
Average	2.946	3.557
Max	3.244	4.208
UL	10.000	10.000

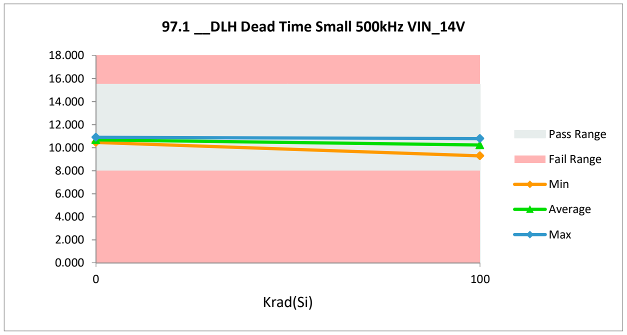


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.1 __DLH Dead Time Small 50(		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.787	10.899	1.112
0	2	9.466	10.445	0.979
100	23	10.068	10.418	0.350
100	24	10.533	9.732	-0.801
100	25	10.105	10.789	0.684
100	26	9.628	9.268	-0.360
100	27	10.347	10.233	-0.114
100	48u	10.054	10.577	0.523
100	49u	10.112	10.726	0.613
100	50u	10.018	9.643	-0.374
100	51u	10.007	10.400	0.393
100	52u	9.782	10.518	0.736
	Max	10.533	10.899	1.112
	Average	9.992	10.304	0.312
	Min	9.466	9.268	-0.801
	Std Dev	0.294	0.502	0.595

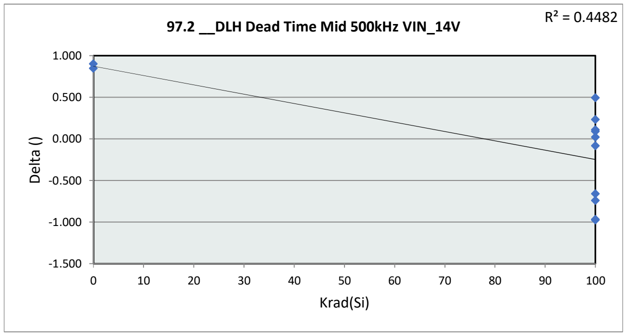


	97.1 __DLH Dead Time Small 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.445	9.268
Average	10.672	10.230
Max	10.899	10.789
UL	15.500	15.500

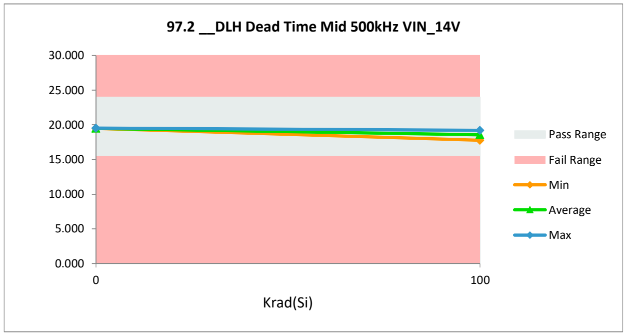


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.2 __DLH Dead Time Mid 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.665	19.513	0.847
0	2	18.565	19.466	0.901
100	23	18.285	18.778	0.494
100	24	18.894	18.153	-0.741
100	25	19.099	19.190	0.090
100	26	18.733	17.765	-0.967
100	27	19.154	18.494	-0.660
100	48u	18.717	18.738	0.020
100	49u	18.841	18.952	0.111
100	50u	18.803	17.831	-0.972
100	51u	18.861	18.781	-0.080
100	52u	18.856	19.090	0.233
	Max	19.154	19.513	0.901
	Average	18.790	18.729	-0.060
	Min	18.285	17.765	-0.972
	Std Dev	0.230	0.578	0.652



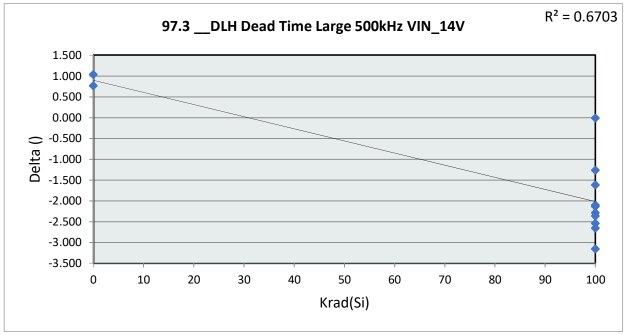
	97.2 __DLH Dead Time Mid 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.466	17.765
Average	19.489	18.577
Max	19.513	19.190
UL	24.000	24.000



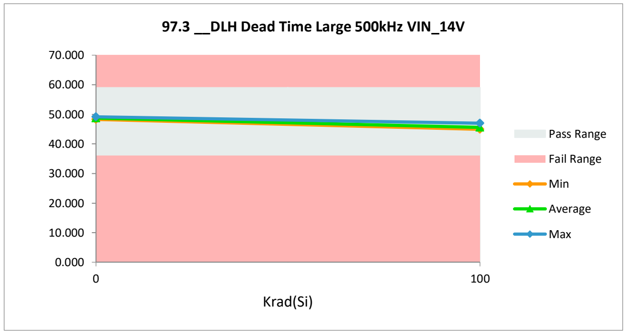
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.3 __DLH Dead Time Large 50	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	59	59
Min Limit	36	36

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	47.517	48.281	0.764
0	2	48.182	49.211	1.029
100	23	45.446	45.429	-0.016
100	24	46.307	45.036	-1.271
100	25	48.542	46.175	-2.367
100	26	48.283	45.126	-3.156
100	27	48.369	45.822	-2.548
100	48u	47.377	45.083	-2.294
100	49u	47.707	45.570	-2.137
100	50u	47.610	44.947	-2.662
100	51u	48.238	46.132	-2.106
100	52u	48.590	46.966	-1.624
	Max	48.590	49.211	1.029
	Average	47.681	46.148	-1.532
	Min	45.446	44.947	-3.156
	Std Dev	0.952	1.362	1.386

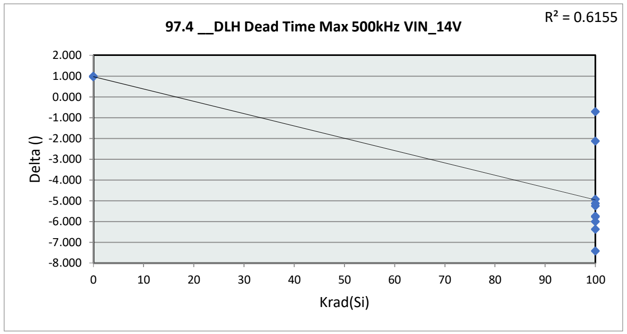


	97.3 __DLH Dead Time Large 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	48.281	44.947
Average	48.746	45.629
Max	49.211	46.966
UL	59.000	59.000

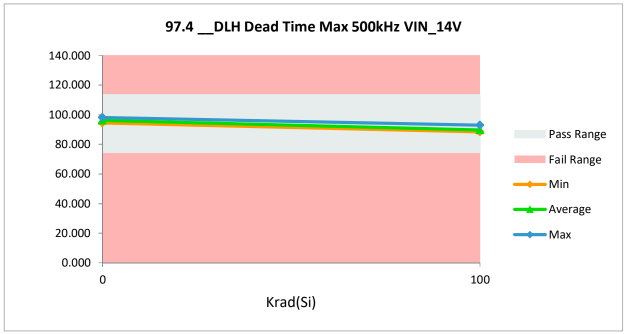


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.4 __DLH Dead Time Max 500k		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		113.5	113.5	
Min Limit		74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	93.518	94.497	0.979
0	2	97.044	98.003	0.958
100	23	89.387	88.658	-0.729
100	24	90.983	88.852	-2.131
100	25	96.376	89.994	-6.382
100	26	96.678	89.252	-7.426
100	27	95.253	90.115	-5.139
100	48u	94.064	88.307	-5.757
100	49u	94.662	88.653	-6.009
100	50u	94.311	88.527	-5.784
100	51u	96.141	90.885	-5.256
100	52u	97.950	93.010	-4.940
	Max	97.950	98.003	0.979
	Average	94.697	90.729	-3.968
	Min	89.387	88.307	-7.426
	Std Dev	2.507	2.989	2.939

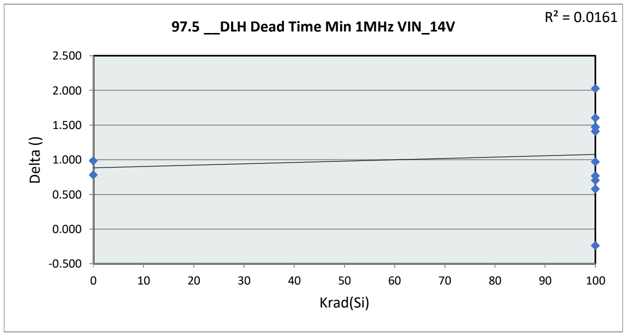


	97.4 __DLH Dead Time Max 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	94.497	88.307
Average	96.250	89.625
Max	98.003	93.010
UL	113.500	113.500

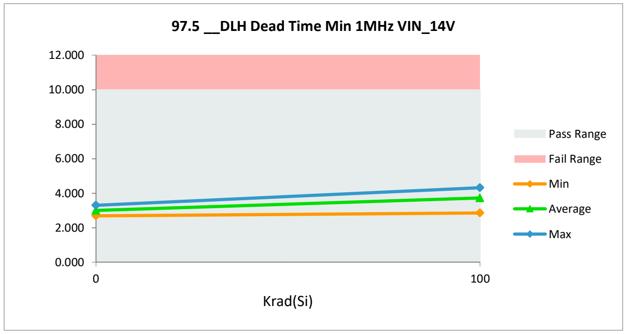


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.5 __DLH Dead Time Min 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.523	3.305	0.782
0	2	1.706	2.690	0.984
100	23	3.051	3.818	0.767
100	24	3.331	3.095	-0.236
100	25	2.708	4.310	1.603
100	26	2.275	2.854	0.579
100	27	2.758	3.729	0.971
100	48u	2.589	4.061	1.473
100	49u	2.721	4.191	1.470
100	50u	2.481	3.184	0.703
100	51u	2.497	3.907	1.410
100	52u	2.048	4.078	2.029
	Max	3.331	4.310	2.029
	Average	2.557	3.602	1.044
	Min	1.706	2.690	-0.236
	Std Dev	0.427	0.552	0.596

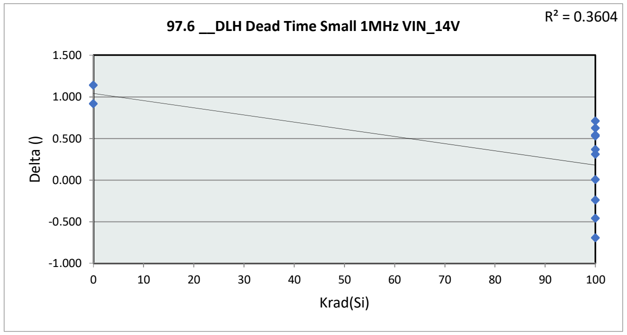


	97.5 __DLH Dead Time Min 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	2.690	2.854
Average	2.997	3.723
Max	3.305	4.310
UL	10.000	10.000

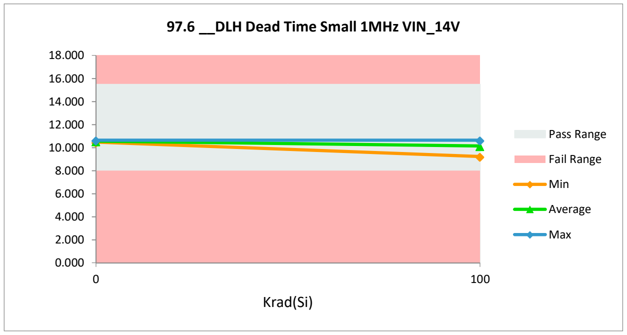


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.6 __DLH Dead Time Small 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	15.5	15.5	
	Min Limit	8	8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.705	10.632	0.927
0	2	9.330	10.481	1.152
100	23	9.925	10.246	0.321
100	24	10.298	9.613	-0.685
100	25	10.091	10.632	0.540
100	26	9.450	9.219	-0.231
100	27	10.266	10.281	0.015
100	48u	9.986	10.362	0.376
100	49u	10.004	10.641	0.637
100	50u	9.985	9.535	-0.451
100	51u	9.875	10.424	0.549
100	52u	9.744	10.462	0.718
	Max	10.298	10.641	1.152
	Average	9.888	10.211	0.322
	Min	9.330	9.219	-0.685
	Std Dev	0.293	0.481	0.558

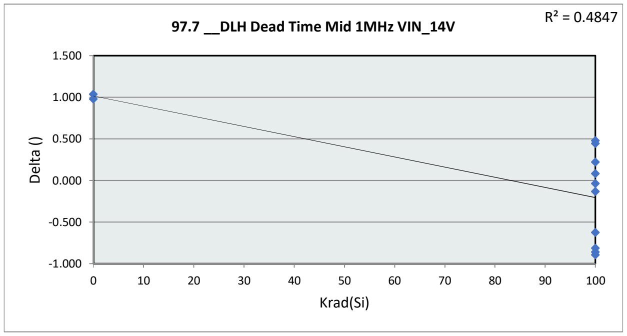


	97.6 __DLH Dead Time Small 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.482	9.220
Average	10.557	10.142
Max	10.632	10.641
UL	15.500	15.500

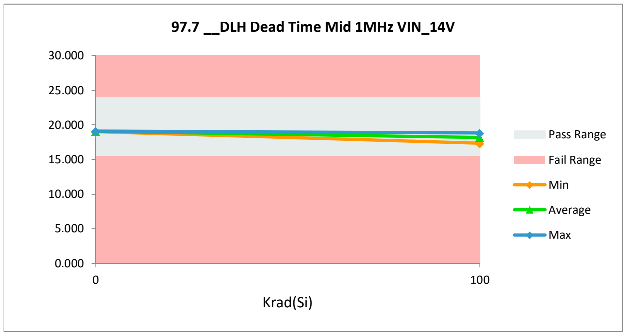


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.7 __DLH Dead Time Mid 1MHz		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.143	19.128	0.985
0	2	17.984	19.028	1.044
100	23	17.973	18.461	0.488
100	24	18.490	17.638	-0.852
100	25	18.732	18.823	0.092
100	26	18.232	17.346	-0.886
100	27	18.779	18.164	-0.615
100	48u	18.315	18.192	-0.123
100	49u	18.414	18.642	0.228
100	50u	18.374	17.570	-0.803
100	51u	18.521	18.494	-0.027
100	52u	18.314	18.764	0.451
	Max	18.779	19.128	1.044
	Average	18.356	18.354	-0.002
	Min	17.973	17.346	-0.886
	Std Dev	0.255	0.585	0.682

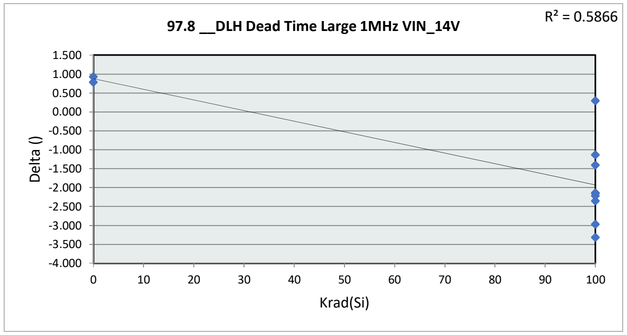


	97.7 __DLH Dead Time Mid 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.028	17.346
Average	19.078	18.210
Max	19.128	18.823
UL	24.000	24.000

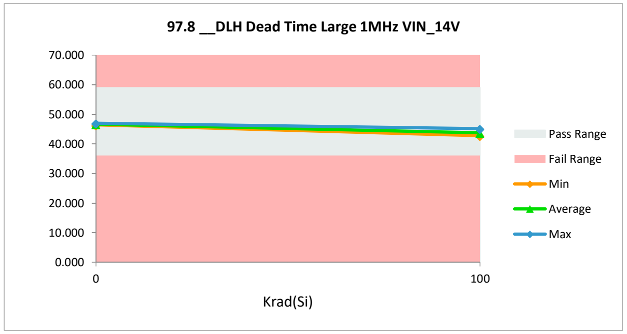


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.8 __DLH Dead Time Large 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.601	46.406	0.805
0	2	46.073	47.020	0.947
100	23	43.383	43.698	0.315
100	24	44.288	43.179	-1.110
100	25	46.521	44.185	-2.336
100	26	46.394	43.097	-3.298
100	27	46.235	44.108	-2.127
100	48u	45.509	43.312	-2.197
100	49u	45.840	43.715	-2.125
100	50u	45.702	42.757	-2.945
100	51u	46.257	44.140	-2.117
100	52u	46.592	45.207	-1.385
	Max	46.592	47.020	0.947
	Average	45.700	44.235	-1.464
	Min	43.383	42.757	-3.298
	Std Dev	0.959	1.330	1.428

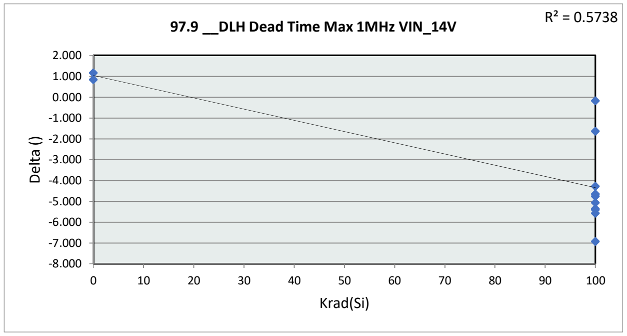


	97.8 __DLH Dead Time Large 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.406	42.757
Average	46.713	43.740
Max	47.020	45.207
UL	59.000	59.000

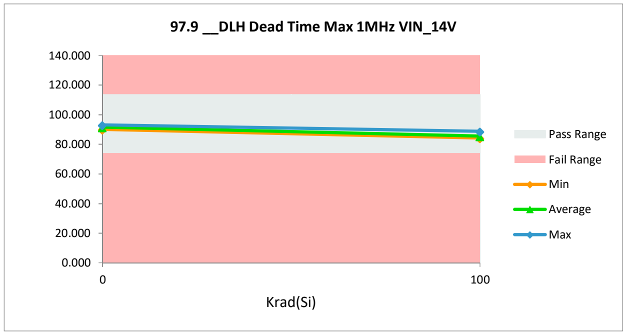


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.9 __DLH Dead Time Max 1MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	88.905	90.102	1.197
0	2	92.330	93.204	0.874
100	23	84.773	84.637	-0.136
100	24	86.416	84.812	-1.604
100	25	91.501	85.973	-5.528
100	26	91.799	84.908	-6.891
100	27	90.579	85.961	-4.618
100	48u	89.377	84.346	-5.031
100	49u	89.838	84.514	-5.324
100	50u	89.570	84.212	-5.359
100	51u	91.409	86.681	-4.727
100	52u	93.031	88.789	-4.241
	Max	93.031	93.204	1.197
	Average	89.961	86.512	-3.449
	Min	84.773	84.212	-6.891
	Std Dev	2.419	2.803	2.765

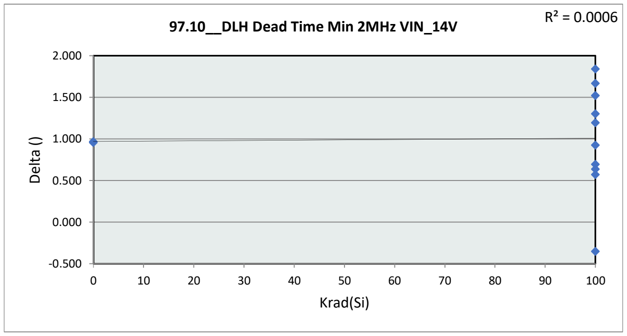


	97.9 __DLH Dead Time Max 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	90.102	84.212
Average	91.653	85.483
Max	93.204	88.789
UL	113.500	113.500

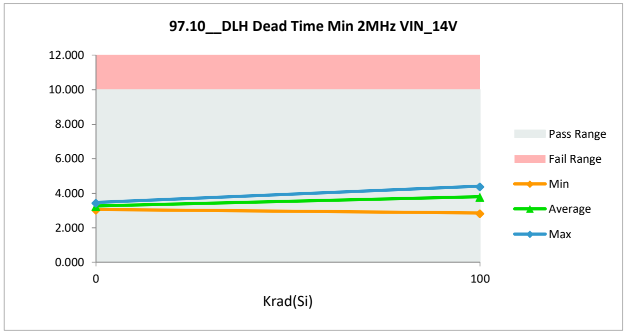


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.10__DLH Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.485	3.461	0.977
0	2	2.092	3.057	0.965
100	23	3.289	3.991	0.702
100	24	3.624	3.282	-0.342
100	25	2.875	4.406	1.531
100	26	2.213	2.859	0.646
100	27	2.867	3.799	0.932
100	48u	2.858	4.061	1.203
100	49u	2.705	4.380	1.675
100	50u	2.695	3.276	0.581
100	51u	2.548	3.858	1.310
100	52u	2.295	4.141	1.846
	Max	3.624	4.406	1.846
	Average	2.712	3.714	1.002
	Min	2.092	2.859	-0.342
	Std Dev	0.439	0.517	0.587



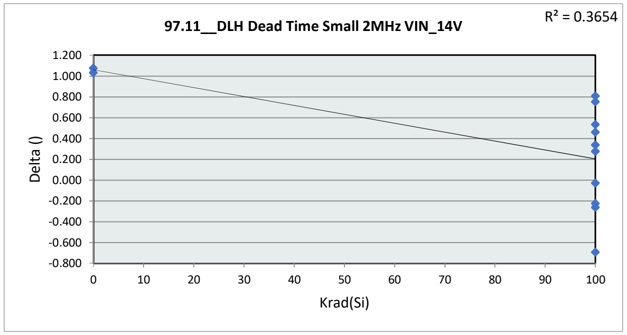
	97.10__DLH Dead Time Min 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.057	2.859
Average	3.259	3.805
Max	3.461	4.406
UL	10.000	10.000



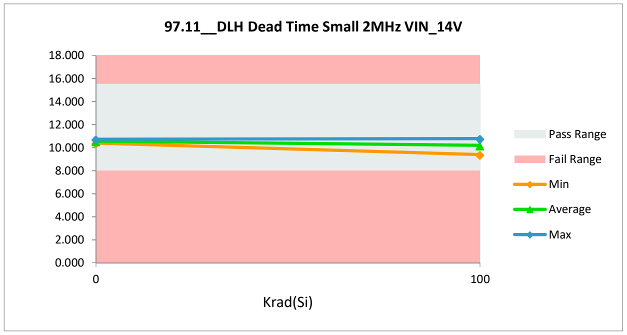
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.11__DLH Dead Time Small 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15.5	15.5
Min Limit	8	8

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.653	10.737	1.083
0	2	9.350	10.388	1.039
100	23	9.908	10.375	0.467
100	24	10.278	9.592	-0.687
100	25	10.016	10.776	0.760
100	26	9.643	9.388	-0.255
100	27	10.295	10.275	-0.020
100	48u	9.957	10.302	0.345
100	49u	10.070	10.611	0.541
100	50u	9.930	9.711	-0.219
100	51u	9.972	10.256	0.285
100	52u	9.775	10.591	0.816
	Max	10.295	10.776	1.083
	Average	9.904	10.250	0.346
	Min	9.350	9.388	-0.687
	Std Dev	0.269	0.454	0.552

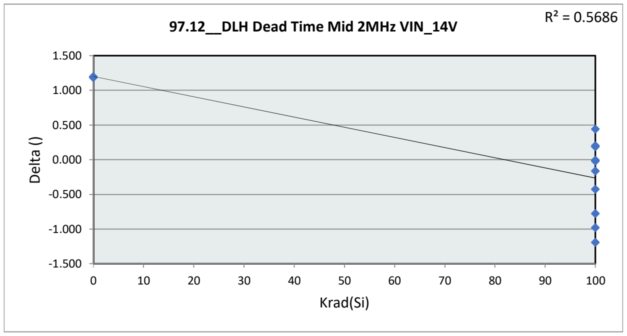


	97.11__DLH Dead Time Small 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15.5	
Min Limit	8	
Krad(Si)	0	100
LL	8.000	8.000
Min	10.388	9.388
Average	10.563	10.188
Max	10.737	10.776
UL	15.500	15.500

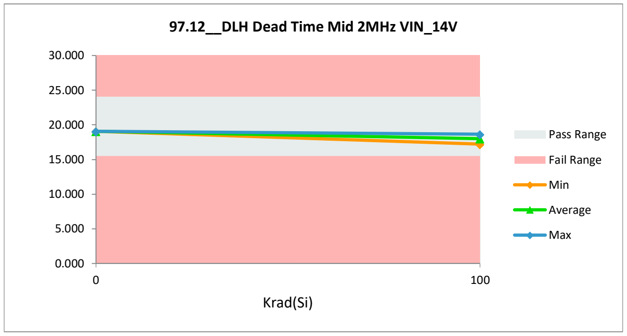


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.12__DLH Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24	24	
Min Limit		15.5	15.5	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	17.842	19.052	1.209
0	2	17.890	19.084	1.194
100	23	17.733	18.185	0.452
100	24	18.390	17.417	-0.972
100	25	18.441	18.635	0.195
100	26	18.069	17.302	-0.767
100	27	18.574	18.158	-0.416
100	48u	18.189	18.191	0.003
100	49u	18.383	18.371	-0.012
100	50u	18.426	17.243	-1.183
100	51u	18.289	18.134	-0.155
100	52u	18.436	18.648	0.212
	Max	18.574	19.084	1.209
	Average	18.222	18.202	-0.020
	Min	17.733	17.243	-1.183
	Std Dev	0.276	0.623	0.757

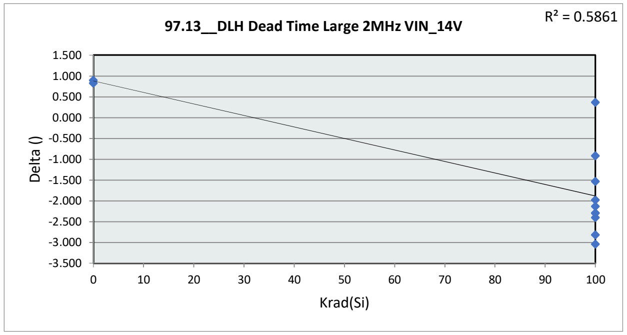


	97.12__DLH Dead Time Mid 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24	
Min Limit	15.5	
Krad(Si)	0	100
LL	15.500	15.500
Min	19.052	17.243
Average	19.068	18.029
Max	19.084	18.648
UL	24.000	24.000

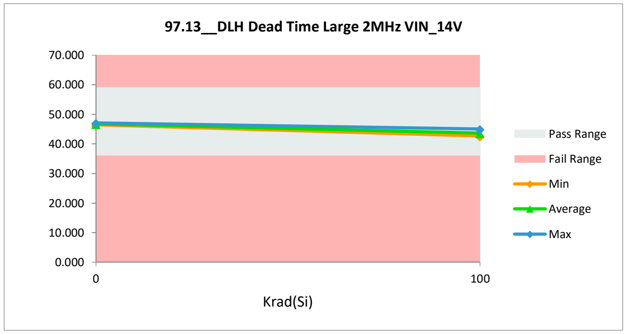


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.13__DLH Dead Time Large 2		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		59	59	
Min Limit		36	36	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	45.511	46.428	0.916
0	2	46.246	47.095	0.849
100	23	43.345	43.731	0.386
100	24	44.011	43.115	-0.896
100	25	46.486	44.212	-2.274
100	26	46.170	43.149	-3.021
100	27	46.292	43.910	-2.381
100	48u	45.551	43.272	-2.279
100	49u	45.576	43.618	-1.958
100	50u	45.523	42.727	-2.796
100	51u	46.101	43.989	-2.111
100	52u	46.607	45.096	-1.511
	Max	46.607	47.095	0.916
	Average	45.618	44.195	-1.423
	Min	43.345	42.727	-3.021
	Std Dev	0.995	1.353	1.407

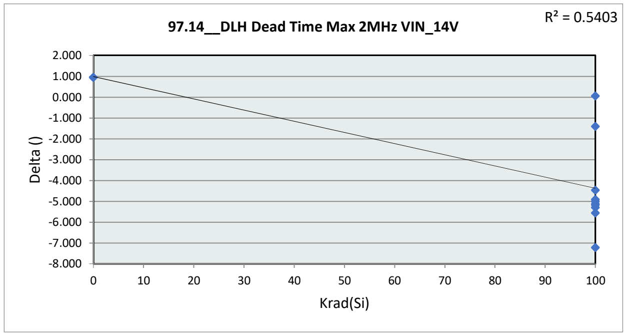


	97.13__DLH Dead Time Large 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	59	
Min Limit	36	
Krad(Si)	0	100
LL	36.000	36.000
Min	46.428	42.727
Average	46.761	43.682
Max	47.095	45.096
UL	59.000	59.000

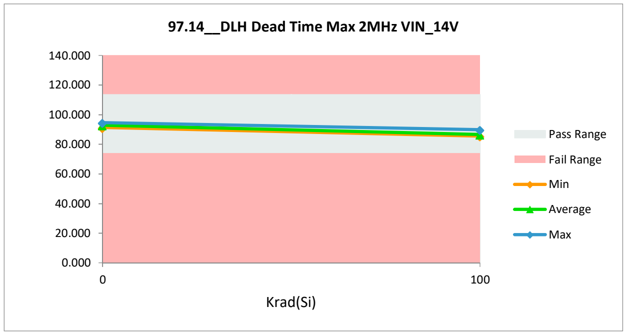


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.14__DLH Dead Time Max 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	113.5	113.5	
	Min Limit	74	74	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	90.321	91.300	0.979
0	2	93.654	94.646	0.992
100	23	85.805	85.897	0.093
100	24	87.479	86.117	-1.363
100	25	92.836	87.314	-5.521
100	26	93.438	86.251	-7.186
100	27	91.961	87.086	-4.876
100	48u	90.562	85.472	-5.090
100	49u	91.202	85.940	-5.261
100	50u	90.774	85.638	-5.136
100	51u	92.839	87.878	-4.961
100	52u	94.386	89.955	-4.432
	Max	94.386	94.646	0.992
	Average	91.271	87.791	-3.480
	Min	85.805	85.472	-7.186
	Std Dev	2.547	2.811	2.838

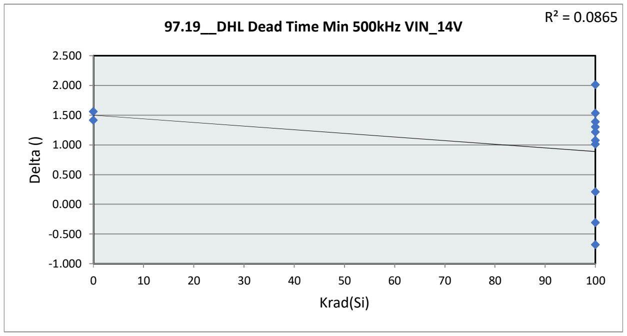


	97.14__DLH Dead Time Max 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	113.5	
Min Limit	74	
Krad(Si)	0	100
LL	74.000	74.000
Min	91.300	85.472
Average	92.973	86.755
Max	94.646	89.955
UL	113.500	113.500

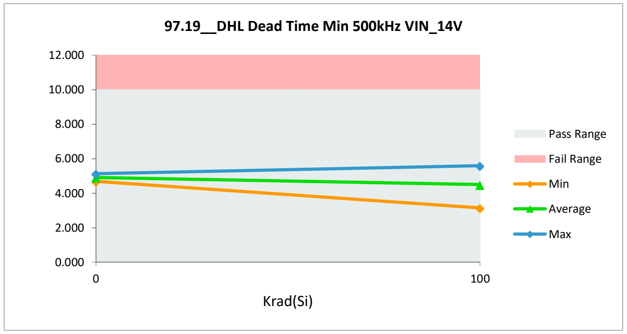


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.19__DHL Dead Time Min 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	10	10	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.256	4.684	1.428
0	2	3.561	5.134	1.573
100	23	3.008	5.033	2.025
100	24	3.040	4.129	1.089
100	25	3.858	4.879	1.021
100	26	3.820	3.154	-0.666
100	27	3.819	3.522	-0.298
100	48u	3.652	5.052	1.400
100	49u	3.422	4.651	1.229
100	50u	3.579	3.802	0.223
100	51u	3.576	5.119	1.543
100	52u	4.283	5.596	1.313
	Max	4.283	5.596	2.025
	Average	3.573	4.563	0.990
	Min	3.008	3.154	-0.666
	Std Dev	0.362	0.746	0.811



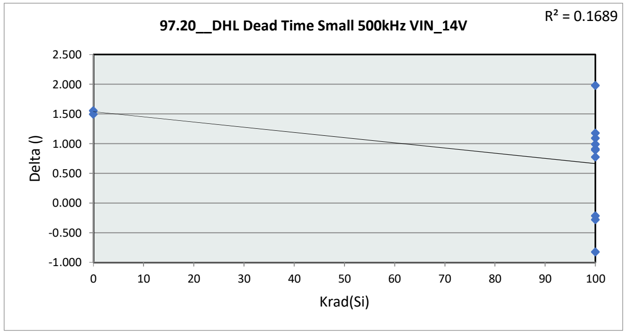
	97.19__DHL Dead Time Min 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.684	3.154
Average	4.909	4.494
Max	5.134	5.596
UL	10.000	10.000



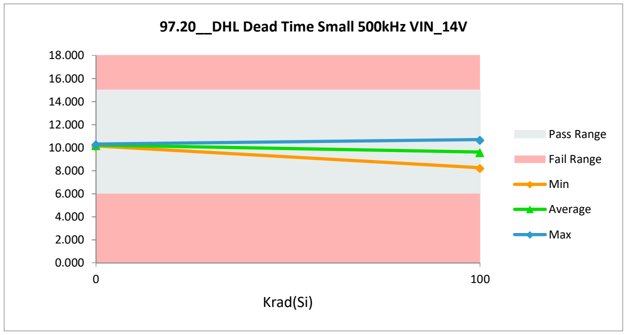
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.20__DHL Dead Time Small 50	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.569	10.139	1.570
0	2	8.796	10.308	1.512
100	23	8.396	10.391	1.995
100	24	8.413	9.321	0.908
100	25	9.148	9.939	0.791
100	26	9.059	8.249	-0.811
100	27	9.066	8.800	-0.267
100	48u	9.338	10.446	1.108
100	49u	8.778	9.779	1.002
100	50u	8.862	8.659	-0.203
100	51u	9.040	9.964	0.924
100	52u	9.490	10.684	1.194
	Max	9.490	10.684	1.995
	Average	8.913	9.723	0.810
	Min	8.396	8.249	-0.811
	Std Dev	0.344	0.788	0.830

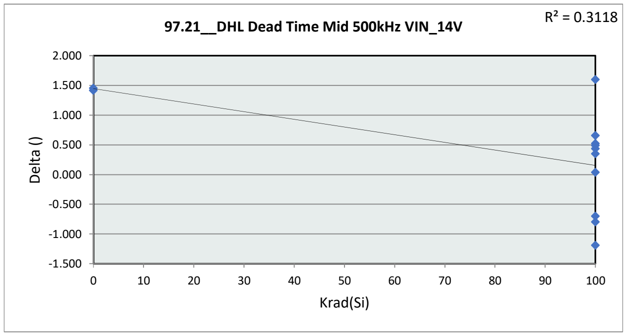


	97.20__DHL Dead Time Small 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.139	8.249
Average	10.223	9.623
Max	10.308	10.684
UL	15.000	15.000

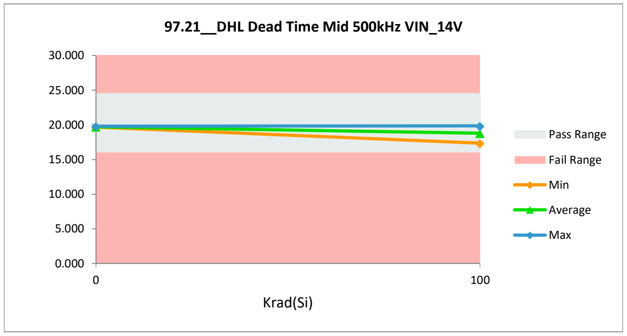


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.21__DHL Dead Time Mid 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	24.5	24.5	
	Min Limit	16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.389	19.817	1.428
0	2	18.192	19.658	1.466
100	23	18.090	19.701	1.611
100	24	17.981	18.430	0.449
100	25	18.986	19.036	0.050
100	26	18.558	17.381	-1.177
100	27	18.772	18.083	-0.689
100	48u	19.195	19.865	0.669
100	49u	18.366	18.727	0.361
100	50u	18.560	17.772	-0.788
100	51u	18.661	19.164	0.503
100	52u	19.053	19.587	0.534
	Max	19.195	19.865	1.611
	Average	18.567	18.935	0.368
	Min	17.981	17.381	-1.177
	Std Dev	0.386	0.855	0.903



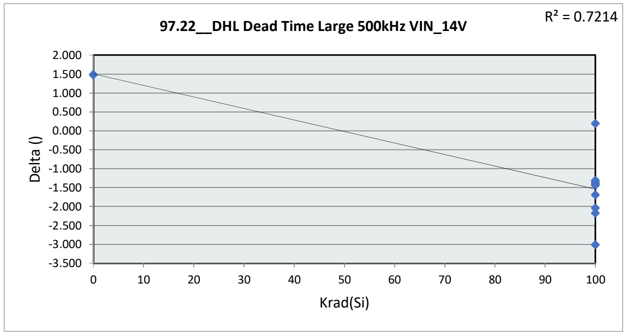
	97.21__DHL Dead Time Mid 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	19.658	17.381
Average	19.738	18.774
Max	19.817	19.865
UL	24.500	24.500



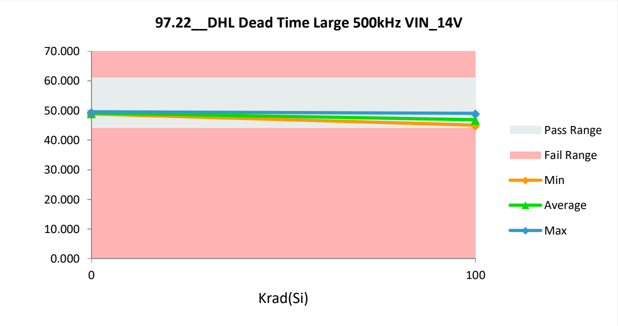
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.22__DHL Dead Time Large 50	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	61	61
Min Limit	44	44

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.036	49.537	1.501
0	2	47.369	48.876	1.508
100	23	48.150	48.364	0.214
100	24	48.040	46.370	-1.670
100	25	49.020	47.001	-2.019
100	26	47.857	45.708	-2.149
100	27	48.383	47.092	-1.291
100	48u	50.366	49.009	-1.356
100	49u	47.803	46.409	-1.393
100	50u	48.056	45.065	-2.990
100	51u	48.154	46.812	-1.342
100	52u	48.293	46.879	-1.414
	Max	50.366	49.537	1.508
	Average	48.294	47.260	-1.034
	Min	47.369	45.065	-2.990
	Std Dev	0.759	1.390	1.396

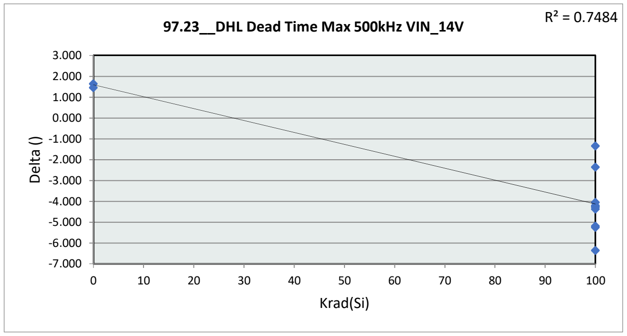


	97.22__DHL Dead Time Large 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	48.876	45.065
Average	49.206	46.871
Max	49.537	49.009
UL	61.000	61.000

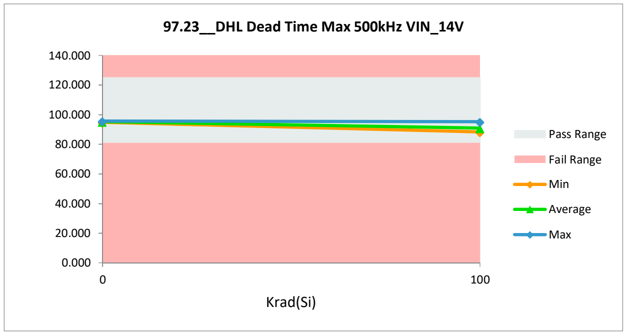


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.23__DHL Dead Time Max 500		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	94.085	95.768	1.684
0	2	93.441	94.934	1.493
100	23	94.873	93.562	-1.311
100	24	95.208	90.063	-5.144
100	25	96.174	90.967	-5.206
100	26	93.648	89.633	-4.015
100	27	94.893	92.576	-2.317
100	48u	99.533	95.366	-4.167
100	49u	93.904	89.692	-4.212
100	50u	94.661	88.344	-6.318
100	51u	94.685	90.439	-4.246
100	52u	93.944	89.601	-4.343
	Max	99.533	95.768	1.684
	Average	94.921	91.746	-3.175
	Min	93.441	88.344	-6.318
	Std Dev	1.639	2.584	2.572

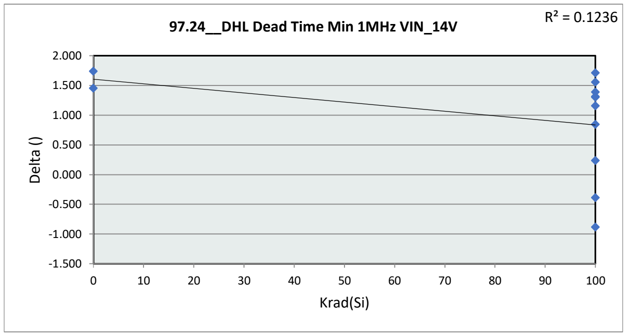


	97.23__DHL Dead Time Max 500kHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	94.934	88.344
Average	95.351	91.024
Max	95.768	95.366
UL	125.000	125.000

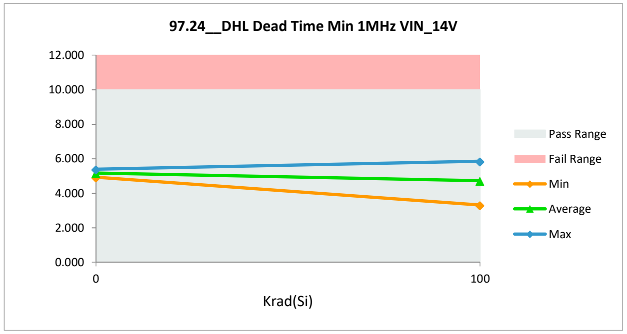


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.24__DHL Dead Time Min 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.473	4.936	1.463
0	2	3.645	5.392	1.747
100	23	3.419	5.141	1.722
100	24	3.305	4.473	1.169
100	25	4.106	4.962	0.856
100	26	4.187	3.313	-0.874
100	27	4.116	3.739	-0.376
100	48u	3.930	5.497	1.567
100	49u	3.644	4.969	1.325
100	50u	3.767	4.014	0.247
100	51u	3.857	5.259	1.402
100	52u	4.535	5.851	1.316
	Max	4.535	5.851	1.747
	Average	3.832	4.795	0.964
	Min	3.305	3.313	-0.874
	Std Dev	0.362	0.763	0.852

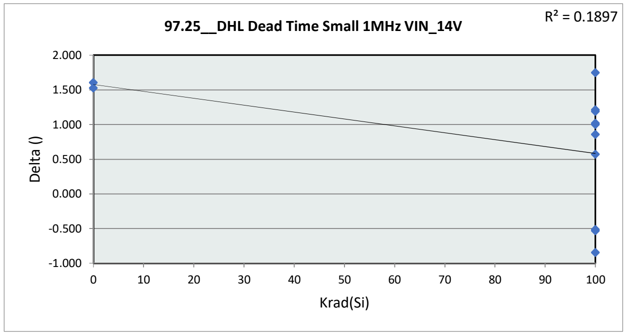


	97.24__DHL Dead Time Min 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.936	3.313
Average	5.164	4.722
Max	5.392	5.851
UL	10.000	10.000

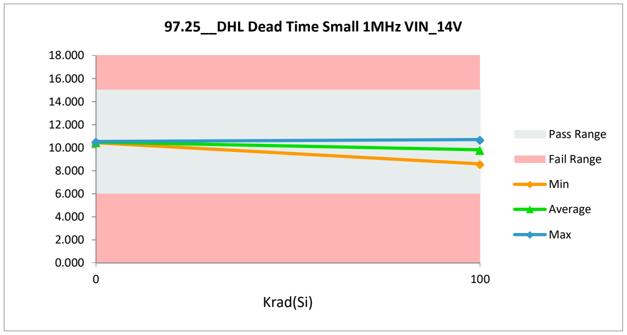


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.25__DHL Dead Time Small 1M		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		15	15	
Min Limit		6	6	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	8.799	10.416	1.617
0	2	9.005	10.544	1.539
100	23	8.741	10.502	1.761
100	24	8.523	9.536	1.013
100	25	9.519	10.102	0.583
100	26	9.432	8.599	-0.833
100	27	9.577	9.056	-0.521
100	48u	9.352	10.577	1.225
100	49u	9.103	9.972	0.870
100	50u	9.264	8.764	-0.500
100	51u	9.097	10.298	1.200
100	52u	9.674	10.706	1.032
	Max	9.674	10.706	1.761
	Average	9.174	9.923	0.749
	Min	8.523	8.599	-0.833
	Std Dev	0.361	0.749	0.889

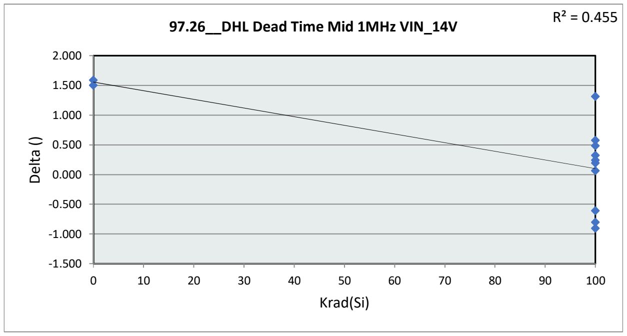


	97.25__DHL Dead Time Small 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.416	8.599
Average	10.480	9.811
Max	10.544	10.706
UL	15.000	15.000

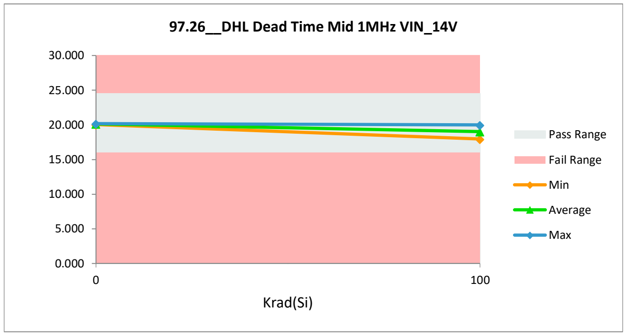


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.26__DHL Dead Time Mid 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.674	20.188	1.514
0	2	18.451	20.049	1.597
100	23	18.560	19.883	1.322
100	24	18.471	18.723	0.252
100	25	19.343	19.421	0.078
100	26	18.847	17.956	-0.891
100	27	19.144	18.547	-0.596
100	48u	19.390	19.975	0.585
100	49u	18.675	19.006	0.332
100	50u	18.792	18.003	-0.789
100	51u	18.977	19.181	0.204
100	52u	19.281	19.777	0.496
	Max	19.390	20.188	1.597
	Average	18.884	19.226	0.342
	Min	18.451	17.956	-0.891
	Std Dev	0.339	0.787	0.841

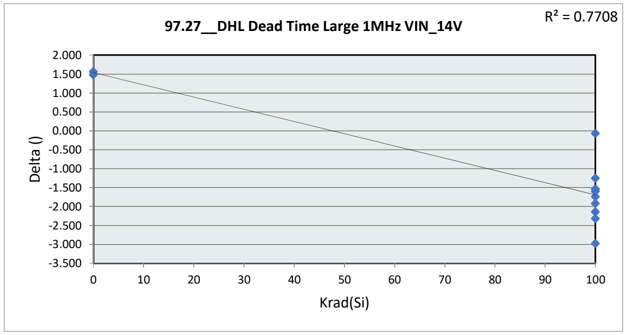


	97.26__DHL Dead Time Mid 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.049	17.956
Average	20.118	19.047
Max	20.188	19.975
UL	24.500	24.500

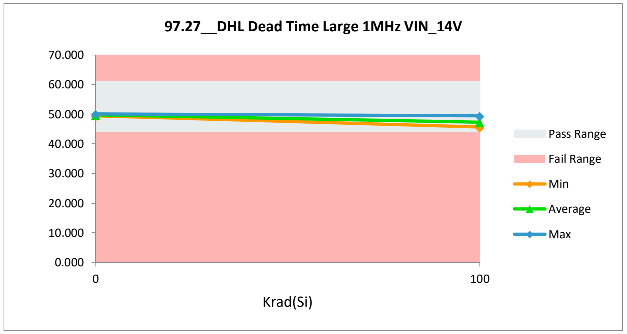


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.27__DHL Dead Time Large 1M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	48.625	50.123	1.498
0	2	47.911	49.494	1.584
100	23	48.729	48.678	-0.051
100	24	48.626	46.724	-1.902
100	25	49.635	47.336	-2.300
100	26	48.298	46.177	-2.121
100	27	48.717	47.488	-1.229
100	48u	50.993	49.471	-1.522
100	49u	48.347	46.768	-1.579
100	50u	48.628	45.675	-2.953
100	51u	48.746	47.229	-1.517
100	52u	48.937	47.219	-1.718
	Max	50.993	50.123	1.584
	Average	48.849	47.699	-1.151
	Min	47.911	45.675	-2.953
	Std Dev	0.789	1.416	1.432

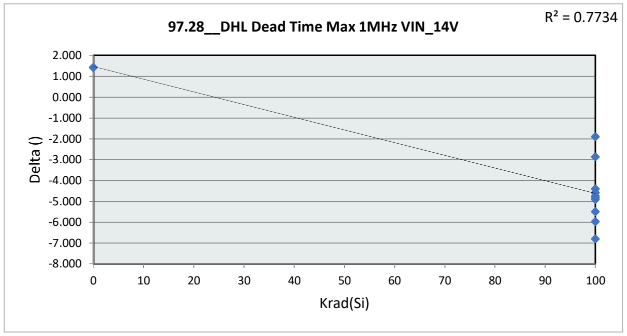


	97.27__DHL Dead Time Large 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	49.494	45.675
Average	49.809	47.277
Max	50.123	49.471
UL	61.000	61.000

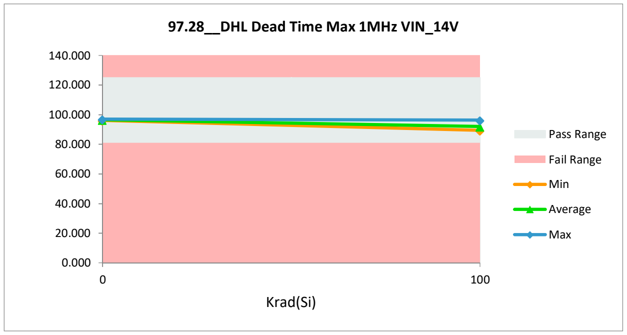


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.28__DHL Dead Time Max 1MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		125	125	
Min Limit		81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	95.633	97.100	1.467
0	2	94.702	96.171	1.469
100	23	96.315	94.461	-1.854
100	24	96.529	91.072	-5.457
100	25	97.767	91.835	-5.932
100	26	95.075	90.704	-4.371
100	27	96.424	93.593	-2.831
100	48u	101.295	96.424	-4.871
100	49u	95.385	90.828	-4.557
100	50u	96.186	89.414	-6.772
100	51u	96.004	91.297	-4.706
100	52u	95.388	90.588	-4.801
	Max	101.295	97.100	1.469
	Average	96.392	92.791	-3.601
	Min	94.702	89.414	-6.772
	Std Dev	1.741	2.649	2.693

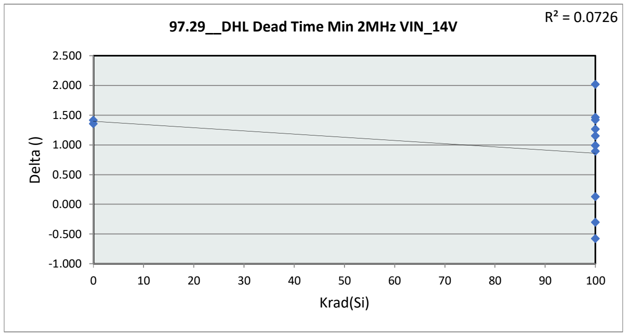


	97.28__DHL Dead Time Max 1MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	96.171	89.414
Average	96.636	92.022
Max	97.100	96.424
UL	125.000	125.000

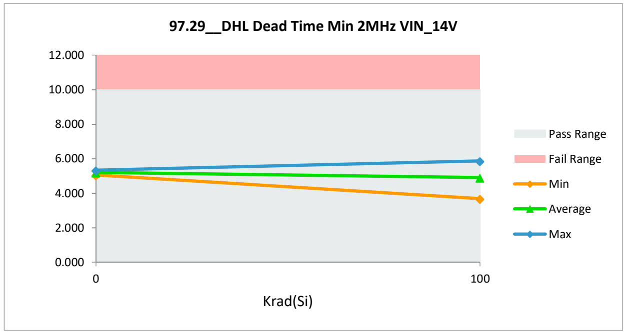


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.29__DHL Dead Time Min 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		10	10	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.693	5.059	1.366
0	2	3.911	5.340	1.429
100	23	3.598	5.628	2.030
100	24	3.595	4.594	0.999
100	25	4.446	5.351	0.905
100	26	4.257	3.691	-0.566
100	27	4.185	3.895	-0.290
100	48u	3.935	5.411	1.476
100	49u	3.808	4.972	1.164
100	50u	3.944	4.084	0.140
100	51u	4.095	5.527	1.432
100	52u	4.607	5.880	1.274
	Max	4.607	5.880	2.030
	Average	4.006	4.953	0.947
	Min	3.595	3.691	-0.566
	Std Dev	0.323	0.724	0.782



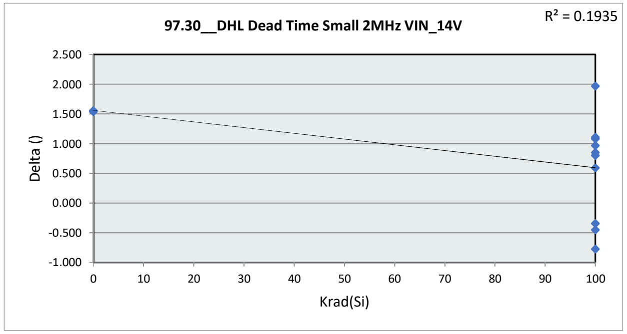
	97.29__DHL Dead Time Min 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	10	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.059	3.691
Average	5.200	4.903
Max	5.340	5.880
UL	10.000	10.000



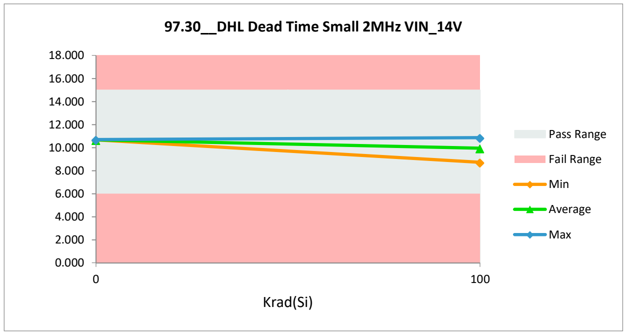
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	97.30__DHL Dead Time Small 2M	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	15	15
Min Limit	6	6

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	9.087	10.657	1.570
0	2	9.146	10.697	1.552
100	23	8.869	10.851	1.982
100	24	8.823	9.685	0.862
100	25	9.579	10.186	0.607
100	26	9.496	8.734	-0.762
100	27	9.518	9.189	-0.329
100	48u	9.534	10.659	1.125
100	49u	9.269	10.086	0.817
100	50u	9.374	8.934	-0.440
100	51u	9.212	10.193	0.981
100	52u	9.779	10.875	1.096
	Max	9.779	10.875	1.982
	Average	9.307	10.062	0.755
	Min	8.823	8.734	-0.762
	Std Dev	0.293	0.761	0.856

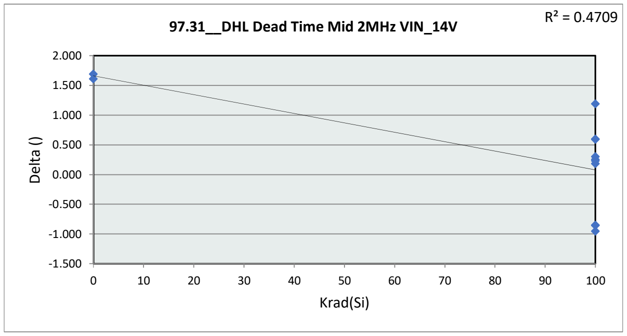


	97.30__DHL Dead Time Small 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	15	
Min Limit	6	
Krad(Si)	0	100
LL	6.000	6.000
Min	10.657	8.734
Average	10.677	9.939
Max	10.697	10.875
UL	15.000	15.000

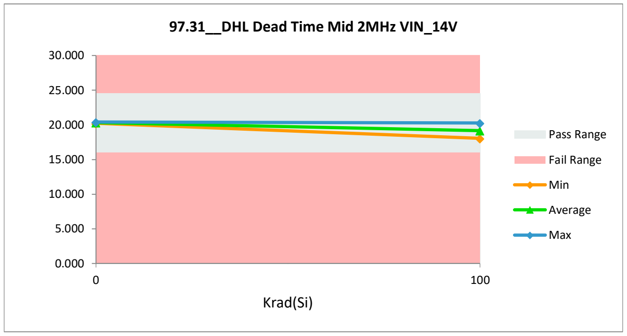


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.31__DHL Dead Time Mid 2MH		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		24.5	24.5	
Min Limit		16	16	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	18.784	20.406	1.621
0	2	18.524	20.225	1.702
100	23	18.665	19.868	1.203
100	24	18.587	18.780	0.193
100	25	19.408	19.653	0.245
100	26	18.967	18.121	-0.846
100	27	19.286	18.448	-0.838
100	48u	19.671	20.273	0.601
100	49u	18.820	19.082	0.262
100	50u	19.004	18.060	-0.944
100	51u	18.955	19.265	0.310
100	52u	19.320	19.926	0.606
	Max	19.671	20.406	1.702
	Average	18.999	19.342	0.343
	Min	18.524	18.060	-0.944
	Std Dev	0.356	0.843	0.897

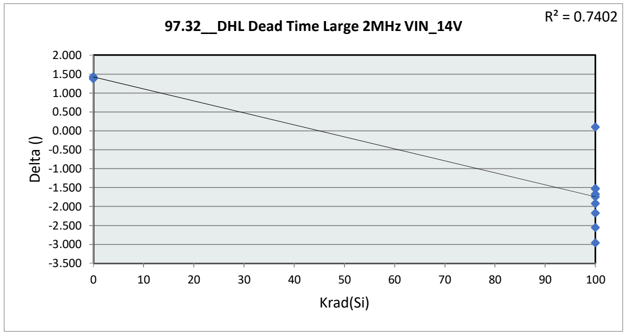


	97.31__DHL Dead Time Mid 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	24.5	
Min Limit	16	
Krad(Si)	0	100
LL	16.000	16.000
Min	20.225	18.060
Average	20.315	19.148
Max	20.406	20.273
UL	24.500	24.500

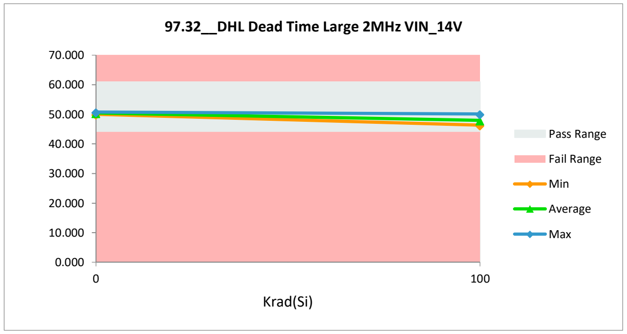


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.32__DHL Dead Time Large 2M		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	61	61	
	Min Limit	44	44	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	49.419	50.816	1.396
0	2	48.607	50.059	1.452
100	23	49.391	49.517	0.125
100	24	49.310	47.413	-1.896
100	25	50.460	47.929	-2.531
100	26	49.007	46.852	-2.154
100	27	49.690	48.182	-1.508
100	48u	51.797	50.140	-1.657
100	49u	49.045	47.327	-1.718
100	50u	49.334	46.394	-2.940
100	51u	49.457	47.801	-1.656
100	52u	49.447	47.946	-1.501
	Max	51.797	50.816	1.452
	Average	49.580	48.365	-1.216
	Min	48.607	46.394	-2.940
	Std Dev	0.825	1.421	1.433

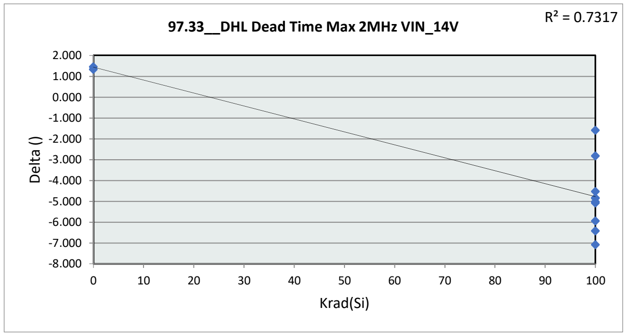


	97.32__DHL Dead Time Large 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	61	
Min Limit	44	
Krad(Si)	0	100
LL	44.000	44.000
Min	50.059	46.394
Average	50.437	47.950
Max	50.816	50.140
UL	61.000	61.000

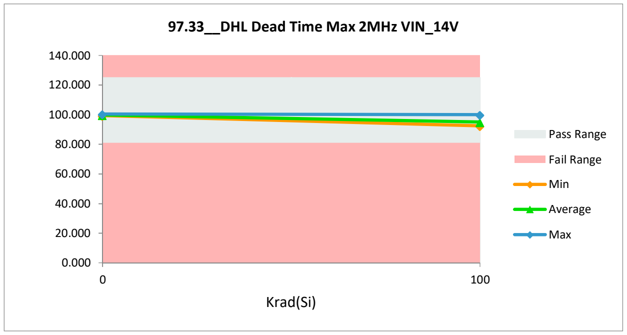


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		97.33__DHL Dead Time Max 2MH		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	125	125	
	Min Limit	81	81	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	99.058	100.433	1.375
0	2	97.919	99.419	1.499
100	23	99.508	97.962	-1.546
100	24	99.944	94.034	-5.910
100	25	101.076	94.688	-6.388
100	26	98.129	93.639	-4.489
100	27	99.855	97.070	-2.785
100	48u	104.806	100.003	-4.803
100	49u	98.510	93.698	-4.813
100	50u	99.529	92.487	-7.043
100	51u	99.448	94.468	-4.980
100	52u	98.690	93.646	-5.045
	Max	104.806	100.433	1.499
	Average	99.706	95.962	-3.744
	Min	97.919	92.487	-7.043
	Std Dev	1.826	2.845	2.829

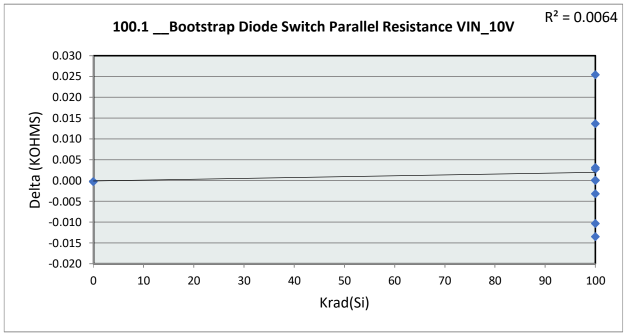


	97.33__DHL Dead Time Max 2MHz VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	125	
Min Limit	81	
Krad(Si)	0	100
LL	81.000	81.000
Min	99.419	92.487
Average	99.926	95.169
Max	100.433	100.003
UL	125.000	125.000

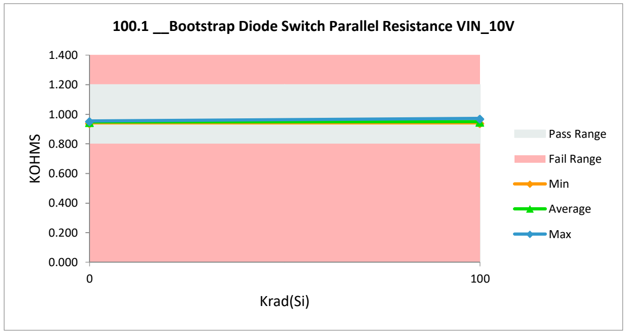


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		100.1 __Bootstrap Diode Switch		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		1.2	1.2	
Min Limit		0.8	0.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.943	0.943	0.000
0	2	0.954	0.954	0.000
100	23	0.946	0.971	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.947	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.960	0.000
100	49u	0.946	0.943	-0.003
100	50u	0.943	0.946	0.003
100	51u	0.945	0.945	0.000
100	52u	0.949	0.949	0.000
	Max	0.960	0.971	0.026
	Average	0.949	0.950	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010

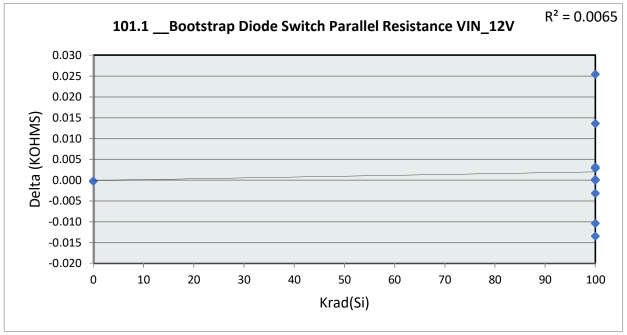


	100.1 __Bootstrap Diode Switch Parallel Resistance VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.951
Max	0.954	0.972
UL	1.200	1.200

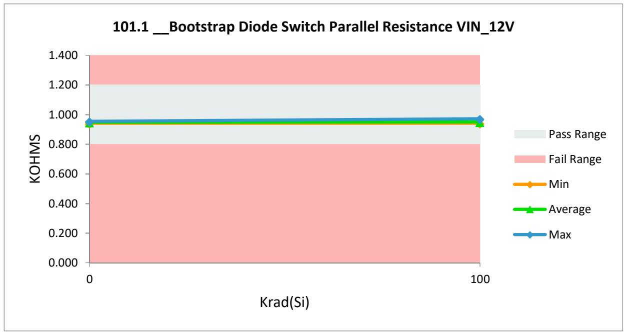


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		101.1 __Bootstrap Diode Switch		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		KOHMS	KOHMS	
Max Limit		1.2	1.2	
Min Limit		0.8	0.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.943	0.943	0.000
0	2	0.955	0.955	0.000
100	23	0.946	0.972	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.948	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.960	0.000
100	49u	0.947	0.943	-0.003
100	50u	0.943	0.947	0.003
100	51u	0.945	0.945	0.000
100	52u	0.949	0.950	0.000
	Max	0.960	0.972	0.026
	Average	0.949	0.951	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010

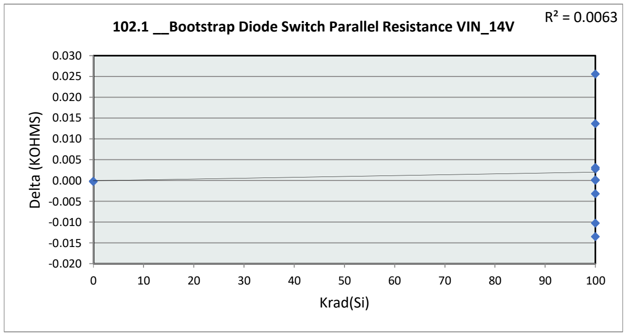


	101.1 __Bootstrap Diode Switch Parallel Resistance VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.951
Max	0.955	0.972
UL	1.200	1.200

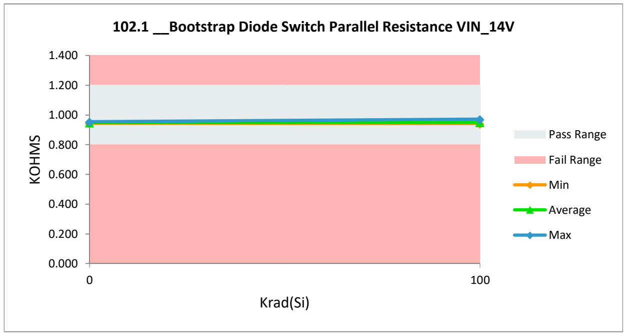


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		102.1 __Bootstrap Diode Switch		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	KOHMS	KOHMS	
	Max Limit	1.2	1.2	
	Min Limit	0.8	0.8	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.943	0.943	0.000
0	2	0.955	0.955	0.000
100	23	0.946	0.972	0.026
100	24	0.955	0.945	-0.010
100	25	0.945	0.948	0.003
100	26	0.955	0.942	-0.013
100	27	0.945	0.959	0.014
100	48u	0.960	0.961	0.000
100	49u	0.947	0.944	-0.003
100	50u	0.943	0.947	0.003
100	51u	0.945	0.945	0.000
100	52u	0.950	0.950	0.000
	Max	0.960	0.972	0.026
	Average	0.949	0.951	0.002
	Min	0.943	0.942	-0.013
	Std Dev	0.006	0.009	0.010

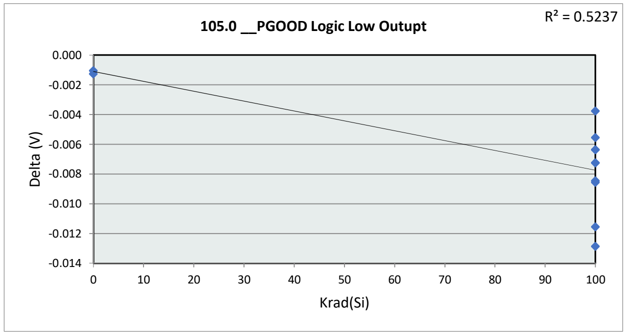


	102.1 __Bootstrap Diode Switch Parallel Resistance VIN	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.2	KOHMS
Min Limit	0.8	KOHMS
Krad(Si)	0	100
LL	0.800	0.800
Min	0.943	0.942
Average	0.949	0.951
Max	0.955	0.972
UL	1.200	1.200

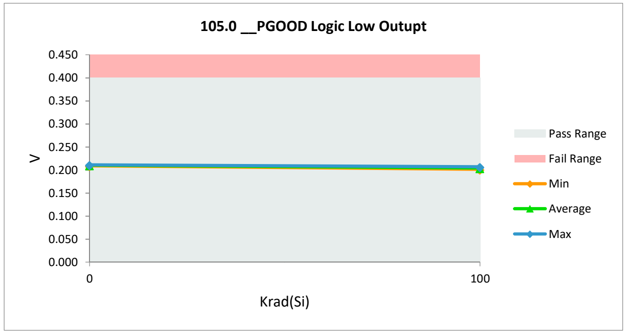


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		105.0 __PGOOD Logic Low Outu		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.4	0.4	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.210	0.209	-0.001
0	2	0.213	0.211	-0.001
100	23	0.214	0.201	-0.013
100	24	0.212	0.205	-0.006
100	25	0.216	0.207	-0.008
100	26	0.213	0.205	-0.007
100	27	0.215	0.204	-0.012
100	48u	0.210	0.205	-0.006
100	49u	0.211	0.202	-0.009
100	50u	0.208	0.205	-0.004
100	51u	0.211	0.204	-0.007
100	52u	0.211	0.205	-0.006
	Max	0.216	0.211	-0.001
	Average	0.212	0.205	-0.007
	Min	0.208	0.201	-0.013
	Std Dev	0.002	0.003	0.004

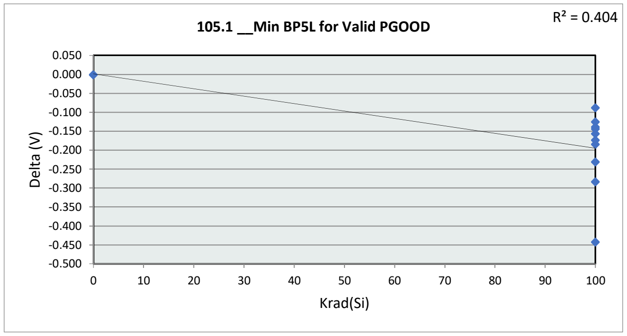


	105.0 __PGOOD Logic Low Output	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.209	0.201
Average	0.210	0.204
Max	0.211	0.207
UL	0.400	0.400

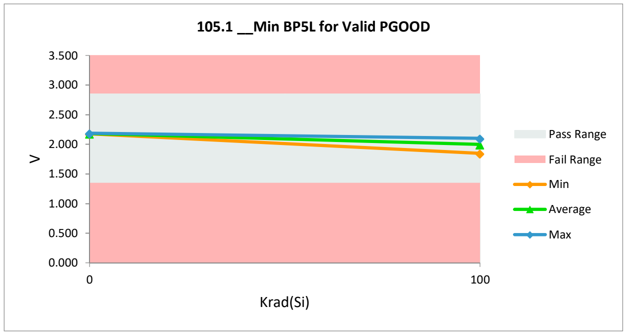


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		105.1 __Min BP5L for Valid PGO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.85	2.85	
	Min Limit	1.35	1.35	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.174	2.175	0.001
0	2	2.185	2.186	0.001
100	23	2.287	1.847	-0.440
100	24	2.198	2.044	-0.154
100	25	2.254	2.025	-0.229
100	26	2.202	2.030	-0.172
100	27	2.194	1.913	-0.282
100	48u	2.094	1.957	-0.137
100	49u	2.172	1.990	-0.182
100	50u	2.123	2.037	-0.086
100	51u	2.243	2.100	-0.142
100	52u	2.183	2.060	-0.123
	Max	2.287	2.186	0.001
	Average	2.192	2.030	-0.162
	Min	2.094	1.847	-0.440
	Std Dev	0.053	0.098	0.120

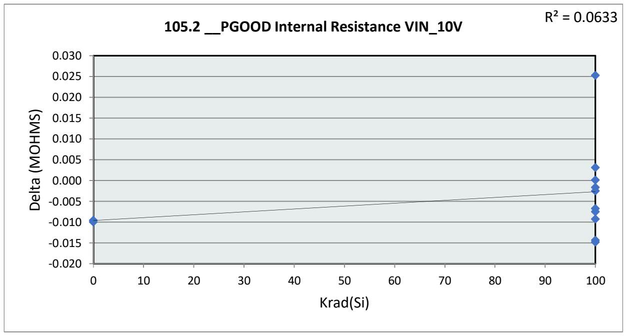


	105.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.847
Average	2.180	2.000
Max	2.186	2.100
UL	2.850	2.850

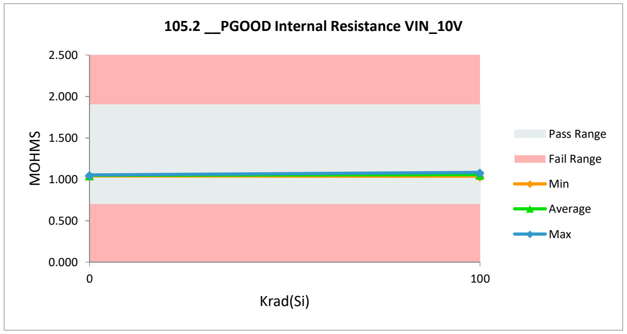


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		105.2 __PGOOD Internal Resista		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		MOHMS	MOHMS	
Max Limit		1.9	1.9	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.051	1.042	-0.009
0	2	1.065	1.055	-0.010
100	23	1.055	1.081	0.025
100	24	1.057	1.061	0.003
100	25	1.045	1.042	-0.002
100	26	1.054	1.040	-0.015
100	27	1.053	1.051	-0.002
100	48u	1.093	1.086	-0.007
100	49u	1.073	1.059	-0.014
100	50u	1.058	1.059	0.000
100	51u	1.052	1.043	-0.009
100	52u	1.065	1.058	-0.007
	Max	1.093	1.086	0.025
	Average	1.060	1.056	-0.004
	Min	1.045	1.040	-0.015
	Std Dev	0.013	0.015	0.011

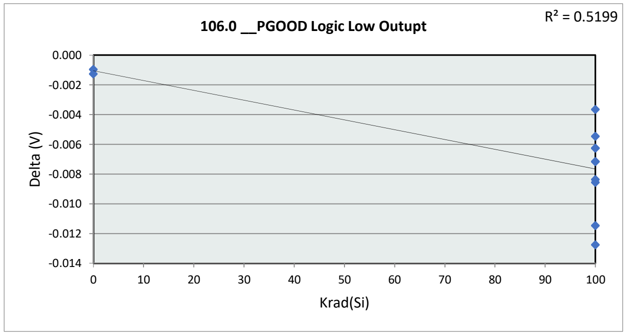


	105.2 __PGOOD Internal Resistance VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.042	1.040
Average	1.049	1.058
Max	1.055	1.086
UL	1.900	1.900

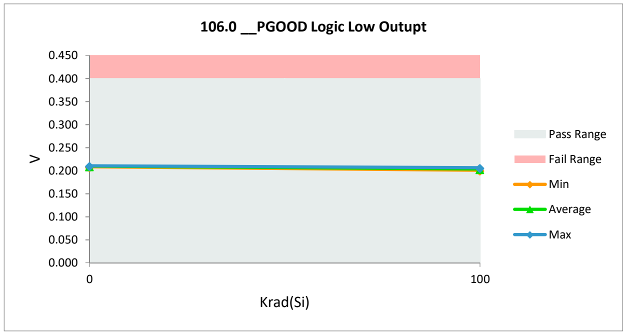


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		106.0 __PGOOD Logic Low Outu		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		0.4	0.4	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.209	0.209	-0.001
0	2	0.212	0.211	-0.001
100	23	0.213	0.201	-0.013
100	24	0.211	0.205	-0.006
100	25	0.215	0.207	-0.008
100	26	0.212	0.205	-0.007
100	27	0.214	0.203	-0.011
100	48u	0.209	0.204	-0.005
100	49u	0.210	0.201	-0.008
100	50u	0.208	0.204	-0.004
100	51u	0.211	0.204	-0.007
100	52u	0.211	0.204	-0.006
	Max	0.215	0.211	-0.001
	Average	0.211	0.205	-0.007
	Min	0.208	0.201	-0.013
	Std Dev	0.002	0.003	0.004

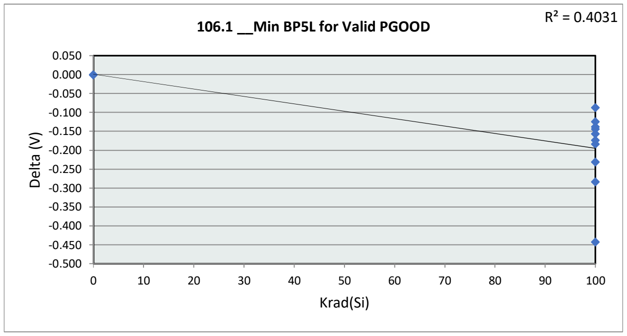


	106.0 __PGOOD Logic Low Output	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.209	0.201
Average	0.210	0.204
Max	0.211	0.207
UL	0.400	0.400

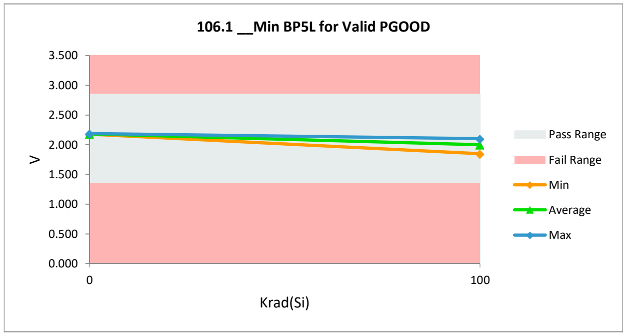


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		106.1 __Min BP5L for Valid PGO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		V	V	
Max Limit		2.85	2.85	
Min Limit		1.35	1.35	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.174	2.175	0.000
0	2	2.185	2.186	0.001
100	23	2.287	1.847	-0.441
100	24	2.199	2.044	-0.155
100	25	2.254	2.025	-0.229
100	26	2.203	2.031	-0.172
100	27	2.195	1.913	-0.282
100	48u	2.094	1.957	-0.137
100	49u	2.172	1.990	-0.182
100	50u	2.123	2.037	-0.086
100	51u	2.243	2.101	-0.142
100	52u	2.183	2.060	-0.123
	Max	2.287	2.186	0.001
	Average	2.193	2.030	-0.162
	Min	2.094	1.847	-0.441
	Std Dev	0.053	0.098	0.120

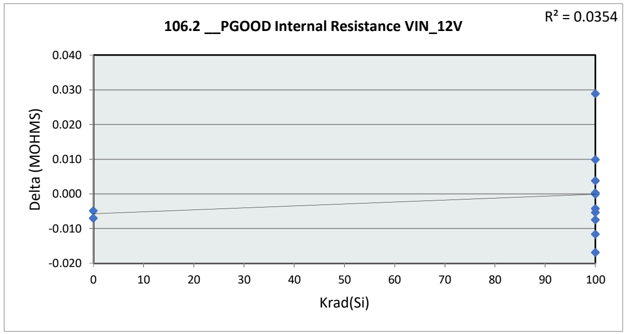


	106.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.847
Average	2.180	2.000
Max	2.186	2.101
UL	2.850	2.850

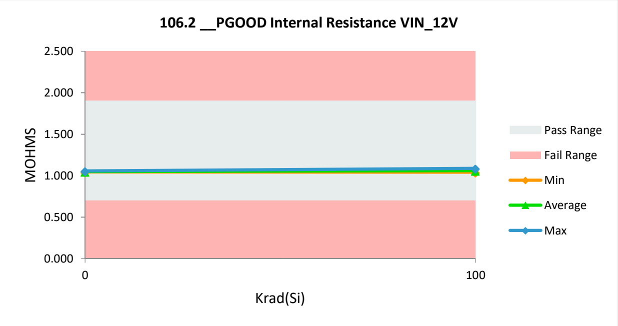


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		106.2 __PGOOD Internal Resista		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	MOHMS	MOHMS	
	Max Limit	1.9	1.9	
	Min Limit	0.7	0.7	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.049	1.044	-0.005
0	2	1.063	1.056	-0.007
100	23	1.052	1.081	0.029
100	24	1.061	1.065	0.004
100	25	1.043	1.043	0.000
100	26	1.059	1.042	-0.017
100	27	1.050	1.050	0.000
100	48u	1.097	1.090	-0.007
100	49u	1.071	1.059	-0.011
100	50u	1.057	1.067	0.010
100	51u	1.049	1.045	-0.004
100	52u	1.065	1.060	-0.005
	Max	1.097	1.090	0.029
	Average	1.060	1.059	-0.001
	Min	1.043	1.042	-0.017
	Std Dev	0.014	0.015	0.012

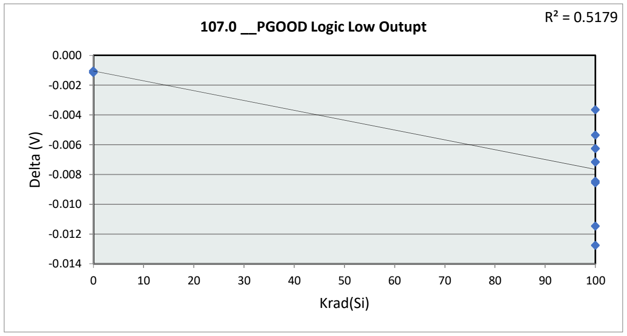


	106.2 __PGOOD Internal Resistance VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.044	1.042
Average	1.050	1.060
Max	1.056	1.090
UL	1.900	1.900

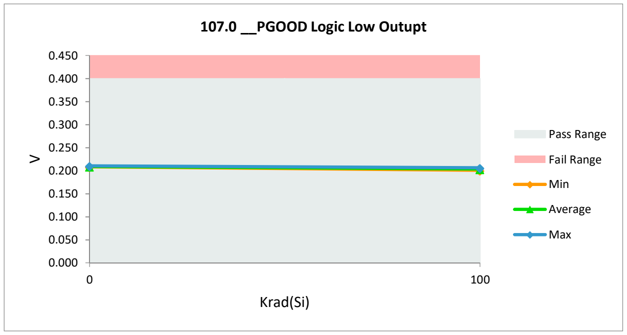


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		107.0 __PGOOD Logic Low Outu		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	0.4	0.4	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	0.209	0.208	-0.001
0	2	0.212	0.211	-0.001
100	23	0.213	0.200	-0.013
100	24	0.211	0.205	-0.006
100	25	0.215	0.206	-0.008
100	26	0.212	0.204	-0.007
100	27	0.214	0.203	-0.011
100	48u	0.209	0.204	-0.005
100	49u	0.210	0.201	-0.008
100	50u	0.207	0.204	-0.004
100	51u	0.210	0.203	-0.007
100	52u	0.210	0.204	-0.006
	Max	0.215	0.211	-0.001
	Average	0.211	0.204	-0.007
	Min	0.207	0.200	-0.013
	Std Dev	0.002	0.003	0.004

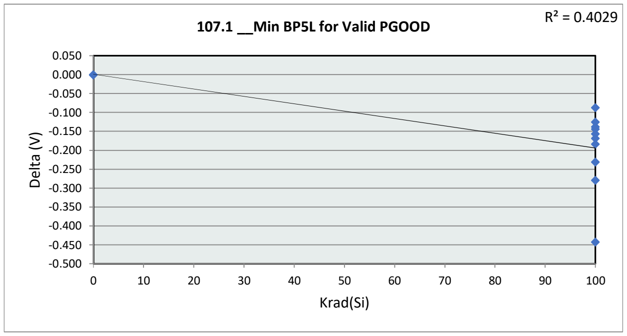


	107.0 __PGOOD Logic Low Outupt	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	0.4	V
Min Limit	0	V
Krad(Si)	0	100
LL	0.000	0.000
Min	0.208	0.201
Average	0.209	0.203
Max	0.211	0.206
UL	0.400	0.400

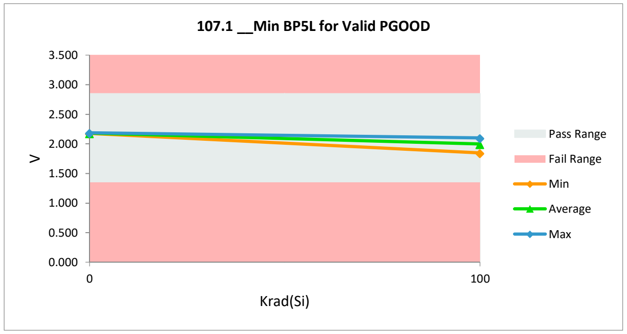


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		107.1 __Min BP5L for Valid PGO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit	V	V	
	Max Limit	2.85	2.85	
	Min Limit	1.35	1.35	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	2.174	2.175	0.001
0	2	2.185	2.187	0.001
100	23	2.288	1.847	-0.441
100	24	2.199	2.044	-0.155
100	25	2.254	2.025	-0.229
100	26	2.203	2.036	-0.167
100	27	2.195	1.918	-0.277
100	48u	2.095	1.958	-0.137
100	49u	2.172	1.990	-0.182
100	50u	2.123	2.037	-0.086
100	51u	2.243	2.101	-0.142
100	52u	2.184	2.059	-0.124
	Max	2.288	2.187	0.001
	Average	2.193	2.031	-0.162
	Min	2.095	1.847	-0.441
	Std Dev	0.053	0.098	0.120

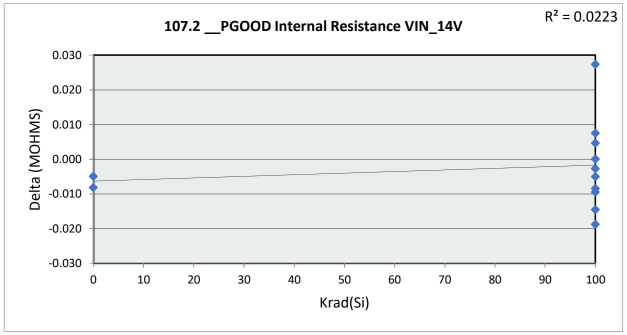


	107.1 __Min BP5L for Valid PGOOD	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	2.85	V
Min Limit	1.35	V
Krad(Si)	0	100
LL	1.350	1.350
Min	2.175	1.847
Average	2.181	2.001
Max	2.187	2.101
UL	2.850	2.850

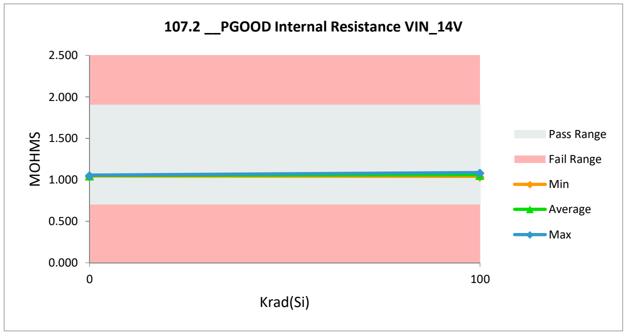


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		107.2 __PGOOD Internal Resista		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit		MOHMS	MOHMS	
Max Limit		1.9	1.9	
Min Limit		0.7	0.7	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.052	1.048	-0.005
0	2	1.064	1.056	-0.008
100	23	1.054	1.082	0.028
100	24	1.057	1.062	0.005
100	25	1.048	1.043	-0.005
100	26	1.062	1.043	-0.018
100	27	1.051	1.052	0.000
100	48u	1.095	1.087	-0.008
100	49u	1.076	1.061	-0.014
100	50u	1.059	1.067	0.008
100	51u	1.054	1.044	-0.009
100	52u	1.066	1.064	-0.002
	Max	1.095	1.087	0.028
	Average	1.062	1.059	-0.002
	Min	1.048	1.043	-0.018
	Std Dev	0.013	0.014	0.012

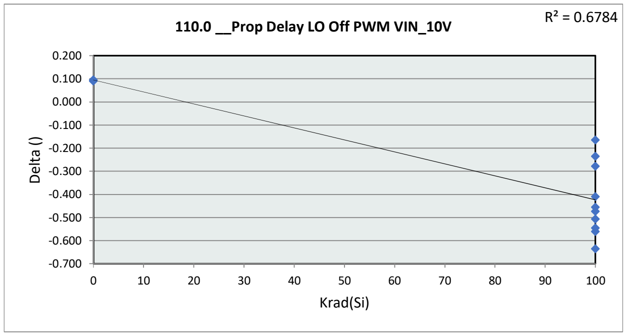


	107.2 __PGOOD Internal Resistance VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	1.9	MOHMS
Min Limit	0.7	MOHMS
Krad(Si)	0	100
LL	0.700	0.700
Min	1.048	1.043
Average	1.052	1.061
Max	1.057	1.087
UL	1.900	1.900

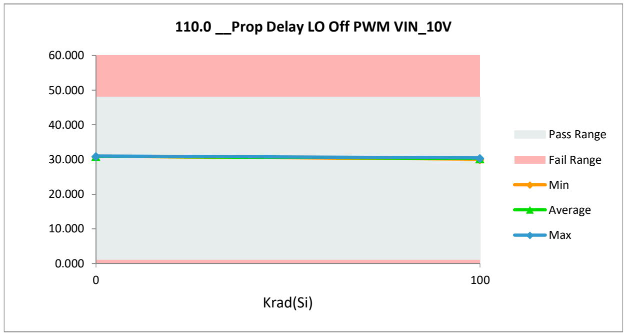


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.0 __Prop Delay LO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	48	48	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	30.896	30.988	0.092
0	2	30.822	30.920	0.098
100	23	30.609	30.447	-0.162
100	24	30.550	30.274	-0.276
100	25	30.746	30.114	-0.632
100	26	31.014	30.457	-0.558
100	27	30.575	30.122	-0.452
100	48u	30.555	30.323	-0.232
100	49u	30.640	30.234	-0.407
100	50u	30.680	30.137	-0.543
100	51u	30.894	30.391	-0.503
100	52u	30.815	30.345	-0.470
	Max	31.014	30.988	0.098
	Average	30.733	30.396	-0.337
	Min	30.550	30.114	-0.632
	Std Dev	0.155	0.286	0.245

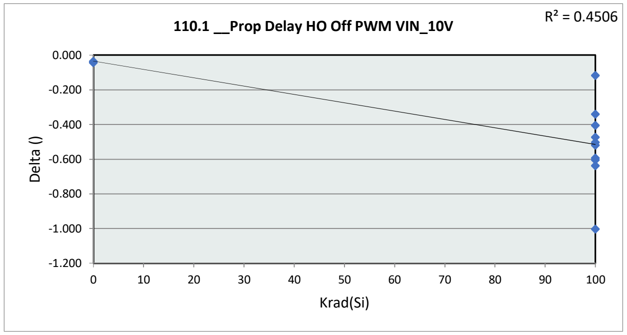


	110.0 __Prop Delay LO Off PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.920	30.114
Average	30.954	30.284
Max	30.988	30.457
UL	48.000	48.000

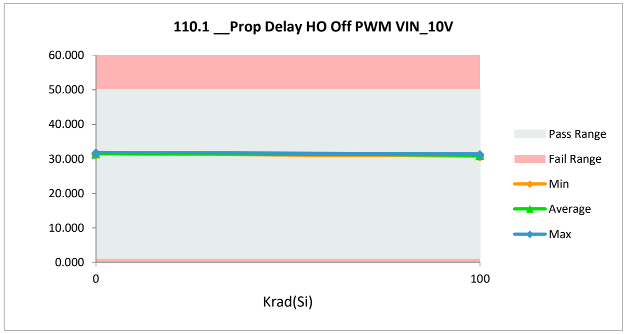


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.1 __Prop Delay HO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	50	50	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	31.879	31.840	-0.038
0	2	31.413	31.382	-0.031
100	23	31.842	31.373	-0.469
100	24	31.780	30.783	-0.997
100	25	31.603	31.015	-0.588
100	26	31.488	31.375	-0.113
100	27	31.655	31.140	-0.515
100	48u	31.732	31.233	-0.499
100	49u	31.465	31.065	-0.400
100	50u	31.466	30.866	-0.600
100	51u	31.617	30.985	-0.633
100	52u	31.099	30.763	-0.336
	Max	31.879	31.840	-0.031
	Average	31.587	31.152	-0.435
	Min	31.099	30.763	-0.997
	Std Dev	0.218	0.310	0.279

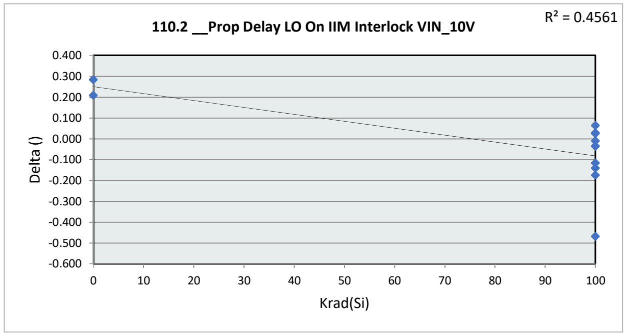


	110.1 __Prop Delay HO Off PWM VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.382	30.763
Average	31.611	31.060
Max	31.840	31.375
UL	50.000	50.000

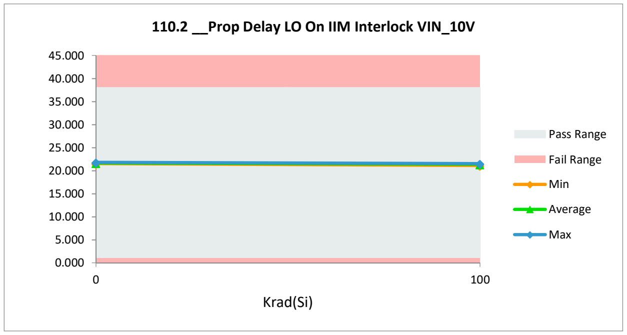


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.2 __Prop Delay LO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.501	21.788	0.288
0	2	21.319	21.532	0.213
100	23	21.396	21.428	0.033
100	24	21.468	21.331	-0.137
100	25	21.538	21.368	-0.170
100	26	21.542	21.429	-0.113
100	27	21.592	21.127	-0.465
100	48u	21.457	21.525	0.068
100	49u	21.471	21.440	-0.031
100	50u	21.338	21.307	-0.032
100	51u	21.449	21.442	-0.007
100	52u	21.394	21.423	0.029
	Max	21.592	21.788	0.288
	Average	21.455	21.428	-0.027
	Min	21.319	21.127	-0.465
	Std Dev	0.083	0.156	0.192

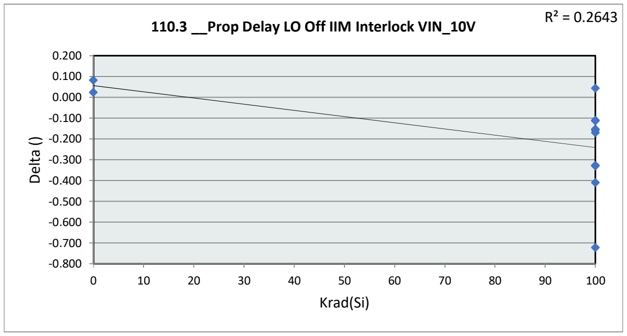


	110.2 __Prop Delay LO On IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.532	21.127
Average	21.660	21.382
Max	21.788	21.525
UL	38.000	38.000

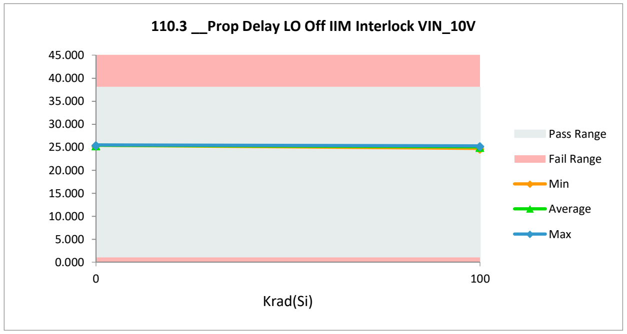


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.3 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.438	25.464	0.026
0	2	25.354	25.440	0.086
100	23	25.206	25.096	-0.110
100	24	25.268	25.113	-0.155
100	25	25.404	24.997	-0.407
100	26	25.577	25.250	-0.327
100	27	25.478	24.760	-0.719
100	48u	25.143	25.191	0.047
100	49u	25.227	25.120	-0.107
100	50u	25.225	24.902	-0.323
100	51u	25.331	25.165	-0.167
100	52u	25.461	25.311	-0.149
	Max	25.577	25.464	0.086
	Average	25.343	25.151	-0.192
	Min	25.143	24.760	-0.719
	Std Dev	0.132	0.205	0.225

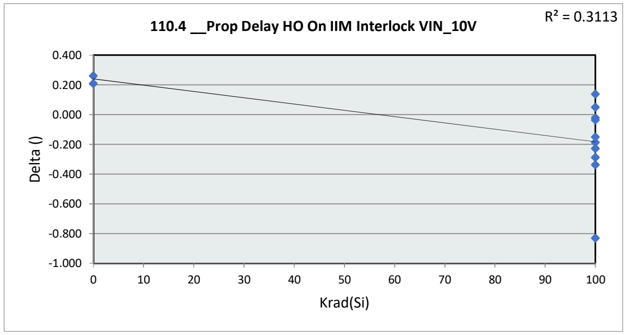


	110.3 __Prop Delay LO Off IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.440	24.760
Average	25.452	25.090
Max	25.464	25.311
UL	38.000	38.000

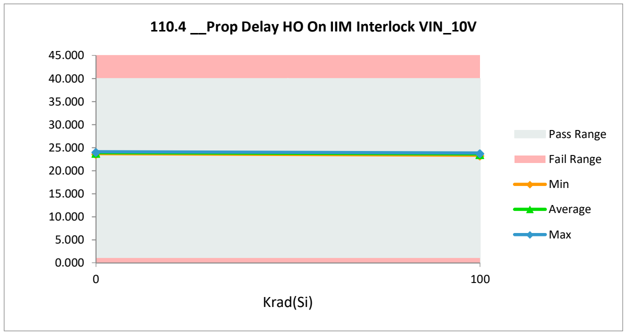


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.4 __Prop Delay HO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.872	24.087	0.215
0	2	23.393	23.659	0.266
100	23	24.101	23.770	-0.331
100	24	24.308	23.484	-0.824
100	25	23.846	23.666	-0.181
100	26	23.644	23.500	-0.145
100	27	23.771	23.549	-0.222
100	48u	23.698	23.842	0.144
100	49u	23.741	23.797	0.056
100	50u	23.615	23.333	-0.282
100	51u	23.775	23.745	-0.030
100	52u	23.558	23.542	-0.016
	Max	24.308	24.087	0.266
	Average	23.777	23.664	-0.112
	Min	23.393	23.333	-0.824
	Std Dev	0.243	0.201	0.296

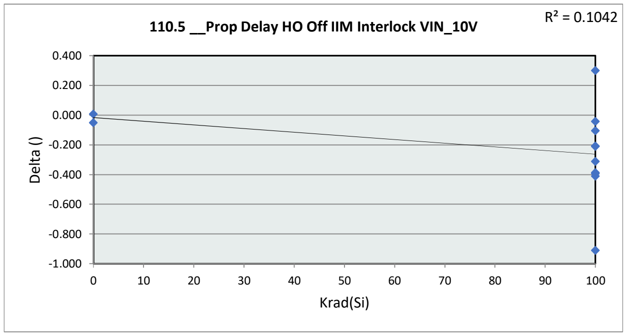


	110.4 __Prop Delay HO On IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.659	23.333
Average	23.873	23.623
Max	24.088	23.842
UL	40.000	40.000

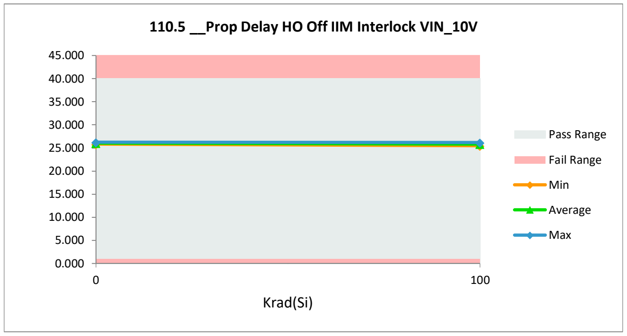


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.5 __Prop Delay HO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.267	26.222	-0.046
0	2	25.805	25.817	0.012
100	23	26.334	25.929	-0.405
100	24	26.421	25.516	-0.905
100	25	26.093	25.886	-0.207
100	26	25.864	26.167	0.304
100	27	26.320	25.938	-0.382
100	48u	26.082	25.980	-0.101
100	49u	25.935	25.898	-0.037
100	50u	25.983	25.594	-0.389
100	51u	26.028	25.720	-0.308
100	52u	25.803	25.600	-0.203
	Max	26.421	26.222	0.304
	Average	26.078	25.856	-0.222
	Min	25.803	25.516	-0.905
	Std Dev	0.214	0.220	0.297

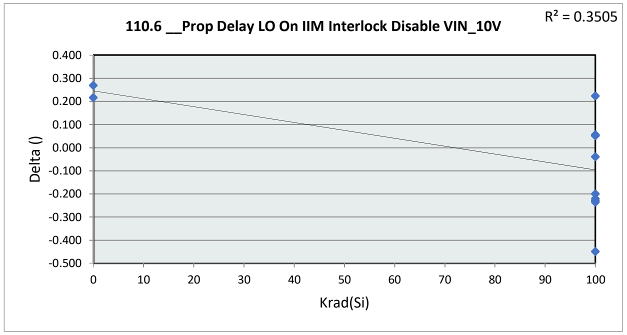


	110.5 __Prop Delay HO Off IIM Interlock VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.818	25.516
Average	26.020	25.823
Max	26.222	26.168
UL	40.000	40.000

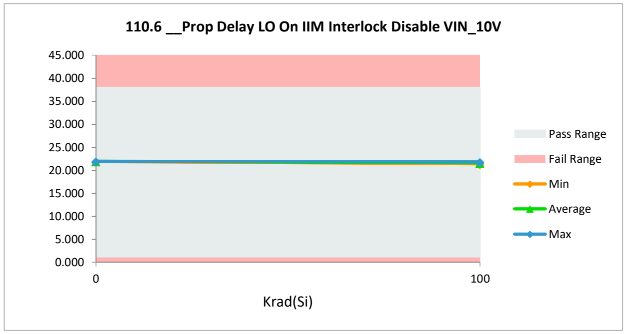


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.6 __Prop Delay LO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.751	21.970	0.220
0	2	21.600	21.872	0.272
100	23	21.652	21.711	0.059
100	24	21.682	21.485	-0.197
100	25	21.733	21.517	-0.217
100	26	21.802	21.569	-0.233
100	27	21.834	21.389	-0.445
100	48u	21.586	21.812	0.227
100	49u	21.628	21.683	0.055
100	50u	21.626	21.400	-0.226
100	51u	21.764	21.727	-0.036
100	52u	21.614	21.669	0.055
	Max	21.834	21.970	0.272
	Average	21.689	21.650	-0.039
	Min	21.586	21.389	-0.445
	Std Dev	0.085	0.184	0.225

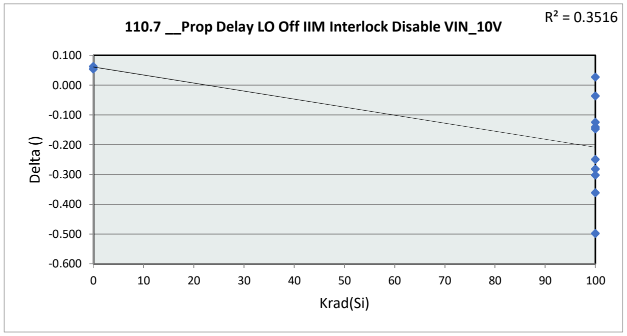


	110.6 __Prop Delay LO On IIM Interlock Disable VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.872	21.389
Average	21.921	21.596
Max	21.970	21.812
UL	38.000	38.000

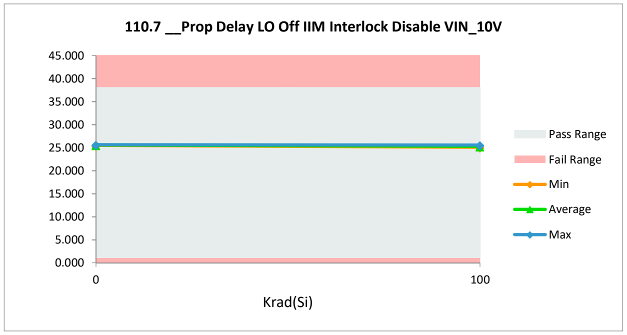


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.7 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.569	25.626	0.057
0	2	25.416	25.481	0.066
100	23	25.431	25.398	-0.033
100	24	25.396	25.117	-0.278
100	25	25.523	25.164	-0.359
100	26	25.721	25.577	-0.144
100	27	25.570	25.076	-0.495
100	48u	25.333	25.363	0.030
100	49u	25.379	25.257	-0.122
100	50u	25.367	25.067	-0.300
100	51u	25.505	25.368	-0.137
100	52u	25.611	25.365	-0.246
	Max	25.721	25.626	0.066
	Average	25.485	25.322	-0.163
	Min	25.333	25.067	-0.495
	Std Dev	0.117	0.189	0.177

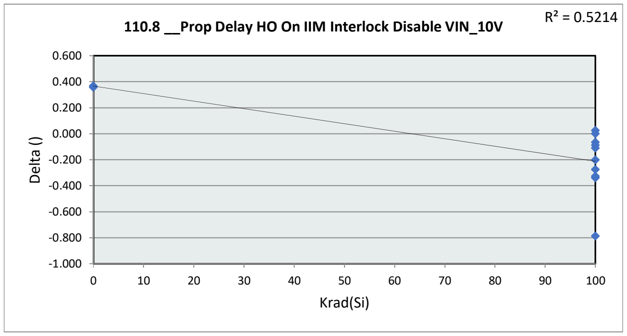


	110.7 __Prop Delay LO Off IIM Interlock Disable VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.481	25.067
Average	25.554	25.275
Max	25.626	25.577
UL	38.000	38.000

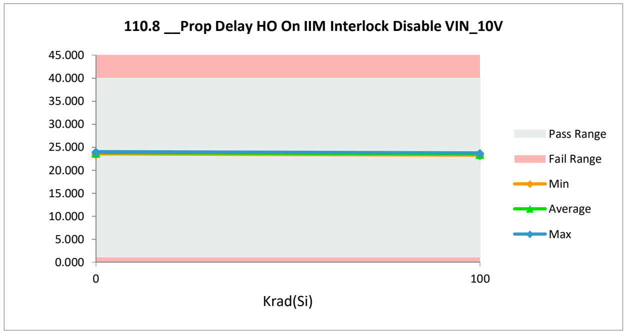


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.8 __Prop Delay HO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.676	24.037	0.361
0	2	23.190	23.563	0.373
100	23	23.989	23.667	-0.322
100	24	24.163	23.382	-0.781
100	25	23.796	23.599	-0.197
100	26	23.552	23.448	-0.105
100	27	23.696	23.427	-0.269
100	48u	23.717	23.657	-0.060
100	49u	23.720	23.751	0.032
100	50u	23.598	23.265	-0.333
100	51u	23.713	23.630	-0.083
100	52u	23.404	23.409	0.005
	Max	24.163	24.037	0.373
	Average	23.685	23.570	-0.115
	Min	23.190	23.265	-0.781
	Std Dev	0.250	0.205	0.312

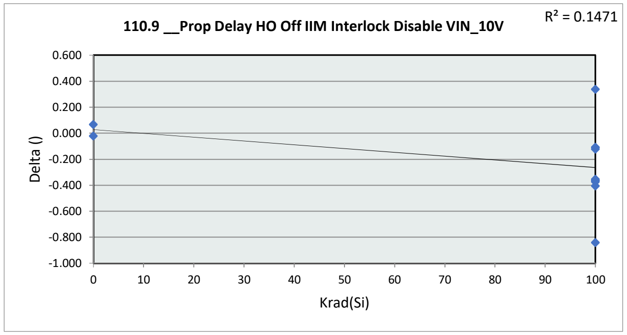


	110.8 __Prop Delay HO On IIM Interlock Disable VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.563	23.265
Average	23.800	23.523
Max	24.037	23.751
UL	40.000	40.000

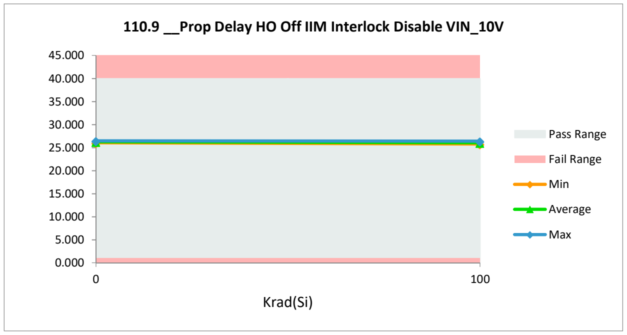


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.9 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.467	26.451	-0.016
0	2	25.972	26.045	0.073
100	23	26.477	26.119	-0.358
100	24	26.645	25.811	-0.834
100	25	26.367	26.020	-0.347
100	26	26.047	26.390	0.343
100	27	26.520	26.164	-0.356
100	48u	26.304	26.189	-0.115
100	49u	26.236	26.133	-0.103
100	50u	26.175	25.777	-0.398
100	51u	26.288	25.920	-0.367
100	52u	25.933	25.832	-0.101
	Max	26.645	26.451	0.343
	Average	26.286	26.071	-0.215
	Min	25.933	25.777	-0.834
	Std Dev	0.225	0.216	0.296

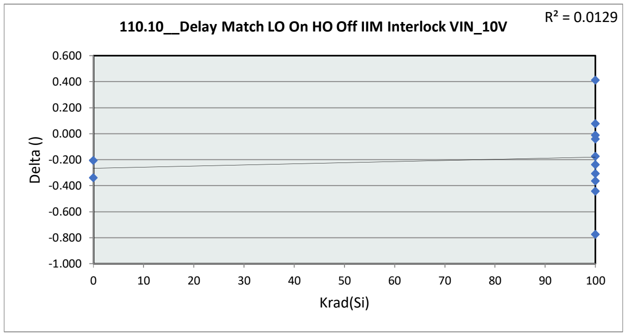


	110.9 __Prop Delay HO Off IIM Interlock Disable VIN_10	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	26.045	25.777
Average	26.248	26.035
Max	26.451	26.390
UL	40.000	40.000

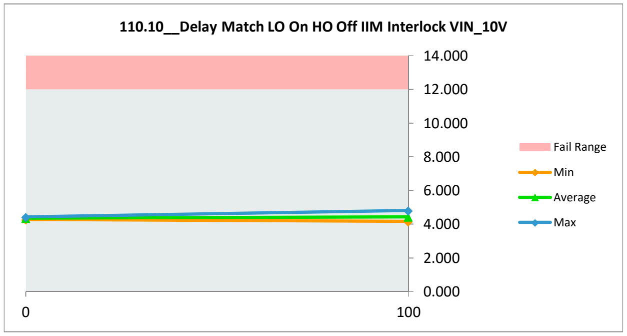


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.10__Delay Match LO On HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.766	4.433	-0.333
0	2	4.486	4.285	-0.201
100	23	4.938	4.500	-0.438
100	24	4.953	4.185	-0.768
100	25	4.555	4.518	-0.036
100	26	4.322	4.739	0.417
100	27	4.727	4.811	0.083
100	48u	4.625	4.456	-0.169
100	49u	4.464	4.458	-0.006
100	50u	4.644	4.287	-0.358
100	51u	4.579	4.278	-0.301
100	52u	4.410	4.177	-0.232
	Max	4.953	4.811	0.417
	Average	4.623	4.427	-0.195
	Min	4.322	4.177	-0.768
	Std Dev	0.197	0.201	0.295

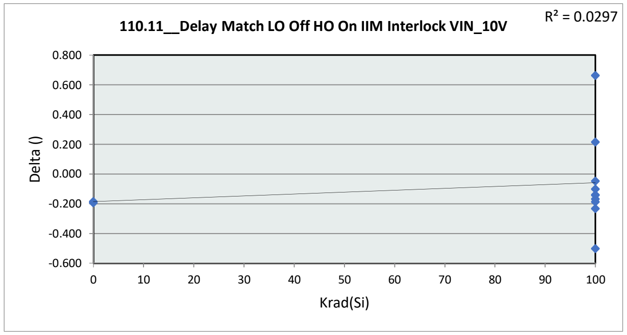


	110.10__Delay Match LO On HO Off IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.285	4.177
Average	4.359	4.441
Max	4.433	4.811
UL	12.000	12.000

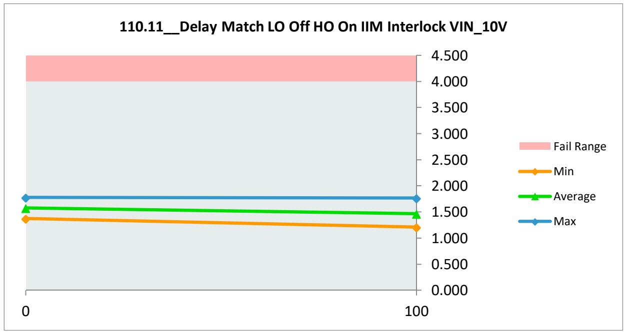


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.11__Delay Match LO Off HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		4	4	
Min Limit				
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.566	1.377	-0.189
0	2	1.961	1.781	-0.180
100	23	1.106	1.326	0.221
100	24	0.960	1.630	0.669
100	25	1.557	1.331	-0.226
100	26	1.933	1.751	-0.182
100	27	1.708	1.211	-0.497
100	48u	1.445	1.348	-0.097
100	49u	1.486	1.323	-0.163
100	50u	1.610	1.569	-0.041
100	51u	1.556	1.419	-0.137
100	52u	1.903	1.769	-0.133
	Max	1.961	1.781	0.669
	Average	1.566	1.486	-0.080
	Min	0.960	1.211	-0.497
	Std Dev	0.305	0.203	0.285

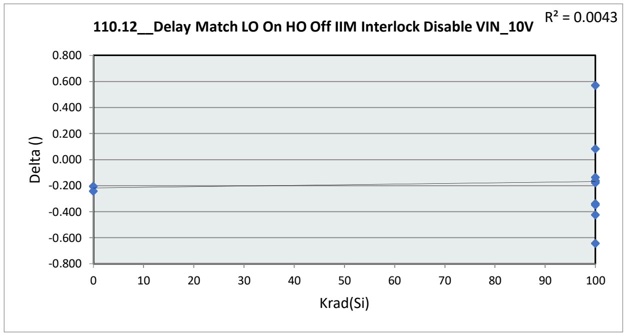


	110.11__Delay Match LO Off HO On IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.377	1.211
Average	1.579	1.468
Max	1.781	1.769
UL	4.000	4.000

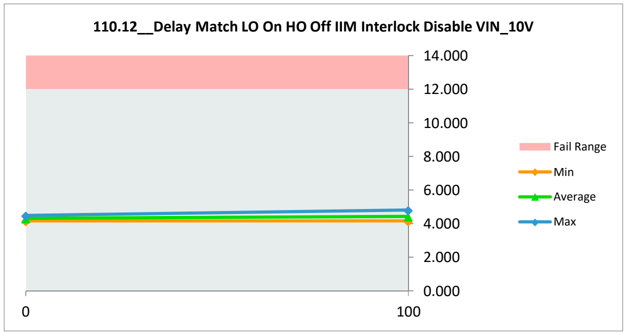


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.12__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.716	4.480	-0.236
0	2	4.372	4.173	-0.199
100	23	4.825	4.408	-0.417
100	24	4.963	4.327	-0.636
100	25	4.634	4.503	-0.131
100	26	4.245	4.821	0.576
100	27	4.686	4.775	0.089
100	48u	4.718	4.377	-0.342
100	49u	4.608	4.450	-0.158
100	50u	4.549	4.377	-0.172
100	51u	4.524	4.193	-0.331
100	52u	4.319	4.163	-0.156
	Max	4.963	4.821	0.576
	Average	4.597	4.421	-0.176
	Min	4.245	4.163	-0.636
	Std Dev	0.210	0.211	0.296

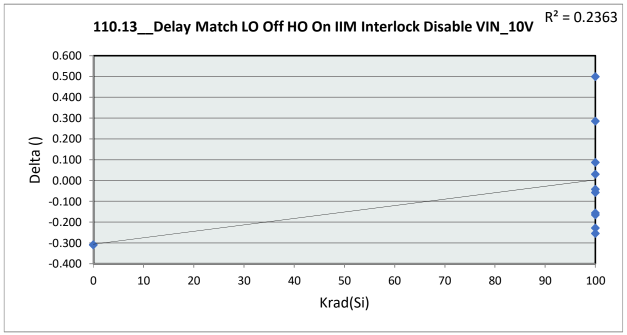


	110.12__Delay Match LO On HO Off IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.173	4.163
Average	4.327	4.439
Max	4.480	4.821
UL	12.000	12.000

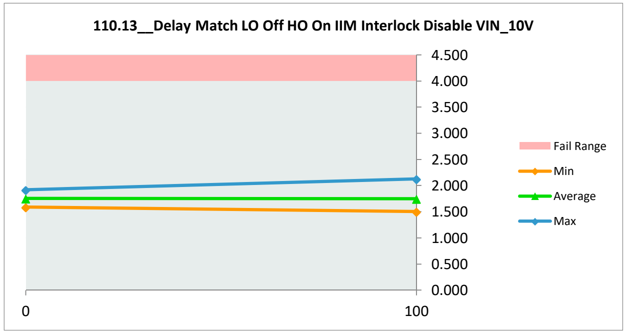


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		110.13__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.894	1.589	-0.304
0	2	2.226	1.919	-0.307
100	23	1.442	1.730	0.289
100	24	1.232	1.735	0.503
100	25	1.727	1.565	-0.162
100	26	2.168	2.129	-0.039
100	27	1.874	1.649	-0.225
100	48u	1.616	1.706	0.090
100	49u	1.660	1.506	-0.153
100	50u	1.769	1.802	0.033
100	51u	1.792	1.738	-0.054
100	52u	2.207	1.956	-0.251
	Max	2.226	2.129	0.503
	Average	1.801	1.752	-0.049
	Min	1.232	1.506	-0.307
	Std Dev	0.303	0.178	0.247

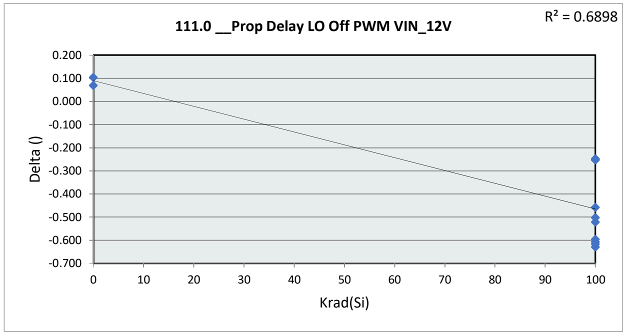


	110.13__Delay Match LO Off HO On IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.589	1.506
Average	1.754	1.752
Max	1.919	2.129
UL	4.000	4.000

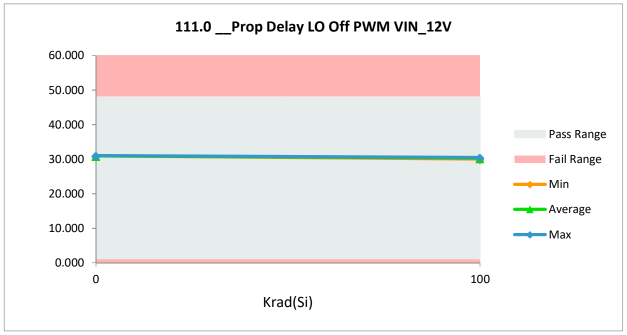


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.0 __Prop Delay LO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	48	48	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	30.919	30.992	0.073
0	2	30.838	30.946	0.108
100	23	30.642	30.398	-0.244
100	24	30.550	30.301	-0.249
100	25	30.781	30.155	-0.626
100	26	30.994	30.495	-0.499
100	27	30.644	30.051	-0.593
100	48u	30.583	30.336	-0.248
100	49u	30.673	30.154	-0.518
100	50u	30.678	30.065	-0.613
100	51u	30.959	30.354	-0.605
100	52u	30.865	30.410	-0.455
	Max	30.994	30.992	0.108
	Average	30.760	30.388	-0.372
	Min	30.550	30.051	-0.626
	Std Dev	0.152	0.305	0.260

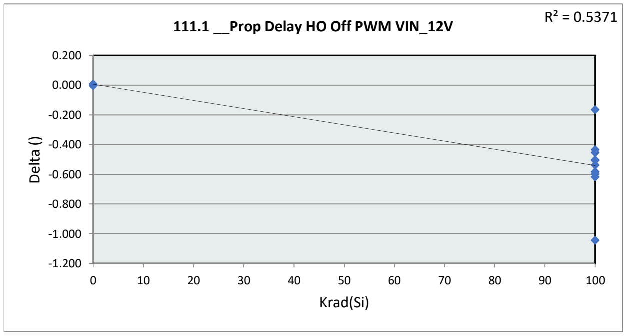


	111.0 __Prop Delay LO Off PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.946	30.051
Average	30.969	30.272
Max	30.992	30.495
UL	48.000	48.000

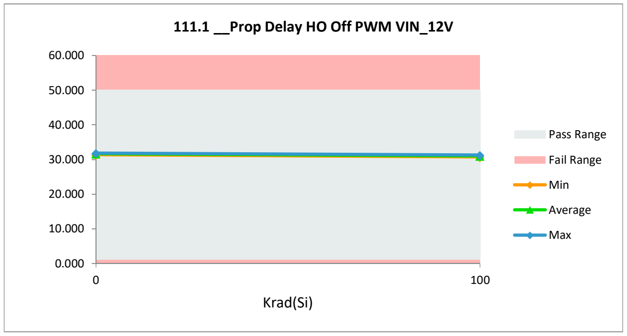


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.1 __Prop Delay HO Off PWM		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	50	50	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	31.891	31.891	0.000
0	2	31.399	31.409	0.011
100	23	31.864	31.330	-0.534
100	24	31.859	30.819	-1.040
100	25	31.595	31.016	-0.579
100	26	31.478	31.318	-0.160
100	27	31.634	31.135	-0.499
100	48u	31.764	31.333	-0.430
100	49u	31.512	31.062	-0.450
100	50u	31.570	30.977	-0.594
100	51u	31.588	30.975	-0.614
100	52u	31.255	30.753	-0.501
	Max	31.891	31.891	0.011
	Average	31.617	31.168	-0.449
	Min	31.255	30.753	-1.040
	Std Dev	0.198	0.310	0.290

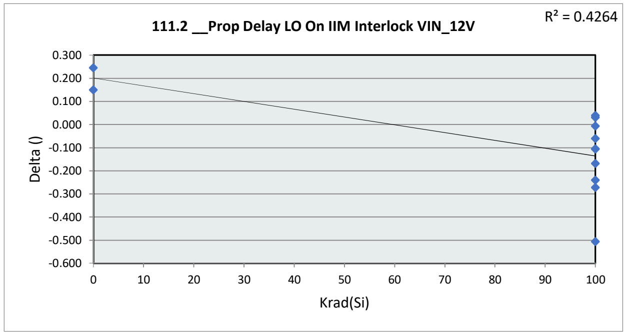


	111.1 __Prop Delay HO Off PWM VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.409	30.753
Average	31.650	31.072
Max	31.891	31.333
UL	50.000	50.000

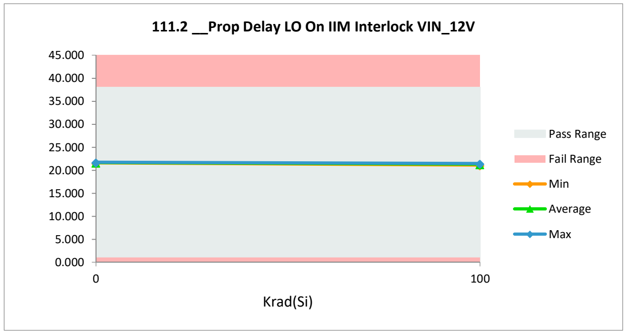


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.2 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.586	21.740	0.153
0	2	21.387	21.636	0.249
100	23	21.471	21.468	-0.003
100	24	21.430	21.265	-0.165
100	25	21.604	21.334	-0.269
100	26	21.616	21.379	-0.237
100	27	21.644	21.142	-0.502
100	48u	21.425	21.459	0.034
100	49u	21.414	21.357	-0.057
100	50u	21.348	21.247	-0.101
100	51u	21.463	21.361	-0.102
100	52u	21.395	21.438	0.043
	Max	21.644	21.740	0.249
	Average	21.482	21.402	-0.080
	Min	21.348	21.142	-0.502
	Std Dev	0.103	0.164	0.201

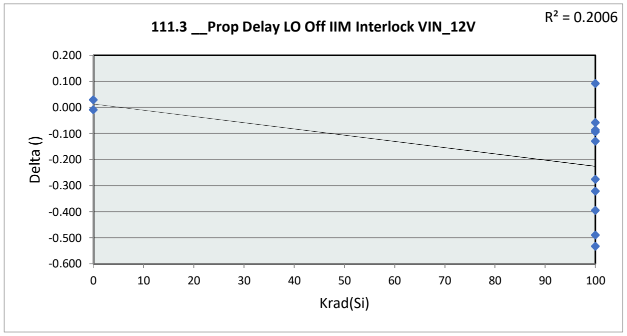


	111.2 __Prop Delay LO On IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.636	21.142
Average	21.688	21.345
Max	21.740	21.468
UL	38.000	38.000

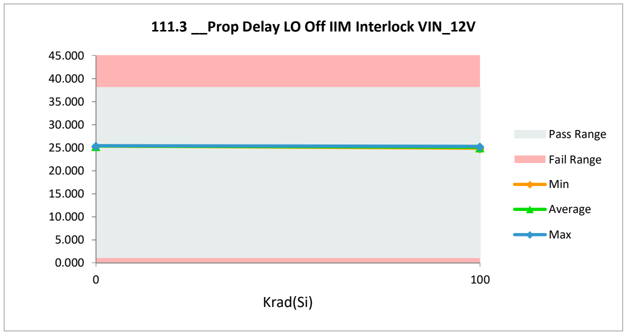


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.3 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.371	25.403	0.032
0	2	25.377	25.372	-0.005
100	23	25.167	25.112	-0.055
100	24	25.208	25.125	-0.083
100	25	25.453	24.923	-0.530
100	26	25.590	25.272	-0.317
100	27	25.348	24.862	-0.486
100	48u	25.087	25.183	0.096
100	49u	25.188	25.062	-0.126
100	50u	25.258	24.867	-0.392
100	51u	25.412	25.140	-0.272
100	52u	25.344	25.253	-0.090
	Max	25.590	25.403	0.096
	Average	25.317	25.131	-0.186
	Min	25.087	24.862	-0.530
	Std Dev	0.141	0.181	0.208

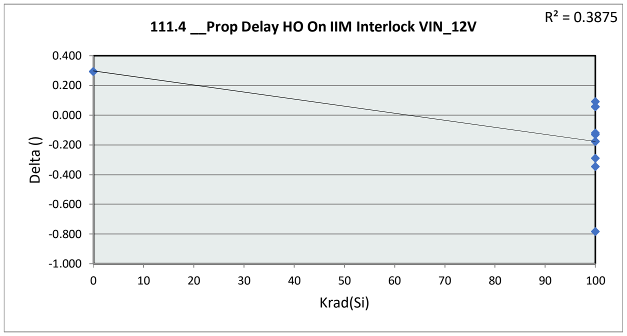


	111.3 __Prop Delay LO Off IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.372	24.863
Average	25.387	25.080
Max	25.403	25.273
UL	38.000	38.000

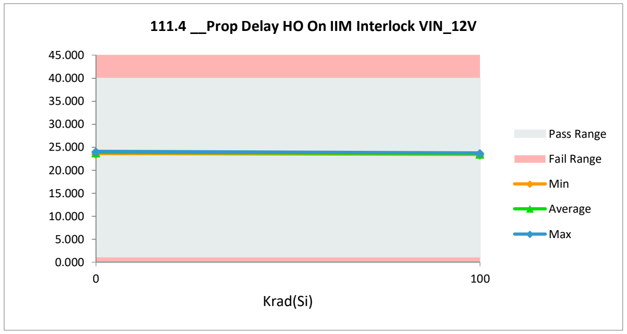


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.4 __Prop Delay HO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.840	24.138	0.298
0	2	23.332	23.629	0.297
100	23	24.085	23.744	-0.341
100	24	24.294	23.515	-0.779
100	25	23.833	23.718	-0.115
100	26	23.666	23.495	-0.171
100	27	23.690	23.563	-0.127
100	48u	23.710	23.772	0.062
100	49u	23.695	23.791	0.096
100	50u	23.723	23.438	-0.285
100	51u	23.911	23.738	-0.173
100	52u	23.487	23.547	0.060
	Max	24.294	24.138	0.298
	Average	23.772	23.674	-0.098
	Min	23.332	23.438	-0.779
	Std Dev	0.253	0.189	0.297

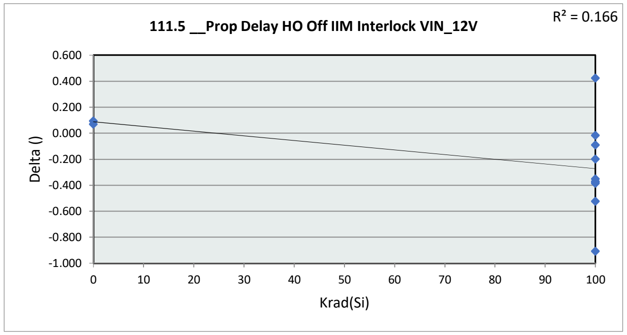


	111.4 __Prop Delay HO On IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.629	23.438
Average	23.884	23.632
Max	24.138	23.791
UL	40.000	40.000

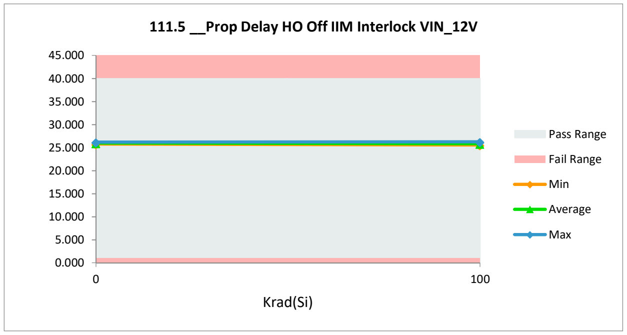


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.5 __Prop Delay HO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.118	26.218	0.100
0	2	25.704	25.780	0.077
100	23	26.336	25.968	-0.368
100	24	26.454	25.552	-0.901
100	25	26.197	25.853	-0.344
100	26	25.811	26.240	0.429
100	27	26.252	25.873	-0.379
100	48u	26.023	25.940	-0.083
100	49u	25.924	25.914	-0.010
100	50u	26.051	25.533	-0.518
100	51u	26.014	25.649	-0.365
100	52u	25.770	25.578	-0.192
	Max	26.454	26.240	0.429
	Average	26.054	25.842	-0.213
	Min	25.704	25.533	-0.901
	Std Dev	0.231	0.238	0.345

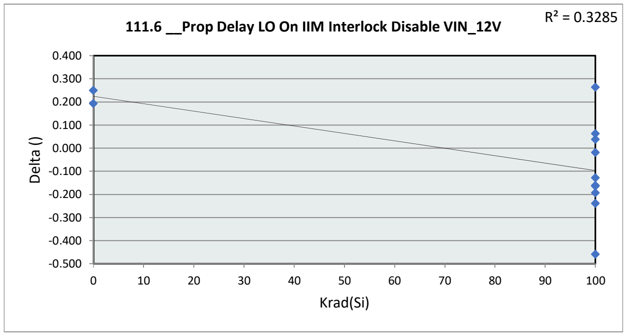


	111.5 __Prop Delay HO Off IIM Interlock VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.780	25.533
Average	25.999	25.810
Max	26.218	26.241
UL	40.000	40.000

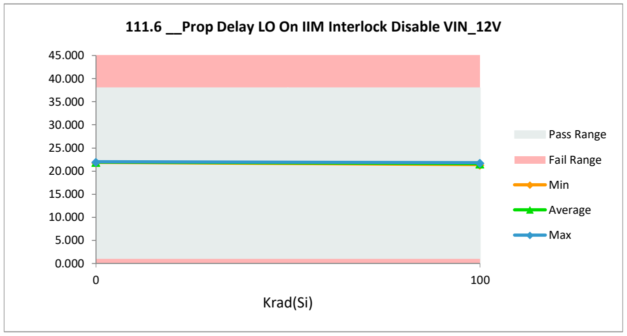


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.6 __Prop Delay LO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.738	21.990	0.253
0	2	21.664	21.861	0.196
100	23	21.624	21.690	0.066
100	24	21.702	21.512	-0.190
100	25	21.774	21.616	-0.158
100	26	21.816	21.580	-0.236
100	27	21.829	21.373	-0.456
100	48u	21.572	21.838	0.267
100	49u	21.716	21.555	-0.161
100	50u	21.640	21.515	-0.126
100	51u	21.703	21.687	-0.016
100	52u	21.653	21.695	0.041
	Max	21.829	21.990	0.267
	Average	21.703	21.659	-0.043
	Min	21.572	21.373	-0.456
	Std Dev	0.078	0.173	0.218

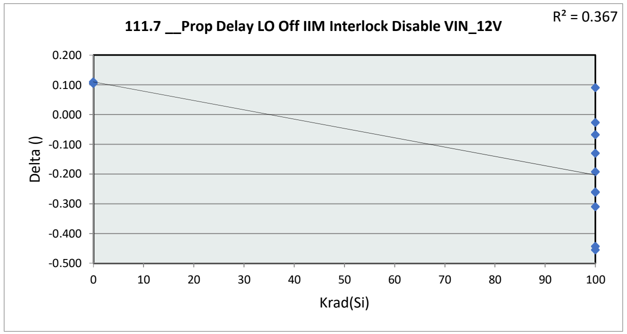


	111.6 __Prop Delay LO On IIM Interlock Disable VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.861	21.373
Average	21.926	21.606
Max	21.991	21.838
UL	38.000	38.000

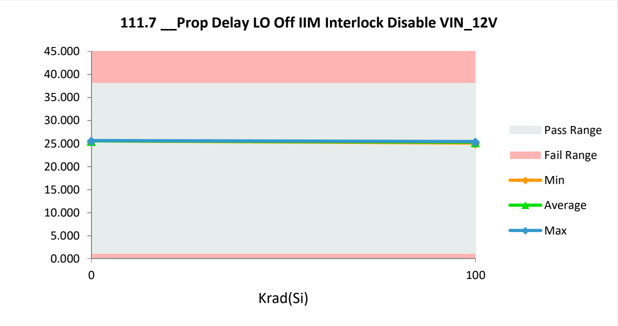


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.7 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.505	25.612	0.107
0	2	25.424	25.537	0.113
100	23	25.284	25.378	0.094
100	24	25.484	25.177	-0.307
100	25	25.597	25.145	-0.453
100	26	25.674	25.416	-0.258
100	27	25.513	25.072	-0.441
100	48u	25.347	25.324	-0.023
100	49u	25.363	25.236	-0.127
100	50u	25.408	25.151	-0.257
100	51u	25.568	25.378	-0.190
100	52u	25.494	25.428	-0.065
	Max	25.674	25.612	0.113
	Average	25.472	25.321	-0.151
	Min	25.284	25.072	-0.453
	Std Dev	0.112	0.167	0.201



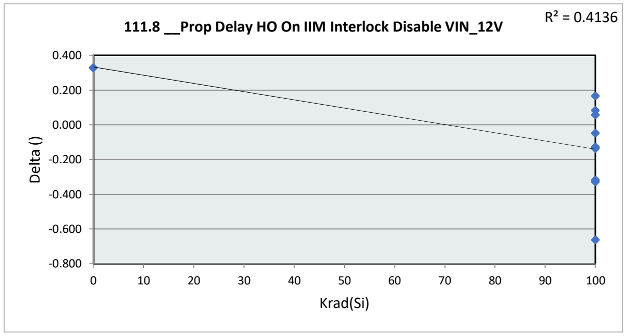
	111.7 __Prop Delay LO Off IIM Interlock Disable VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.537	25.072
Average	25.574	25.270
Max	25.612	25.428
UL	38.000	38.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

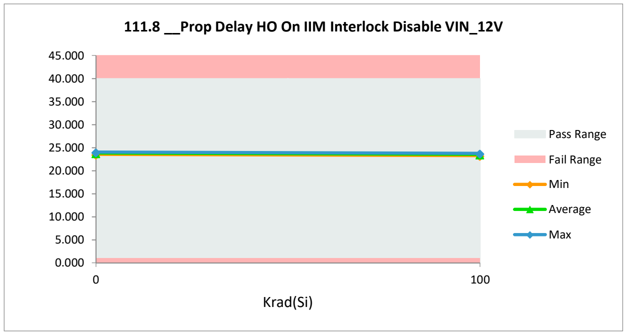
111.8 __Prop Delay HO On IIM I

	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.695	24.028	0.334
0	2	23.243	23.577	0.334
100	23	23.980	23.657	-0.323
100	24	24.071	23.414	-0.657
100	25	23.730	23.601	-0.128
100	26	23.458	23.416	-0.042
100	27	23.609	23.487	-0.122
100	48u	23.564	23.651	0.087
100	49u	23.581	23.752	0.171
100	50u	23.613	23.302	-0.311
100	51u	23.762	23.631	-0.132
100	52u	23.379	23.442	0.062
	Max	24.071	24.028	0.334
	Average	23.641	23.580	-0.061
	Min	23.243	23.302	-0.657
	Std Dev	0.233	0.192	0.286



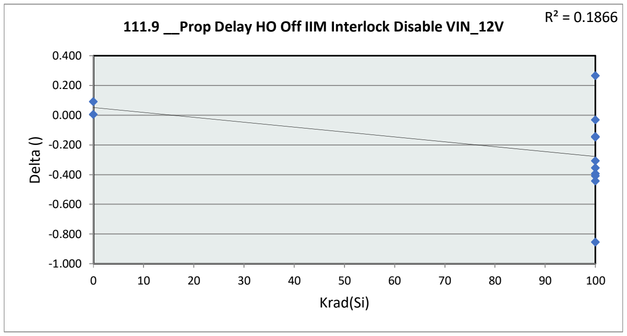
111.8 __Prop Delay HO On IIM Interlock Disable VIN_12

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.577	23.302
Average	23.803	23.535
Max	24.029	23.752
UL	40.000	40.000

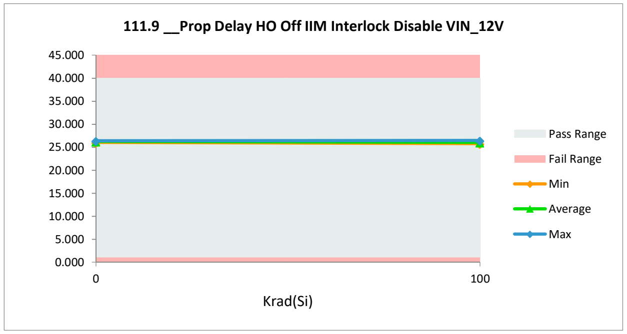


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.9 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.400	26.409	0.009
0	2	25.960	26.055	0.095
100	23	26.517	26.166	-0.351
100	24	26.588	25.738	-0.850
100	25	26.391	26.088	-0.303
100	26	26.185	26.454	0.269
100	27	26.499	26.094	-0.405
100	48u	26.353	26.214	-0.139
100	49u	26.165	26.137	-0.028
100	50u	26.202	25.764	-0.438
100	51u	26.299	25.911	-0.388
100	52u	25.969	25.825	-0.144
	Max	26.588	26.454	0.269
	Average	26.294	26.071	-0.223
	Min	25.960	25.738	-0.850
	Std Dev	0.204	0.231	0.297

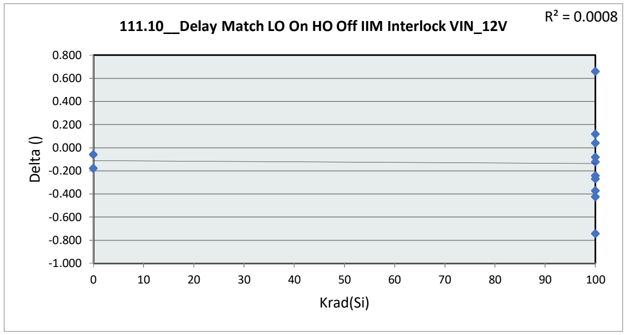


	111.9 __Prop Delay HO Off IIM Interlock Disable VIN_12	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	26.055	25.738
Average	26.232	26.039
Max	26.409	26.454
UL	40.000	40.000

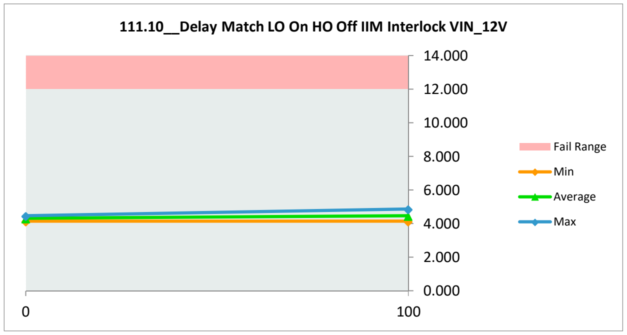


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.10__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.532	4.479	-0.053
0	2	4.316	4.144	-0.172
100	23	4.865	4.500	-0.366
100	24	5.023	4.287	-0.736
100	25	4.593	4.518	-0.075
100	26	4.195	4.861	0.666
100	27	4.607	4.731	0.124
100	48u	4.598	4.481	-0.117
100	49u	4.510	4.557	0.047
100	50u	4.703	4.286	-0.417
100	51u	4.551	4.288	-0.263
100	52u	4.375	4.140	-0.235
	Max	5.023	4.861	0.666
	Average	4.572	4.439	-0.133
	Min	4.195	4.140	-0.736
	Std Dev	0.226	0.221	0.340

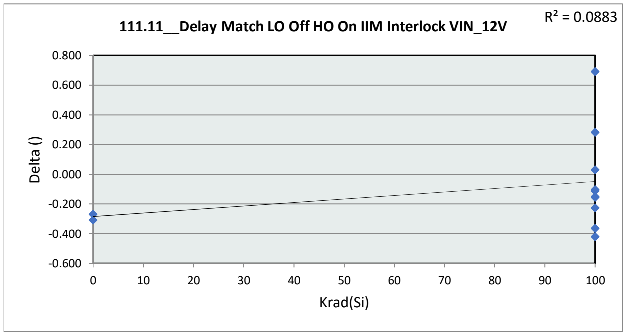


	111.10__Delay Match LO On HO Off IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.144	4.140
Average	4.311	4.465
Max	4.479	4.861
UL	12.000	12.000

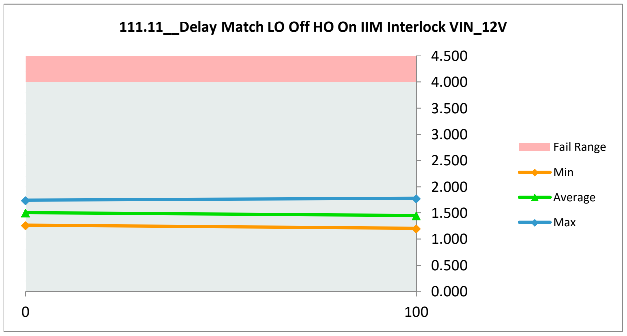


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.11__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.530	1.265	-0.266
0	2	2.045	1.742	-0.303
100	23	1.081	1.367	0.286
100	24	0.914	1.610	0.696
100	25	1.620	1.206	-0.414
100	26	1.924	1.777	-0.147
100	27	1.658	1.300	-0.359
100	48u	1.378	1.412	0.034
100	49u	1.493	1.271	-0.222
100	50u	1.535	1.428	-0.106
100	51u	1.501	1.401	-0.099
100	52u	1.857	1.707	-0.150
	Max	2.045	1.777	0.696
	Average	1.545	1.457	-0.088
	Min	0.914	1.206	-0.414
	Std Dev	0.324	0.201	0.309

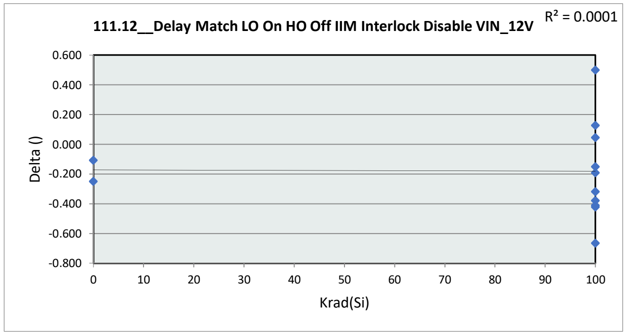


	111.11__Delay Match LO Off HO On IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.265	1.206
Average	1.504	1.448
Max	1.742	1.777
UL	4.000	4.000

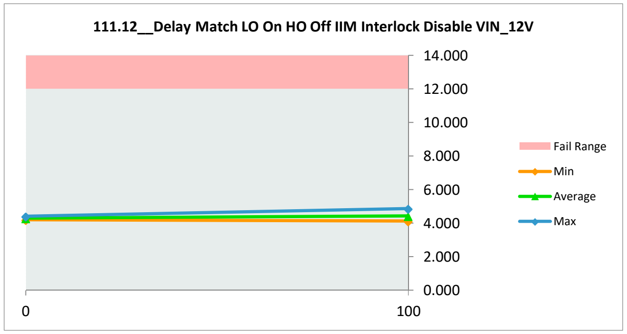


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.12__Delay Match LO On HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	12	
Min Limit				
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.662	4.418	-0.244
0	2	4.295	4.194	-0.101
100	23	4.893	4.476	-0.417
100	24	4.886	4.226	-0.660
100	25	4.618	4.473	-0.145
100	26	4.368	4.874	0.505
100	27	4.669	4.720	0.051
100	48u	4.781	4.376	-0.405
100	49u	4.450	4.582	0.133
100	50u	4.562	4.249	-0.312
100	51u	4.596	4.224	-0.372
100	52u	4.315	4.130	-0.185
	Max	4.893	4.874	0.505
	Average	4.591	4.412	-0.179
	Min	4.295	4.130	-0.660
	Std Dev	0.205	0.228	0.305

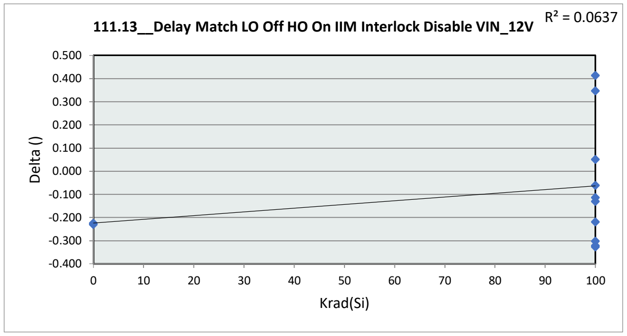


	111.12__Delay Match LO On HO Off IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.194	4.130
Average	4.306	4.433
Max	4.418	4.874
UL	12.000	12.000

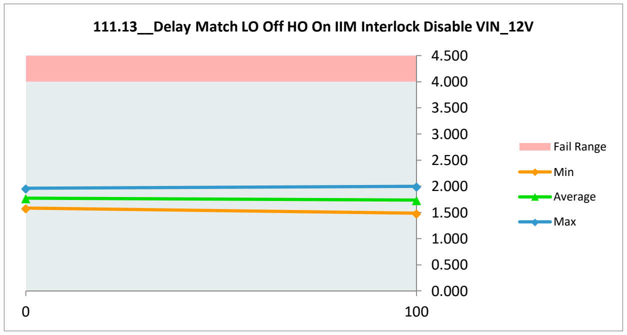


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		111.13__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.810	1.583	-0.227
0	2	2.181	1.960	-0.221
100	23	1.304	1.721	0.417
100	24	1.413	1.763	0.350
100	25	1.867	1.543	-0.324
100	26	2.216	2.000	-0.216
100	27	1.903	1.585	-0.318
100	48u	1.783	1.672	-0.111
100	49u	1.782	1.484	-0.298
100	50u	1.795	1.849	0.054
100	51u	1.806	1.747	-0.058
100	52u	2.114	1.987	-0.127
	Max	2.216	2.000	0.417
	Average	1.831	1.741	-0.090
	Min	1.304	1.484	-0.324
	Std Dev	0.273	0.178	0.248



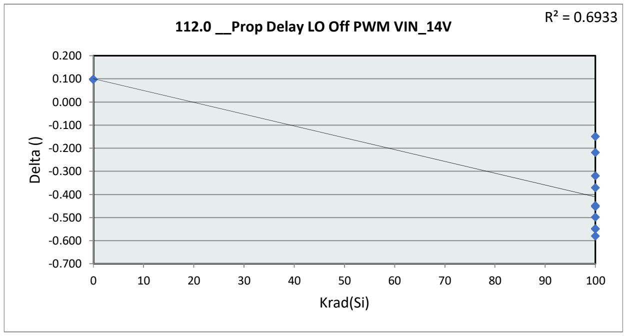
	111.13__Delay Match LO Off HO On IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.583	1.484
Average	1.772	1.735
Max	1.960	2.000
UL	4.000	4.000



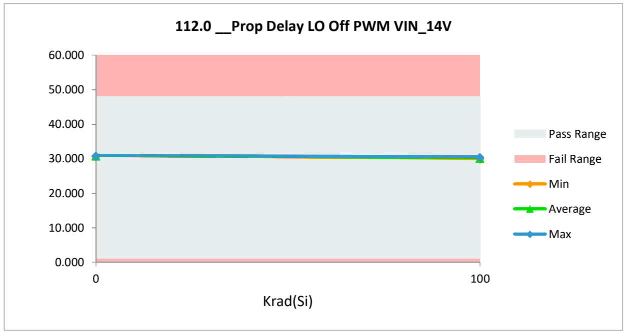
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	112.0 __Prop Delay LO Off PWM	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	48	48
Min Limit	1	1

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	30.874	30.975	0.101
0	2	30.873	30.973	0.100
100	23	30.568	30.421	-0.146
100	24	30.497	30.281	-0.217
100	25	30.737	30.160	-0.577
100	26	31.027	30.576	-0.451
100	27	30.573	30.077	-0.496
100	48u	30.628	30.311	-0.317
100	49u	30.654	30.209	-0.446
100	50u	30.664	30.118	-0.545
100	51u	30.916	30.369	-0.547
100	52u	30.748	30.380	-0.368
	Max	31.027	30.975	0.101
	Average	30.730	30.404	-0.326
	Min	30.497	30.077	-0.577
	Std Dev	0.162	0.300	0.239

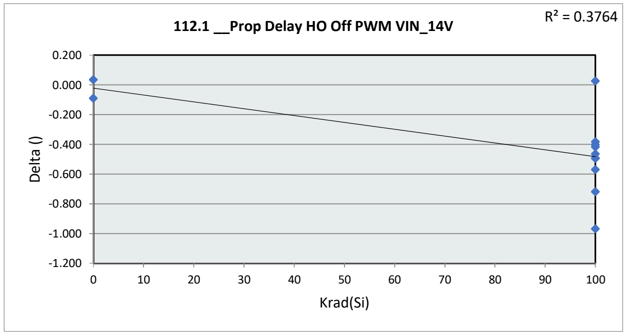


	112.0 __Prop Delay LO Off PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	48	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	30.973	30.077
Average	30.974	30.290
Max	30.975	30.577
UL	48.000	48.000

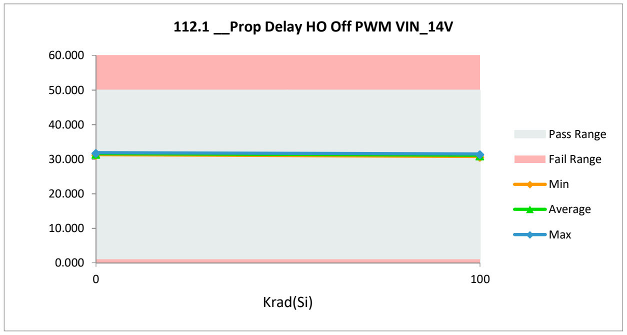


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.1 __Prop Delay HO Off PWM		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		50	50	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	31.819	31.860	0.042
0	2	31.434	31.349	-0.085
100	23	31.733	31.322	-0.410
100	24	31.788	30.826	-0.962
100	25	31.493	31.005	-0.488
100	26	31.482	31.514	0.032
100	27	31.581	31.123	-0.458
100	48u	31.663	31.265	-0.397
100	49u	31.475	31.097	-0.378
100	50u	31.523	30.959	-0.563
100	51u	31.683	30.970	-0.713
100	52u	31.235	30.748	-0.487
	Max	31.819	31.860	0.042
	Average	31.576	31.170	-0.406
	Min	31.235	30.748	-0.962
	Std Dev	0.169	0.313	0.292



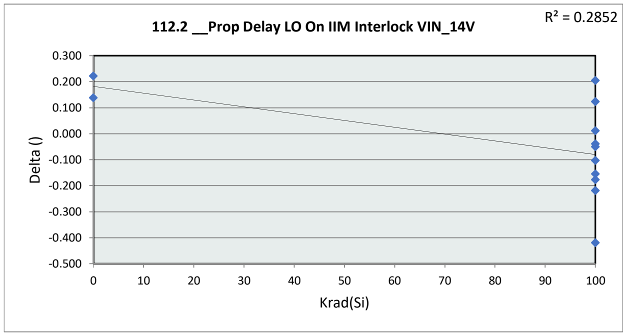
	112.1 __Prop Delay HO Off PWM VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	50	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	31.349	30.748
Average	31.605	31.083
Max	31.860	31.514
UL	50.000	50.000



TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

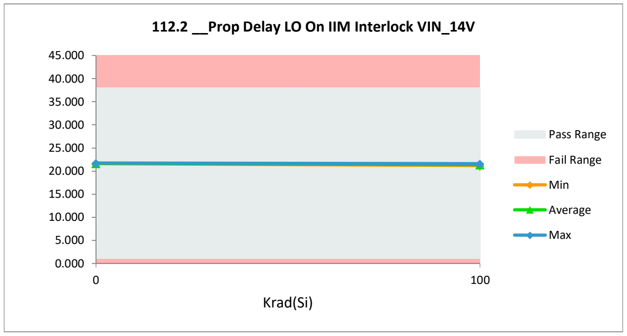
112.2 __Prop Delay LO On IIM I

Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.580	21.720	0.141
0	2	21.386	21.610	0.224
100	23	21.468	21.420	-0.048
100	24	21.458	21.242	-0.216
100	25	21.495	21.395	-0.101
100	26	21.561	21.387	-0.174
100	27	21.597	21.180	-0.417
100	48u	21.399	21.605	0.207
100	49u	21.463	21.427	-0.036
100	50u	21.387	21.235	-0.152
100	51u	21.504	21.518	0.014
100	52u	21.362	21.489	0.126
	Max	21.597	21.720	0.224
	Average	21.472	21.436	-0.036
	Min	21.362	21.180	-0.417
	Std Dev	0.079	0.164	0.191



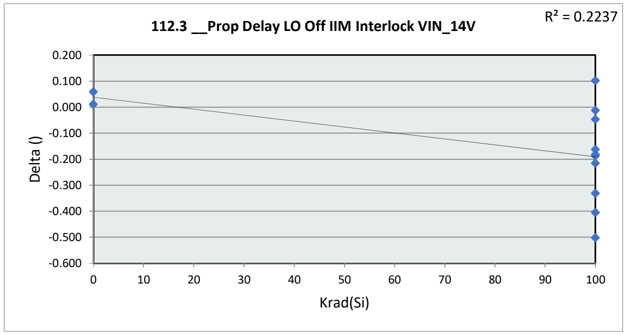
112.2 __Prop Delay LO On IIM Interlock VIN_14V

Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.610	21.180
Average	21.665	21.390
Max	21.720	21.605
UL	38.000	38.000

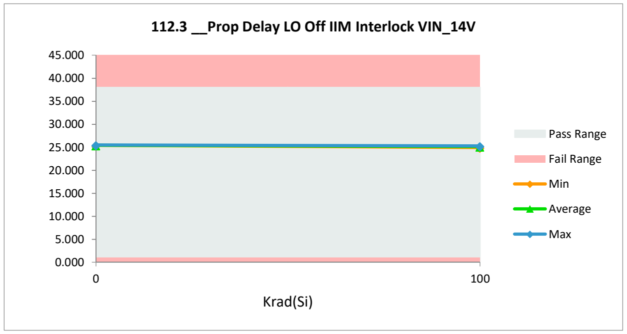


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.3 __Prop Delay LO Off IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.401	25.462	0.062
0	2	25.396	25.410	0.014
100	23	25.220	25.210	-0.010
100	24	25.211	25.167	-0.044
100	25	25.387	24.985	-0.402
100	26	25.478	25.266	-0.212
100	27	25.435	24.937	-0.498
100	48u	25.118	25.223	0.105
100	49u	25.237	25.058	-0.179
100	50u	25.250	24.922	-0.327
100	51u	25.311	25.127	-0.184
100	52u	25.394	25.235	-0.159
	Max	25.478	25.462	0.105
	Average	25.320	25.167	-0.153
	Min	25.118	24.922	-0.498
	Std Dev	0.111	0.172	0.188

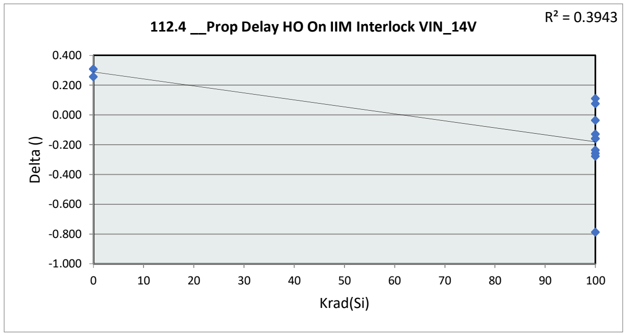


	112.3 __Prop Delay LO Off IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.410	24.922
Average	25.436	25.113
Max	25.463	25.266
UL	38.000	38.000

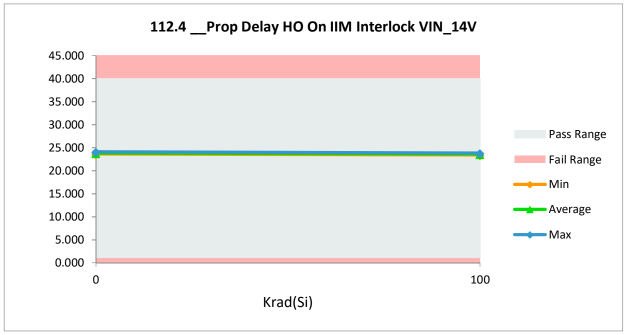


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.4 __Prop Delay HO On IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.776	24.090	0.314
0	2	23.348	23.611	0.263
100	23	24.011	23.759	-0.253
100	24	24.235	23.452	-0.782
100	25	23.785	23.662	-0.123
100	26	23.658	23.505	-0.154
100	27	23.795	23.523	-0.272
100	48u	23.736	23.816	0.081
100	49u	23.677	23.793	0.115
100	50u	23.655	23.424	-0.231
100	51u	23.884	23.730	-0.154
100	52u	23.459	23.429	-0.030
	Max	24.235	24.090	0.314
	Average	23.752	23.650	-0.102
	Min	23.348	23.424	-0.782
	Std Dev	0.232	0.199	0.291

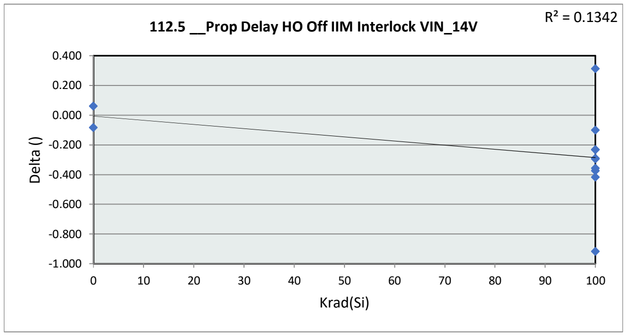


	112.4 __Prop Delay HO On IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.611	23.424
Average	23.850	23.609
Max	24.090	23.816
UL	40.000	40.000

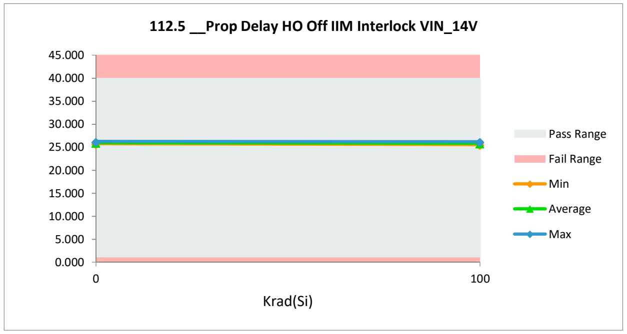


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.5 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.157	26.223	0.066
0	2	25.832	25.753	-0.079
100	23	26.337	25.923	-0.413
100	24	26.495	25.582	-0.913
100	25	26.156	25.870	-0.286
100	26	25.882	26.200	0.318
100	27	26.186	25.896	-0.289
100	48u	26.204	25.976	-0.228
100	49u	25.982	25.886	-0.096
100	50u	25.956	25.587	-0.369
100	51u	26.010	25.658	-0.352
100	52u	25.787	25.559	-0.228
	Max	26.495	26.223	0.318
	Average	26.082	25.843	-0.239
	Min	25.787	25.559	-0.913
	Std Dev	0.212	0.225	0.297

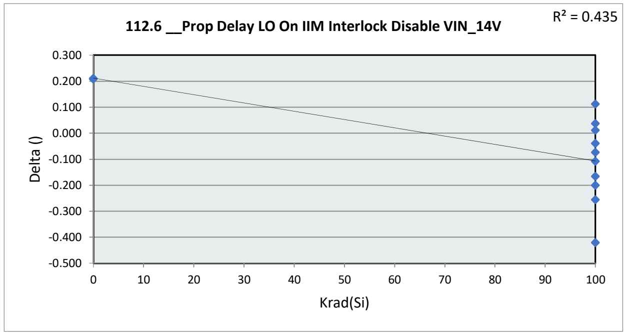


	112.5 __Prop Delay HO Off IIM Interlock VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.753	25.559
Average	25.988	25.814
Max	26.223	26.200
UL	40.000	40.000

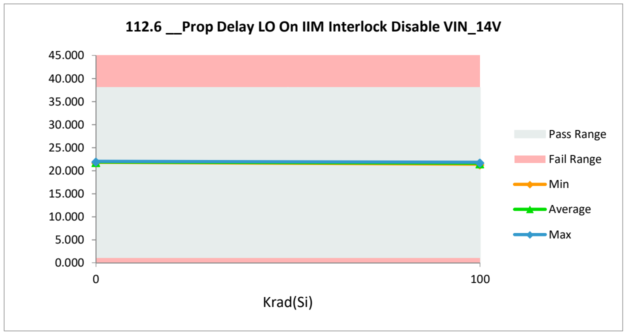


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.6 __Prop Delay LO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	38	38	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	21.780	21.991	0.211
0	2	21.583	21.797	0.214
100	23	21.605	21.646	0.040
100	24	21.711	21.549	-0.162
100	25	21.772	21.575	-0.197
100	26	21.894	21.642	-0.252
100	27	21.820	21.404	-0.417
100	48u	21.708	21.823	0.116
100	49u	21.642	21.538	-0.104
100	50u	21.606	21.536	-0.070
100	51u	21.709	21.673	-0.036
100	52u	21.687	21.701	0.014
	Max	21.894	21.991	0.214
	Average	21.710	21.656	-0.054
	Min	21.583	21.404	-0.417
	Std Dev	0.094	0.157	0.188

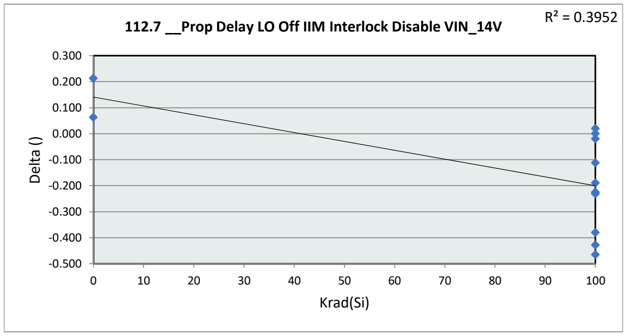


	112.6 __Prop Delay LO On IIM Interlock Disable VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	21.797	21.404
Average	21.894	21.609
Max	21.991	21.823
UL	38.000	38.000

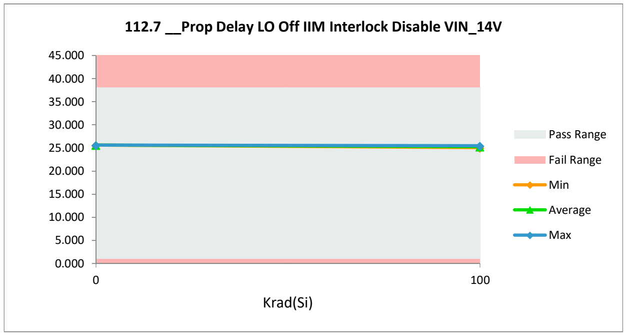


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.7 __Prop Delay LO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		38	38	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	25.553	25.619	0.065
0	2	25.400	25.616	0.216
100	23	25.391	25.282	-0.109
100	24	25.419	25.233	-0.186
100	25	25.560	25.099	-0.462
100	26	25.711	25.483	-0.228
100	27	25.519	25.094	-0.425
100	48u	25.369	25.372	0.003
100	49u	25.210	25.233	0.023
100	50u	25.420	25.043	-0.377
100	51u	25.556	25.334	-0.222
100	52u	25.531	25.513	-0.017
	Max	25.711	25.619	0.216
	Average	25.470	25.327	-0.143
	Min	25.210	25.043	-0.462
	Std Dev	0.128	0.199	0.211

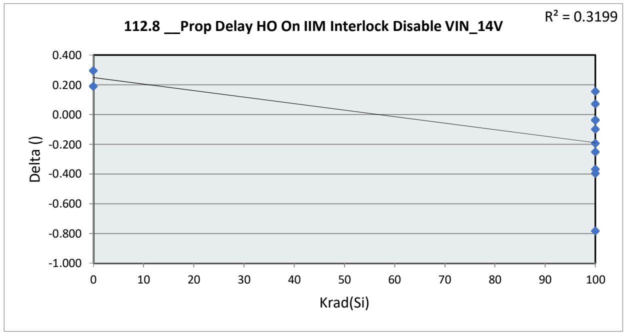


	112.7 __Prop Delay LO Off IIM Interlock Disable VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	38	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.616	25.043
Average	25.617	25.269
Max	25.619	25.513
UL	38.000	38.000

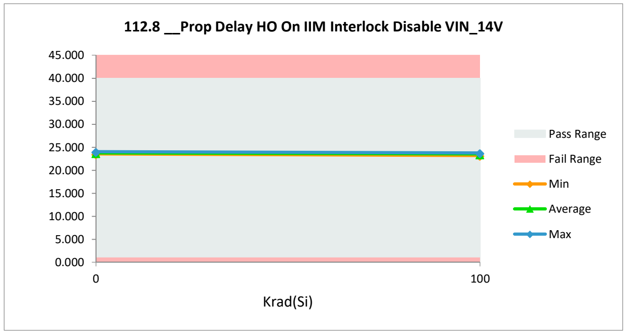


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.8 __Prop Delay HO On IIM I		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	40	40	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	23.704	24.006	0.302
0	2	23.380	23.576	0.196
100	23	23.969	23.607	-0.362
100	24	24.096	23.318	-0.778
100	25	23.792	23.605	-0.187
100	26	23.522	23.428	-0.094
100	27	23.687	23.441	-0.246
100	48u	23.637	23.714	0.077
100	49u	23.596	23.757	0.161
100	50u	23.599	23.208	-0.391
100	51u	23.745	23.713	-0.031
100	52u	23.395	23.363	-0.032
	Max	24.096	24.006	0.302
	Average	23.677	23.561	-0.115
	Min	23.380	23.208	-0.778
	Std Dev	0.210	0.222	0.301

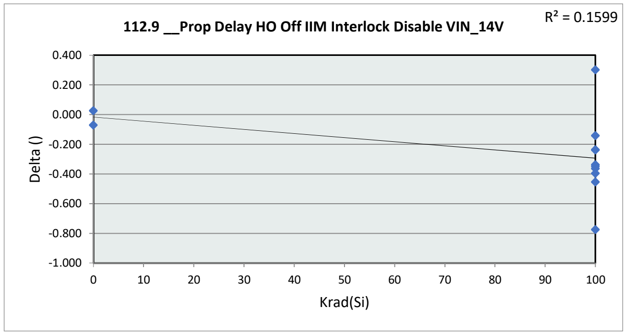


	112.8 __Prop Delay HO On IIM Interlock Disable VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	23.576	23.208
Average	23.791	23.515
Max	24.006	23.757
UL	40.000	40.000

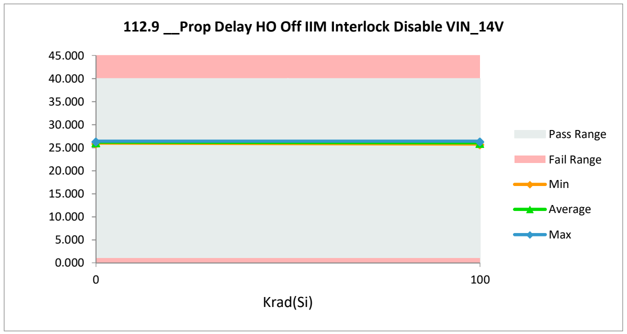


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.9 __Prop Delay HO Off IIM I		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		40	40	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	26.475	26.410	-0.065
0	2	25.955	25.986	0.031
100	23	26.503	26.170	-0.333
100	24	26.545	25.776	-0.768
100	25	26.410	26.066	-0.344
100	26	26.072	26.380	0.308
100	27	26.448	26.091	-0.357
100	48u	26.440	26.209	-0.231
100	49u	26.235	26.100	-0.135
100	50u	26.254	25.805	-0.449
100	51u	26.274	25.883	-0.391
100	52u	26.025	25.793	-0.232
	Max	26.545	26.410	0.308
	Average	26.303	26.056	-0.247
	Min	25.955	25.776	-0.768
	Std Dev	0.200	0.216	0.269

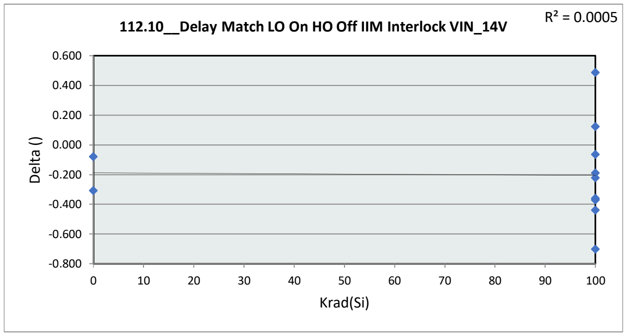


	112.9 __Prop Delay HO Off IIM Interlock Disable VIN_14	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	40	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	25.986	25.776
Average	26.198	26.027
Max	26.410	26.380
UL	40.000	40.000

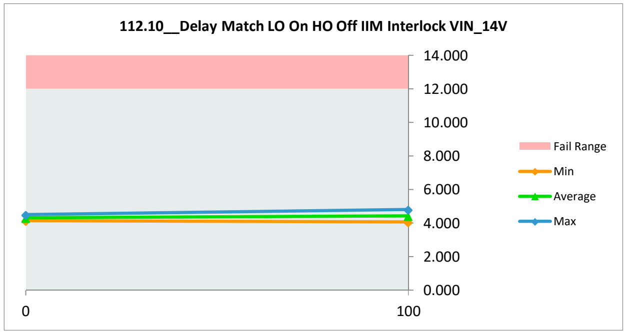


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.10__Delay Match LO On HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.577	4.503	-0.075
0	2	4.446	4.143	-0.303
100	23	4.869	4.503	-0.365
100	24	5.037	4.340	-0.697
100	25	4.661	4.476	-0.185
100	26	4.321	4.813	0.492
100	27	4.588	4.716	0.128
100	48u	4.806	4.371	-0.435
100	49u	4.519	4.459	-0.060
100	50u	4.569	4.352	-0.217
100	51u	4.506	4.140	-0.366
100	52u	4.424	4.070	-0.354
	Max	5.037	4.813	0.492
	Average	4.610	4.407	-0.203
	Min	4.321	4.070	-0.697
	Std Dev	0.204	0.224	0.304

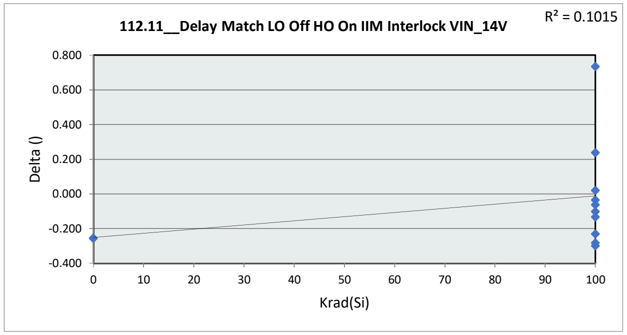


	112.10__Delay Match LO On HO Off IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.143	4.070
Average	4.323	4.424
Max	4.503	4.813
UL	12.000	12.000

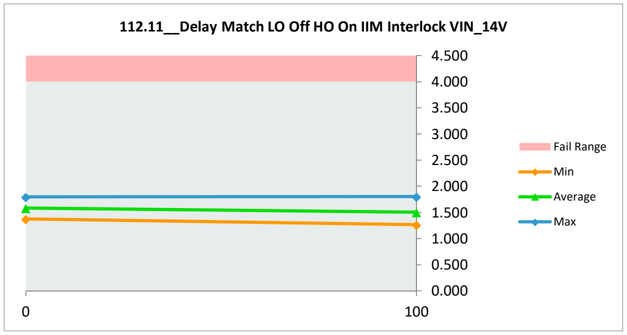


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.11__Delay Match LO Off HO		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		4	4	
Min Limit				
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.625	1.373	-0.252
0	2	2.048	1.799	-0.249
100	23	1.208	1.451	0.243
100	24	0.976	1.715	0.738
100	25	1.602	1.323	-0.278
100	26	1.819	1.761	-0.058
100	27	1.641	1.414	-0.226
100	48u	1.382	1.407	0.025
100	49u	1.559	1.265	-0.294
100	50u	1.594	1.498	-0.096
100	51u	1.427	1.397	-0.030
100	52u	1.935	1.806	-0.129
	Max	2.048	1.806	0.738
	Average	1.568	1.517	-0.051
	Min	0.976	1.265	-0.294
	Std Dev	0.297	0.197	0.293



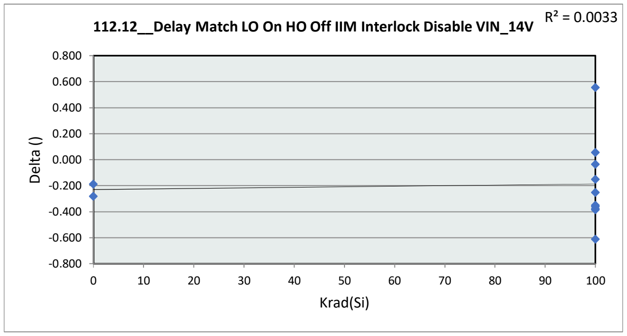
	112.11__Delay Match LO Off HO On IIM Interlock VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.373	1.265
Average	1.586	1.504
Max	1.799	1.806
UL	4.000	4.000



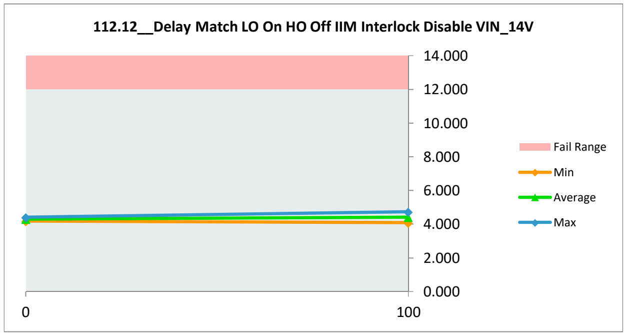
TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

	112.12__Delay Match LO On HO	
Test Site	DAL-FL	DAL-FL
Tester	ETS364	ETS364
Test Number	EB937004	EB937004
Unit		
Max Limit	12	12
Min Limit		

Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.695	4.419	-0.276
0	2	4.372	4.189	-0.183
100	23	4.897	4.524	-0.373
100	24	4.833	4.227	-0.606
100	25	4.638	4.491	-0.147
100	26	4.178	4.738	0.561
100	27	4.627	4.687	0.060
100	48u	4.733	4.386	-0.347
100	49u	4.593	4.562	-0.031
100	50u	4.648	4.270	-0.379
100	51u	4.565	4.211	-0.354
100	52u	4.339	4.092	-0.247
	Max	4.897	4.738	0.561
	Average	4.593	4.400	-0.193
	Min	4.178	4.092	-0.606
	Std Dev	0.208	0.207	0.295

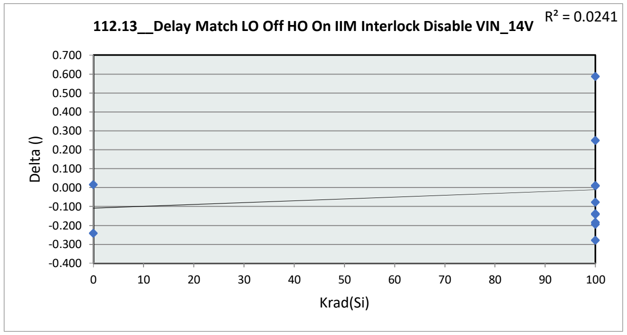


	112.12__Delay Match LO On HO Off IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit		
Krad(Si)	0	100
LL		
Min	4.189	4.092
Average	4.304	4.419
Max	4.419	4.738
UL	12.000	12.000

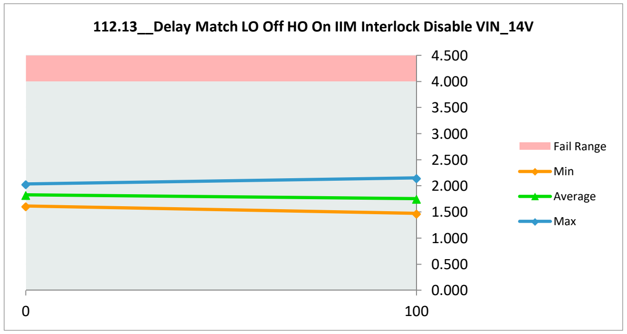


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		112.13__Delay Match LO Off HO		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	4	4	
	Min Limit			
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	1.849	1.612	-0.236
0	2	2.020	2.039	0.020
100	23	1.423	1.676	0.253
100	24	1.324	1.915	0.591
100	25	1.769	1.494	-0.275
100	26	2.188	2.055	-0.134
100	27	1.833	1.653	-0.179
100	48u	1.732	1.658	-0.074
100	49u	1.614	1.476	-0.138
100	50u	1.821	1.835	0.014
100	51u	1.811	1.621	-0.190
100	52u	2.136	2.151	0.015
	Max	2.188	2.151	0.591
	Average	1.793	1.765	-0.028
	Min	1.324	1.476	-0.275
	Std Dev	0.257	0.227	0.243

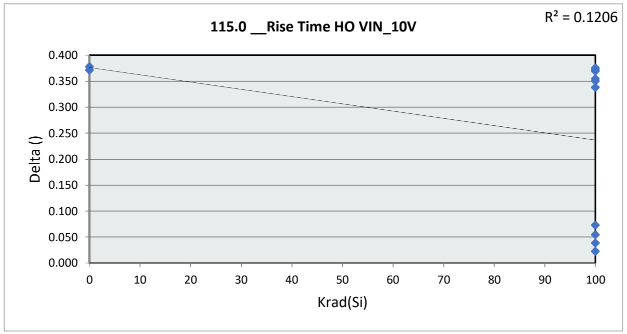


	112.13__Delay Match LO Off HO On IIM Interlock Disabl	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	4	
Min Limit		
Krad(Si)	0	100
LL		
Min	1.613	1.476
Average	1.826	1.753
Max	2.039	2.151
UL	4.000	4.000

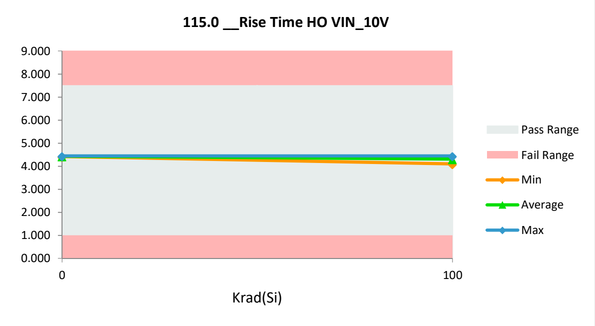


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		115.0 __Rise Time HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		7.5	7.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.045	4.425	0.380
0	2	4.078	4.451	0.373
100	23	4.067	4.444	0.377
100	24	4.039	4.114	0.075
100	25	4.071	4.423	0.352
100	26	4.053	4.109	0.056
100	27	4.075	4.115	0.040
100	48u	4.066	4.437	0.371
100	49u	4.075	4.415	0.340
100	50u	4.071	4.095	0.024
100	51u	4.081	4.437	0.357
100	52u	4.056	4.431	0.374
	Max	4.081	4.451	0.380
	Average	4.065	4.325	0.260
	Min	4.039	4.095	0.024
	Std Dev	0.013	0.160	0.157

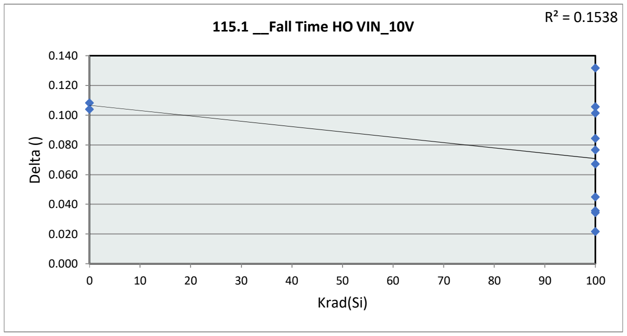


	115.0 __Rise Time HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.425	4.095
Average	4.438	4.302
Max	4.451	4.444
UL	7.500	7.500

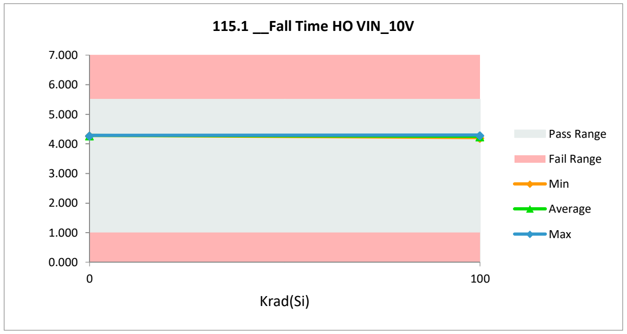


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		115.1 __Fall Time HO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.183	4.287	0.104
0	2	4.180	4.289	0.109
100	23	4.190	4.292	0.102
100	24	4.177	4.212	0.035
100	25	4.182	4.289	0.106
100	26	4.186	4.222	0.036
100	27	4.186	4.232	0.045
100	48u	4.198	4.275	0.077
100	49u	4.180	4.247	0.068
100	50u	4.189	4.212	0.022
100	51u	4.192	4.277	0.085
100	52u	4.174	4.306	0.132
	Max	4.198	4.306	0.132
	Average	4.185	4.262	0.077
	Min	4.174	4.212	0.022
	Std Dev	0.007	0.034	0.035

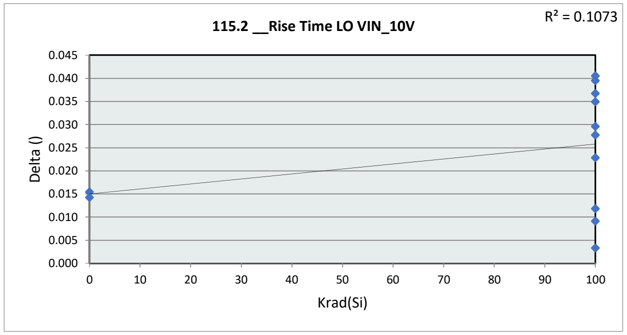


	115.1 __Fall Time HO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.287	4.212
Average	4.288	4.256
Max	4.289	4.306
UL	5.500	5.500

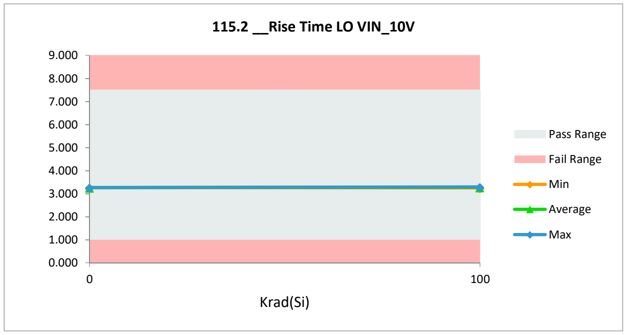


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		115.2 __Rise Time LO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		7.5	7.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.252	3.268	0.016
0	2	3.250	3.265	0.014
100	23	3.237	3.273	0.035
100	24	3.253	3.293	0.040
100	25	3.246	3.274	0.028
100	26	3.274	3.277	0.003
100	27	3.245	3.282	0.037
100	48u	3.253	3.263	0.009
100	49u	3.234	3.257	0.023
100	50u	3.243	3.284	0.041
100	51u	3.238	3.250	0.012
100	52u	3.259	3.289	0.030
	Max	3.274	3.293	0.041
	Average	3.249	3.273	0.024
	Min	3.234	3.250	0.003
	Std Dev	0.011	0.013	0.013

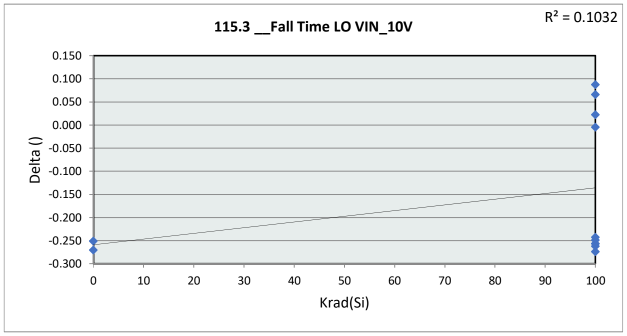


	115.2 __Rise Time LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.265	3.250
Average	3.266	3.274
Max	3.268	3.293
UL	7.500	7.500

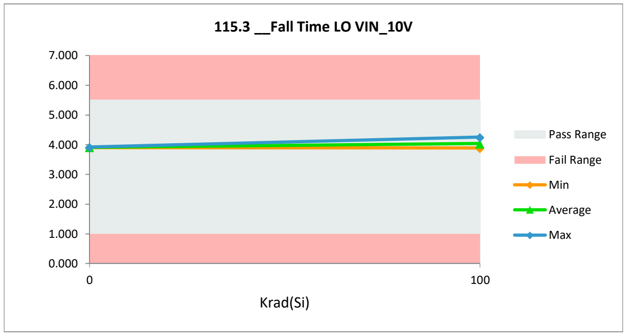


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		115.3 __Fall Time LO VIN_10V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.172	3.923	-0.250
0	2	4.170	3.901	-0.269
100	23	4.164	3.908	-0.255
100	24	4.172	4.196	0.023
100	25	4.167	3.912	-0.255
100	26	4.187	4.184	-0.003
100	27	4.169	4.258	0.089
100	48u	4.164	3.916	-0.248
100	49u	4.166	3.894	-0.272
100	50u	4.172	4.239	0.067
100	51u	4.184	3.923	-0.261
100	52u	4.162	3.921	-0.241
	Max	4.187	4.258	0.089
	Average	4.171	4.015	-0.156
	Min	4.162	3.894	-0.272
	Std Dev	0.008	0.152	0.150

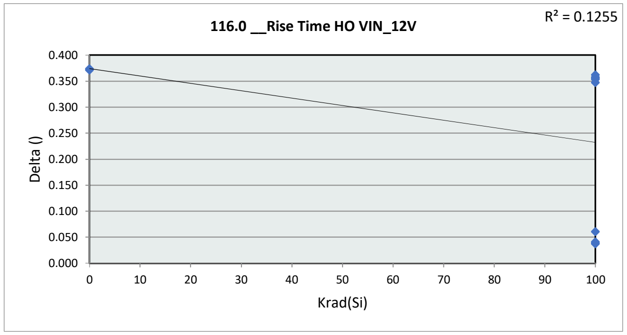


	115.3 __Fall Time LO VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.901	3.894
Average	3.912	4.035
Max	3.923	4.258
UL	5.500	5.500

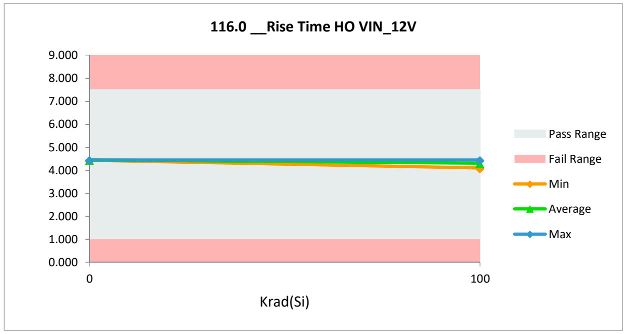


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		116.0 __Rise Time HO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.062	4.435	0.373
0	2	4.069	4.444	0.375
100	23	4.078	4.433	0.355
100	24	4.066	4.105	0.039
100	25	4.078	4.438	0.360
100	26	4.058	4.120	0.062
100	27	4.071	4.114	0.043
100	48u	4.066	4.430	0.364
100	49u	4.062	4.420	0.358
100	50u	4.065	4.105	0.040
100	51u	4.071	4.420	0.349
100	52u	4.087	4.443	0.356
	Max	4.087	4.444	0.375
	Average	4.069	4.326	0.256
	Min	4.058	4.105	0.039
	Std Dev	0.008	0.159	0.155

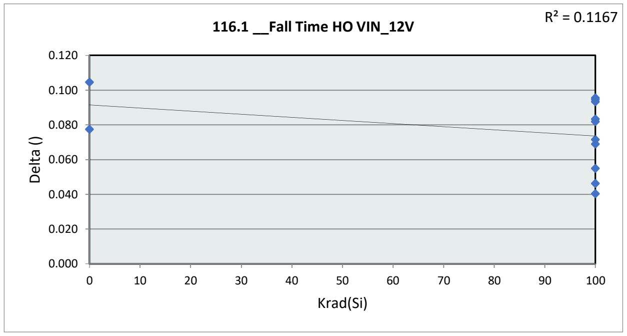


	116.0 __Rise Time HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.435	4.105
Average	4.440	4.303
Max	4.444	4.443
UL	7.500	7.500

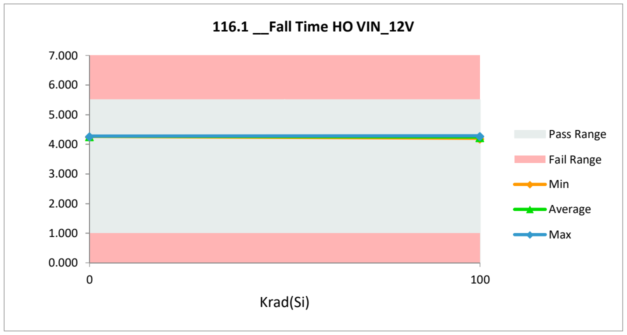


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		116.1 __Fall Time HO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	5.5	5.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.189	4.267	0.078
0	2	4.175	4.280	0.105
100	23	4.180	4.276	0.096
100	24	4.156	4.212	0.055
100	25	4.179	4.263	0.084
100	26	4.188	4.229	0.041
100	27	4.163	4.235	0.072
100	48u	4.192	4.286	0.094
100	49u	4.174	4.243	0.069
100	50u	4.161	4.208	0.047
100	51u	4.169	4.251	0.082
100	52u	4.186	4.281	0.095
	Max	4.192	4.286	0.105
	Average	4.176	4.253	0.077
	Min	4.156	4.208	0.041
	Std Dev	0.012	0.027	0.020

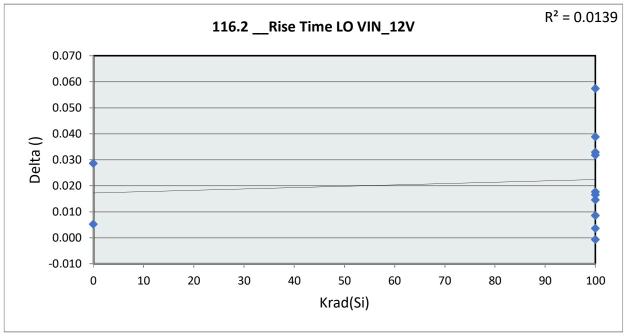


	116.1 __Fall Time HO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.267	4.208
Average	4.274	4.248
Max	4.280	4.286
UL	5.500	5.500

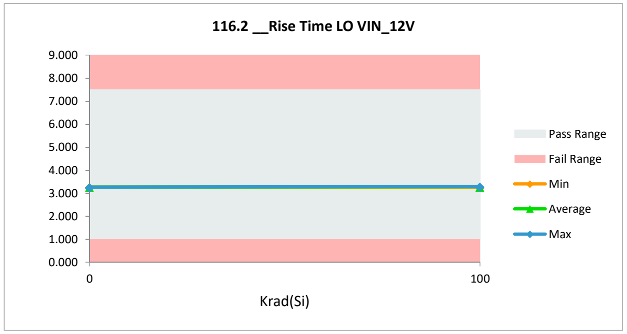


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		116.2 __Rise Time LO VIN_12V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.236	3.265	0.029
0	2	3.257	3.263	0.005
100	23	3.260	3.274	0.015
100	24	3.252	3.291	0.039
100	25	3.264	3.273	0.009
100	26	3.273	3.276	0.004
100	27	3.266	3.283	0.017
100	48u	3.245	3.277	0.032
100	49u	3.249	3.267	0.018
100	50u	3.235	3.292	0.058
100	51u	3.260	3.260	0.000
100	52u	3.254	3.287	0.033
	Max	3.273	3.292	0.058
	Average	3.254	3.276	0.022
	Min	3.235	3.260	0.000
	Std Dev	0.012	0.011	0.017

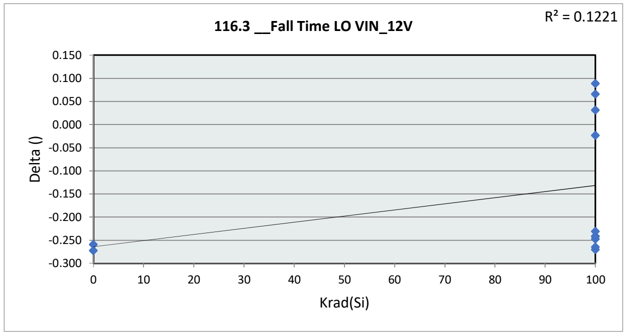


	116.2 __Rise Time LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.263	3.260
Average	3.264	3.278
Max	3.265	3.292
UL	7.500	7.500

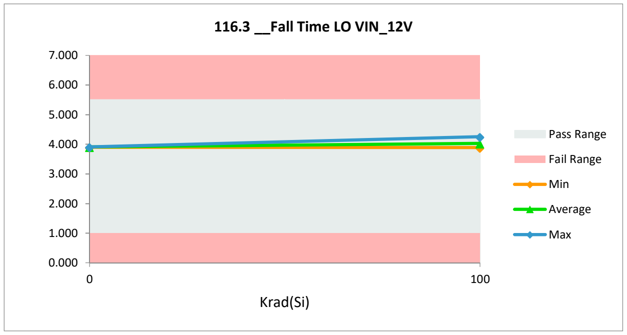


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		116.3 __Fall Time LO VIN_12V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.171	3.914	-0.258
0	2	4.171	3.900	-0.271
100	23	4.155	3.909	-0.246
100	24	4.170	4.203	0.033
100	25	4.153	3.913	-0.239
100	26	4.202	4.180	-0.022
100	27	4.163	4.254	0.091
100	48u	4.160	3.920	-0.240
100	49u	4.162	3.893	-0.269
100	50u	4.162	4.230	0.068
100	51u	4.160	3.931	-0.229
100	52u	4.176	3.913	-0.263
	Max	4.202	4.254	0.091
	Average	4.167	4.013	-0.154
	Min	4.153	3.893	-0.271
	Std Dev	0.013	0.151	0.148

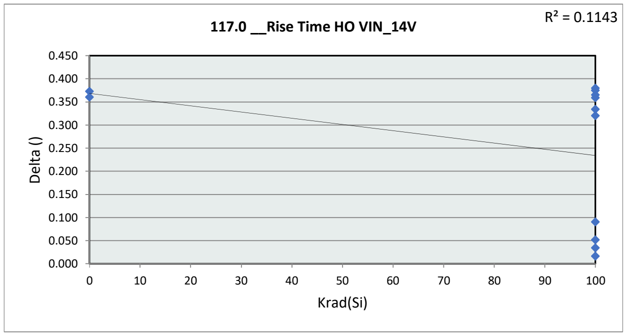


	116.3 __Fall Time LO VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.900	3.893
Average	3.907	4.035
Max	3.914	4.254
UL	5.500	5.500

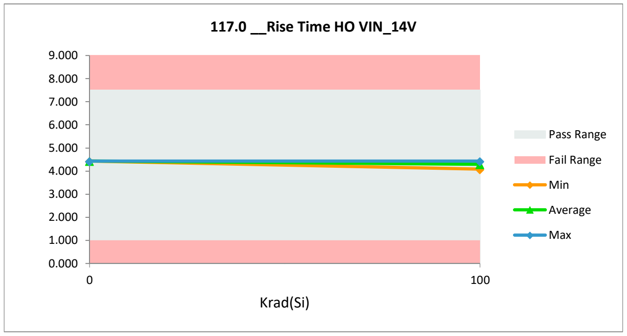


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		117.0 __Rise Time HO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	7.5	7.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.070	4.432	0.362
0	2	4.062	4.437	0.374
100	23	4.054	4.435	0.381
100	24	4.075	4.092	0.018
100	25	4.063	4.439	0.376
100	26	4.068	4.103	0.036
100	27	4.048	4.139	0.092
100	48u	4.089	4.410	0.322
100	49u	4.057	4.424	0.367
100	50u	4.047	4.100	0.053
100	51u	4.083	4.419	0.336
100	52u	4.076	4.437	0.360
	Max	4.089	4.439	0.381
	Average	4.066	4.322	0.256
	Min	4.047	4.092	0.018
	Std Dev	0.013	0.158	0.155

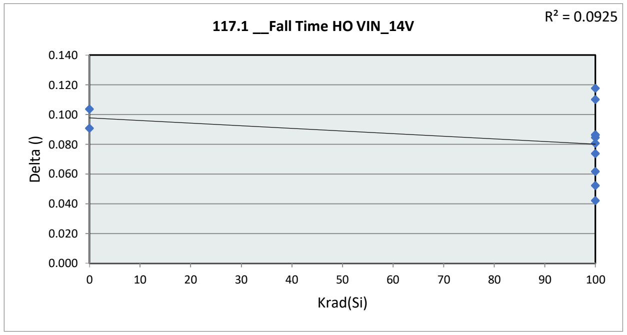


	117.0 __Rise Time HO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.432	4.092
Average	4.435	4.300
Max	4.437	4.439
UL	7.500	7.500

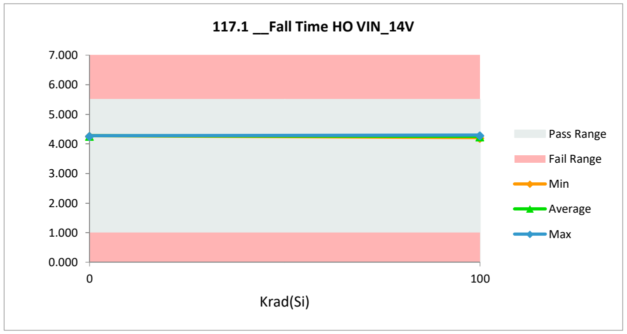


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		117.1 __Fall Time HO VIN_14V		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	5.5	5.5	
	Min Limit	1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.178	4.282	0.104
0	2	4.186	4.277	0.091
100	23	4.184	4.302	0.118
100	24	4.154	4.228	0.074
100	25	4.181	4.268	0.087
100	26	4.175	4.228	0.053
100	27	4.163	4.249	0.085
100	48u	4.185	4.272	0.087
100	49u	4.187	4.230	0.043
100	50u	4.149	4.212	0.062
100	51u	4.184	4.265	0.081
100	52u	4.182	4.293	0.111
	Max	4.187	4.302	0.118
	Average	4.176	4.259	0.083
	Min	4.149	4.212	0.043
	Std Dev	0.013	0.029	0.023

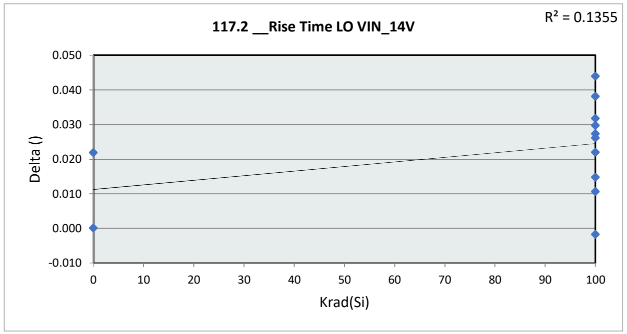


	117.1 __Fall Time HO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	4.277	4.212
Average	4.280	4.255
Max	4.282	4.302
UL	5.500	5.500

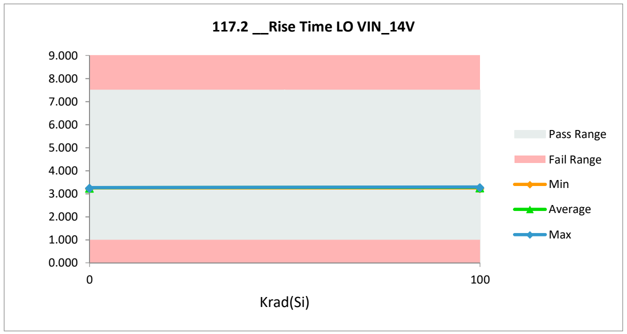


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		117.2 __Rise Time LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		7.5	7.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.257	3.257	0.000
0	2	3.244	3.266	0.022
100	23	3.248	3.274	0.026
100	24	3.258	3.288	0.030
100	25	3.259	3.274	0.015
100	26	3.267	3.278	0.011
100	27	3.255	3.283	0.028
100	48u	3.241	3.280	0.038
100	49u	3.247	3.270	0.022
100	50u	3.251	3.295	0.044
100	51u	3.260	3.258	-0.002
100	52u	3.246	3.277	0.032
	Max	3.267	3.295	0.044
	Average	3.253	3.275	0.022
	Min	3.241	3.257	-0.002
	Std Dev	0.008	0.011	0.014

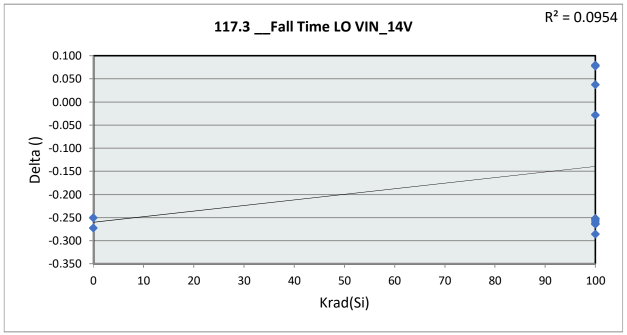


	117.2 __Rise Time LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	7.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.257	3.258
Average	3.261	3.278
Max	3.266	3.295
UL	7.500	7.500

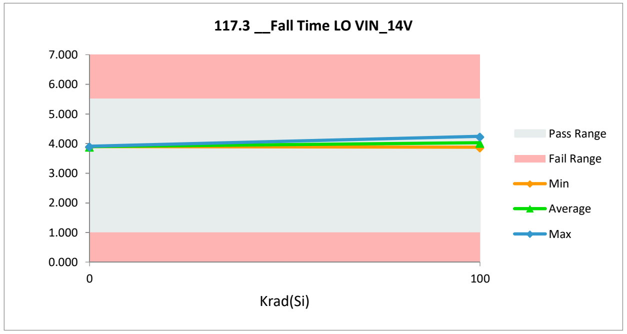


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		117.3 __Fall Time LO VIN_14V		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		5.5	5.5	
Min Limit		1	1	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.157	3.908	-0.249
0	2	4.169	3.897	-0.271
100	23	4.168	3.908	-0.261
100	24	4.156	4.195	0.039
100	25	4.161	3.910	-0.250
100	26	4.205	4.177	-0.027
100	27	4.172	4.250	0.079
100	48u	4.168	3.905	-0.263
100	49u	4.166	3.882	-0.284
100	50u	4.151	4.232	0.081
100	51u	4.184	3.928	-0.256
100	52u	4.165	3.913	-0.252
	Max	4.205	4.250	0.081
	Average	4.168	4.009	-0.160
	Min	4.151	3.882	-0.284
	Std Dev	0.014	0.153	0.152

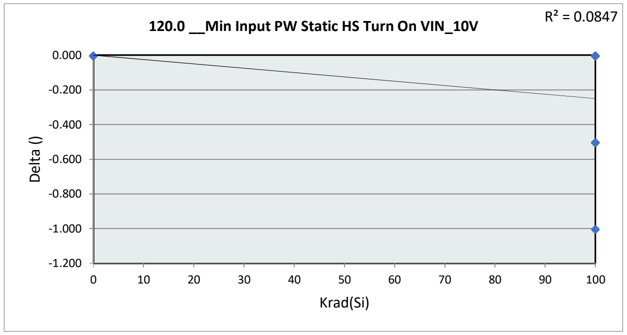


	117.3 __Fall Time LO VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	5.5	
Min Limit	1	
Krad(Si)	0	100
LL	1.000	1.000
Min	3.897	3.882
Average	3.903	4.030
Max	3.908	4.250
UL	5.500	5.500

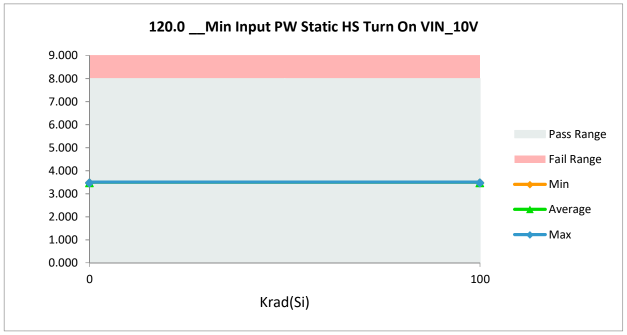


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.0 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

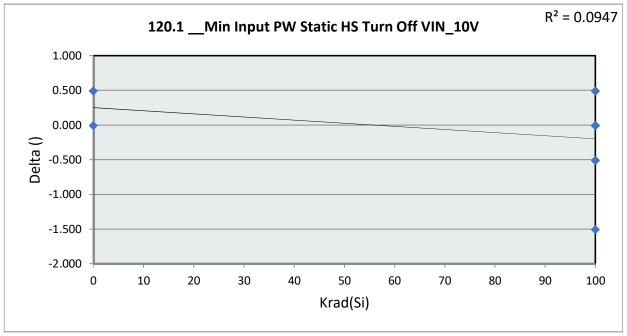


	120.0 __Min Input PW Static HS Turn On VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

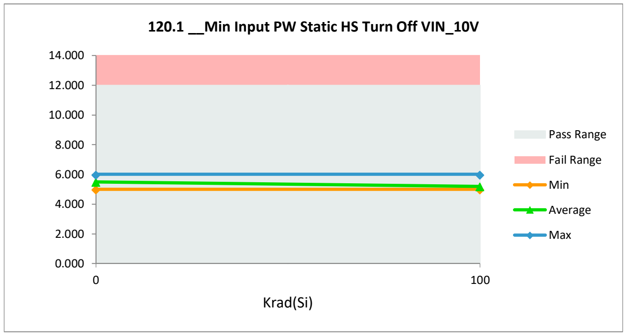


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.1 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	5.500	-0.500
100	48u	5.000	5.000	0.000
100	49u	5.000	5.500	0.500
100	50u	5.000	5.000	0.000
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.250	-0.125
	Min	4.500	5.000	-1.500
	Std Dev	0.569	0.399	0.569

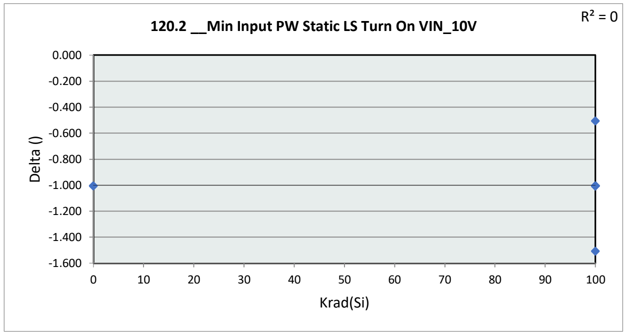


	120.1 __Min Input PW Static HS Turn Off VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	5.000
Average	5.500	5.200
Max	6.000	6.000
UL	12.000	12.000

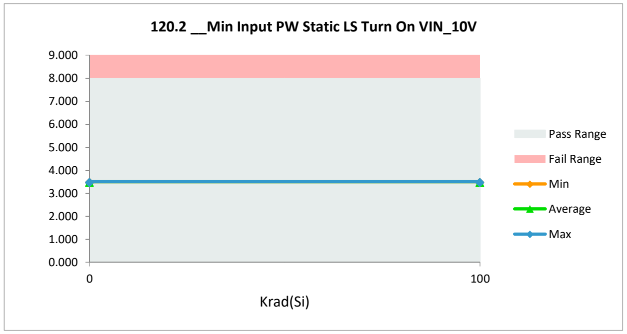


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.2 __Min Input PW Static LS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.500	3.500	-1.000
0	2	4.500	3.500	-1.000
100	23	4.500	3.500	-1.000
100	24	4.500	3.500	-1.000
100	25	4.500	3.500	-1.000
100	26	5.000	3.500	-1.500
100	27	4.500	3.500	-1.000
100	48u	4.000	3.500	-0.500
100	49u	4.500	3.500	-1.000
100	50u	4.500	3.500	-1.000
100	51u	4.500	3.500	-1.000
100	52u	4.500	3.500	-1.000
	Max	5.000	3.500	-0.500
	Average	4.500	3.500	-1.000
	Min	4.000	3.500	-1.500
	Std Dev	0.213	0.000	0.213

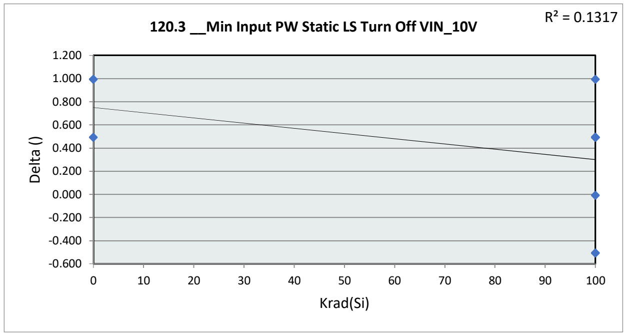


	120.2 __Min Input PW Static LS Turn On VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

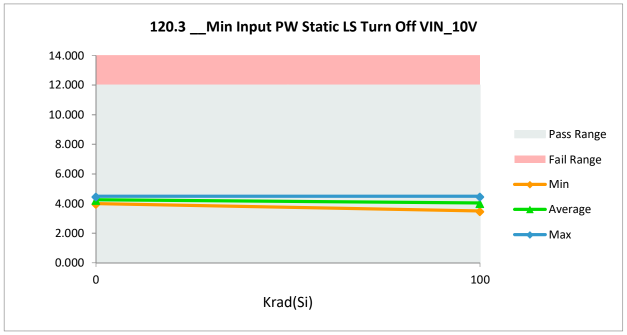


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.3 __Min Input PW Static LS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		8	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	4.000	0.500
0	2	3.500	4.500	1.000
100	23	4.000	4.500	0.500
100	24	4.500	4.000	-0.500
100	25	4.000	3.500	-0.500
100	26	3.500	4.000	0.500
100	27	4.000	4.000	0.000
100	48u	3.500	4.000	0.500
100	49u	3.500	4.000	0.500
100	50u	3.500	4.500	1.000
100	51u	3.500	4.000	0.500
100	52u	3.500	4.000	0.500
	Max	4.500	4.500	1.000
	Average	3.708	4.083	0.375
	Min	3.500	3.500	-0.500
	Std Dev	0.334	0.289	0.483

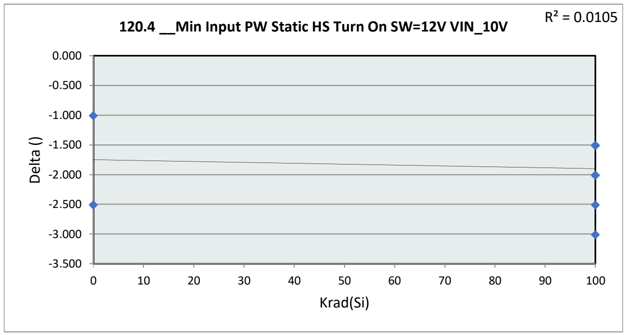


	120.3 __Min Input PW Static LS Turn Off VIN_10V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.000	3.500
Average	4.250	4.050
Max	4.500	4.500
UL	12.000	12.000

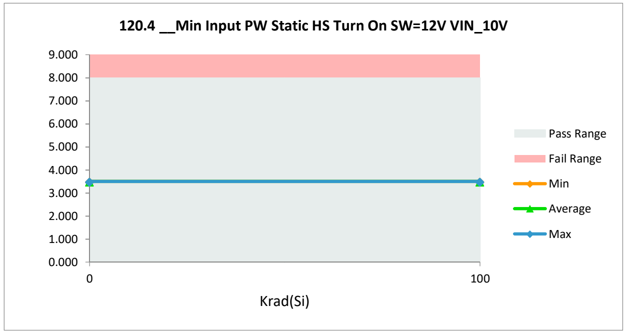


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.4 __Min Input PW Static HS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		12	8	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	3.500	-2.500
0	2	4.500	3.500	-1.000
100	23	5.500	3.500	-2.000
100	24	6.500	3.500	-3.000
100	25	5.500	3.500	-2.000
100	26	5.500	3.500	-2.000
100	27	6.000	3.500	-2.500
100	48u	5.000	3.500	-1.500
100	49u	5.000	3.500	-1.500
100	50u	5.000	3.500	-1.500
100	51u	5.000	3.500	-1.500
100	52u	5.000	3.500	-1.500
	Max	6.500	3.500	-1.000
	Average	5.375	3.500	-1.875
	Min	4.500	3.500	-3.000
	Std Dev	0.569	0.000	0.569

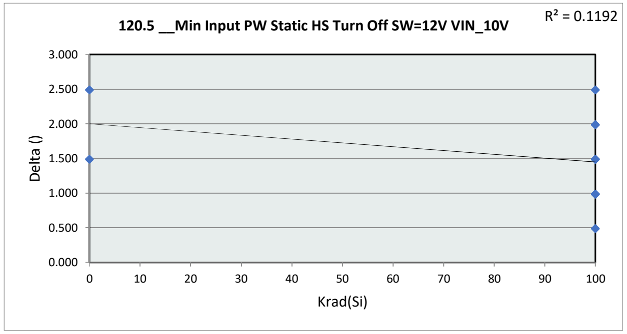


	120.4 __Min Input PW Static HS Turn On SW=12V VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

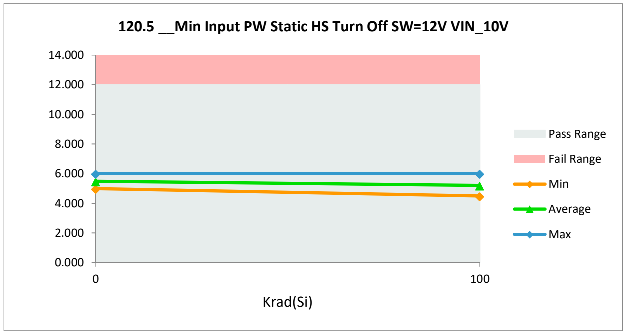


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		120.5 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	6.000	2.500
0	2	3.500	5.000	1.500
100	23	4.000	5.000	1.000
100	24	4.500	5.000	0.500
100	25	4.000	5.000	1.000
100	26	3.500	6.000	2.500
100	27	4.000	5.500	1.500
100	48u	3.500	5.500	2.000
100	49u	3.500	5.500	2.000
100	50u	3.500	4.500	1.000
100	51u	3.500	5.000	1.500
100	52u	3.500	5.000	1.500
	Max	4.500	6.000	2.500
	Average	3.708	5.250	1.542
	Min	3.500	4.500	0.500
	Std Dev	0.334	0.452	0.620

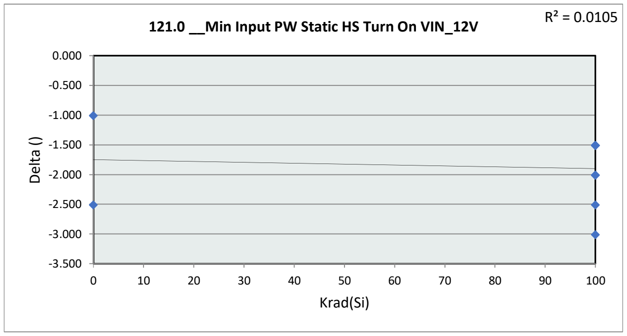


	120.5 __Min Input PW Static HS Turn Off SW=12V VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	4.500
Average	5.500	5.200
Max	6.000	6.000
UL	12.000	12.000

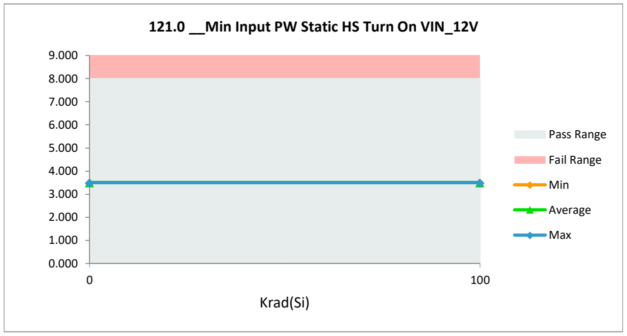


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		121.0 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	3.500	-2.500
0	2	4.500	3.500	-1.000
100	23	5.500	3.500	-2.000
100	24	6.500	3.500	-3.000
100	25	5.500	3.500	-2.000
100	26	5.500	3.500	-2.000
100	27	6.000	3.500	-2.500
100	48u	5.000	3.500	-1.500
100	49u	5.000	3.500	-1.500
100	50u	5.000	3.500	-1.500
100	51u	5.000	3.500	-1.500
100	52u	5.000	3.500	-1.500
	Max	6.500	3.500	-1.000
	Average	5.375	3.500	-1.875
	Min	4.500	3.500	-3.000
	Std Dev	0.569	0.000	0.569

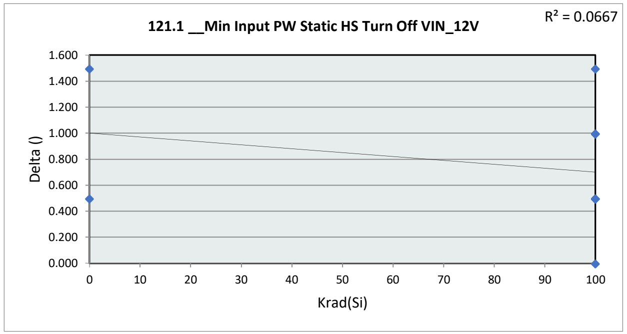


	121.0 __Min Input PW Static HS Turn On VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

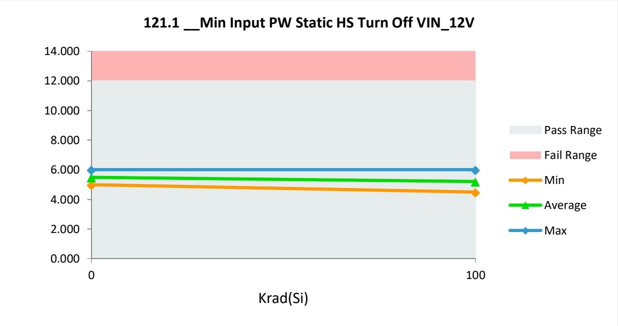


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		121.1 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.500	6.000	1.500
0	2	4.500	5.000	0.500
100	23	4.500	5.000	0.500
100	24	4.500	5.000	0.500
100	25	4.500	5.000	0.500
100	26	5.000	6.000	1.000
100	27	4.500	5.500	1.000
100	48u	4.000	5.500	1.500
100	49u	4.500	5.500	1.000
100	50u	4.500	4.500	0.000
100	51u	4.500	5.000	0.500
100	52u	4.500	5.000	0.500
	Max	5.000	6.000	1.500
	Average	4.500	5.250	0.750
	Min	4.000	4.500	0.000
	Std Dev	0.213	0.452	0.452

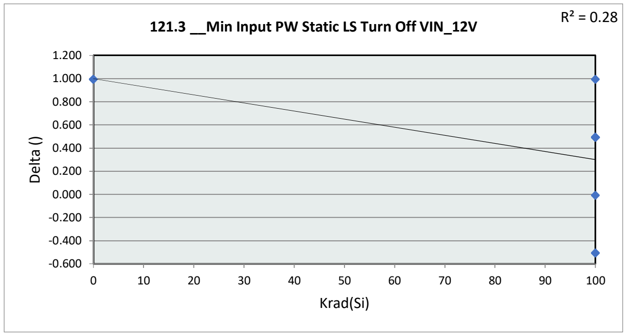


	121.1 __Min Input PW Static HS Turn Off VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	4.500
Average	5.500	5.200
Max	6.000	6.000
UL	12.000	12.000

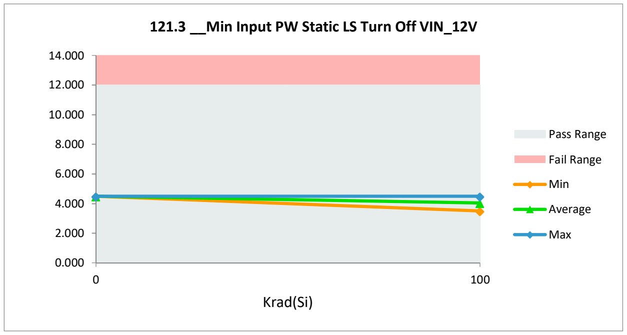


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		121.3 __Min Input PW Static LS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		8	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	4.500	1.000
0	2	3.500	4.500	1.000
100	23	4.000	4.500	0.500
100	24	4.500	4.000	-0.500
100	25	4.000	3.500	-0.500
100	26	3.500	4.000	0.500
100	27	4.000	4.000	0.000
100	48u	3.500	4.000	0.500
100	49u	3.500	4.000	0.500
100	50u	3.500	4.500	1.000
100	51u	3.500	4.000	0.500
100	52u	3.500	4.000	0.500
	Max	4.500	4.500	1.000
	Average	3.708	4.125	0.417
	Min	3.500	3.500	-0.500
	Std Dev	0.334	0.311	0.515

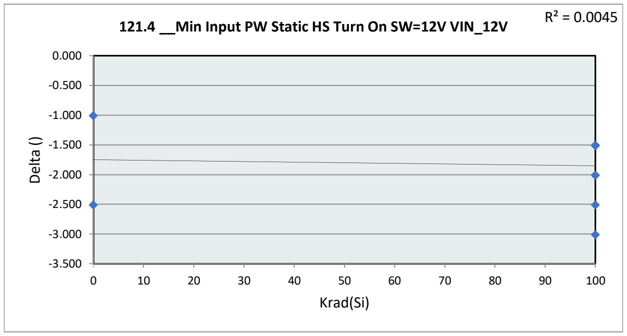


	121.3 __Min Input PW Static LS Turn Off VIN_12V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.500	3.500
Average	4.500	4.050
Max	4.500	4.500
UL	12.000	12.000

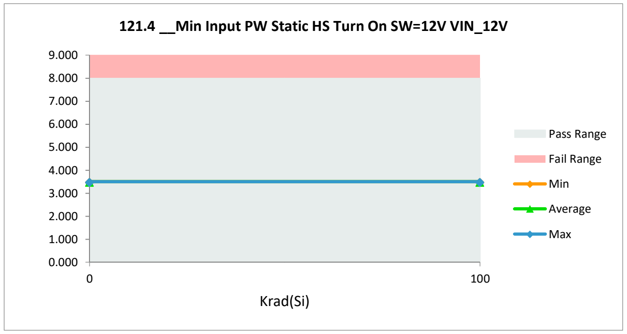


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		121.4 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	3.500	-2.500
0	2	4.500	3.500	-1.000
100	23	5.500	3.500	-2.000
100	24	6.500	3.500	-3.000
100	25	5.500	3.500	-2.000
100	26	5.000	3.500	-1.500
100	27	6.000	3.500	-2.500
100	48u	5.000	3.500	-1.500
100	49u	5.000	3.500	-1.500
100	50u	5.000	3.500	-1.500
100	51u	5.000	3.500	-1.500
100	52u	5.000	3.500	-1.500
	Max	6.500	3.500	-1.000
	Average	5.333	3.500	-1.833
	Min	4.500	3.500	-3.000
	Std Dev	0.577	0.000	0.577

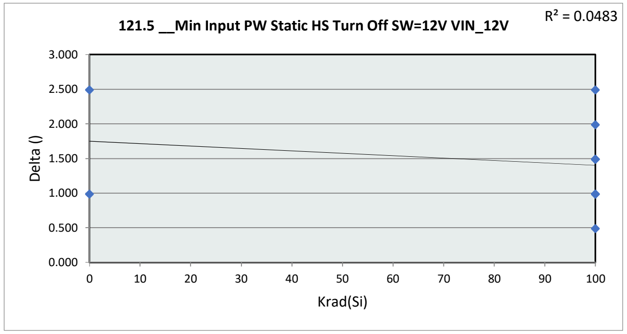


	121.4 __Min Input PW Static HS Turn On SW=12V VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

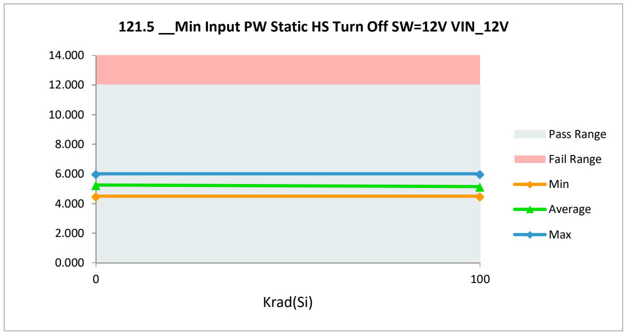


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		121.5 __Min Input PW Static HS		
Test Site		DAL-FL	DAL-FL	
Tester		ETS364	ETS364	
Test Number		EB937004	EB937004	
Unit				
Max Limit		8	12	
Min Limit		0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	6.000	2.500
0	2	3.500	4.500	1.000
100	23	4.000	5.000	1.000
100	24	4.500	5.000	0.500
100	25	4.000	5.000	1.000
100	26	3.500	6.000	2.500
100	27	4.000	5.500	1.500
100	48u	3.500	5.000	1.500
100	49u	3.500	5.500	2.000
100	50u	3.500	4.500	1.000
100	51u	3.500	5.000	1.500
100	52u	3.500	5.000	1.500
	Max	4.500	6.000	2.500
	Average	3.708	5.167	1.458
	Min	3.500	4.500	0.500
	Std Dev	0.334	0.492	0.620

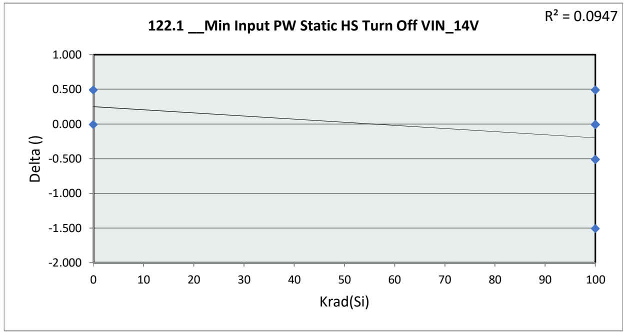


	121.5 __Min Input PW Static HS Turn Off SW=12V VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.500	4.500
Average	5.250	5.150
Max	6.000	6.000
UL	12.000	12.000

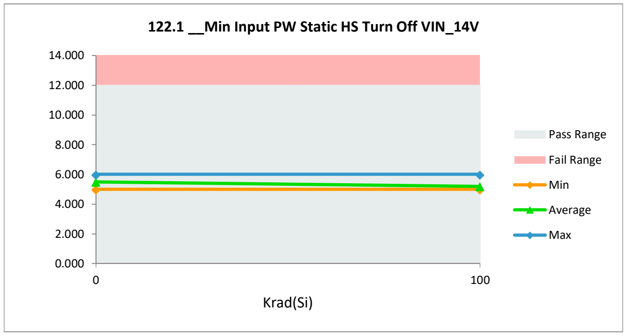


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		122.1 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	5.500	-0.500
100	48u	5.000	5.000	0.000
100	49u	5.000	5.500	0.500
100	50u	5.000	5.000	0.000
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.250	-0.125
	Min	4.500	5.000	-1.500
	Std Dev	0.569	0.399	0.569

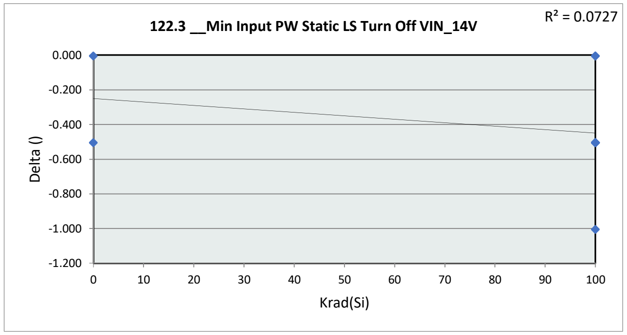


	122.1 __Min Input PW Static HS Turn Off VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	5.000
Average	5.500	5.200
Max	6.000	6.000
UL	12.000	12.000

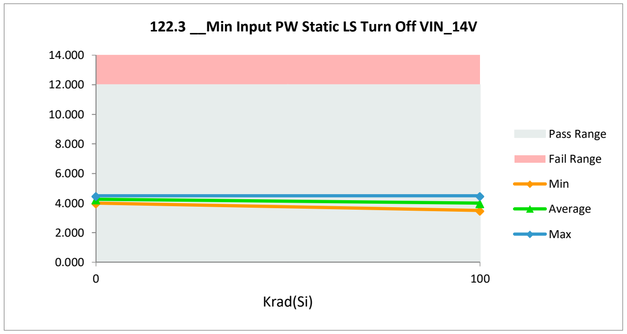


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		122.3 __Min Input PW Static LS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	4.500	4.000	-0.500
0	2	4.500	4.500	0.000
100	23	4.500	4.500	0.000
100	24	4.500	4.000	-0.500
100	25	4.500	3.500	-1.000
100	26	4.500	4.000	-0.500
100	27	4.500	4.000	-0.500
100	48u	4.000	4.000	0.000
100	49u	4.500	4.000	-0.500
100	50u	4.500	4.000	-0.500
100	51u	4.500	4.000	-0.500
100	52u	4.500	4.000	-0.500
	Max	4.500	4.500	0.000
	Average	4.458	4.042	-0.417
	Min	4.000	3.500	-1.000
	Std Dev	0.144	0.257	0.289

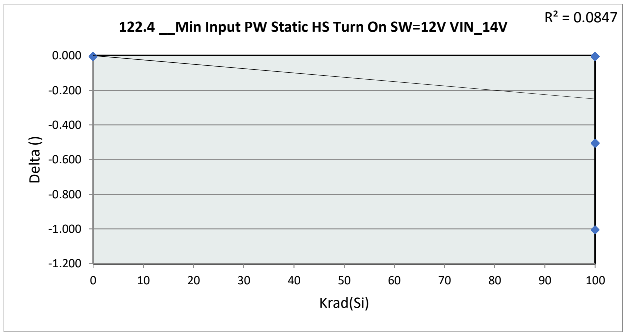


	122.3 __Min Input PW Static LS Turn Off VIN_14V	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	4.000	3.500
Average	4.250	4.000
Max	4.500	4.500
UL	12.000	12.000

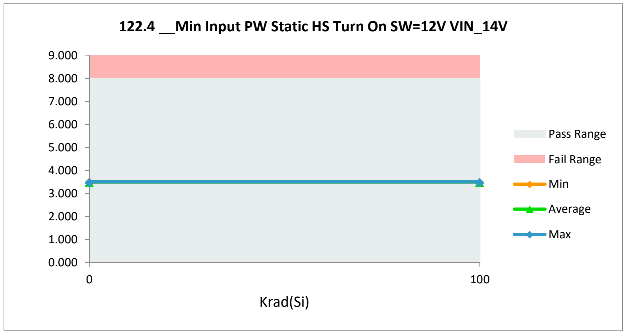


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		122.4 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	8	8	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	3.500	3.500	0.000
0	2	3.500	3.500	0.000
100	23	4.000	3.500	-0.500
100	24	4.500	3.500	-1.000
100	25	4.000	3.500	-0.500
100	26	3.500	3.500	0.000
100	27	4.000	3.500	-0.500
100	48u	3.500	3.500	0.000
100	49u	3.500	3.500	0.000
100	50u	3.500	3.500	0.000
100	51u	3.500	3.500	0.000
100	52u	3.500	3.500	0.000
	Max	4.500	3.500	0.000
	Average	3.708	3.500	-0.208
	Min	3.500	3.500	-1.000
	Std Dev	0.334	0.000	0.334

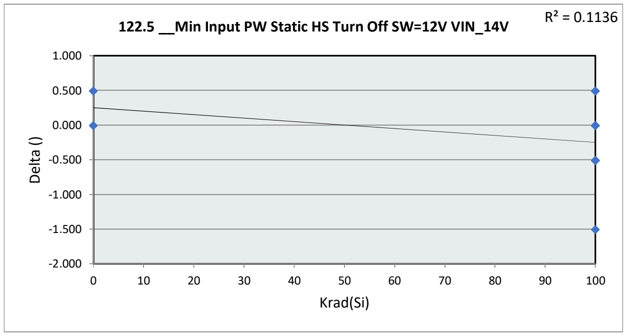


	122.4 __Min Input PW Static HS Turn On SW=12V VIN_1	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	8	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	3.500	3.500
Average	3.500	3.500
Max	3.500	3.500
UL	8.000	8.000

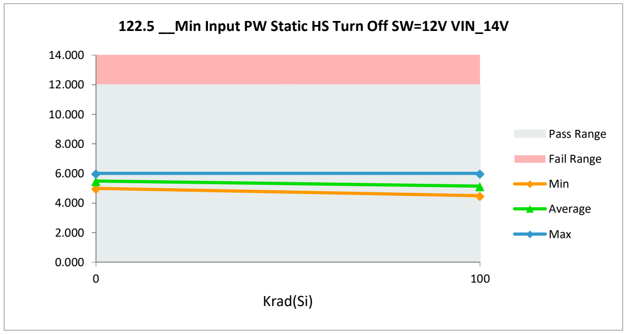


TID HDR Report
5962R2220106PYE (TPS7H6025-SP)

		122.5 __Min Input PW Static HS		
	Test Site	DAL-FL	DAL-FL	
	Tester	ETS364	ETS364	
	Test Number	EB937004	EB937004	
	Unit			
	Max Limit	12	12	
	Min Limit	0	0	
Krad(Si)	Serial #	Pre_6025	Post_6025	Delta
0	1	6.000	6.000	0.000
0	2	4.500	5.000	0.500
100	23	5.500	5.000	-0.500
100	24	6.500	5.000	-1.500
100	25	5.500	5.000	-0.500
100	26	5.500	6.000	0.500
100	27	6.000	5.500	-0.500
100	48u	5.000	5.000	0.000
100	49u	5.000	5.500	0.500
100	50u	5.000	4.500	-0.500
100	51u	5.000	5.000	0.000
100	52u	5.000	5.000	0.000
	Max	6.500	6.000	0.500
	Average	5.375	5.208	-0.167
	Min	4.500	4.500	-1.500
	Std Dev	0.569	0.450	0.577



	122.5 __Min Input PW Static HS Turn Off SW=12V VIN_	
Test Site	DAL-FL	
Tester	ETS364	
Test Number	EB937004	
Max Limit	12	
Min Limit	0	
Krad(Si)	0	100
LL	0.000	0.000
Min	5.000	4.500
Average	5.500	5.150
Max	6.000	6.000
UL	12.000	12.000



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